

DISSERTATION

FUNDAMENTAL INVESTIGATIONS OF HYDROCARBON PLASMA CHEMISTRY:
MECHANISTIC STUDIES OF GAS-PHASE PROCESSES
AND PLASMA-SURFACE INTERACTIONS

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ABSTRACT

FUNDAMENTAL INVESTIGATIONS OF HYDROCARBON PLASMA CHEMISTRY: MECHANISTIC STUDIES OF GAS-PHASE PROCESSES AND PLASMA-SURFACE INTERACTIONS

Pollution arising from industrial and vehicular combustion continues to cause increasing environmental concerns. Non-thermal plasma (NTP) technology has attracted growing interest as a pollution abatement strategy because the highly reactive chemical environment can enhance decomposition and conversion of pollutants (e.g., volatile organic compounds, nitrogen oxides) at ambient conditions. When NTP is combined with a catalyst a synergistic effect is often observed, whereby the catalyst-plasma coupling enhances the overall process; however, the implementation of plasma-assisted catalysis (PAC) is currently inhibited by a lack of knowledge on the fundamental processes contributing to observed plasma-catalyst synergies. Understanding both the roles of the catalyst and the plasma as well as the interactions occurring at the plasma-catalyst interface in a PAC system can help the community efficiently utilize plasma-catalysis systems. As such, fundamental investigations focused on gas-phase processes and plasma-surface interactions are considered vital to the future of PAC development.

The research presented within this dissertation aims to elucidate molecular-level processes in environmentally relevant low temperature plasmas (e.g., CH₄, H₂, N₂) via a suite of spectroscopic techniques and complementary materials analyses in an effort to advance plasma technologies like PAC. Plasma diagnostic tools are employed to evaluate kinetic and energetic processes for multiple molecular species in low-temperature, inductively-coupled plasma

systems with precursors of increasing complexity, including CH₄-based mixed gas systems. A primary goal of this work has been the determination of molecular temperatures [i.e., rotational (T_R) and vibrational (T_V) temperatures] within PAC systems via optical emission spectroscopy (OES). This emphasis comes from the estimation that these values collectively represent a key component to understanding the reactions that drive the chemistry and the mechanisms involved in plasma-surface interactions. Formation and destruction rates of excited state plasma species derived from time-resolved OES (TR-OES) studies are another metric used to evaluate fundamental gas phase processes and provide additional insight into formation mechanisms and decomposition pathways.

Chapter 3 includes a discussion on $T_R(\text{CH})$ and $T_V(\text{CH})$ values in 100% CH₄ and CH₄/Ar plasma systems as functions of plasma parameters (e.g., pressure, power). Yet, one important consideration with internal plasma temperature determination is that different molecular species within the same plasma system may exhibit vastly different rotational and vibrational temperatures. Thus, examining several molecular species within a plasma system provides enhanced insight into the overall plasma chemistry. Additionally, a single plasma species may be produced via different mechanisms (e.g., direct impact excitation, decomposition, recombination) and may exhibit different T_R or T_V values as a function of plasma parameters. Chapter 4 expands on the studies presented in Chapter 3 by including an evaluation of $T_R(\text{H}_2)$ values in a 100% CH₄ plasma. Generally, $T_R(\text{CH})$ values (~1700 – 2100 K) are much higher than $T_R(\text{H}_2)$ values (~500 – 700 K) in a 100% CH₄ plasma. These disparate values likely result from a combination of the differences in the species densities, radiative lifetimes, and consequently their excitation pathways. $T_R(\text{H}_2)$ values and trends are also compared to a 100% H₂ plasma where excitation mechanisms for H₂ are expected to differ from a CH₄ plasma.

The addition of a catalyst to plasma can significantly alter the gas phase chemistry of the plasma. The impact of a TiO₂ catalyst on plasma energetics and kinetics is explored in H₂ (Chapter 5), CH₄ (Chapter 5), and N₂ (Chapter 6) discharges. The introduction of TiO₂ into the discharge has minimal effect on $T_R(\text{H}_2)$ in a 100% H₂ plasma but reduces $T_R(\text{H}_2)$ values by up to 300 K in a 100% CH₄ plasma. Time-resolved OES studies echo energy partitioning results and reveal further details about the kinetics of H₂ formation and the impact of the catalyst on gas-phase processes. Comprehensive materials analysis of the catalyst before and after plasma exposure reveals that the H₂ plasma acts as primarily an etching system whereas competing etching and deposition processes may be occurring under some conditions in CH₄ plasma system. The presence of the catalyst in the N₂ discharge resulted in a pronounced decrease of N₂ vibrational temperatures while no clear or significant impact on the rotational temperature was reported.

Gas-phase studies of increasingly complex environmentally relevant systems (i.e., mixed gas CH₄/H₂O and CH₄/N₂ plasmas) and additional molecules (i.e., CN, CO, OH) are also investigated and presented in Chapter 7 of this dissertation. Determination of rotational and vibrational temperatures for several molecular species in each plasma system demonstrate that the excited state species in our systems are not equilibrated with each other and that different species have achieved different degrees of equilibration between rotational and vibrational modes. When combined with energy partitioning results, TR-OES data provide further insight into molecule formation pathways.

The results presented within this dissertation help to establish the relationship between system parameters and the kinetic and energetic outcomes. Such information is crucial for developing systems that can potentially be implemented at the industrial level. Combined with

gas-phase analysis, complementary materials characterization of the catalyst provides a holistic approach towards understanding plasma-surface interactions and unraveling the fundamental chemical processes that occur during plasma processing. Overall, the results presented within this dissertation emphasize the intimate connections between the catalyst, plasma parameters (e.g., precursor, pressure, power), and fundamental plasma properties, all crucial components to understanding and optimizing plasma conditions for PAC.

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CHAPTER 1

INTRODUCTION

This chapter provides information on the premise and motivation behind the work detailed within this dissertation. A brief introduction to plasma chemistry and plasma deposition processes in hydrocarbon plasma systems are first presented to outline the inherent convoluted nature of the plasma systems used in this research. Plasmas are useful for a host of potential applications (e.g., materials fabrication and processing, waste gas remediation) and thus, are of significant interest to the scientific community as well as to manufacturing and industry; however, the lack of understanding of the fundamental processes occurring in plasma systems severely hinders their utility in many applications. To fully utilize the advantages of plasmas, information on energy partitioning, kinetics, plasma-surface interactions, and other mechanistic phenomena occurring in these systems must be developed and integrated into real-world applications and device design. A discussion on approaches for analyzing the inherently complex nature of these environments is included within this chapter, along with an overview of the research presented within the remainder of the dissertation.

1.1 Plasma Chemistry

The term “plasma” describes a partially-ionized gas comprising ions, electrons, radicals, and neutral atoms or molecules in ground and excited states.¹ Plasmas occur naturally (e.g., lightning, auroras) but can also be created under laboratory conditions where they are useful for a variety of commercial applications including pollution remediation, medical sterilization, and semiconductor processing, among a myriad of other surface modification applications. The

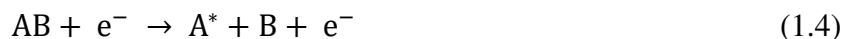
research in this dissertation aims to unravel underlying chemical processes occurring in these multi-faceted systems to further advance several technologies. Specifically, the work described within this dissertation investigates radio frequency (rf) inductively coupled non-thermal plasma (NTP) systems, wherein local thermodynamic equilibrium is not achieved. In NTP discharges, the electron temperature (T_e) exceeds the ion temperature (T_i) by up to two orders of magnitude.¹ This energy distribution is favorable in many plasma technology applications because the relatively “cold” ions and neutral species can be controlled via a range of plasma parameters to promote specific types of chemical reactions.

In general, the ignition of a plasma discharge occurs when an electric field is applied to a volume of gas causing acceleration of free electrons and sequential collisions with other gas species. In this way, a cascade of electron-mediated interactions sustains the plasma discharge. Inelastic collisions between electrons and gas species, wherein nearly all of the electron’s energy is transferred to its collision partner,¹ allow a variety of reactions to take place within these discharges:



These reactions describe electron impact ionization, excitation, and dissociation, respectively.

Reaction 1.3 can also result in an electronically excited radical A or B. This dissociative excitation process is generically illustrated in reaction 1.4.



Plasma discharges involve many different reactions, such as the ones shown above. Even with a relatively simple precursor gas, the inherent complexity of the chemistry occurring within

these systems is apparent. In many applications, these systems are even more complicated by the use of several precursors or gas mixtures containing larger molecules. Moreover, aside from gas feed composition, additional plasma parameters (e.g., pressure, applied power, substrate identity and position) can considerably influence the chemistry occurring within the discharge.

Through plasma diagnostic techniques, characteristic plasma temperatures may be measured from the plasma to construe information on the chemical processes occurring within the discharge and aid in unraveling the mechanistic phenomena in the system. Beyond the aforementioned T_e and T_i , there are a number of characteristic energies that can be monitored within plasmas.¹ Specifically, vibrational (T_V) and rotational (T_R) temperatures of several plasma species will be discussed throughout this dissertation. Some of these temperatures are influenced by plasma parameters, including the presence and type of substrate placed within the discharge, demonstrating the significant impact of the material on plasma chemistry.

Notably, the addition of a substrate to a plasma introduces additional variables to the plasma systems as both the chemical and morphological nature of the substrate can significantly influence plasma chemistry. Indeed, the bulk of plasma applications involve etching, deposition, or functionalization of a material as routes toward surface modification, whereas other plasma applications (e.g., atmospheric remediation applications) utilize gas-surface interactions to ultimately influence the gas-phase chemistry. Although plasmas are widely employed for such applications, the gas-phase chemistry and plasma-surface interactions that lead to the desired surface modification or waste-gas conversion outcomes are often poorly understood. To more efficiently utilize plasmas for materials processing and gas-feed conversion or decomposition, an understanding of the molecular-level processes occurring in these systems is imperative.

Our efforts to unravel the chemistry of these systems focus on understanding the intricate interplay between each of the three distinct regions of the plasma-surface composite [(1) gas-phase, (2) substrate, (3) plasma-substrate interface], Figure 1.1. Each of these regions are theoretically tunable, although it requires a significant amount of fundamental knowledge of the molecular-level processes occurring throughout a wide parameter space and understanding the role that each specific parameter has on the chemistry of the system. Both the material and plasma impact the chemistry in these systems. Thus, we aim to specifically understand both the impact that the material has on the gas-phase plasma chemistry and the plasma's impact on the chemistry of material post plasma exposure. Throughout this dissertation, optical diagnostic techniques are employed as a means to elucidate key chemical processes occurring in the plasma discharge. These tools are used to identify key species and determine species kinetics and energy partitioning trends, which is of high interest to the plasma community.²⁻³ In addition, thorough characterization of the substrate prior to and post plasma exposure allows us to investigate the impact that the plasma has on the substrate morphology and chemistry. Our holistic approach to plasma diagnostics and materials characterization provides insight to the chemistry occurring in the bulk plasma, at the plasma-surface interface, and within the material of interest. As such, this dissertation seeks to contribute to the plasma community by providing a foundational basis of key chemical processes occurring in low temperature plasmas.

1.2 Plasma-Enhanced Chemical Vapor Deposition

As mentioned above, the use of NTP for plasma processing of materials is of significant interest among the scientific and industrial communities because the non-thermal nature of the plasma allows for a reactive, low temperature (gas temperature < 1000 K) environment to

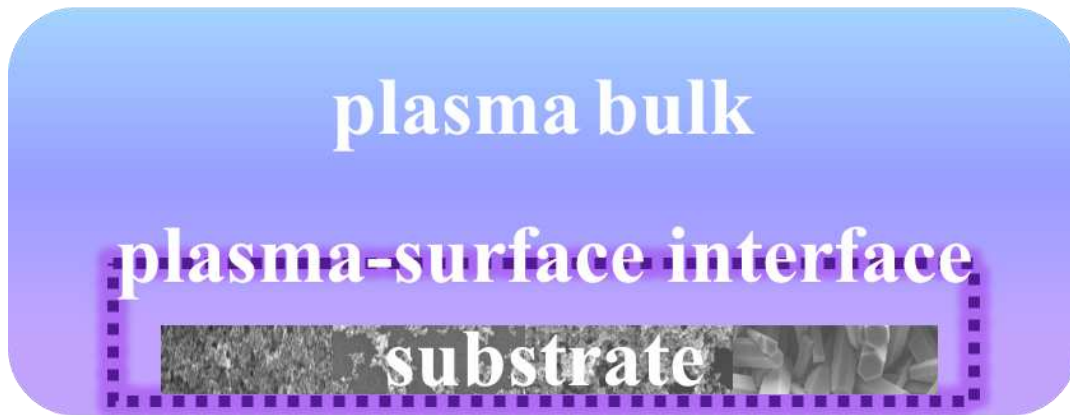


Figure 1.1. An illustrative representation of the three distinct regions of the plasma-surface composite: the plasma bulk, plasma-surface interface, and substrate.

modify materials.¹ Moreover, NTP environments typically offer a wide, tunable parameter space (e.g., precursors, pressure, power) to tailor materials properties for desired applications. As such, NTP are useful for plasma processing because they can modify surfaces via (1) etching of the material, (2) implanting functional groups with a desired chemistry, or (3) deposition of a film via plasma-enhanced chemical vapor deposition (PECVD).¹ In some cases, these modification schemes occur simultaneously and are often in competition with each other. Controlling plasma parameters offers a mechanism for potentially enhancing one process over another. PECVD is discussed here because it often dominates carbon-containing systems, such as those employed here (e.g. CH₄).

PECVD offers several advantages over other methods for thin film deposition, such as thermal CVD, which requires high (≥ 500 °C) operating temperatures and is often limited by mass transport velocity, leading to poor film quality.⁴⁻⁵ Because of the non-thermal nature of low-temperature plasmas, film growth via PECVD can be performed at much lower temperatures (~100 – 500 °C), thereby, reducing the probability of substrate damage. In addition, PECVD allows conformal film deposition over larger areas making this technique suitable for a variety of substrates. For example, the Fisher group has previously shown that plasma co-polymerization can be achieved via PECVD on relatively delicate three-dimensional scaffold materials for biologically-relevant systems by producing films that conformally coat the porous structure without compromising the architecture of the material.⁶ PECVD has been used to deposit a variety of materials,⁷⁻¹¹ but it finds the most utility in the deposition of amorphous materials, such as amorphous carbon and silicon materials. As noted above, we observe amorphous carbon film deposition in the systems studied here and although this process can be viewed as competing with the overall target of converting CH₄ through a gas-phase catalytic transformation

in plasma-assisted catalysis systems, it can also be viewed as a potential sink for the CH₄. One potential downside to the formation of carbon layers on our catalysts is that this coating could reduce or ultimately eliminate the catalytic activity of the catalytic materials being employed. Concomitant etching within the plasma systems could slow film deposition and thereby mitigate this “poisoning” of the catalyst. These ideas are further explored below and in subsequent chapters.

1.3 Motivation for Research

1.3.1. Bridging Plasma Diagnostics and Film Properties in Plasma-Enhanced Chemical Vapor Deposition Systems. Production of diamond-like carbon (DLC) films, amorphous carbon consisting of varying ratios of sp² and sp³ hybridized carbon and hydrogen, is often accomplished via PECVD.¹²⁻¹³ High hardness, low friction, and chemical inertness are among a few of the properties of DLC films that make them useful for applications in protective coatings, optics, and electronics.¹⁴⁻¹⁶ Several hydrocarbon precursors have been used in PECVD systems for deposition of DLC films, but C₂H₂ and CH₄ are the most commonly used precursors because of their relatively simple dissociation patterns and low bias voltages required for quality DLC fabrication.¹² It is well known that DLC properties are strongly affected by the relative sp² and sp³ hybridization ratios; thus, other gases, such as H₂ and Ar, are typically added to the hydrocarbon gas feed to create active sites and tune the sp²/sp³ ratio to tailor material properties.^{12, 17}

The bulk of the research presented within this dissertation reports on CH₄ plasma chemistry; consequently, as noted above, amorphous hydrocarbon films, a type of DLC film, are deposited in nearly all of the studies described within this document. Characteristics of DLC

films deposited via PECVD have been thoroughly analyzed with respect to various plasma parameters by several researchers.^{14-16, 18-19} However, the relationship between such plasma parameters and resulting film characteristics is poorly understood, making it tedious and time-consuming to reproduce similar coating technologies in different reactor set-ups.^{5, 13} One approach to overcome this hurdle is to utilize plasma diagnostic techniques to elucidate the molecular-level processes occurring in the plasma bulk and correlate these plasma characteristics with resulting DLC film properties.

Several plasma diagnostic techniques have been used to study carbon-containing plasmas such as Langmuir probes,²⁰⁻²² optical absorption and emission spectroscopies,^{13, 23-24} and mass spectrometry.²⁵⁻²⁶ Each of these plasma diagnostic techniques has distinct advantages and disadvantages; thus, it is ideal to use an approach involving several of these methods to comprehensively characterize the gas-phase chemistry. For example, Langmuir probes are a common method for determining the electron energy distribution within the plasma, but it is an intrusive characterization technique that perturbs the plasma environment.¹ Optical emission spectroscopy (OES), on the other hand, is a non-intrusive diagnostic technique that can provide information on key gas-phase species, species densities, and energy partitioning trends. Such information provided by OES is essential in illuminating gas-phase mechanisms that may be crucial to the formation of key species involved in hydrocarbon film deposition. This technique is, however, limited to excited state, light-emitting species, and the emission intensity is not always directly related to species concentration.¹

To further illustrate the importance of using plasma diagnostics, Anooshehpour *et al.* employed a partial least squares regression modelling approach to find the correlation between both deposition process parameters (i.e., bias voltage, plasma duty cycle, plasma pressure,

applied power) and OES data (i.e., FWHM of H_{α} line, actinometry) with DLC structural and mechanical properties.¹³ Although bias voltage was an essential component to keep in any model for controlling film deposition, the authors found that all other plasma parameters studied could be replaced by OES data to predict DLC properties. This finding provides basis for using plasma diagnostic techniques to understand and control plasma processes and ultimately, overcome the hurdle of establishing the relationship between reactor-dependent plasma parameters and materials properties.

In addition to probing the gas-phase chemistry in PECVD systems, information about gas-surface interactions provides valuable insight into DLC film formation and characteristics. The Fisher research group has previously investigated the gas-surface interface in CH_4 -containing plasma systems using imaging of radicals interacting with surfaces (IRIS), a laser-induced fluorescence-based technique. Zhou *et al.* reported the surface reactivity of CH radicals to be near unity with no dependence on several plasma parameters, suggesting that CH radicals have a significant impact on the properties of amorphous hydrocarbon films despite their relatively low gas phase density.²⁷ Such information on gas-surface interactions is currently limited but is crucial to advancing plasma technologies for PECVD applications. Furthermore, when diagnostic techniques such as OES and IRIS are used in conjunction with material characterization techniques to analyze a film's chemistry and morphology, molecular-level information essential to deciphering the relationship between such plasma parameters and resulting film characteristics can be construed. Gaining an understanding of the chemistry occurring in PECVD plasma systems, specifically those used for DLC film deposition, can allow us to provide more control over the deposition of carbon materials by creating a tunable space to tailor a material's properties for desired applications.

1.3.2. Addressing the Need for Fundamental Investigations of Plasma-Assisted Catalysis

Processes. Plasma-assisted catalysis (PAC), or the coupling of a plasma with a catalyst, is a widely applicable tool that has been used for treatment of waste gas,²⁸⁻²⁹ ammonia synthesis,³⁰ hydrogen production,³¹⁻³² hydrocarbon reforming,³³⁻³⁶ and fabrication of carbon nanostructures.³⁷⁻³⁸ For example, in PECVD systems used for fabrication of carbon nanostructures, a hydrocarbon plasma is typically brought into contact with a catalyst (usually Ni, Fe, or Co).³⁹ The non-thermal nature of the plasma employed in PAC systems allows for access to processes that are energetically unavailable under thermal conditions and thus, has an enormous potential to increase gas feed conversion.⁴⁰⁻⁴² PAC also improves upon energy efficiency and reduces unwanted byproduct formation in waste gas conversion and decomposition of nitrogen oxides and volatile organic compounds (VOCs) compared to use of either NTP or catalysis alone.^{3,43} Regardless of the application, the future of this emerging technology resides on a more comprehensive understanding of the inherently complex plasma-catalyst system.

Optimization of PAC setups (e.g., reactor design, plasma process parameters, catalyst choice) currently remains a challenge within the community and is typically approached by trial and error processes. To date, many experimental studies have focused on parametric optimization for increasing process performance⁴⁴⁻⁴⁷ and how plasma exposure affects the material.⁴⁸⁻⁴⁹ Few studies have, however, focused on elucidating the influence of the catalyst on the fundamental physical characteristics of the plasma discharge, and thus, the underlying mechanistic phenomena of PAC processes are still largely unknown, reducing its overall applicability. To improve PAC applications, it is crucial to understand the underlying physiochemical mechanisms to be able to optimize processing conditions.

The combination of the plasma and catalyst can affect processes occurring in the gas phase and on the catalyst surface. For example, the plasma can modify the morphology and chemical composition of the catalyst.^{37, 50} Additionally, the catalyst's properties (e.g., roughness, dielectric constant) can alter the electrical properties of the plasma and ultimately affect the physiochemical properties of the plasma [e.g., electron energy distribution (EEDF)].^{37, 50} For example, Tu *et al.* demonstrated a change in discharge behavior (i.e., less filaments and more surface discharges) and an ultimate increase in the high energy tail of the EEDF upon packing their reactor bed with TiO₂ pellets.⁵¹ Similarly, zeolites⁵² and other ferroelectric materials⁵³ have been known to enhance the electric field. While an enhancement of the electric field is a physical effect, this can directly influence the chemistry of the plasma by altering the EEDF. Consequently, the electron impact dissociation and ionization rates are impacted, which ultimately determine the chemical composition of the plasma.

Overall, the mutual dependence of the plasma and catalyst properties results in an intricate system wherein the plasma and the catalyst can interact synergistically.^{3, 40, 54} In PAC systems, feed gas conversion is often enhanced as the plasma modifies/activates both the precursor gas and the material surface, such that the plasma-catalyst combination yields improved results over either component acting alone. The origin of this synergistic environment, however, is not yet well understood.^{3, 40, 50} Thus, both the chemistry in the plasma and at the surface of the catalyst are affected by the intricate interplay between the two. Given the resulting enhancement of the complexity inherent to plasma-surface interactions, fundamental investigations of gas-phase plasma species and plasma-surface interactions are required to increase the effectiveness of PAC. Knowledge of the roles of gas-phase radicals and radical-surface interactions is key to understanding overall plasma chemistry. To further illuminate the

effect of the catalyst on the plasma environment, it is vital to investigate the gas-phase chemistry of the plasma both with and without a catalyst. Specifically, an understanding of how energy is partitioned into vibrational, rotational, and translational modes provides insight into formation mechanisms, decomposition pathways, and overall plasma chemistry. Figures of merit such as T_R and T_V describe the energetics of species within the plasma system. Moreover, information gleaned from these internal temperatures and trends can expound the overall character of the plasma.

Our holistic approach towards comprehensive analyses of plasma systems aims to address the paucity of fundamental plasma information currently limiting PAC technologies. We examine the impact of the plasma on the catalyst by exploiting chemical and morphological characterization techniques to assess the material prior to and post plasma exposure.

Additionally, we investigate the impact that the catalyst has on the chemistry of the plasma via optical spectroscopy techniques, which allow us to non-intrusively probe the bulk plasma region and ultimately elucidate the kinetic and energetic characteristics of the system. Understanding both the roles of the catalyst and the plasma as well as the interactions occurring at the plasma-catalyst interface in a PAC system can help the community bypass trial-and-error approaches to optimizing plasma-catalysis systems. As such, investigations focused on gas-phase processes and plasma-surface interactions are considered vital to the future of PAC development.

1.4 Research Overview

The work described within this dissertation aims to elucidate molecular-level processes in low temperature plasmas via a suite of spectroscopic techniques and complementary materials analyses in an effort to advance plasma technologies. A comprehensive investigation into each

region of a plasma-substrate system [(1) gas-phase, (2) substrate, (3) plasma-substrate interface] is critical to understanding the underlying phenomena contributing to plasma processes. A primary goal of this work has been the determination of molecular temperatures within plasma systems. This emphasis comes from the estimation that these values collectively represent a key component to understanding the reactions that drive the chemistry and the mechanisms involved in plasma-surface interactions. Moreover, these data help to establish the relationship between system parameters and energetic outcomes. Such information is crucial for developing systems that can potentially be implemented at the industrial level. Combined with gas-phase analysis, complementary materials characterization provides a holistic approach towards understanding plasma-surface interactions and unraveling the fundamental chemical processes that occur during plasma processing. Chapter 2 details the techniques utilized in this experimental approach.

Chapter 3 serves as the foundation of the work reported in this dissertation as all subsequent chapters build upon the results reported in this chapter. Chapter 3 reports on energy partitioning trends of $\text{CH A}^2\Delta \rightarrow \text{X}^2\Pi$ in 100% CH_4 and CH_4/Ar plasma systems. Here, $T_R(\text{CH})$ and $T_V(\text{CH})$ are presented with respect to plasma pressure and applied rf power parameters. In addition, chemical and morphological properties of amorphous hydrocarbon films deposited on glass slides and silicon wafers by these plasma systems are analyzed. Gas-phase analysis and material properties are linked and discussed.

The dissociation of CH_4 , which has applications in several plasma technologies including the fabrication of carbon materials⁵⁵⁻⁶⁰ and PAC systems,⁶¹⁻⁶² has been studied extensively.^{59, 61-64} Notably, a hydrogen-rich plasma environment is created during CH_4 dissociation,⁶⁵⁻⁶⁶ thus, it is essential to consider the roles of hydrogen species when elucidating mechanistic processes occurring in CH_4 plasmas. We have measured $T_R(\text{H}_2)$ in addition to determining energy

partitioning trends for CH. These results are described in Chapter 4 where we employed OES to investigate energy partitioning in H₂ and CH₄ inductively coupled plasma systems. In 100% H₂ plasmas, $T_R(\text{H}_2)$ values are ~500 – 550 K, whereas generally higher $T_R(\text{H}_2)$ values (~500 – 700 K) are reported for 100% CH₄ plasmas. These results highlight the differences in the H₂ excitation pathways occurring in each of these two plasma systems. As such, mixed gas CH₄/H₂ plasma systems were also explored to gain further insight into these mechanistic details.

Results discussed in Chapter 5 expand upon gas-phase studies in H₂ and CH₄ plasmas by introducing a TiO₂ catalyst into the discharge. More specifically, Chapter 5 details both a gas-phase analysis of the plasma discharge and a comprehensive material analysis of the catalyst before and after plasma exposure to elucidate the contributions of both the plasma and the catalyst in a model PAC system. Energetics and kinetics of multiple excited state species are evaluated and discussed. Furthermore, materials analysis also demonstrates the impact that the plasma has on the catalyst's properties. For example, XPS data show the presence of an amorphous hydrocarbon film after exposure to the CH₄ plasma system. Additionally, Raman data reveal the presence of oxygen vacancies in the material after plasma exposure.

Additional PAC studies are presented in Chapter 6 where the impact of TiO₂ on fundamental gas phase properties is examined in a 100% N₂ plasma. The addition of the catalyst to the discharge introduces additional excited state species (e.g., NO, OH) and significantly reduces $T_V(\text{N}_2)$. XPS analysis reveals incorporation of nitrogen into the TiO₂ catalyst. Moreover, an increase in adsorbed surface oxygen and reduction of Ti are also noted post plasma exposure. Together, these results suggest the possibility of several surface modification processes that may be occurring during N₂ plasma processing.

Chapter 7 examines plasma systems of increasing complexity. Specifically, gas-phase data for mixed gas CH_4/N_2 and $\text{CH}_4/\text{H}_2\text{O}$ plasmas provide insight on how plasma parameters affect gas-phase chemistry in these plasma systems of interest to real-world catalysis applications. OES spectra indicate the presence of key species in these systems, including the formation of CN and CO in the CH_4/N_2 and $\text{CH}_4/\text{H}_2\text{O}$ systems, respectively. Relative densities, kinetics, and energy partitioning trends of several excited state species (e.g., CH, CN, H_2 , OH, and N_2) are assessed within these mixed gas systems to illuminate mechanistic details of gas phase processes in these systems.

A summary of the entire dissertation work is presented in Chapter 8. Future avenues of investigation for this project are also briefly discussed. Overall, the results presented within this dissertation emphasize the intimate connections between the catalyst, plasma parameters (e.g., precursor, pressure, power), and fundamental plasma properties, all crucial components to understanding and optimizing plasma conditions for plasma technologies.

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CHAPTER 2

EXPERIMENTAL METHODS

This chapter describes the materials, methods, and instrumentation used to complete the materials characterization and gas-phase analyses described within this dissertation. The information described within this chapter comprises five sections: plasma reactor set up and plasma conditions (2.1), materials preparation (2.2), materials characterization techniques (2.3), optical spectroscopy techniques (2.4), and characteristic plasma temperature determination (2.5).

2.1 Plasma Systems

All inductively coupled plasmas (ICP) studied herein were ignited in two different styles of glass tubular-style reactors via coupling of radio frequency (rf) power through an eight-turn Ni-plated Cu coil. Precursor gases used in this work include CH₄ (Air Products, >99.97% purity), H₂ (Airgas, 99.9%), N₂ (Airgas, >99.99%), and Ar (Airgas, >99.999% purity). A liquid precursor, deionized H₂O (Millipore, 18 mΩ cm⁻¹), was placed in a 50 mL borosilicate sidearm vacuum flask equipped with a Teflon™ stopcock and subjected to three consecutive freeze-pump-thaw cycles to remove dissolved atmospheric gases prior to use. In the experiments described Chapters 3 – 5 and Chapter 7, plasmas were ignited in a reactor created from two borosilicate glass tubes joined with a 50 mm o-ring joint allowing for easy access to the interior of the plasma reactor, Figure 2.1a.¹ The joined tubes create a reactor 35 cm in length, and the interior wall of the reactor has a diameter of 4.5 cm. In addition, a replaceable quartz window is centrally affixed to the downstream end of the reactor to allow for coaxial collection of plasma emission. In some experiments described in Chapter 5, a replaceable quartz window was also

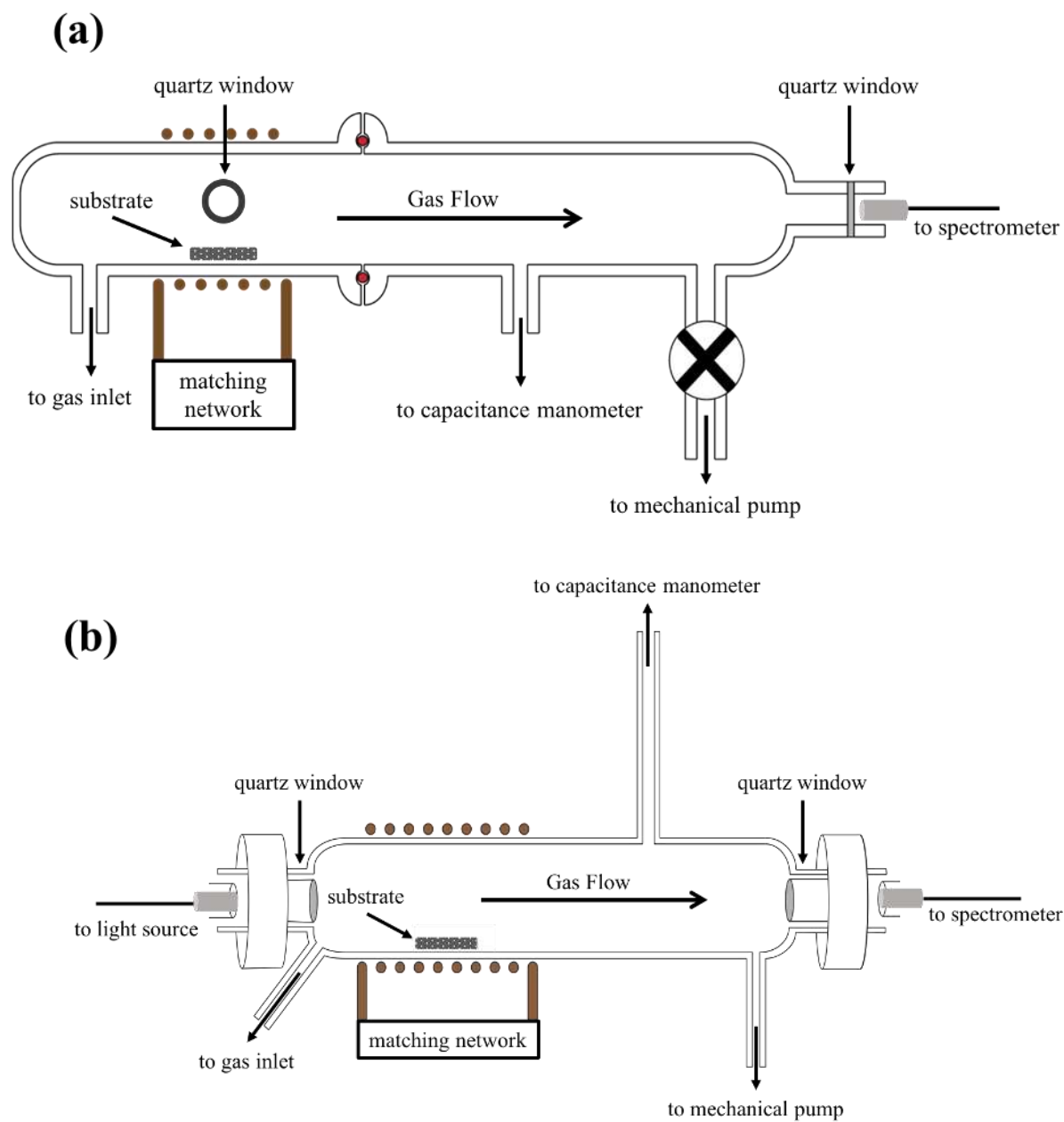


Figure 2.1. Schematics of glass barrel ICP reactors used for (a) OES and film deposition studies and (b) N₂ plasma OES and CH₄ plasma BAS data collection.

utilized on the inlet half of the reactor to monitor relative species densities directly above the substrate. For the experiments described in Chapter 6, plasmas were ignited in a separate reactor, Figure 2.1b, to reduce the possibility of hydrocarbon contamination from the interior walls of the plasma reactor. The reactor setup shown in Figure 2.1b is a modified version of the reactor in Figure 2.1a. This reactor is similar in size with a 24 cm length and 4.5 cm inner diameter.² With the addition of an upstream quartz window, the modified reactor allows for the collection of plasma absorption spectra in addition to emission spectra. Thus, the type of reactor shown in Figure 2.1b was also used for collection of broadband absorption spectroscopy (BAS) data in Chapter 8. Base pressure of the CH₄, H₂, and mixed gas plasma systems ranged from ~12 – 15 mTorr whereas base pressure for the 100% N₂ system was ~2 – 4 mTorr. Gas flow for these reactors was maintained by either a series of needle valves or MKS mass flow controllers, and pressure (*p*) ranged from 50 – 200 mTorr and was monitored by a Baratron® capacitance monometer. For all experiments, power (*P*) values ranged from 25 to 150 W and was applied by rf power at 13.56 MHz via a matching network.

2.2 Materials Preparation

For the purpose of characterizing the amorphous hydrocarbon (HC) films in Chapter 3, clean glass slides (VWR micro slides, plain, 1.2 mm thickness) cut to ~5 cm × 5 cm were used as the substrate material. Commercially purchased TiO₂ AEROXIDE P25 nanopowder (Acros Organics, 21 nm primary particle size) substrates were made by creating a slurry of as received nanoparticles and methanol, as described previously.³ The nanoparticles (NP) were suspended in methanol until saturation; then the NP solution dropcast on to glass slides and p-type <100> silicon wafers (Wacker-Chemitronic GMBH, Germany) of ~3 × 3 cm. All substrates used were

placed in the coil region of the plasma reactor ~30 cm upstream from the quartz window, as shown in Figure 2.1.

2.3 Materials Characterization

2.3.1. X-ray Photoelectron Spectroscopy (XPS). Surface compositional analysis of HC films and catalytic materials prior to and after plasma exposure was performed using a PHI-5800 Electron Spectroscopy for Chemical Analysis system (Chanhassen, MN, USA) equipped with a monochromatic Al $K\alpha$ X-ray source (1486.6 eV photons). Three distinct spots on at least two different samples ($n \geq 6$) were analyzed at a 45° takeoff angle. Survey spectra were collected for 5 minutes over a range of 10 – 1100 eV to obtain approximate elemental composition. High resolution spectra were collected for 20 minutes for elements present in $> 1\%$ in the survey scan including C_{1s} and O_{1s} spectra, and N_{1s} and Ti_{2p} in relevant cases. CasaXPS v2.3 was used to deconvolute spectra and to determine atomic percent compositions. Charge correction of binding energies was performed by setting the C_{1s} aliphatic carbon signal to 285.0 eV. Peak FWHMs values were constrained to ≤ 2.0 eV.

2.3.2. Fourier Transform Infrared (FTIR) Spectroscopy. Film composition was also explored via FTIR spectroscopy using a Thermo Scientific Nicolet Magna 760 spectrometer (Madison, WI), with a resolution of 4 cm^{-1} and 256 averaged scans. The spectrometer was purged for > 2 hours with N_2 gas before spectra of the films deposited on pressed KBr pellets (FTIR-grade, Sigma-Aldrich, St. Louis, MO, USA) were collected. Atmospheric and baseline corrections were applied to all spectra via the onboard software (Omnice v8.2) to suppress any signals arising from water vapor or CO_2 .

2.3.3. Optical Profilometry. Film morphology was assessed on HC films deposited on glass slides with a Zygo ZeScope optical profilometer (Middlefield, CT). Single scans were collected over a $250 \times 350 \mu\text{m}$ area using a $20\times$ magnification objective lens. A scan length of $100 \mu\text{m}$ in the z-axis and a signal threshold of 0.5% were used to assess the films. At least three scans were collected on three different samples ($n \geq 9$) to ensure accurate representation of the film morphology and roughness.

2.3.4. Water Contact Angle (WCA) Goniometry. A Krüss DSA 30S contact angle goniometer (Matthews, NC) was utilized to acquire surface wettability data. The static WCA for each film deposited on a clean glass slide ($3 \times 3 \text{ cm}$) was measured by capturing an image of a $2\text{-}\mu\text{L}$ drop of ultrapure water (Millipore, $18 \text{ m}\Omega \text{ cm}^{-1}$) stabilized on each substrate surface. WCAs were measured using the tangent fitting method for each film investigated. Values reported are the average and standard deviation of $n \geq 6$ where at least two measurements were acquired on three separate samples.

2.3.5. Scanning Electron Microscopy-Energy Dispersive Spectroscopy (SEM-EDS). Material morphology and chemical composition pre and post plasma exposure was evaluated via assessment of SEM-EDS images. Prior to imaging, silicon substrates were mounted on an aluminum stub with copper tape. SEM and EDS data were obtained via a JSM-6500F (JEOL, Ltd., Japan) scanning electron microscope equipped with a field emission source; an accelerating voltage of 15.0 kV and $\sim 10 \text{ mm}$ working distance were used.

2.3.6. Raman Spectroscopy. Raman spectroscopy was performed on TiO_2 substrates prior to and after plasma exposure on an Olympus IX-73 optical microscope with an OndaxTHz-Raman laser source (5 mW , 532 nm laser with $1.2 \mu\text{m}$ spot size). The Raman signal was collected in a backscattering geometry, passed through a Horiba iHR-550 imaging spectrometer,

and detected on a Synapse back-illuminated deep depletion charge-coupled device. Individual spectra were acquired for 30-60 seconds across a 1 mm × 1 mm sample area.

2.4 Optical Spectroscopies

Steady state optical emission spectra data reported in Chapters 3 – 5 and Chapter 7 were collected with an Avantes AvaSpec-3648-USB2 multichannel spectrometer. Four gratings (1200 lines/nm) each linked to a 3648-pixel charged-coupled device (CCD) detector over a wavelength range of 187 – 1016 nm and a 0.1 nm FWHM resolution are comprised within this spectrometer. OES and BAS data reported in Chapter 6 and Chapter 8 were collected with an Avantes AvaSpec-2048L-USB2-RM multichannel spectrometer. This spectrometer houses six gratings, each linked with a 2048-pixel CCD detector and allows for simultaneous data collection over a wavelength range of 197 – 1061 nm.

For all OES and BAS data, a fiber optic probe was placed against a quartz window downstream from the coil, allowing for coaxial data collection along the length of the reactor to maximize signal intensity. Additionally, for some experiments described in Chapter 5, emission spectra were also collected through a quartz window placed in the coil region of the reactor. For BAS experiments (Chapter 8), an AvaLight-DHS deuterium-halogen lamp was interfaced with a quartz window on the upstream end of the plasma reactor. Integration time and number of averages collected depend on the specific experiment to maximize signal-to-noise ratios. A minimum of 3 trials were executed at each plasma parameter condition.

Actinometry was utilized where described to determine relative excited electronic state densities of several emitting plasma species. In these cases, a small amount of Ar ($\leq 10\%$ of total gas feed pressure) was added to the plasma, and the ratio of emission intensities for the species

of interest (X) are reported relative to Ar (750.4 nm) (I_X/I_{Ar}) to allow for comparison of species densities between systems. Table 2.1 contains a concise list of the emitting species analyzed and discussed within this document as well as the associated actinometric wavelengths and transitions.

Time-resolved optical emission spectroscopy (TR-OES) data were collected to study formation and decomposition mechanisms of species within our plasma systems. For enhanced temporal resolution, an AvaSpec-ULS4096CL-EVO spectrometer (10-micron slit; 0.5 nm spectral resolution) was used to monitor emission intensity of the species of interest as a function of time. Integration times for TR-OES experiments ranged from 1.5 ms to 25 ms, depending on the experiment. Figure 2.2a demonstrates that data collection began before plasma ignition and lasted for approximately ~4 – 10 seconds after ignition. For data analysis, the first non-zero data point was set at time (t) = 0.0 s and all subsequent data points were adjusted accordingly (Figure 2.2b). The point(s) of highest intensity in the temporal profile were identified, and the rise to maximum intensity is denoted as rate constant of formation (k_f). The subsequent decrease in signal intensity to a steady state is denoted as the rate constant of destruction (k_d). A first order exponential function (e^{-kt}) was used to fit the formation and destruction curves and ultimately obtain the k_f and k_d values reported herein (Figure 2.2b). In some cases, no clear formation or destruction curves were detected on the time scale of our system.

2.5 Characteristic Plasma Temperature Determination

2.5.1. Electron Temperature. An analysis of Ar emission lines yielded mean electron temperature (T_e) values calculated via Equation 2.1,⁴

$$\frac{(E_n - E_1)}{kT_e} = \ln \left[\frac{I_1 \nu_n A_n (E_n + 2kT_e)}{I_n \nu_n A_1 (E_1 + 2kT_e)} \right] \quad (2.1)$$

Table 2.1. Transitions and corresponding wavelengths used for actinometric analyses of selected species.

Emitting Species	Transition	Wavelength (nm)
Ar	$4p^1 \rightarrow 4s^1$	750.3
CH	$A^2\Delta \rightarrow X^2\Pi$	431.1
CN	$B^2\Sigma^+ \rightarrow X^2\Sigma^+$	388.3
H_α	$^2P^0 \rightarrow ^2D$	656.3
H_2	$d^3\Pi_u \rightarrow a^3\Sigma_g^+$	601.8
N	$4d^4P \rightarrow 3p^4P^0$	674.0
N_2	$C^3\Pi_u \rightarrow B^3\Pi_g$	337.1
NO	$A^2\Sigma^+ \rightarrow X^2\Pi$	235.9
O	$^3S^0 \rightarrow ^3P$	777.2
OH	$A^2\Sigma^+ \rightarrow X^2\Pi$	309.0

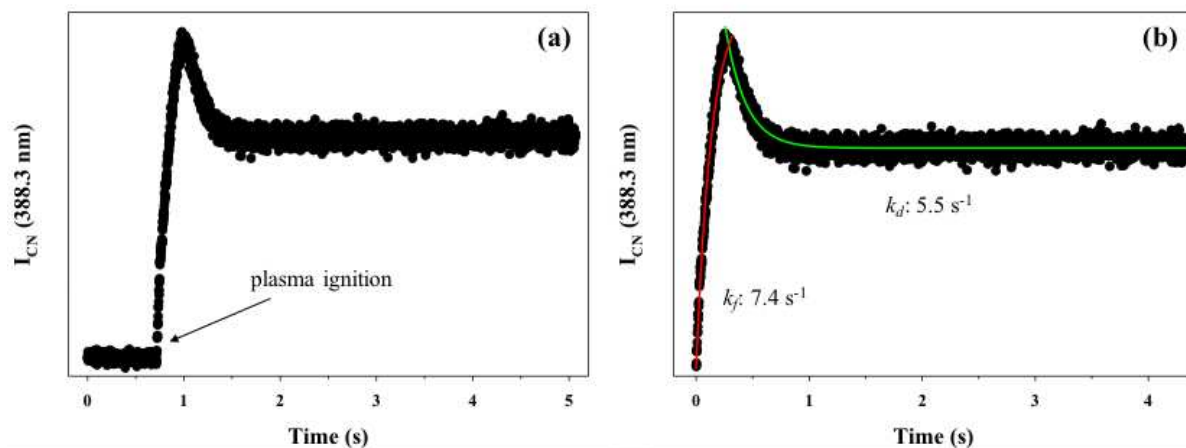


Figure 2.2. Time-resolved emission signal for CN in a 1:2 CH_4/N_2 plasma (150 mTorr, 75 W). Panel (a) displays raw emission data and highlights plasma ignition point. Panel (b) shows time-adjusted data for determination of k_f and k_d .

where E_n represents the excitation energy of arbitrarily defined transition n , I_n is the emission intensity obtained from OES, ν_n is the frequency of transition, and A_n is the transition probability. This process, summarized in greater detail previously,⁴⁻⁵ involves an iterative comparison of three Ar emission lines to the 3d-4p line of Ar⁺ ($\lambda = 617.2$ nm), yielding three T_e values for each OES spectrum collected. Reported T_e values are weighted averages and standard deviations from $n \geq 3$ spectra.

2.5.2. Determination of Rotational and Vibrational Temperatures. Vibrational and rotational temperatures (T_V and T_R , respectively) were determined for several molecular species in the plasma systems described above from spectral data fit with SpecAir⁶ and LIFBASE⁷ programs or calculated via a Boltzmann plot. Details on the fitting parameters for each of these molecular species are reported in Table 2.2. Additionally, the role of the of the spectrometer grating efficiency on the emission spectra was considered. Corrections for the grating efficiency were applied to the raw data and T_R and T_V values reported herein reflect this correction.

In LIFBASE, imported spectra were evaluated by manually manipulating the vibrational histogram for a representative best fit of the vibrational state populations. These vibrational state populations were used to determine $T_V(\text{CH}, \text{CN}, \text{OH})$ using Equation 2.2,

$$T_V = \frac{\sum_{v_i}^v n(h\omega)(v+1/2)}{k_B} \quad (2.2)$$

where n represents the fractional population of an individual vibrational state, ω is the vibrational constant;⁷ v is the numerical vibrational state, and k_B is Boltzmann's constant. A thermalized distribution was assumed for determination of $T_R(\text{CH}, \text{CN}, \text{OH})$ where the rotational temperature was adjusted within LIFBASE to best match FWHM. Figure 2.3 displays a CH A²Δ → X²Π emission spectrum acquired under in a CH₄ plasma with a TiO₂ substrate at $p = 150$ mTorr and $P = 50$ W. For this specific spectrum, simulation via LIFBASE yields $T_R(\text{CH}) = 1970$ K and

Table 2.2. Temperature determination methods for plasma species of interest.

Molecule	OES Transition	Wavelength Range (nm)	Temperature Determination Method	
			T_R	T_V
CH	$A^2\Delta \rightarrow X^2\Pi$	425 – 440	LIFBASE	LIFBASE
CN	$B^2\Sigma^+ \rightarrow X^2\Sigma^+$	370 – 400	LIFBASE	LIFBASE
H ₂	$d^3\Pi_u \rightarrow a^3\Sigma_g^+$	601 – 612	Boltzmann plot	--
N ₂	$C^3\Pi_u \rightarrow B^3\Pi_g$	290 – 370	Specair	Boltzmann plot
OH	$A^2\Sigma^+ \rightarrow X^2\Pi$	305 – 325	LIFBASE	LIFBASE

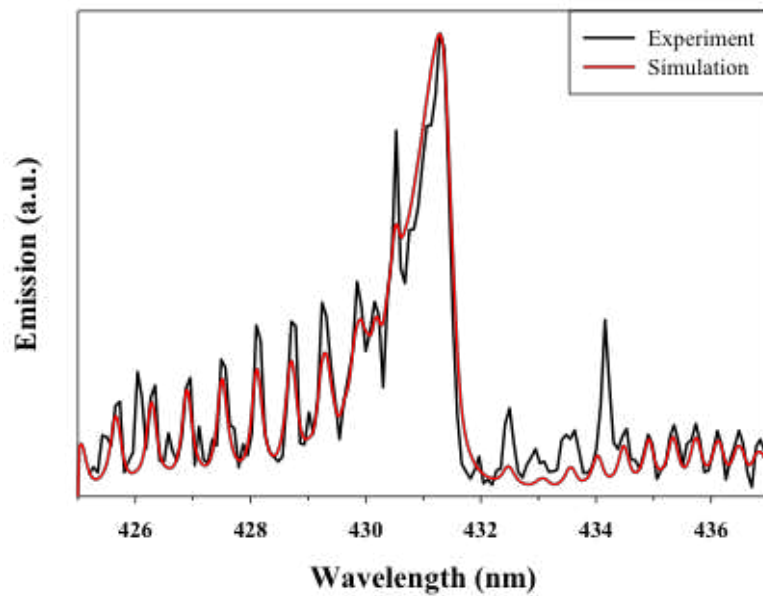


Figure 2.3. Representative emission spectrum ($p = 150$ mTorr, $P = 50$ W) for CH $A^2\Delta \rightarrow X^2\Pi$ in a CH_4 plasma with TiO_2 . Simulation of the spectrum using LIFBASE yields $T_R = 1970$ K, $T_V = 2550$ K.

$T_V(\text{CH}) = 2550 \text{ K}$. Note that error is not reported for these simulations because they were determined for a single trial. Peak correlation for all the simulations reported herein is $> 80\%$.

A Boltzmann plot of $\ln(I\lambda/A)$ as a function of vibrational energy (E) was used to calculate $T_V(\text{N}_2)$, where I and λ are the intensity (a.u.) and wavelength (nm) of a specific emission line and A (s^{-1}) is the corresponding Einstein transition probability coefficient for the transition. A typical N_2 emission spectrum acquired with a TiO_2 substrate placed in the coil region of the plasma reactor is shown in Figure 6.1. The N_2 transitions, corresponding wavelengths, and A values used to calculate $T_V(\text{N}_2)$ are reported previously.⁸⁻¹⁰ The inset in Figure 6.1 shows a representative Boltzmann plot for a 100% N_2 plasma (with TiO_2 catalyst) created from the corresponding spectrum. The slope of the linear regression is inversely proportional to T_V , which ultimately yields $T_V(\text{N}_2) = 3140 \pm 20 \text{ K}$ for that particular set of conditions. $T_R(\text{N}_2)$ for the $\text{C}^3\Pi_u \rightarrow \text{B}^3\Pi_g$ transition was determined from simulated fits of experimental spectral data using the “Temperature Loop” function in SpecAir⁶ by inputting the calculated $T_V(\text{N}_2)$ value obtained from the Boltzmann plot.

A Boltzmann plot was also used to calculate $T_R(\text{H}_2)$ values. For these calculations, $\ln(I\lambda^4/S)$ is plotted as a function of the upper state rotational energy (E), where I and λ are the intensity (a.u.) and wavelength (nm) of a specific emission line and S is the Hönl-London factor. Table 2.3 lists the selected H_2 transitions¹¹, corresponding wavelengths and energies, and Hönl-London factors.¹² These specific transitions for calculating $T_R(\text{H}_2)$ were selected because they have no overlap with other transitions.¹¹⁻¹² All reported T_V and T_R values are the result of calculated averages and ± 1 standard deviation from $n \geq 3$ spectra.

Table 2.3. Parameters for selected H₂ rotational lines used to determine $T_R(\text{K})$ using a Boltzmann plot.

Rotational transition	(nm)	E_J (cm^{-1})	$S_{J,J'}$
Q ₁	601.83	59.18	4.5
Q ₂	602.38	177.55	2.5
Q ₄	604.27	591.83	4.5
Q ₆	607.20	1242.84	6.5
Q ₈	611.11	2130.59	8.5

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CHAPTER 3
DETERMINATION OF ROTATIONAL AND VIBRATIONAL TEMPERATURES
OF CH IN CH₄ PLASMAS

This chapter contains data from a full paper published under the same title in *Journal of Vacuum Science and Technology A* written by Tara L. Van Surksum, Joshua M. Blechle, and Ellen R. Fisher and is reproduced with permission from *J. Vac. Sci. Technol., A* 2018, 36 (4), 041302 (Copyright 2018, American Vacuum Society). These studies investigate rotational and vibrational energy partitioning trends of CH $A^2\Delta \rightarrow X^2\Pi$ in 100% CH₄ and CH₄/Ar inductively coupled plasma systems via optical emission spectroscopy. Characterization of the amorphous hydrocarbon films deposited by these plasma systems is also discussed. This work was supported by the National Science Foundation (NSF-1152963). I would also like to thank Dr. Patrick McCurdy for assistance with the XPS and the Dr. Charles Henry research group for profilometry technical support.

3.1 Introduction

Volatile organic compounds (VOCs) emitted from anthropogenic sources primarily result from fuel combustion of vehicle exhaust and various industrial processes.¹ Many VOCs are carcinogenic, and excessive exposure to them can cause headaches, dizziness, and damage to the liver, kidneys, and central nervous system.²⁻⁴ In addition to their negative impacts on human health, VOCs also have serious undesirable environmental impacts. For example, reactions with nitrogen oxides (NO_x) result in the formation of photochemical smog and ozone.^{3,5} Thus, increasing concerns arising from deleterious pollution-related issues require effective and

efficient techniques for the abatement of toxic species such as NO_x and VOCs.

Plasma-assisted catalysis (PAC), a proposed pollutant mitigation method, couples a non-thermal plasma (NTP) with a catalyst to produce outcomes that cannot be attained by plasma or catalysis individually.^{2-3, 6-8} A NTP consists of electrons, ions, radicals, and neutral and excited state species which interact with each other and in a synergistic manner with a catalyst.⁷ Thus, the active species in the plasma, coupled with a catalyst, enhances selectivity and efficiency and gives rise to a plasma environment that allows for conversion and abatement of toxic pollutant species.^{2, 9-10} Atmospheric pressure NTPs have shown great promise as an effective means to achieve VOC conversion and abatement because of the apparent advantages such as low cost, low operating temperatures, and wide range of applicability towards removal of VOCs and NO_x species.⁹⁻¹³ However, current PAC application is limited because of selectivity issues, unwanted byproduct formation, and overall low energy efficiency.^{9, 11-15} Overcoming these challenges requires a need for fundamental investigations of gas-phase plasma processes and plasma-surface interactions. Thus, emphasizing the importance of plasma diagnostic approaches in conjunction with computational strategies for plasma modeling purposes.

Knowledge of the roles of gas-phase radicals and radical-surface interactions is key to understanding fundamental plasma processes and plasma-surface chemistry. In molecular gases (e.g., methane, methane-containing mixtures), direct electron impact could lead not only to the decomposition of molecules into radicals and smaller molecules but also to the excitation of electronic, vibrational, and rotational states of species of interest.¹⁶⁻¹⁷ Excited state reactions provide routes to different processes/products relative to similar processes for the same molecules or radicals in the ground state and must be taken into account when developing plasma models and elucidating overall plasma chemistry.¹⁷ Thus, an understanding of how

energy is partitioned into vibrational, rotational, and translational modes provides insight into formation mechanisms, decomposition pathways, and overall plasma chemistry. Specifically, figures of merit such as gas temperature (T_g), vibrational temperature (T_V), and rotational temperature (T_R) describe the energetics of species within the plasma system. NTPs generally follow a relationship where $T_V > T_R \approx T_T$, yet each temperature is significantly lower than the electron temperature (T_e).¹⁸⁻²⁴ T_R and T_T are often assumed to equilibrate with each other and the T_g because of the relatively small energy separations between rotational and translational levels.²³⁻²⁴ However, because of larger energy separations between vibrational levels, collisions able to produce a change in vibrational quantum number are much less frequent, and therefore, the vibrational distribution is not expected to necessarily equilibrate with the T_R or T_g .²³⁻²⁴

Here, we have chosen to examine CH₄ and CH₄/Ar plasmas as model systems because methane is a simple, model hydrocarbon representative of VOCs. Moreover, methane plasmas have been used extensively to deposit diamond and diamond-like carbon films.²⁵⁻²⁸ Despite the extensive use of CH₄-based plasmas and several studies focused on temperature measurements under a prescribed set of conditions,²⁹⁻³² few studies report on energy partitioning trends of CH₄ discharges with catalytic substrates. Thus, a primary goal of this study is to elucidate energy partitioning trends through determination of T_R and T_V of excited state CH ($CH\ A^2\Delta$) in CH₄ and CH₄/Ar plasma systems as a function of system pressure (p) and applied rf power (P). We also seek to elucidate molecular-level processes occurring at the plasma-surface interface. Understanding these processes remains an important component towards elucidating more complex plasma catalyst interactions in PAC applications. Thus, in addition to characterization of the gas-phase, the chemical composition and morphology of the amorphous hydrocarbon films

deposited from the plasma were also investigated to explore the effect of the gas-phase chemistry on resulting film chemistry.

3.2 Results

The representative raw OES data depicted in Figure 3.1a for a 100% CH₄ plasma show emitting atomic and molecular hydrogen species dominate the spectrum. Emission from CH radicals is also observed at 431.1 nm. Figure 3.1b highlights the wavelength region of 425 – 437 nm, allowing for a closer examination of the CH A²Δ → X²Π band. Emission data simulated using LIFBASE to elucidate characteristic temperatures, $T_R(\text{CH})$ and $T_V(\text{CH})$, are shown in Figure 3.1b. The simulated spectrum closely matches the experimental emission spectrum [peak correlation (PC) = 0.98]. $T_R(\text{CH})$ and $T_V(\text{CH})$ values obtained from the spectrum shown in Figure 3.1b are 1880 K and 2690 K, respectively. To demonstrate the sensitivity of the fit to changes in T_R and T_V , two additional simulations for both T_R and T_V (± 50 K and ± 100 K of the reported values, respectively) were performed for the experimental spectrum shown in Figure 3.1b and are shown in Figure 3.2. The four additional simulations also each have peak correlations of 0.98 and thus, demonstrate that the goodness of fit does not change appreciably near the upper range of our reported error.

Similar data for $T_R(\text{CH})$ and $T_V(\text{CH})$ were obtained for over the range of plasma parameters specified above. $T_R(\text{CH})$ values, Figure 3.3a, display a negative, linear correlation ($R^2 = 0.84$) with pressure in the 100% CH₄ plasma system. Table 3.1 lists all the calculated $T_R(\text{CH})$ values, which range from ~1750 K to ~2360 K for the studied parameter space. T_V data for CH in 100% CH₄ plasmas, Figure 3.3b, display a trend similar to the $T_R(\text{CH})$ data [albeit somewhat non-linear ($R^2 < 0.7$)], where an increase in pressure results in an overall decrease in

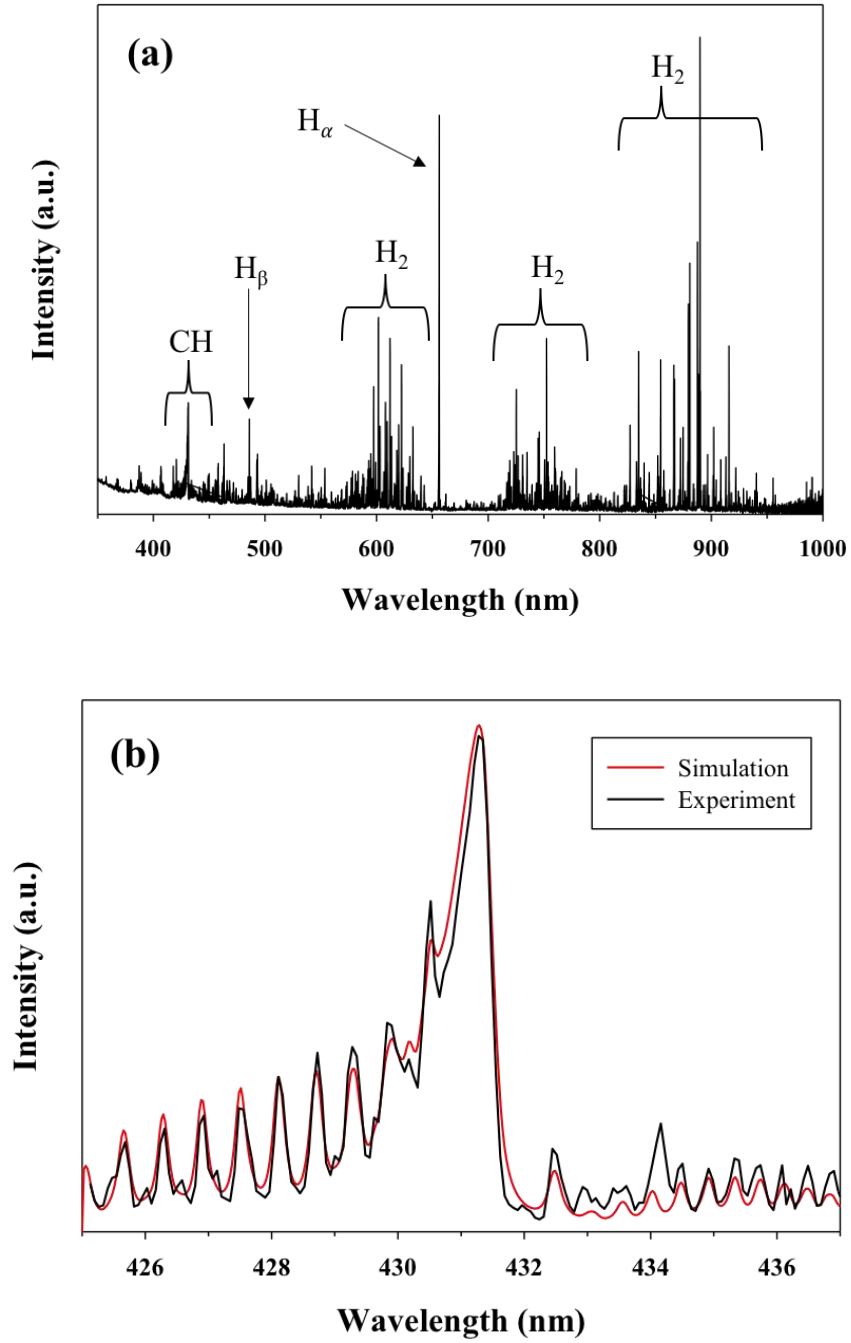


Figure 3.1. (a) Representative emission spectrum for a 100% CH₄ plasma system at $p = 200$ mTorr, $P = 75$ W. (b) Enlarged view of the CH $A^2\Delta \rightarrow X^2\Pi$ band, along with the simulated fit from LIFBASE, giving rise to $T_R = 1800$ K, $T_V = 2690$ K.

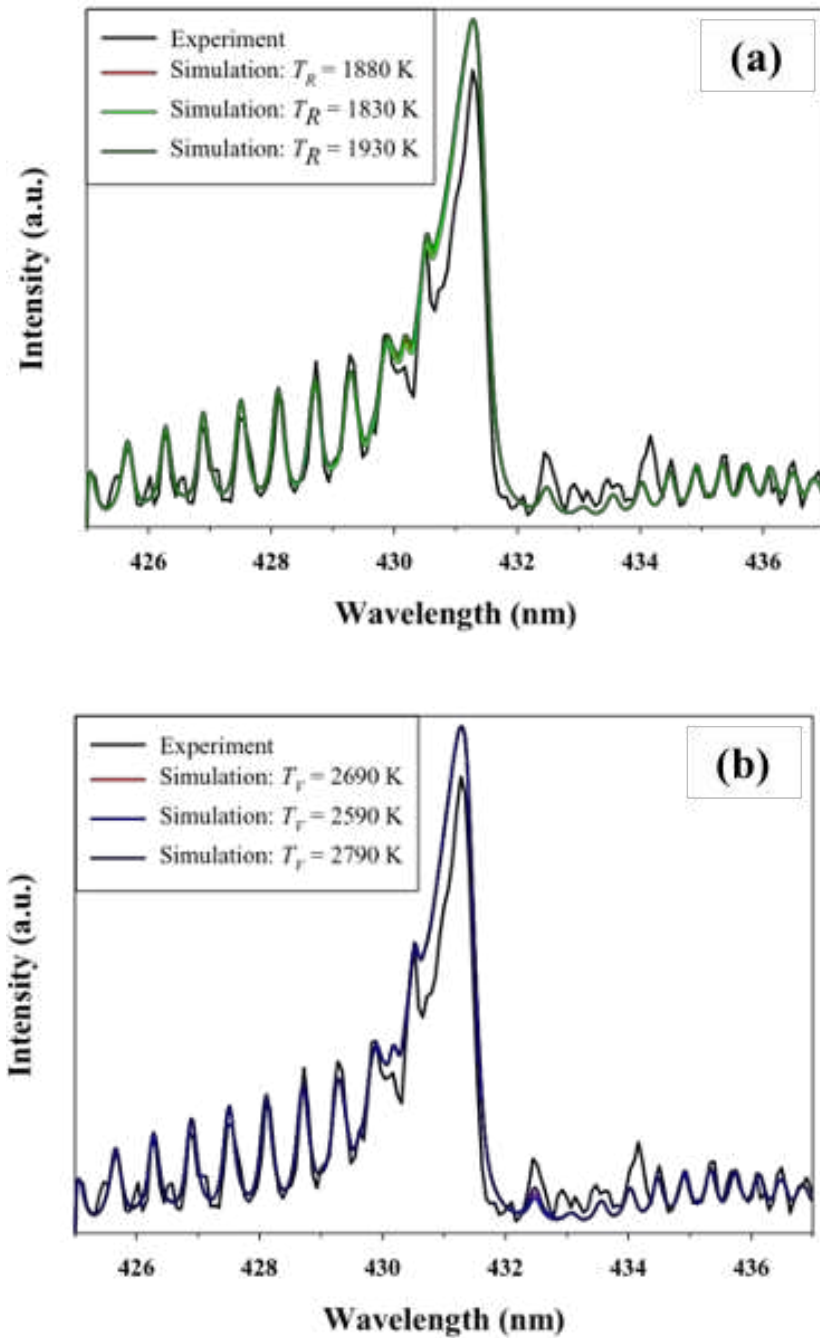


Figure 3.2. Emission spectra and reported simulated data of the CH $A^2\Delta \rightarrow X^2\Pi$ band for a 100% CH_4 plasma system at $p = 200$ mTorr, $P = 75$ W; additional simulations to demonstrate sensitivity of change in (a) $T_R \pm 50$ K and (b) $T_V \pm 100$ K.

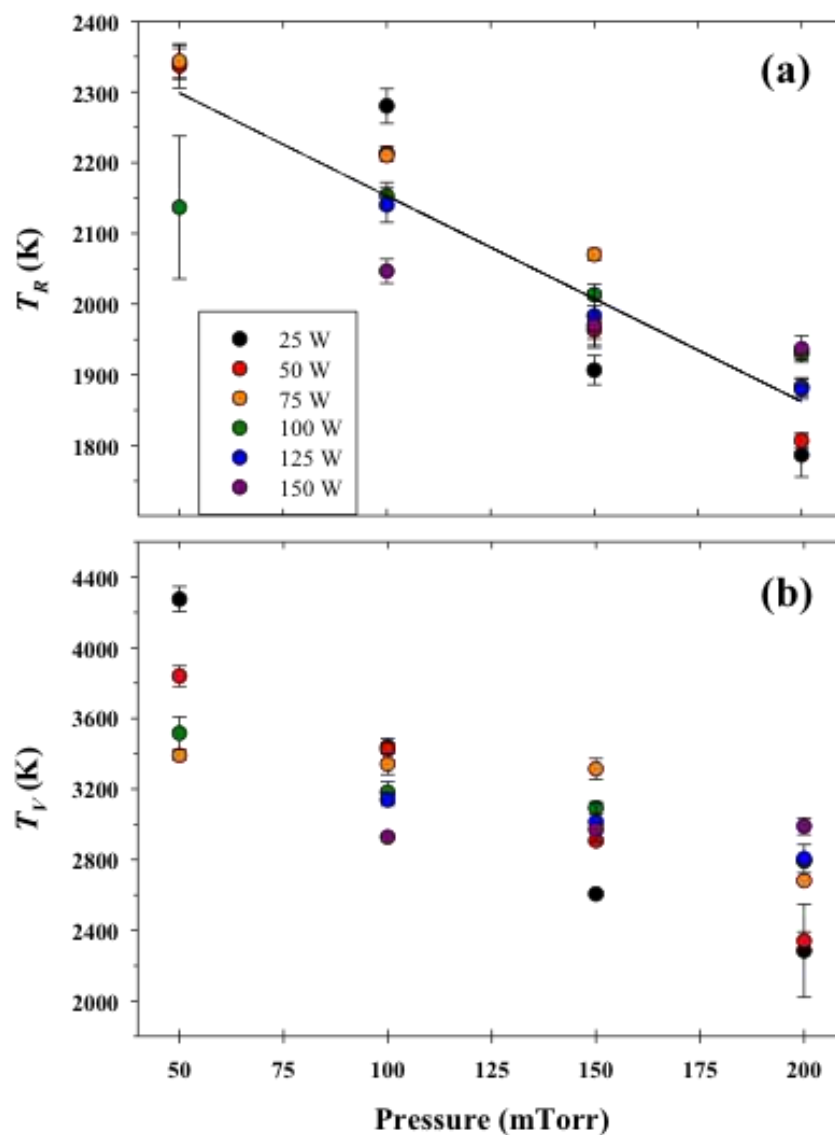


Figure 3.3. (a) $\text{CH A}^2\Delta T_R$ and (b) $\text{CH A}^2\Delta T_V$ as a function of pressure over a range of applied rf powers in a 100% CH_4 plasma system. The dependence of $T_R(\text{CH})$ on p was fit using a global linear regression ($R^2 = 0.84$).

Table 3.1. T_R , T_V values for CH in a 100% CH₄ plasma system.^a

Pressure (mTorr)	Applied rf Power (W)	T_R (K)	T_V (K)
50	25	2340 (20)	4270 (70)
	50	2340 (30)	3840 (60)
	75	2340 (20)	3390 (20)
	100	2140 (100)	3520 (90)
	125	-	-
	150	-	-
100	25	2280 (20)	3440 (20)
	50	2210 (10)	3420 (60)
	75	2210 (10)	3340 (60)
	100	2150 (20)	3180 (60)
	125	2240 (20)	3140 (40)
	150	2050 (20)	2930 (10)
150	25	1910 (20)	2610 (10)
	50	1960 (10)	2910 (20)
	75	2070 (10)	3310 (60)
	100	2010 (10)	3090 (30)
	125	1980 (40)	3010 (110)
	150	1970 (30)	2970 (20)
200	25	1790 (30)	2280 (260)
	50	1810 (10)	2340 (10)
	75	1880 (10)	2680 (10)
	100	1930 (10)	2790 (10)
	125	1880 (10)	2810 (80)
	150	1940 (20)	2990 (50)

?

^aValues in parentheses represent one standard deviation for the measurement.

$T_V(\text{CH})$ values. Notably, under all conditions T_V values are higher than T_R values, ranging from ~2020 K to ~4340 K.

The impact of applied rf power on rotational and vibrational temperatures in a 100% CH_4 plasma system was also elucidated. Figure 3.4a shows $T_R(\text{CH})$ plotted as a function of P under a range of pressure conditions. At low P , the p dependence noted above is once again clear where lower pressures are concomitant with higher $T_R(\text{CH})$ values and higher pressures with lower $T_R(\text{CH})$ values. Notably, at $P = 25$ W, the range of $T_R(\text{CH})$ values is larger than any other P condition studied, ~1750 K to ~2360 K. An interesting trend emerges at $P = 150$ W, where $T_R(\text{CH})$ values essentially converge to a smaller range of ~1920 K to ~2070 K, approximately halfway between the two most extreme reported rotational temperatures over the studied parameter range. Similar results are noted for $T_V(\text{CH})$, Figure 3.4b. At $P = 25$ W, $T_V(\text{CH})$ values range from ~2020 K to ~4340 K whereas at $P = 150$ W, T_V values are ~2950 K, regardless of plasma system pressure.

Diluents are often used in plasma systems for a variety of reasons, including increasing non-reactive collisions and increased precursor dissociation. To determine the potential effects that diluents have on energy partitioning in our plasmas, Ar was added to the plasma in a 3:1 CH_4/Ar ratio. Notably, the experimental spectra differed more from the calculated spectra in this system. This could arise from the formation mechanism for CH in the methane plasma, namely dissociative excitation, which can lead to non-equilibrium population of rovibrational states.^{17, 33} Figure 3.5 shows emission spectra of the CH $A^2\Delta \rightarrow X^2\Pi$ band for a CH_4 plasma with 0%, 10%, and 25% Ar added to the precursor mixture. Notably, adding 10% Ar only minimally changes the emission spectrum compared to the 100% CH_4 plasma. Yet, when the Ar fraction is increased to 25%, the emission spectrum of this band changes more dramatically. Specifically,

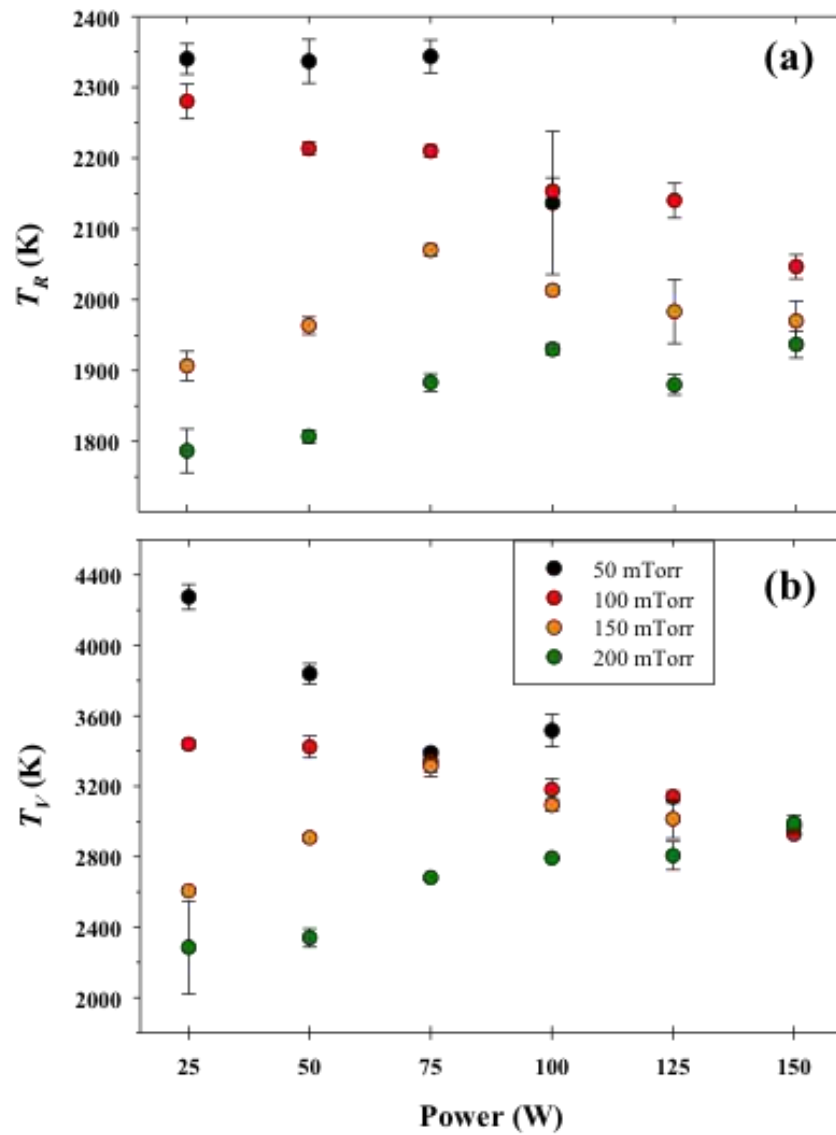


Figure 3.4. Measured CH A²Δ internal temperatures (a) T_R and (b) T_V as a function of applied rf power over a range of pressures in a 100% CH₄ plasma.

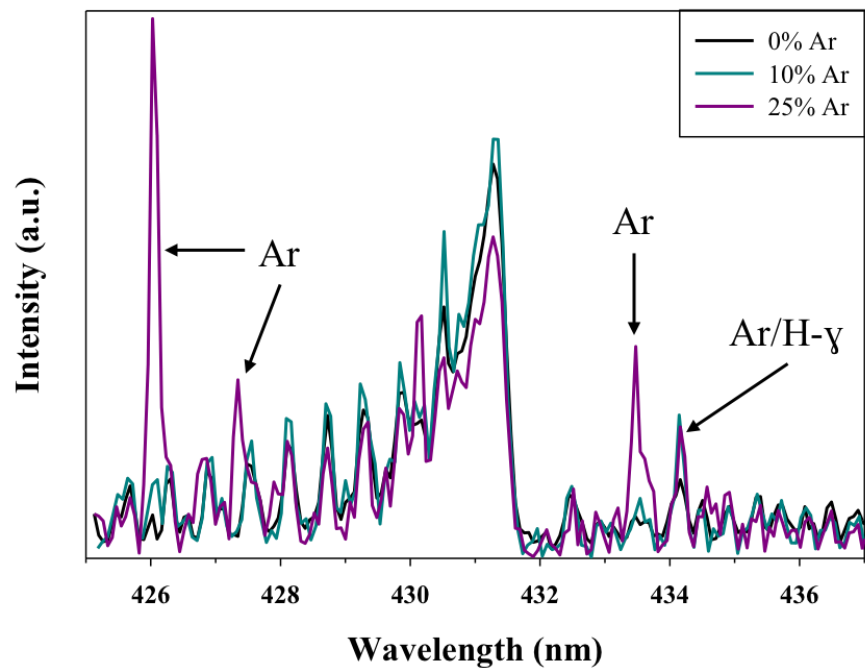


Figure 3.5. Emission spectra of the CH A²Δ → X²Π band for a CH₄ plasma system at $p = 200$ mTorr, $P = 75$ W with varying amounts of Ar added to the precursor mixture.

Ar peaks overlap with the CH $A^2\Delta \rightarrow X^2\Pi$ band, also helping to explain the lower peak correlations when fitting these spectra.

Figure 3.6 demonstrates the impact of P on $T_R(\text{CH})$ and $T_V(\text{CH})$. $T_R(\text{CH})$ values, with specific determined values listed in Table 3.2, range from ~1700 K to ~2150 K and as demonstrated in Figure 3.6a, generally decrease as P increases. Under the same plasma pressure and power conditions, calculated $T_V(\text{CH})$ values for the mixed gas system, Table 3.2, are similar to those in the 100% CH₄ plasma system (~2050 K to ~3550 K). Unlike the 100% CH₄ plasma system, however, a different trend for the mixed gas plasma system is noted here. Figure 3.6b, demonstrates that $T_V(\text{CH})$ decreases linearly ($R^2 \geq 0.91$) with an increase in P for each studied pressure condition. A pressure dependence is also noted for vibrational temperatures in the 3:1 CH₄/Ar plasma system where higher pressures correspond to higher $T_V(\text{CH})$ values.

Figure 3.7 provides details on the surface and bulk chemical composition of films deposited in CH₄ plasmas. XPS data reveal the surface composition consists mainly of elemental C (~88%) and O (~12%). A representative high-resolution C_{1s} XPS spectrum for films deposited in a 100% CH₄ plasma, Figure 3.7a, displays three specific binding environments: -C-C/-C-H (285.0 eV), -C-O-C/-C-O-H (286.6 eV), and -C=O (288.7 eV) bonds with relative component percentages of $84.8 \pm 3.3 \%$, $11.8 \pm 2.8 \%$, and $3.4 \pm 0.6 \%$, respectively. Notably, no appreciable differences in the high resolution C_{1s} spectra are observed between films deposited under plasma parameter conditions of varying p and P . FTIR data, Figure 3.7b, also indicate no change in chemical functionality for films deposited under different conditions. C=O and C-O stretches are noted at $\sim 1025 \text{ cm}^{-1}$ and $\sim 1630 \text{ cm}^{-1}$, respectively. Absorption peaks attributed to C-H bending are seen in the range of $1350 - 1460 \text{ cm}^{-1}$ and a prominent peak centered at 2923 cm^{-1} is indicative of C-H stretching. Additionally, the broad peak centered at 3442 cm^{-1} can be

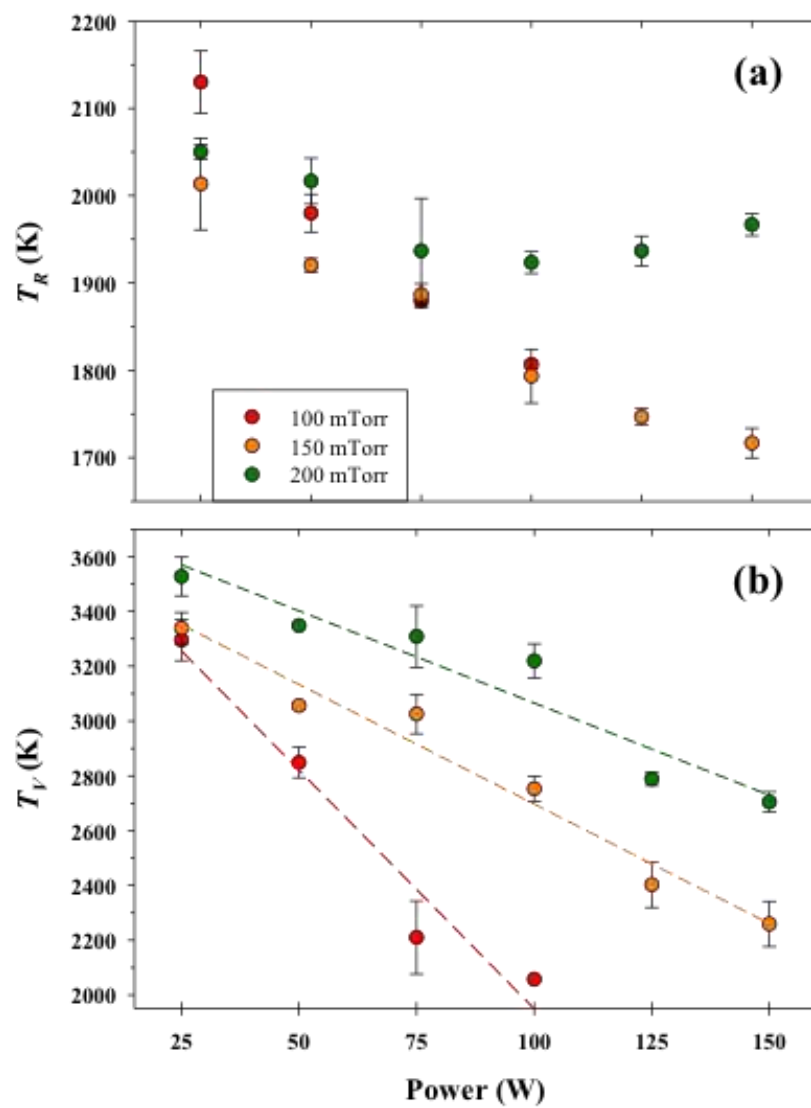


Figure 3.6. CH A²Δ (a) T_R and (b) T_V as a function of applied rf power over a range of pressures in a 3:1 CH₄/Ar plasma. The dependence of $T_V(\text{CH})$ on P was fit using global linear regressions.

Table 3.2. T_R , T_V values for CH in a 3:1 CH₄/Ar plasma system.^a

Pressure (mTorr)	Applied rf Power (W)	T_R (K)	T_V (K)
100	25	2130 (40)	3300 (80)
	50	1980 (20)	2850 (60)
	75	1880 (10)	2210 (130)
	100	1810 (10)	2060 (10)
	125	-	-
	150	-	-
150	25	2010 (50)	3340 (60)
	50	1920 (10)	3060 (10)
	75	1890 (10)	3030 (70)
	100	1790 (30)	2750 (50)
	125	1750 (10)	2400 (80)
	150	1720 (20)	2260 (80)
200	25	2050 (10)	3530 (70)
	50	2020 (30)	3350 (10)
	75	1940 (60)	3310 (110)
	100	1920 (10)	3220 (60)
	125	1940 (20)	2790 (20)
	150	1970 (10)	2700 (40)

□

^aValues in parentheses represent one standard deviation for the measurement.

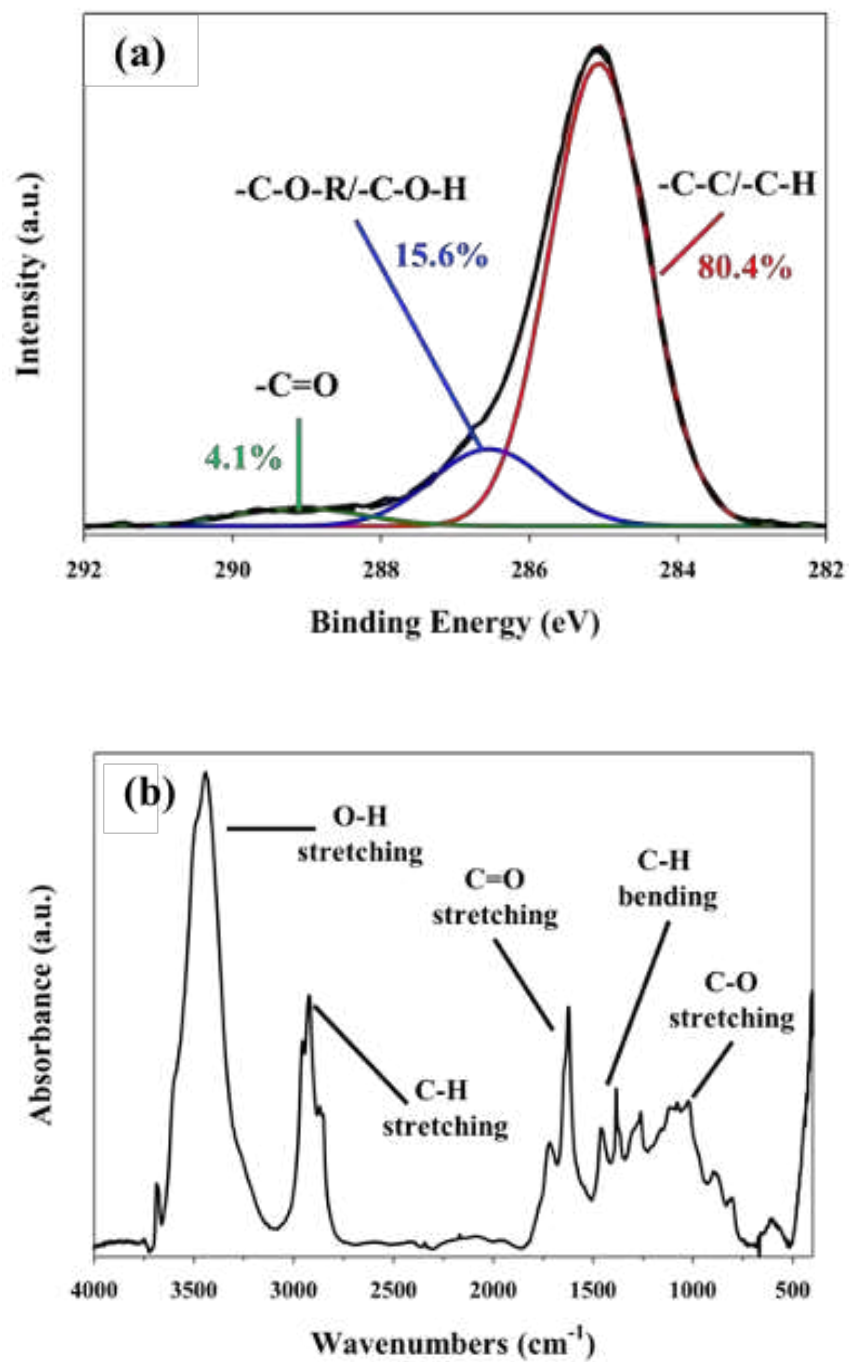


Figure 3.7. Representative (a) high-resolution C_{1s} XPS spectrum and (b) FTIR spectrum for HC film deposited by a 100% CH_4 plasma.

attributed to O-H stretching.

Optical profilometry data, Figure 3.8, display representative morphologies of HC films across designated plasma parameters. Clearly, distinct differences in HC film morphology arise between films deposited at a lower power of $P = 25$ W and those deposited at higher applied rf power. Differences between films deposited at $P = 50$ W and $P = 100$ W are also apparent, but subtle. For example, the morphology matrix also demonstrates that an increase in P corresponds to a general increase in the length of the cracks in the films.

Plasma system pressure also affects film morphology. As p is increased from 100 mTorr to 200 mTorr, an increase in the number of cracks in the film is generally observed, as illustrated in Figure 3.8 by films deposited at $P = 25$ W (Figures 3.8a, d, and g). Figure 3.8a displays an overall smooth film with several small indents whereas Figure 3.8g shows many small cracks extending across the image. At an intermediate p condition ($p = 150$ mTorr), Figure 3.8d, “island-like” formations of film cracking are observed. The insets in Figure 3.8 display representative WCA images and average WCA values for HC films deposited in a 100% CH₄ plasma under the specified parameter conditions. Overall, there are no appreciable differences in the measured WCA values for these films. Yet, these values tend to decrease as P increases. This is especially apparent for films deposited at the lowest applied rf power studied ($P = 25$ W) where WCA values are slightly higher, $\sim 78^\circ$ to $\sim 90^\circ$, than those deposited at higher P ($P = 50$ W, 100 W), $\sim 69^\circ$ to $\sim 76^\circ$. All of these values are significantly higher than the WCA value of a clean glass slide prior to CH₄ plasma exposure is $\sim 10^\circ$, further demonstrating that a film is deposited. As one additional characterization of our deposited films, optical profilometry was performed on a few samples specifically to determine film thickness and roughness features. The thickness on these select samples ranged from $\sim 150 - 350$ nm, with roughness values $\sim 30 -$

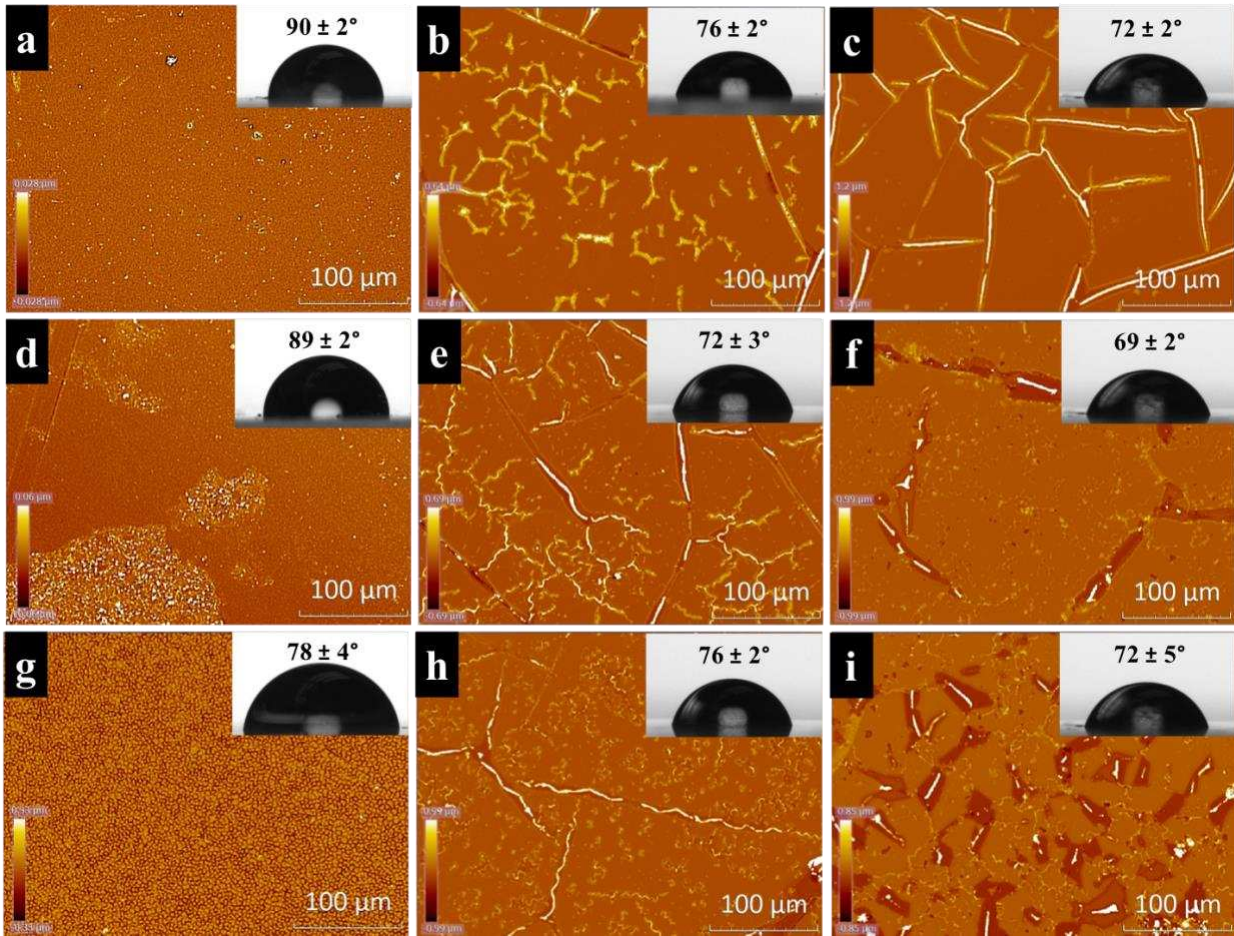


Figure 3.8. Optical profilometry images and static WCA data for HC films deposited at 100 mTorr as a function of applied rf power: (a) 25 W, (b) 50 W, and (c) 100 W; and at 150 mTorr as a function of applied rf power: (d) 25 W, (e) 50 W, and (f) 100 W; and at 200 mTorr as a function of rf power: (g) 25 W, (h) 50 W, and (i) 100 W.

150 nm, depending on conditions. These features were relatively uniform across the entire surface of a 3×3 cm substrate.

3.3 Discussion

As noted in the introduction, knowledge of key plasma processes as well as correlations between gas-phase data and resulting film properties for materials deposited via plasma enhanced chemical vapor deposition (PECVD) are important components towards elucidating a complete plasma chemistry profile. Specifically, energy partitioning trends can provide insight concerning the distribution of the upper state and potentially, may provide control over film deposition processes and chemistry.^{19, 34-35} Here, trends in $T_R(\text{CH})$ and $T_V(\text{CH})$ have been investigated in CH_4 and CH_4/Ar plasma systems and potential links between these values and the properties of films deposited via PECVD in 100% CH_4 systems have been assessed.

Focusing first on the T_R and T_V data for the first excited state of CH (i.e. $\text{CH A}^2\Delta$), presented in Tables 3.1 – 3.2, we note a few interesting trends. $T_R(\text{CH})$ values reported herein range from ~1750 K to ~2360 K, significantly lower than the concomitant $T_V(\text{CH})$ values, and illustrate clear trends with respect to both system p and P . It is instructive to compare these trends with previously published data, both from our labs and from others. Similar relationships between T_R and T_V were observed by Avtaeva and Lapochkina who examined multiple molecules in rf capacitive methane discharges.¹⁷ They found $T_R(\text{CH}) < T_V(\text{CH})$, similar to the results found here, but also noted that $T_R(\text{CH})$ decreased with increasing p whereas $T_V(\text{CH})$ increased. In addition, previously reported T_R values for ground state CH, acquired using laser-induced fluorescence (LIF) in our laboratory, indicated no clear trends in T_R with respect to either p or P .³⁶ In this previous work, $T_R(\text{CH}) = \sim 1500$ K in 100% CH_4 plasmas, significantly

lower than the T_R values reported herein for excited CH radicals. This suggests energy transfer in the ground state is fast enough to achieve some level of thermalization, relative to energy transfer in excited state species. Rotational temperatures were, however, only reported for two pressures, 50 mTorr and 110 mTorr. Indeed, the excited state $T_R(\text{CH})$ data reported herein (Figure 3.3a) show that at these lower pressures ($p = 50$ and 100 mTorr), the reported $T_R(\text{CH})$ values are the same within experimental error. An extension of the parameter space to $p = 200$ mTorr in the present work, however, reveals the expected negative dependence of $T_R(\text{CH})$ on p , wherein higher pressures result in lower $T_R(\text{CH})$. It should also be noted that ground state $T_R(\text{CH})$ measurements from Zhou et al. were determined from an effectively collision-free molecular beam downstream from the ignition of the plasma,³⁶ whereas those reported herein essentially probe the bulk of the plasma, including the coil region.

Generally, rotational relaxation can be achieved relatively quickly, typically in <10 collisions;³⁷ hence, T_R typically decreases as the number of collisions increase. This is exemplified in Figure 3.3a, where the increase in p from 50 mTorr to 200 mTorr concomitantly results in a decrease in $T_R(\text{CH})$. Ar addition to the plasma increases the probability of thermalizing conditions.³⁸⁻³⁹ Figure 3.6 demonstrates this concept wherein the addition of Ar to the gas feed (3:1 CH_4/Ar) effectively reduces $T_R(\text{CH})$ values relative to the 100% CH_4 plasma system. This effect is especially notable at lower p , where there is a larger discrepancy in $T_R(\text{CH})$ values between the two plasma systems. As p increases from $p = 100$ mTorr to $p = 200$ mTorr, the gap between $T_R(\text{CH})$ values also decreases. In general, at $p = 200$ mTorr the values in the two systems essentially converge and are virtually the same, indicating that at $p = 200$ mTorr CH $A^2\Delta$ radicals are rotationally relaxed in our systems. Notably, the first excited state of CH has a lifetime of 5×10^{-7} s.¹⁷ Thus, under the conditions in our plasma system, the preferred

depopulation rate is likely via emission rather than through thermalizing collisions.

Additionally, as evidenced by the smaller slope for the 3:1 CH₄/Ar plasma system in Figure 3.6, the addition of Ar appears to mitigate the effect of p on $T_R(\text{CH})$, indicating that Ar indeed promotes thermalization of rotational energy in these systems.¹⁹ Similar relationships have been observed for other radicals in a variety of plasma systems.^{19, 35, 40}

Previous studies in our laboratory have demonstrated the effects of P on T_R and T_V on other plasma species such as NO, N₂ and CF.^{19, 34-35} In these studies, T_V generally increases with increasing P . Interestingly, in the current work, the dependence of $T_V(\text{CH})$ on P changes as the system pressure increases. At lower p , the dependence appears to mimic that for $T_R(\text{CH})$, Figure 3.4b, decreasing as P increases. In contrast, at higher p , $T_V(\text{CH})$ increases with P up to $P = 75\text{-}100$ W, leveling out and decreasing slightly at higher P . Although these trends are perhaps counter intuitive, power and pressure are two plasma parameters that are intimately connected. As such, changes in one of these parameters could produce changes in the other parameter. In particular, at higher P , we are likely increasing the overall system pressure via formation of additional molecules in the system via additional decomposition of plasma gases. As it is difficult to achieve an accurate pressure reading when the plasma is on, this effect may not be reflected in our reported pressure values. Perusing the literature for comparable systems, we find little to directly compare with respect to the exact pressure-power parameter space used here. For comparison in a much higher pressure regime, Moon *et al.* examined the parameter dependence of the internal temperatures of both CH and CN in atmospheric discharges.³² In these systems, they found $T_V(\text{CH})$ nominally increased with increasing power, but was relatively sensitive to other plasma parameters. In previous work in our laboratory,⁴¹ we found that CH₄-containing plasmas can often be characterized by two modes. In particular, the shift from a

capacitive-coupled electrostatic pre-discharge mode (low P) and an inductively-coupled electromagnetic main discharge (higher P) occurs at ~ 75 W. Thus, the trend in $T_V(\text{CH})$ dependence on P may be related to this shift in plasma mode. Another explanation that could also contribute to the observed P dependence relies on the observation that the rovibrational states of CH $A^2\Delta$ radicals may be populated with a non-equilibrium distribution, as they are formed via a dissociative excitation process.⁴² Du *et al.* noted a similar situation occurs for OH formed in H_2O based discharges and that an understanding of the mechanism(s) for formation of a particular species is critical to understanding molecular temperatures in a plasma. Similarly, Berthelot and Bogaerts,⁴³ examined CO_2 decomposition via computational models and concluded that vibrational excitation can dramatically impact the dissociation process. Unfortunately, this is one of the largest sources of error that contribute to less reliable plasma models. Notably, one of Berthelot and Bogaerts' recommendations is to measure kinetic rates, species densities, and temperature data as a function of plasma conditions, such as was performed here, as these data are a result of the plasma chemistry and are heavily coupled to the plasma chemistry model.

Additional insight into film deposition processes and morphological changes can be gained through consideration of internal plasma temperatures and surface reactivities. Notably, dissociation in CH_4 plasmas occurs rapidly and fairly completely, leading to an array of product species, including CH_x , H, H_2 and C_2 .^{28, 44} Although formation of CH has been correlated directly with the decomposition of CH_4 ,²⁹ interpretation of our energy partitioning results, must also consider the relevant amount of the discharge power that may be converted into rotational and vibrational excitation of species other than CH $A^2\Delta$. For example, hydrogen species play an important role in the production of amorphous hydrocarbon films deposited via PECVD

processes.^{28, 44-46} Although not all of these examples are directly comparable, as the mechanism for plasma production is different and the operating pressures may also be different, it is still instructive to note some of the most relevant results. Avtaeva and Lapochkina examined formation of excited state H₂ and CH in rf capacitive methane plasmas. They attributed these disparate values to the differences in the molecules' excited state lifetimes and to their relative concentrations in their plasmas.¹⁷ Likewise, Heintze *et al.* studied methane dissociation and formation of C₂ in methane pulsed microwave plasmas.²⁹ They found hydrogen to be an important component of methane plasma chemistry and reported T_R of both ground and excited state C₂ and H₂.²⁹ In particular, addition of H₂ to the methane plasma resulted in higher CH₄ conversion at a lower energy per molecule, especially under low power conditions. Notably, the rotational temperature of C₂ d ³Π_g was considerably lower than that of either the lower electronic state of C₂ a³Π_u or either of the H₂ states (d ³Π_u or X ¹Σ⁺_g). The observation that three of these four states were the same within experimental error led the authors to conclude that the gas temperature corresponded to these temperatures, nominally 1500 – 2500 K. This suggests that a similar amount of the energy being supplied to our plasmas is being partitioned into rotational and vibrational modes of a number of methane decomposition products. These results will inform our future studies, which are focused on measuring internal temperatures for C₂ and H₂ within methane and other hydrocarbon-based plasma.

As an additional consideration, we examine CH surface interactions in relation to the current results. Previous imaging of radicals interacting with surfaces (IRIS) studies for CH₄ and CH₄/Ar plasma systems reveal that the surface reactivity of CH is near unity and independent of all experimental variables studied.³⁶ The high CH rotational and vibrational temperature data presented herein indicate significant internal excitation of CH radicals. It is possible that this

helps promote surface reactions that lead to film formation.⁴⁷ This idea was further explored in a previously published work, wherein gas-phase energetics of several diatomic plasma species in a range of plasma systems were investigated.⁴⁰ Perhaps more importantly, the gas-phase energetics were linked to surface reaction probabilities, or surface reactivity (R). In that study, radical species with high surface reactivity values ($R > 0.8$) also had relatively high T_R , T_V , and translational temperature (T_T) values. Moreover, the reactivity of these species (CH, CN, and SiH) also appeared to be independent of plasma parameters. In contrast, species such as OH, NH, and NH₂ had moderate to low R values (depending on plasma parameters) with low T_R and T_T values. Notably, the molecules with high surface reactivity were formed in film deposition systems, whereas those with moderate reactivity were formed in systems with little to no film formation, but rather the overarching plasma process was either etching or surface modification (functional group implantation).

Such observed correlations suggest connections between gas-phase energetics and film deposition characteristics. For example, we have previously observed a correlation between vibrationally hot CF in excited electronic states and the amount of surface scatter measured for ground state CF.³⁵ Here, our film composition data, Figure 3.7, confirm a uniform chemical composition throughout the surface and bulk of the material, typical of previous studies of films deposited from methane-based plasmas.^{25-26, 45, 48-49} Notably, film composition remains relatively uniform, regardless of system p or P . In contrast, WCA values decrease with increasing P , a phenomenon likely attributable to the observed morphological changes seen in the optical profilometry images. More importantly, the relatively high T_R and T_V values measured here for excited CH radicals along with the previously measured high surface reaction probabilities for ground state CH,³⁶ suggest that CH radicals play an important role in film formation processes.

Similar to what we observed with CF radicals, the higher internal energies of excited state CH may have a significant influence on the properties of the deposited films.

3.4 Summary

Energy partitioning for excited state CH radicals in CH₄ and CH₄/Ar plasmas were explored along with film formation and characterization studies. In general, $T_V(\text{CH})$ is higher than $T_R(\text{CH})$, regardless of gas mixture, system pressure or applied rf power, and T_R decreases with increasing pressure and upon addition of Ar to the system. Both $T_R(\text{CH})$ and $T_V(\text{CH})$ values are significantly above room temperature, suggesting that formation of excited state CH in the plasma happens in a non-equilibrium manner. Film characterization studies indicate that the resulting film composition does not change appreciably with plasma parameters; however, morphological changes are apparent over the studied parameter range. Ultimately, these observations provide insight towards the complexity inherent to plasma-surface interactions and fundamental energy partitioning investigations that are key to increasing the utility of PAC.

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CHAPTER 4
GAS-PHASE DIAGNOSTIC STUDIES OF H₂ AND CH₄
INDUCTIVELY COUPLED PLASMAS

This chapter contains results published as a full paper under the same title in the *Journal of Vacuum Science and Technology A* written by Tara L. Van Surksun and Ellen R. Fisher and is reproduced with permission from *J. Vac. Sci. Technol., A* 2020, 38 (3), 033010 (Copyright 2020, American Vacuum Society). Optical emission spectroscopy (OES) is employed to elucidate energy partitioning information for H₂ $d^3\Pi_u \rightarrow a^3\Sigma_g^+$ and CH $A^2\Delta \rightarrow X^2\Pi$ within several plasma systems (H₂, CH₄, CH₄/H₂, H₂/Ar). Disparities in the rotational temperature trends of H₂ ($d^3\Pi_u$) between H₂ and CH₄ plasmas highlight the differences in H₂ excitation pathways occurring in each of these plasma systems. When energy partitioning trends are combined with additional information that can be obtained via OES (relative species densities, kinetics), mechanistic information can also be construed. This chapter focuses on illuminating mechanisms of H₂ formation and excitation pathways in different plasma systems using fundamental information obtained via OES. This work was supported by funding through the National Science Foundation (NSF CBET-1803067).

4.1 Introduction

Knowledge of fundamental gas-phase processes and gas-surface interactions are crucial to the advancement of numerous plasma technologies. Optical plasma diagnostics provide a non-intrusive platform for obtaining a molecular-level understanding of plasma chemistry via species identification and energy partitioning of gas phase species.¹⁻² For example, an

understanding of how energy is partitioned into vibrational, rotational, and translational modes of a gas-phase molecule lends critical insight into formation mechanisms, decomposition pathways, and overall plasma chemistry. Figures of merit, such as vibrational (T_V) and rotational (T_R) temperatures, describe the energetics of molecular species within the system and are applicable to plasma modelling and estimates of gas temperature.³⁻⁴ As such, reports on internal molecular plasma temperatures (e.g., T_V and T_R) are key to elucidating molecular-level processes that dictate overall plasma chemistry.

Nonthermal plasmas generally follow a relationship where T_V is greater than T_R and/or the translational temperature (T_T), yet each temperature is significantly lower than the electron temperature (T_e).⁵⁻¹⁰ Interestingly, T_R values have been used as a metric to determine the gas temperature (T_g), with the assumption that T_R and T_T equilibrate with each other and thus, T_g , because of the relatively small energy separations between translational and rotational levels.⁹⁻¹⁰ Yet, previous studies from our labs and others have demonstrated that significant differences can exist between T_R and T_T .¹¹⁻¹³ Bruggeman *et al.* stated that T_R equilibrates with T_T only when a nascent rotational distribution is a thermalized distribution or when rotational energy transfer occurs relatively quickly.¹⁴ Moreover, different molecules in the same plasma system can exhibit vastly different T_R values.^{4, 15-16} In addition, the same type of plasma species within a system may be formed via different mechanisms (e.g., direct-impact excitation, decomposition of the parent molecule, recombination, etc.). As a consequence of all of these potential issues, it is valuable to measure molecular plasma temperatures as a means to examine possible species formation pathways.

We have previously reported plasma temperatures for several plasma species (e.g., N_2 , NO , CH) within environmentally relevant plasma systems.^{6, 17-19} In one study, energy

partitioning trends of $\text{CH } A^2\Delta \rightarrow X^2\Pi$ in methane plasmas were reported as functions of plasma parameters.¹⁸ Yet, optical emission studies have shown that methane plasma decomposition results in atomic and molecular hydrogen as well as carbon-containing products such as C_2 and CH ;^{18, 20-23} thus, we must also consider energy partitioned into these species as well. Avtaeva and Lapochkina determined that molecular hydrogen concentrations exceed CH concentrations in a methane-containing capacitive radio-frequency (rf) discharge.³ In contrast, although Morrison *et al.* determined similar molecular hydrogen and CH concentrations in low-pressure CH_4 plasma systems, atomic hydrogen concentrations exceeded both of these by a few orders of magnitude.²⁴ These studies emphasize the hydrogen-rich plasma environment created during CH_4 dissociation. The dissociation of methane, which has applications in several plasma technologies including plasma-assisted catalysis for pollution remediation,²⁵⁻²⁶ and the fabrication of carbon materials,²⁷⁻³⁰ has been studied extensively.^{25-27, 31-32} As such, the role of hydrogen in these systems has also been given considerable attention.^{28, 33-34} Although these studies have provided significant insight into the roles of hydrogen species in CH_4 plasmas, the design and optimization of plasma systems for processing (i.e., plasma-assisted catalysis, materials fabrication) remains a challenge as fundamental properties of plasma species must be measured to accurately construe mechanistic phenomena and increase the utility of plasma technologies.

Information on molecular-level plasma processes are indispensable for understanding and optimizing plasma systems. Shivkumar *et al.* built a numerical model to analyze hydrogen plasmas in a microwave plasma enhanced chemical vapor deposition system and determine several plasma properties (electric field, electron number density, electron temperature, and the gas temperature).³⁵ Their results highlight the connections between these fundamental plasma

properties and plasma parameters, a key component to understanding and optimizing plasma conditions for the future development of a host of plasma technologies. Moreover, the gas temperature simulations obtained via modeling by Shivkumar *et al.* are in good agreement with $T_R(\text{H}_2)$ values determined experimentally via optical emission spectroscopy (OES).³⁵ For hydrogen discharges, rovibrational excitation of the H_2 molecule can have a significant impact on several molecular reaction rates;³⁶ thus, studies focused on determining and understanding rotational and vibrational energy partitioning of H_2 are of interest to the plasma community.

Numerous experimental studies have examined the rotational and vibrational populations of molecular hydrogen in plasmas.³⁷⁻⁴⁴ Although plasmas produce rotationally excited H_2 molecules,^{35-36, 39-40, 45} the influence of this excitation and the specific reactions involving rotationally excited H_2 are not well known. Consideration of rotational excitation is essential for a detailed understanding of plasmas comprising molecular hydrogen. For example, H^- ions in negative hydrogen ion sources are formed by dissociative attachment of electrons to hydrogen molecules.⁴⁶ The reaction rate for this process increases by five orders of magnitude if the H_2 molecule is vibrationally excited to a state with the vibrational quantum number $v = 5$.⁴⁷ Rotational excitation has an analogous effect, as the rate is dependent only on the total internal energy of the molecule rather than the fractions of energy in particular rotational and vibrational modes.⁴⁸

As noted above, hydrogen is an important component not only to CH_4 plasma chemistry, but it is also a key component in several plasma technology applications including plasma-assisted catalysis and fabrication of carbon materials. A goal of the work described herein is to delve deeper into understanding CH_4 plasma chemistry and the contributions of hydrogen species by elucidating rotational energy distribution trends of H_2 $d^3\Pi_u \rightarrow a^3\Sigma_g^+$. Optical emission

spectroscopy (OES) was employed to measure relative species densities and determine $T_R(\text{H}_2)$ in several plasma systems comprising H_2 (i.e. CH_4 , H_2 , CH_4/H_2 , and H_2/Ar plasmas) to elucidate the probable excitation mechanisms occurring in each of these plasma systems. These fundamental plasma investigations that uncover information about the internal energies of hydrogen plasma species are required to utilize the full potential of multiple plasma technologies.

4.2 Results and Discussion

As T_R can be affected by the mechanism for molecule formation, we determined T_R of H_2 $d^3\Pi_u \rightarrow a^3\Sigma_g^+$ and $\text{CH } A^2\Delta \rightarrow X^2\Pi$ in H_2 and CH_4 inductively coupled plasmas with the goal of illuminating mechanistic phenomena that may be key components to overall processes occurring in these systems. Figure 4.1 shows a raw emission spectrum of the Q-branch of the H_2 $d^3\Pi_u \rightarrow a^3\Sigma_g^+$ (0,0) Fulcher (α) band in a 100% H_2 plasma at $p = 200$ mTorr, $P = 100$ W. The rotational transitions used to calculate $T_R(\text{H}_2)$ are labeled in the spectrum and the inset shows the corresponding Boltzmann plot, yielding $T_R(\text{H}_2) = 530$ K, significantly higher than room temperature, but lower than $T_R(\text{CH})$ values measured under similar conditions ($\sim 1700 - 2300$ K), reported previously.¹⁸

In low pressure hydrogen discharges, rotational level populations are known to be non-thermal.^{37, 39, 41, 45, 49-50} Rotational states with a low rotational quantum number ($J < 5$) follow a Boltzmann distribution, whereas higher rotational levels may be overpopulated by several orders of magnitude, described in detail previously.^{36, 39} Overpopulation of the higher rotational levels often leads to overestimated $T_R(\text{H}_2)$ values when using a single Boltzmann plot to calculate $T_R(\text{H}_2)$. Briefi *et al.* demonstrated that H_2 rotational populations can be described using a two-

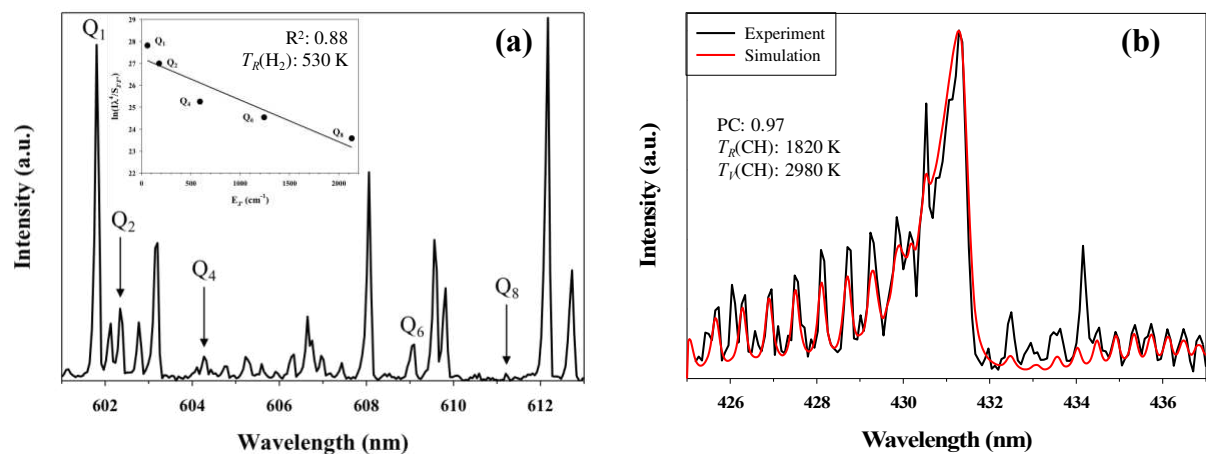


Figure 4.1. Representative emission spectra ($p = 200$ mTorr, $P = 100$ W) for (a) H_2 $d^3\Pi_u \rightarrow a^3\Sigma_g^+$ in a 100% H_2 plasma and (b) CH $A^2\Delta \rightarrow X^2\Pi$ in a CH_4/H_2 plasma (4:1 feed gas ratio). Inset in (a) shows corresponding Boltzmann plot for H_2 rotational distribution.

temperature distribution which reflects both the “cold” (lower rotational levels) and “hot” (upper rotational levels) parts of the distribution.³⁶ They found that by using this method, the calculated rotational temperature of H₂ in their system was reduced from 737 ± 45 K (one-temperature method) to 601 ± 12 K (two-temperature method).³⁶ The two-temperature method involves the use of use of several rotational lines to distinguish and ultimately fit both the “cold” and “hot” parts of the spectrum individually. Yet, the determination of the “hot temperature” can be difficult as the emission lines from the high rotational states are weak and often overlap with other species.³⁶

The non-Boltzmann character of the rotational populations is evident in our own data (inset, Figure 4.1a) where Q₁, Q₂, and Q₄ follow a linear trend, but Q₆ and Q₈ appear to deviate slightly from linearity. This result mirrors what has been previously described by Briefi *et al.* in a rf inductively coupled H₂ plasma (10^{-7} mbar) where the first five rotational levels of H₂ $d^3\Pi_u \rightarrow a^3\Sigma_g^+$ (0,0) follow a linear trend; yet, the higher rotational levels deviate from linearity.³⁶ As noted above, however, determining $T_R(\text{H}_2)$ using the two-temperature method is challenging. In our systems, many of the higher rotational emission lines are weak, especially at low P . Moreover, several rotational lines are often obscured by other species. Although this is not a significant concern in 100% H₂ and 100% CH₄ plasmas, obscured rotational lines becomes a noteworthy challenge with some of the other precursor mixtures, particularly when N₂ $B^3\Pi_g \rightarrow A^3\Sigma_u^+$ is present. Using one method to calculate $T_R(\text{H}_2)$ allows comparison of $T_R(\text{H}_2)$ values and trends between all of our plasma systems. As such, we have used the Boltzmann plot method described by Garg *et al.* and Shivkumar *et al.* to calculate $T_R(\text{H}_2)$ in our systems.^{35, 51} The specific rotational transitions used to calculate $T_R(\text{H}_2)$ (Q₁, Q₂, Q₄, Q₆, Q₈) were chosen as this part of the spectrum is relatively free from perturbations.^{35, 51}

As discussed in Section 4.1, a goal of this work is to delve deeper into understanding CH₄ plasma chemistry. This includes interpretation of the energy partitioning trends of multiple species within our plasma systems. As such, in addition to determination of $T_R(\text{H}_2)$, we utilized LIFBASE⁵² to simulate raw emission spectra of CH A²Δ → X²Π in mixed gas CH₄/H₂ plasma systems and calculate $T_R(\text{CH})$ and $T_V(\text{CH})$. Figure 4.1b shows an experimental emission spectrum of CH A²Δ → X²Π and the corresponding simulated fit in a mixed gas CH₄/H₂ (4:1 feed gas ratio) plasma at $p = 200$ mTorr, $P = 100$ W. For this particular spectrum, $T_R(\text{CH}) = 1820$ K and $T_V(\text{CH}) = 2980$ K; a peak correlation value (PC) of 0.97 indicates fair agreement between the raw and simulated data.

To further investigate energy partitioning in H₂ and CH₄ plasmas, a range of pressures and powers were explored. Figure 4.2 shows $T_R(\text{H}_2)$ as a function of p and P in two different plasma systems. In a 100% H₂ plasma, Figure 4.2a, $T_R(\text{H}_2)$ values are ~500 – 550 K and have minimal p or P dependence. Alternatively, $T_R(\text{H}_2)$ values are typically higher in a 100% CH₄ plasma, where values range from ~500 – 700 K, Figure 4.2b. Moreover, interesting trends with respect to both p and P are apparent in the 100% CH₄ plasma system. Here, $T_R(\text{H}_2)$ values concomitantly increase with p . We have previously determined T_R of several other excited state species (e.g., N₂, NO) in numerous plasma systems over similar pressure and applied power ranges.^{6, 17} In each of these studies, we have reported an opposite trend with respect to system p , where an increase in pressure results in a decrease in T_R values to varying degrees, mostly attributing this trend to rotational cooling processes. Importantly, this is also true of CH A²Δ molecules in a 100% CH₄ plasma, indicating opposing p trends for two molecules (CH and H₂) in the same plasma system.¹⁸ This trend was also observed by Cruden *et al.* in a low-pressure CF₄/O₂/Ar ICP system,¹⁵ where $T_R(\text{CO})$ rises with p while $T_R(\text{CF})$ drops as p increases. The

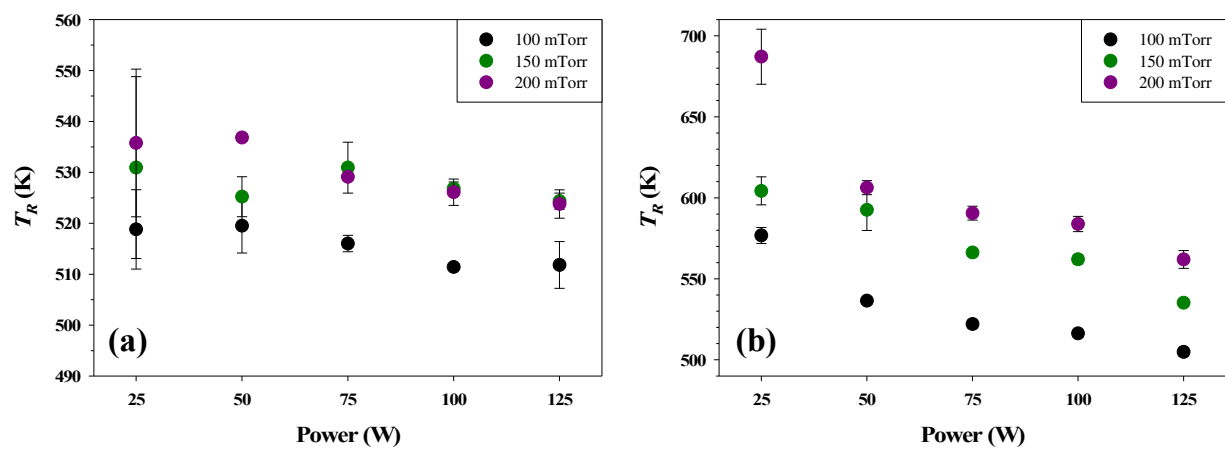


Figure 4.2. $T_R(H_2)$ in (a) 100% H_2 and (b) 100% CH_4 plasmas as a function of applied rf power at three different system pressures.

authors attribute the different p trends to differences between the kinetic energies of the species. Species possessing a kinetic energy above the mean neutral plasma temperature will experience a decrease in temperature as p increases, as a result of a higher collision rate allowing thermal equilibration of the species with the rest of the plasma.¹⁵ Moreover, Cruden *et al.* further suggested that CF is produced with a highly rovibrationally excited nascent distribution, possibly explaining the higher rotational temperatures compared to CO in their system.¹⁵ Similarly, CH $A^2\Delta$ is also typically produced with significant rovibrational excitation.^{14, 53} This suggests that dissociative electron excitation is a likely pathway for CH excitation and may help to explain the larger T_R values for CH compared to H₂ in our plasma systems. Moreover, this may also be an important factor in determining and understanding T_R trends with respect to system pressure.

Rotational energy partitioning trends of H₂ with respect to P also differ from several of our previous studies investigating molecules in N_xO_y and fluorocarbon plasmas.^{6, 17, 54} In those systems, the rotational temperature of the species of interest (e.g., N₂, NO, CF) increased with respect to applied rf P . Conversely, in the 100% CH₄ plasma system, $T_R(\text{H}_2)$ generally decreases with a concomitant increase in P , indicating opposing P trends from most of our previous studies. Nevertheless, our preceding study on rotational energy partitioning of CH $A^2\Delta$ in a 100% CH₄ plasma demonstrated a more complex relationship between $T_R(\text{CH})$ and P .¹⁸ The dependence of $T_R(\text{CH})$ on P changed as system p increased, suggesting intimate connections between plasma parameters in this system, where a change in one parameter likely produces a change in the other parameter, both of which affect energy partitioning. For example, at higher P , we are likely increasing the overall pressure via decomposition of plasma gases and formation of additional molecules. As it is difficult to obtain an accurate pressure reading when the plasma is on, this effect may not be reflected in our reported pressure values. Moon *et al.* examined

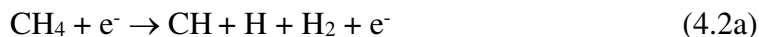
molecular plasma temperatures in atmospheric discharges and noted that the positive P dependence of $T_R(\text{CH})$ and $T_R(\text{CN})$ were relatively sensitive to other plasma parameters.⁵⁵ Previous studies from our lab indicated that CH_4 -containing plasmas can often be characterized by two modes.⁵⁶ Specifically, a shift from a capacitively coupled electrostatic mode at low P to an inductively coupled electromagnetic mode at high P occurs at ~ 75 W in our systems. As $T_R(\text{H}_2)$ values appear to level out at $\sim 75 - 100$ W and decrease slightly at higher P , the trend in $T_R(\text{H}_2)$ with respect to applied rf power may be related to a shift in the overall mode of the plasma.

Understanding mechanisms of formation for a particular species is critical to comprehending molecular plasma temperatures. In a 100% H_2 plasma, H_2^* is formed primarily through direct electron impact excitation from the ground state,^{3, 36, 57} Reaction 4.1,

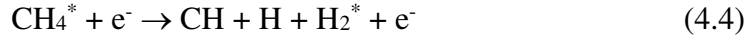
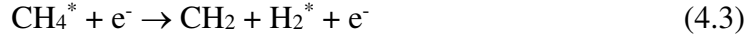


whereas in CH_4 plasmas, numerous additional pathways for H_2^* formation exist. Importantly, in 100% CH_4 plasmas, H_2^* must be formed through decomposition of the precursor, a process that can occur in a single step or multiple steps.

Similar to a hydrogen plasma, electron impact excitation of H_2 from the ground state is also the main pathway for H_2^* formation in methane plasmas,³ Reaction 4.2.



Besides direct electron impact excitation of hydrogen molecules that may be produced via decomposition and/or recombination reactions, dissociative excitation of methane molecules via collisions with electrons may also contribute to the production of H_2^* in 100% CH_4 plasmas, Reactions 4.3 – 4.5.



The discernable differences between the $T_R(\text{H}_2)$ values, listed in Table 4.1, and p and P trends in these two plasma systems prompted us to further investigate these systems by combining H_2 and CH_4 in various gas mixtures.

Mixed gas CH_4/H_2 plasmas with varying precursor ratios were investigated via OES to decipher how $T_R(\text{H}_2)$ changes as a function of % H_2 in the feed gas. Figure 4.3 shows $T_R(\text{H}_2)$ in a CH_4/H_2 plasma as a function of % H_2 in the gas feed at $p = 200$ mTorr and two different powers. Notably, there is an inverse linear relationship between $T_R(\text{H}_2)$ and % H_2 in CH_4/H_2 plasmas. The P trend for $T_R(\text{H}_2)$ in 100% CH_4 plasmas (0% H_2) is again highlighted in Figure 4.3 where there is a >100 K difference in $T_R(\text{H}_2)$ values between $P = 25$ W and $P = 125$ W plasmas. As more H_2 is added to the system, however, the P dependence essentially disappears as $T_R(\text{H}_2)$ values at $P = 25$ W and $P = 125$ W are within error of each other in a 100% H_2 plasma. Moreover, at $p = 200$ mTorr, the dependence on % H_2 decreases by nearly a factor of 4 as P is increased from 25 W to 125 W, highlighting the significant effects of P and precursor ratio on fundamental plasma processes and, consequently, $T_R(\text{H}_2)$.

At $P = 125$ W, $T_R(\text{H}_2)$ values are only ~ 35 K higher in the 100% CH_4 plasma system than in the 100% H_2 plasma system. This subtle difference in $T_R(\text{H}_2)$ values between the two plasma systems at $P = 125$ W, suggests that similar excitation mechanisms for H_2^* may be occurring under these plasma conditions. Thus, in the CH_4 plasma system, at high P , we hypothesize that direct electron impact of molecular hydrogen, Reaction 4.2, is the predominant route for excitation. In contrast, at low P , dissociative excitation, Reactions 4.3 – 4.4, may

Table 4.1. $T_R(\text{H}_2)$ values for H_2 and CH_4 plasma systems.^a

Pressure (mTorr)	Applied rf Power (W)	100% H_2	100% CH_4	75% CH_4 / 25% Ar
50	25	--	560 (5)	--
	50	--	545 (5)	--
	75	--	535 (5)	--
	100	--	540 (5)	--
100	25	520 (10)	575 (5)	540 (10)
	50	520 (5)	535 (5)	525 (5)
	75	515 (5)	520 (5)	525 (5)
	100	510 (5)	515 (5)	520 (5)
	125	510 (5)	505 (5)	535 (10)
150	25	530 (20)	605 (10)	590 (10)
	50	525 (5)	590 (15)	550 (5)
	75	530 (5)	565 (5)	540 (5)
	100	525 (5)	560 (5)	535 (10)
	125	525 (5)	535 (5)	530 (5)
200	25	535 (15)	690 (20)	635 (20)
	50	535 (5)	605 (5)	580 (20)
	75	530 (5)	590 (5)	580 (10)
	100	525 (5)	585 (5)	565 (5)
	125	525 (5)	560 (5)	545 (5)

^aValues in parentheses represent standard deviation calculated from the mean of $n \geq 3$ trials.

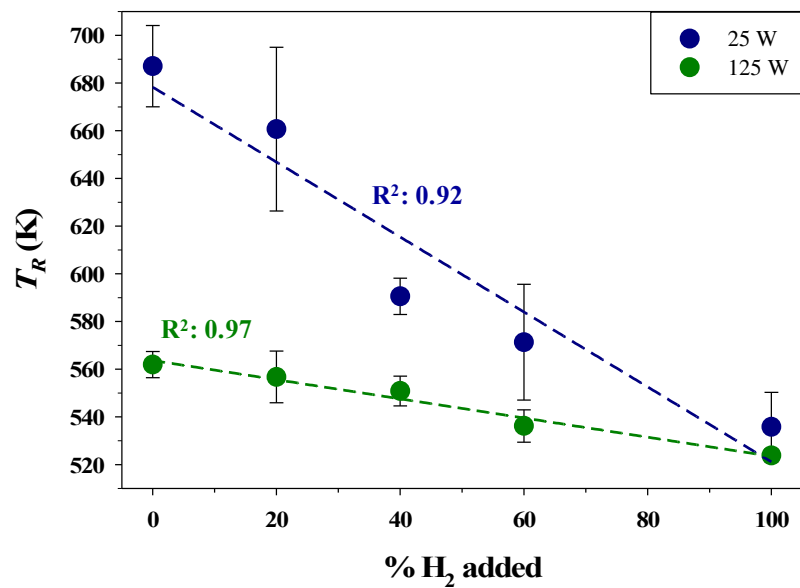
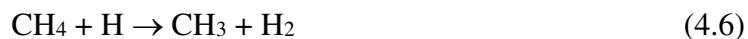


Figure 4.3. $T_R(\text{H}_2)$ as a function of % H₂ in CH₄/H₂ plasmas ($p = 200$ mTorr) at two applied rf powers (25 and 125 W).

become a more prominent mechanism for H_2^* formation, ultimately resulting in the higher $T_R(H_2)$ values observed at low P .

Furthermore, additional routes for H_2^* formation can occur in CH_4/H_2 gas mixtures. NASA groups have focused on gas phase reactions crucial to deposition processes and have noted that the CH_4 dissociation process is not only the result of electron impact dissociation but also to the hydrogen abstraction mechanism, Reaction 4.6, where the hydrogen atom can be sourced from either precursor.⁵⁸⁻⁶¹



The molecular hydrogen product is subsequently excited via electron impact. In 100% CH_4 plasmas, methane is initially dissociated via collisions with energetic electrons. As soon as H atoms are formed, however, hydrogen abstraction becomes an important channel for further dissociation of methane. Previous studies of hydrogen-hydrocarbon mixtures (e.g., H_2/CH_4 , H_2/C_2H_2) agree that hydrogen abstraction from methane by atomic hydrogen dominates over electron impact dissociation, except at low pressures.⁶²⁻⁶⁶ Specifically, a study on methane dissociation in low-pressure plasmas described the likelihood of hydrogen abstraction contributing to methane dissociation at pressures of 1 Torr and 6 Torr.⁶⁶ Several plasma properties (e.g., electron temperature, electron density, atomic hydrogen density, T_g) contribute to the ratio between the two main processes involved in methane dissociation, electron impact and hydrogen abstraction.^{20, 66} Consequently, each of these plasma properties is dependent on the gas pressure. Reaction rates reported by Mechold *et al.* suggest that electron impact is the predominate route to methane dissociation at 1 Torr whereas hydrogen abstraction dominates methane dissociation processes at 6 Torr.⁶⁶ Thus, in our systems, we believe Reaction 4.6 does

not significantly contribute to production of molecular hydrogen, even as H-alpha density increases with P .

$T_R(\text{CH})$ and $T_V(\text{CH})$ were also measured in the CH_4/H_2 plasma systems at $p = 200$ mTorr, Table 4.2. $T_R(\text{CH})$ values range from $\sim 1700 - 2100$ K over the studied parameter space, with no clear trends relating to applied rf power or precursor ratio. Reported $T_V(\text{CH})$ values are higher than T_R values, a well-documented phenomenon,⁶⁷ and range from ~ 2000 to 3000 K. Similar to $T_R(\text{CH})$ results, there are no clear trends corresponding to P or precursor ratio. Overall, $T_R(\text{CH})$ and $T_V(\text{CH})$ values are similar to previously reported values from our lab in a 100% CH_4 plasma, discussed in Chapter 3.¹⁸ These results indicate that H_2 does not appreciably affect CH formation mechanisms or vibrational excitation pathways.

Notably, $T_R(\text{H}_2)$ values are significantly lower than what is observed for $T_R(\text{CH})$ in CH_4 -containing plasma systems where $T_R(\text{CH})$ is $\sim 1700 - 2400$ K, Table 4.2.¹⁸ Similarly, Avtaeva and Lapochkina observed disparate ground state $T_R(\text{H}_2 \text{X}^1\Sigma)$ and excited state $T_R(\text{CH A}^2\Delta)$ values in a methane-containing rf capacitive discharge, which they attributed to the molecules' radiative lifetimes and concentrations in the plasma.³ The concentration of molecular hydrogen in methane discharges is fairly high, especially when compared to $\text{CH A}^2\Delta$ concentration.³ As such, direct electron impact excitation of H_2 from the ground state tends to dominate over dissociative excitation of H_2 from a methane molecule, corresponding to the relatively low reported $T_R(\text{H}_2 \text{X}^1\Sigma)$ values (487 – 564 K) reported by Avtaeva and Lapochkina.^{3, 36}

In another study, Heintze *et al.* examined methane plasma dissociation and formation of C_2 and H_2 in pulsed microwave discharges.²⁰ Notably, they determined T_R of both ground and excited states species for C_2 ($\text{a}^3\Pi_u$, $\text{d}^3\Pi_g$) and H_2 ($\text{X}^1\Sigma_g^+$, $\text{d}^3\Pi_u^-$) and found the rotational temperature of excited state H_2 ($\text{d}^3\Pi_u^-$) ($\sim 800 - 1500$ K) was significantly lower than that for

Table 4.2. T_R and T_V values for CH₄/H₂ plasma at $p = 200$ mTorr.^a

Applied rf Power (W)	% H ₂	$T_R(\text{H}_2)$	$T_R(\text{CH})$	$T_V(\text{CH})$
25 W	0	690 (20)	1790 (30)	2280 (260)
	20	660 (30)	1720 (70)	2250 (120)
	40	590 (10)	1890 (50)	2060 (10)
	60	570 (25)	2090 (120)	2700 (50)
	100	535 (15)	--	--
75 W	0	590 (5)	1880 (10)	2680 (10)
	20	570 (10)	1790 (30)	2770 (140)
	40	560 (5)	1780 (70)	2060 (10)
	60	550 (15)	1870 (50)	2700 (210)
	100	530 (5)	--	--
125 W	0	560 (5)	1880 (10)	2810 (80)
	20	555 (10)	1770 (30)	2910 (100)
	40	550 (5)	1730 (70)	2060 (10)
	60	535 (5)	1840 (50)	2700 (40)
	100	525 (5)	--	--

^aValues in parentheses represent standard deviation calculated from the mean of $n \geq 3$ trials.

ground state H_2 ($X^1\Sigma_g^+$) and either of the C_2 electronic states ($d^3\Pi_g$ or $a^3\Pi_u$) (all were ~ 1500 – 2500 K).²⁰ The authors attributed the lower rotational temperature of H_2 $d^3\Pi_u^-$ to the short radiative lifetime (40 ns)⁶⁸ of the upper state, which does not allow for sufficient time to achieve thermal equilibrium of rotational level populations.²⁰ Furthermore, the observation that three of the four electronic states had similar rotational temperatures led the authors to assume that the gas temperature corresponded to these temperatures (~ 1500 – 2500 K).²⁰ This suggests that a similar amount of energy may be partitioned into the rotational and vibrational modes of all methane decomposition products. Our studies, however, demonstrate disparate $T_R(H_2)$ and $T_R(CH)$ values are obtained in our methane-based plasma systems. Possible explanations for the differences between rotational temperature values in these systems may be related to the disparities in the plasma systems studied and the production mechanisms and nascent rotational distributions of the molecules of interest. Emission intensity within a plasma is influenced by several factors including the electron energy distribution function (EEDF), formation mechanisms, cascade processes, radiation transport, and collisions.⁶⁹ Importantly, the operation frequency (microwave vs. rf) may further affect this as frequency can alter the shape of EEDF and thereby control electron-molecule reaction channels.⁷⁰⁻⁷¹ Moreover, our system operates in the mTorr pressure range (~ 0.13 – 0.26 mbar), whereas the system used by Heintze *et al.* operates at 30 mbar.²⁰ The much lower pressures used in our system increases the mean free path, reducing the possibility of thermalizing collisions. In their system, Heintze *et al.* demonstrate that C_2 is mainly formed via dimerization of CH_x species and subsequent dehydrogenation via hydrogen abstraction from atomic hydrogen present in the discharge.²⁰ Furthermore, they believe excited state C_2 $d^3\Pi_g$ is formed via electron impact excitation from the ground state. In our systems, we believe CH $A^2\Delta$ is produced via dissociative excitation of a

CH_x parent molecule. Previous studies showed that CH X²Π radicals typically react very quickly with residual gas molecules;^{3, 31, 72} thus, in CH₄ plasmas, CH A²Δ is primarily formed via dissociative excitation of CH₄ rather than electron impact excitation of CH from the ground state. Furthermore, the excited state lifetime of CH A²Δ is relatively short, ~ 5 × 10⁻⁷ seconds,³ so the rotational distribution formed in the course of dissociative excitation has little time to relax to an equilibrium distribution with a temperature close to the gas temperature.³ This may explain the much higher $T_R(\text{CH})$ values compared to $T_R(\text{H}_2)$ as reported herein and by Avtaeva and Lapochkina.³

In a related system, Cruden *et al.* determined rotational temperatures of multiple diatomic species in a low pressure (30 mTorr), inductively coupled CF₄ plasma to examine the accuracy of using T_R to estimate the neutral gas temperature.⁴ Four different rotational temperatures were obtained for five molecular species ranging from ~1200 – 2300 K. Species produced in the plasma bulk (CF and CN) yielded the lowest T_R values (~1250 K), whereas SiF, an etch product from plasma interaction with the quartz window in the reactor, had the highest T_R values (~2300 K). C₂ and CO, produced both in the plasma bulk and via plasma-surface interactions had intermediate T_R values (1600 K and 1800 K, respectively). Their results demonstrate a thermal nonequilibrium between molecular species and further imply that formation mechanisms play a significant role in rotational temperature determination. A follow up study by Cruden *et al.* focused on determination of $T_R(\text{CF})$ and $T_R(\text{CO})$ in a CF₄/O₂/Ar ICP.¹⁵ In this study, $T_R(\text{CF})$ was elevated in comparison to $T_R(\text{CO})$. The difference between $T_R(\text{CF})$ and $T_R(\text{CO})$ was attributed to an incomplete equilibration of $T_R(\text{CF})$ with the average neutral gas temperature. The authors stated that CF created via CF₄ dissociation will possess a kinetic energy above that of other neutral species in the discharge because of Franck-Condon heating.¹⁵ Franck-Condon heating

occurs when an electron strikes a neutral molecule with sufficient energy to raise the molecule to a dissociative state, usually greater than the dissociation energy of the molecule resulting in extra kinetic energy being distributed to the dissociated fragments.⁷³

Few other studies have investigated energy partitioning of multiple species in low temperature plasmas. As discussed in the Section 4.1, insight into fundamental plasma processes can be gained through consideration of energy partitioning trends of multiple species. Such information is crucial to advancing plasma technologies (e.g., plasma-assisted catalysis, film/coating technologies) which rely on knowledge of fundamental chemical processes in systems of interest to optimize plasma conditions for plasma processing. As such, a goal of this work is to examine the energetics of multiple species in low temperature plasma systems to gain a deeper understanding of the molecular-level processes occurring in these systems. Although we have reported on both $T_R(\text{H}_2 \text{ d}^3\Pi_u)$ and $T_R(\text{CH A}^2\Delta)$ herein, these are only two of the many possible products in methane plasma dissociation, and as such, future investigations should include the use of other plasma diagnostic techniques to elucidate additional underlying processes in these plasma systems. For example, our lab has previously investigated energy partitioning of $\text{N}_2 \text{ B}^3\Pi_g \leftrightarrow \text{C}^3\Pi_u$ and $\text{NO X}^2\Pi \leftrightarrow \text{A}^2\Sigma^+$ in N_xO_y plasma systems using broadband absorption spectroscopy (BAS) to probe energetics of ground state molecules as a complimentary technique to OES.^{6, 17} $T_R(\text{NO})$ was almost exclusively higher for the ground state ($\text{X}^2\Pi$) compared to the excited state ($\text{A}^2\Sigma^+$) in a 100% NO plasma suggesting that energy transfer in the excited state may be fast enough to achieve some level of thermalization.⁶ Similar investigations in CH_4 and CH_4/H_2 plasmas may illuminate further mechanistic details. As such, future studies shall include employing BAS in conjunction with OES to obtain energy partitioning information on ground state species as well as excited state species.

Further spectral analysis allows us to monitor changes in species densities as functions of plasma parameters, which can help elucidate reaction mechanisms, especially when combined with characteristic plasma temperatures (e.g., T_R and T_V). Within this chapter, we utilized inert gas actinometry to determine relative densities of several gas-phase species of interest. In these cases, a small amount of Ar (~5 – 10%) was added as an actinometer to the H₂ and CH₄ plasmas, allowing for species comparisons across systems. Relative densities of H₂ and H _{α} within H₂ and CH₄ plasma systems are shown in Figure 4.4 as a function of P ($p = 200$ mTorr). H₂ density increases with respect to P in a CH₄ plasma system but has virtually no dependence on P in a H₂ plasma. Similarly, in a 100% H₂ plasma, $T_R(\text{H}_2)$ has no P dependence and is relatively constant among changes in plasma system p and P . Conversely, there is a clear, linear ($R^2 = 0.91$) P dependence for $T_R(\text{H}_2)$ in a 100% CH₄ plasma where $T_R(\text{H}_2)$ concomitantly decreases with increasing P . As H₂^{*} concentration increases in the plasma, direct electron impact excitation, Reaction 4.2, may become a more dominant process because of the increasing concentration of molecular hydrogen in the discharge.³ Ultimately, this may correspond to the lower $T_R(\text{H}_2)$ values observed at high P in the CH₄ plasma system.

Conversely, in the 100% H₂ plasma system, precursor gas flow is continuous, and molecular hydrogen does not have to be formed from the precursor through decomposition reactions. Thus, direct electron impact excitation, Reaction 4.1, is the primary route to H₂ excitation. Furthermore, H₂ density remains relatively constant as a function of P . Together, these may help explain the lack of pressure or power dependence of $T_R(\text{H}_2)$ observed in a 100% H₂ plasma. However, H₂^{*} may not be formed exclusively via Reaction 4.1 in a H₂ plasma, as other possible routes to H₂^{*} formation exist. For example, atomic hydrogen may also recombine

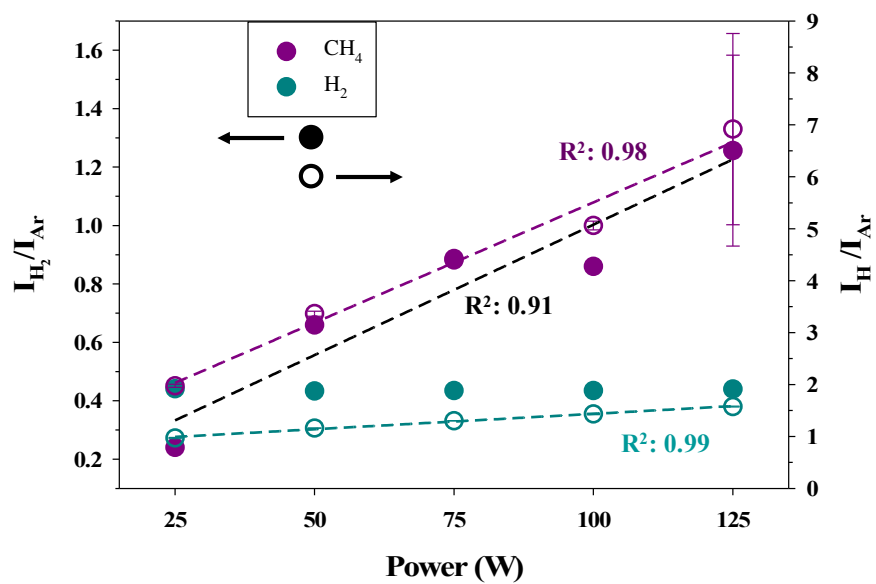


Figure 4.4. Relative density of H₂ (closed circles, left axis) and H_α (open circles, right axis) as a function of applied rf power in CH₄ and H₂ plasmas (each with 10% Ar, $p = 200$ mTorr). Dashed lines represent linear regression analyses for: H₂ (black, slope: 0.0089) and H_α (purple, slope: 0.0463) in a CH₄ plasma, and H_α (cyan, slope: 0.0059) in a H₂ plasma.

to form H₂, Reaction 4.7, where either one or both hydrogen atoms may already be in an excited state:



Reaction 4.7 may occur in either the 100% CH₄ or the 100% H₂ plasma system, and as such, the atomic hydrogen density in the plasma may also be an important consideration for determining the likelihood of Reaction 4.7. Figure 4.4 also shows the relative densities of H_α^{*}, revealing H_α^{*} increases with increasing *P* in both systems, indicating the probability of Reaction 4.4 may rise at higher *P*. Although H_α density increases with increasing *P* in both CH₄ and H₂ plasma systems, the *P* dependence is ~5 times greater in the CH₄ plasma relative to the H₂ plasma. These results highlight the significant role of *P* in hydrogen species concentrations in CH₄ plasmas whereas this role is significantly less important in H₂ plasmas.

As one additional way to visualize the relationships between different molecular temperatures in this system, Figure 4.5 shows the relationship between *T_R*(CH) and *T_R*(H₂) in a 100% CH₄ plasma at different *p* and *P*. As reported previously, *T_R*(CH) generally decreases with increasing *p* with values decreasing from ~ 2350 K at 50 mTorr to ~ 1750 K at 200 mTorr.¹⁸ Although the pressure dependence for *T_R*(H₂) is not as dramatic, it is still evident. *T_R*(H₂) values range from ~500 to ~600 K at lower pressures (*p* = 50 – 100 mTorr) compared to the slightly higher values (~550 – 700 K) measured at higher pressures (*p* = 150 – 200 mTorr). The *P* dependence of *T_R*(CH) in a 100% CH₄ plasma is complex and appears to also depend on other plasma parameters and thus, is not as apparent in Figure 4.5.¹⁸ Nevertheless, these data clearly display a *P* dependence for *T_R*(H₂). High applied rf power (125 W) results in lower *T_R*(H₂) values (~500 – 570 K) for a CH₄ plasma, whereas lower applied rf power (25 W) results in higher *T_R*(H₂) values (~570 – 700 K).

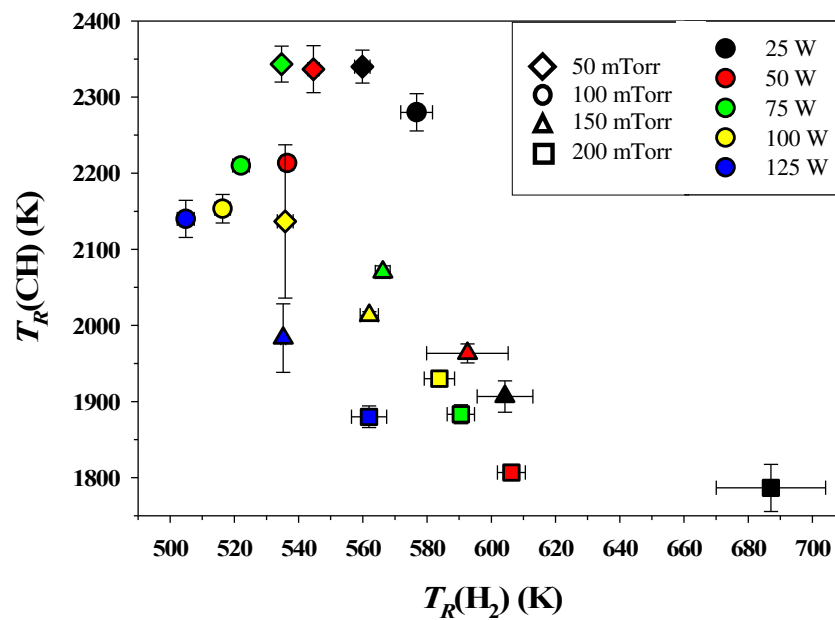


Figure 4.5. Relationship between $T_R(\text{CH})$ (y-axis) and $T_R(\text{H}_2)$ (x-axis) over a range of pressures and applied rf powers in 100% CH_4 plasmas. Each shape corresponds to a different p and each color corresponds to a different P .

Based on the $T_R(\text{CH}, \text{H}_2)$ measurements in the mixed gas CH_4/H_2 system and the results displayed in Figure 4.5, it is apparent that $T_R(\text{CH}, \text{H}_2)$ depend heavily on p and P of the plasma system in a 100% CH_4 plasma. By more closely examining these energy partitioning trends we observe that at low p and low P , both $T_R(\text{CH})$ and $T_R(\text{H}_2)$ values are generally high. For example, at $p = 50$ mTorr, $P = 25$ W $T_R(\text{CH}) = \sim 2350$ K and $T_R(\text{H}_2) = \sim 580$ K; both of these values are on the higher end of the reported ranges for the investigated parameter space. Conversely, at high p and high P , $T_R(\text{CH})$ and $T_R(\text{H}_2)$ values are both on the lower end of the reported ranges for the investigated parameter space. For instance, at $p = 200$ mTorr, $P = 125$ W, $T_R(\text{CH}) = \sim 1900$ K and $T_R(\text{H}_2) = \sim 560$ K.

Previously, we studied the effect of Ar in the plasma on $T_R(\text{CH})$ and $T_V(\text{CH})$ energy partitioning trends in CH_4 plasmas.¹⁸ Addition of Ar as a precursor gas changed the emission spectrum of the $\text{CH A}^2\Delta$ band.¹⁸ This, in turn, had a profound effect on the energy partitioning trends for $\text{CH A}^2\Delta$ compared to a 100% CH_4 plasma. As such, here we further investigated the effect of Ar addition on $T_R(\text{H}_2)$ in CH_4 and H_2 plasmas. $T_R(\text{H}_2)$ values were calculated for a CH_4/Ar (3:1) system, Table 4.1. Notably, $T_R(\text{H}_2)$ values and trends in the CH_4/Ar mixed gas system do not differ appreciably from the 100% CH_4 plasma system. Similarly, in H_2/Ar plasmas, $T_R(\text{H}_2)$ was unaffected by addition of Ar as a precursor gas. Figure 4.6 shows $T_R(\text{H}_2)$ in H_2/Ar plasmas comprising up to 60% Ar at a total pressure of 150 mTorr. At greater than 60% Ar, some H_2 Fulcher rotational band emissions were either very weak or obscured so the Boltzmann plot method was ineffective at calculating $T_R(\text{H}_2)$. $T_R(\text{H}_2)$ values range from ~ 500 to 550 K, Figure 4.6, and appear to be independent of both P and % Ar in the gas feed. Similarly, this trend was documented for all studied pressures ($p = 100 - 200$ mTorr).

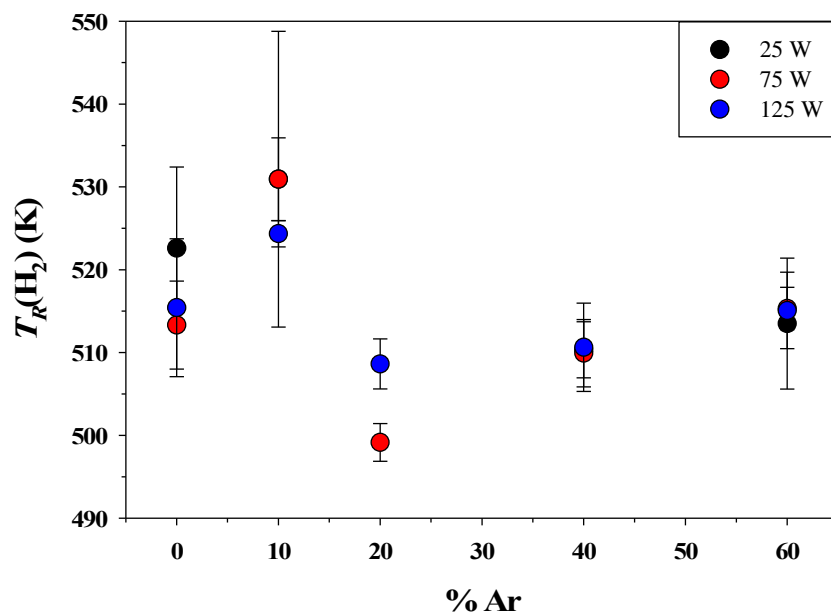


Figure 4.6. $T_R(\text{H}_2)$ as a function of % Ar in a H_2/Ar plasma system at three different P ($p = 150$ mTorr).

Adding an inert precursor like Ar increases the number of nonreactive gas-phase collisions and thus, can be used to distinguish between the effects of collision environment and formation mechanisms of species of interest. Studies from Stillahn and Fisher measured the effect of Ar addition on $T_R(\text{CN } X^2\Sigma^+)$ in CH_3CN plasmas.⁷⁴ In a $\text{CH}_3\text{CN}/\text{Ar}$ plasma, $T_R(\text{CN})$ remained unaffected by an increase in the %Ar in the feed gas mixture.⁷⁴ Yet, a negative dependence of $T_R(\text{CN})$ on system p in their study suggests that collisional cooling effects are dependent on the frequency of collisions rather than the nature of them. In a 100% H_2 plasma system, there is no p dependence for $T_R(\text{H}_2)$ (Figure 4.2), suggesting that H_2 is not rotationally thermalized via collisions in this system. Excited H_2 ($d^3\Pi_u^-$) has a short radiative lifetime of 40 ns⁶⁸ and is depopulated rather quickly via radiative decay, reducing the likelihood of thermalizing collisions with other species.^{3, 36} Ultimately, we believe that the work presented herein demonstrates the significance of employing optical plasma diagnostics as a tool to determine molecular temperature trends and elucidate probable mechanistic information. Yet, significant additional work must be done to more fully elucidate the fundamental chemical processes in the gas phase and at the gas-surface interface to address the current limitations of plasma technologies.

4.3 Summary

Plasma species can be produced via a variety of mechanisms (direct-impact excitation, decomposition, recombination, etc.); therefore, fundamental investigations of the energetics of plasma species are crucial components to understanding and optimizing plasma conditions for the future development of a host of plasma technologies. OES was employed to elucidate energy partitioning trends of H_2 $d^3\Pi_u \rightarrow a^3\Sigma_g^+$ and $\text{CH } A^2\Delta \rightarrow X^2\Pi$ in H_2 and CH_4 plasma systems.

Generally, $T_R(\text{CH})$ values ($\sim 1700 - 2100$ K) are much higher than $T_R(\text{H}_2)$ values ($\sim 500 - 700$ K) in a 100% CH_4 plasma. These disparate values likely result from a combination of the differences in the species densities, radiative lifetimes, and consequently their excitation pathways. Direct electron impact excitation is indicated as the primary H_2^* formation pathway in a 100% H_2 plasma, but elevated $T_R(\text{H}_2)$ values in a 100% CH_4 plasma suggest that other excitation mechanisms are likely contributing to the production of H_2^* . Additionally, studies of CH_4/H_2 mixed gas plasma systems highlight the significant effects of plasma parameters (e.g., applied rf power, feed gas composition) on $T_R(\text{H}_2)$ values and trends. Nevertheless, $T_R(\text{CH})$ and $T_V(\text{CH})$ do not change appreciably as function of feed gas composition in mixed gas CH_4/H_2 plasmas indicating that H_2 does not appreciably affect CH formation mechanisms or vibrational excitation pathways. Ultimately, these data provide information that may lend critical insight into the overall character of the plasma and aid in understanding key mechanistic phenomena occurring during plasma processing.

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CHAPTER 5

EMPLOYING OPTICAL EMISSION SPECTROSCOPY TO ELUCIDATE THE IMPACT OF TITANIUM DIOXIDE IN PLASMA ASSISTED CATALYSIS SYSTEMS

This chapter contains results to be submitted as a full paper under the same title to *Applied Catalysis B* by Tara L. Van Surksun and Ellen R. Fisher. Optical emission spectroscopy (OES) was employed to investigate gas-phase processes in H₂ and CH₄ plasma systems in the presence of a catalytic TiO₂ substrate. The introduction of TiO₂ into the discharge has minimal effect on the rotational temperature of H₂ [$T_R(\text{H}_2)$] in a 100% H₂ plasma but reduces $T_R(\text{H}_2)$ values by up to 300 K in a 100% CH₄ plasma. TR-OES studies echo energy partitioning results and reveal further details about the kinetics of H₂ formation and the impact of the catalyst on gas-phase processes. Comprehensive materials analysis of the catalyst before and after plasma exposure reveals that the H₂ plasma acts as primarily an etching system whereas competing etching and deposition processes may be occurring under some conditions in CH₄ plasma system. This work was supported by funding through the National Science Foundation (NSF CBET – 1803067) and the American Chemical Petroleum Research Fund (ACS PRF 59776 – ND6). I also thank the staff of the CSU Analytical Resources Core for assistance with the XPS and SEM analyses and the Dr. Justin Sambur research group for support with the Raman spectroscopy analyses.

5.1 Introduction

Plasma-assisted catalysis (PAC) has recently gained attention in the plasma community because of its enormous potential to enhance feed gas conversion.¹⁻³ Generally, PAC describes the coupling of a plasma with a catalyst for enhanced processing of the input gas stream to either

convert the feed gas mixture to another gas mixture or to grow a material from the precursor gas. For example, in plasma-enhanced chemical vapor deposition (PECVD) systems used for fabrication of carbon nanostructures, a hydrocarbon plasma is typically brought into contact with a catalyst (usually Ni, Fe, or Co).⁴ PAC, however, is more traditionally used to describe waste gas stream processing such as for the abatement of volatile organic compounds⁵⁻⁷ or hydrocarbon reforming for the production of value-added chemicals such as syngas or methanol.⁸⁻¹⁰ Regardless of the end application, the underlying fundamental phenomena in PAC systems are still not well understood, reducing its overall utility.

To improve the utility of PAC, it is crucial to understand and optimize the underlying physicochemical mechanisms for their desired applications. Although many studies have focused on parametric optimization for increasing gas conversion efficiency,¹¹⁻¹⁴ relationships between plasma parameters and performance are ultimately poorly understood, making it tedious and time-consuming to try to reproduce similar results in different reactor setups. Few studies have actually addressed fundamental aspects of PAC systems. Specifically, the need for fundamental insight in this field requires an understanding of plasma generation and general operating conditions, catalyst selection (including consideration of both chemical and physical properties), and the interactions between the plasma and catalyst. Importantly, an understanding of how the plasma affects the catalyst properties and vice versa must also be construed to address current challenges with implementing PAC technologies. As such, fundamental investigations that probe the molecular-level processes in PAC are central to improving PAC processes.

Knowledge of the roles of gas-phase radicals and radical-surface interactions is key to understanding overall plasma chemistry. To further illuminate the effect of the catalyst on the plasma environment, it is vital to investigate the gas-phase chemistry of the plasma both with and

without a catalyst. Specifically, an understanding of how energy is partitioned into vibrational, rotational, and translational modes provides insight into formation mechanisms, decomposition pathways, and overall plasma chemistry. Figures of merit such as rotational and vibrational temperatures (T_R and T_V , respectively) describe the energetics of species within the plasma system. One study that examined the impact of a catalyst on internal plasma temperatures measured T_R and T_V of $\text{CH A}^2\Delta \rightarrow \text{X}^2\Pi$ in a packed bed dielectric barrier discharge (DBD) using optical emission spectroscopy (OES).¹⁵ Nozaki *et al.* found that although $T_R(\text{CH})$ was dependent on the catalyst bed temperature, $T_R(\text{CH})$ remained unchanged upon addition of the catalyst to the reactor.¹⁵ The explanation for this observation lies in the assumption that the rotational equilibrium of $\text{CH A}^2\Delta$ is reached within its radiative lifetime and that the R branches display a similar intensity distribution with or without the catalyst. In contrast, $T_V(\text{CH})$ increased significantly with bed temperature only when the Ni catalyst was present. Specifically, the relative intensity of the $\nu(2, 2)$ vibrational band remained independent of bed temperature but decreases in the $\nu(0, 0)$ and $\nu(1, 1)$ vibrational bands were observed as bed temperature increased only with the catalyst present. Consequently, the decreased contributions of the $\nu(0,0)$ and $\nu(1,1)$ vibrational bands to the overall spectral structure results in the observed increase in vibrational temperature in the presence of the catalyst. As the electric and optical properties (e.g., reduced field strength, average electron density, rotational temperature) were not affected by the presence of the Ni catalyst,¹⁵⁻¹⁶ the authors hypothesize that the $\text{CH A}^2\Delta$ $\nu(0, 0)$ and $\nu(1, 1)$ states selectively react on the Ni surface.

We have previously investigated energy partitioning trends of $\text{CH A}^2\Delta \rightarrow \text{X}^2\Pi$ and $\text{H}_2 d^3\Pi_u \rightarrow a^3\Sigma_g^+$ in CH_4 -based low pressure, inductively-coupled plasmas as functions of plasma parameters (Chapters 3 and 4, respectively).¹⁷⁻¹⁸ An overview of the internal temperature values

and parameter trends determined from 100% H₂ and 100% CH₄ plasmas sans catalyst are displayed in Table 5.1. Notably, $T_V(\text{CH})$ was higher than $T_R(\text{CH})$ regardless of gas mixture, pressure, or power, and both $T_V(\text{CH})$ and $T_R(\text{CH})$ decreased with increasing pressure, suggesting collisional quenching. $T_R(\text{CH})$ values were also nominally much higher than $T_R(\text{H}_2)$ values in a 100% CH₄ plasma system, Table 5.1. Moreover, studies using a 100% H₂ plasma reveal relatively low $T_R(\text{H}_2)$ values (~500 – 550 K) with virtually no trends with respect to system pressure and power.¹⁸ These disparate values and trends may be attributed to a combination of the differences in species densities, radiative lifetimes, and their excitation pathways. In this work, we expand on these fundamental studies by introducing a TiO₂ catalyst to H₂ and CH₄ plasmas. We examine the impact of the plasma on the catalyst by exploiting chemical and morphological characterization techniques to assess the material prior to and post plasma exposure. Additionally, we investigate the impact of the catalyst on gas phase chemistry via OES, which allows us to non-intrusively probe the energetic and kinetic characteristics of the system. T_R and T_V are measured for three excited state species (CH, H₂, OH) and are discussed in comparison to values obtained without a catalyst.

5.2 Results

A major focus of this work is to investigate fundamental plasma-catalyst interactions in environmentally relevant systems. Our multi-pronged approach towards unravelling complex PAC environments involves an investigation of both the gas phase processes and an analysis of the catalyst's chemical and morphological properties. Raw OES spectra of a H₂ plasma (10% Ar) show emission arising from atomic and molecular hydrogen species and Ar species, Figure 5.1a. With a TiO₂ substrate present, additional spectral peaks are observed, arising from OH and CO emission, Figure 5.1b. As these species are not detected above experimental noise in the

Table 5.1. Internal temperature values and trends from 100% H₂ and 100% CH₄ plasmas sans catalyst (reported previously).¹⁷⁻¹⁸

	100% H ₂	100% CH ₄		
	$T_R(\text{H}_2)$	$T_R(\text{H}_2)$	$T_R(\text{CH})$	$T_V(\text{CH})$
internal temperature value range (K)	~500 – 550	~500 – 700	~1750 – 2350	~2280 – 3440
pressure increase (100 mTorr → 200 mTorr)	no trend	increases	decreases	decreases
power increase (25 W → 125 W)	no trend	decreases	trend dependent on system pressure	trend dependent on system pressure

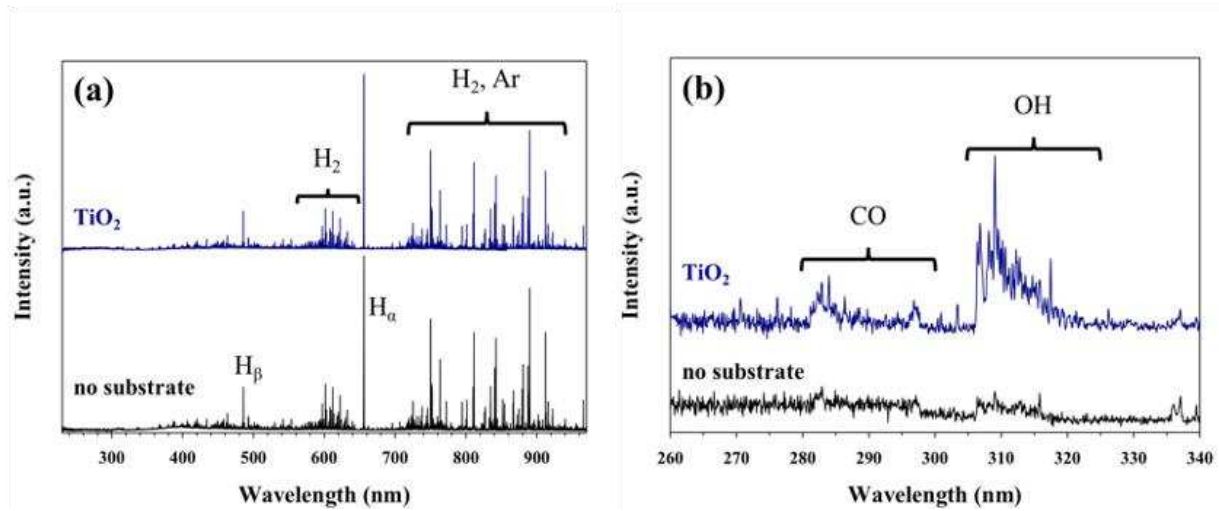


Figure 5.1. Raw OES spectra of H_2 plasma ($p = 100$ mTorr, $P = 100$ W, $t = 30$ s) collected coaxially without a substrate and with a TiO_2 substrate: (a) full spectral range and (b) expanded view of the 260 – 340 nm range.

substrate-free system, OH production likely occurs through removal of oxygen from the TiO₂ catalyst and the small amounts of CO_(g) also likely arise via interaction of gas-phase species with adventitious carbon on the catalyst surface.

Further spectral comparison via inert gas actinometry elucidates details about relative densities of excited state species (denoted here with brackets, e.g. [OH]). For these studies, emissions from OH (309.0 nm), H_α (656.5 nm), H₂ (601.8 nm), and Ar (750.4 nm) were monitored. Actinometry studies were performed for several power conditions in H₂ plasmas ($p = 100$ mTorr) both with and without TiO₂ for 5 min immediately following plasma ignition. Measurements were made at two locations, in the coil region directly above the substrate (cross-sectional) and downstream (coaxial). Figure 5.2a shows [OH] as a function of time ($p = 100$ mTorr, $P = 100$ W) with and without TiO₂ present in the reactor. Notably, [OH] is nearly zero without the substrate; however, when TiO₂ is introduced into the plasma [OH] is initially greater than the no substrate system, then decreases as a function of time. After ~2 min of plasma on time, the [OH] is within error of the no substrate system and essentially zero for all P studied. Actinometry results from the coil region demonstrate that [OH] may be only slightly elevated compared to the coaxially collected data, suggesting that when OH is formed from plasma-substrate interactions it likely remains intact as it travels downstream in the reactor.

Actinometric analysis of hydrogen species in the plasma provides insight on the impact of TiO₂ on gas phase properties. [H₂] remained relatively constant as a function of time (Figure 5.2b), and both the addition of the catalyst and the measurement location essentially has no effect on [H₂]. Yet, the atomic hydrogen density is significantly elevated in the coil region compared to the coaxially collected data, Figure 5.2c. This is expected given the constant source of H₂ gas, which can dissociate to form H in the coil region of the reactor. Moreover, [H] does not change

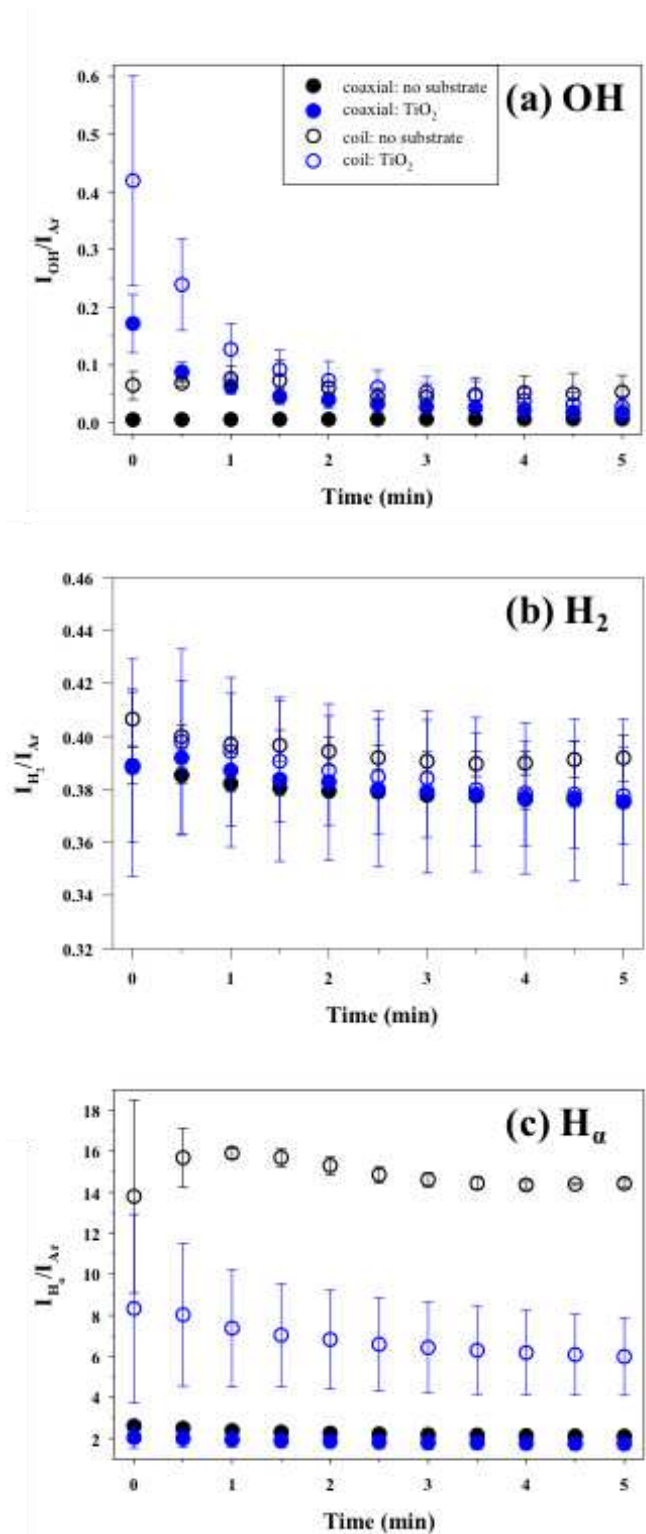


Figure 5.2. Relative density from OES spectra collected coaxially and in the coil region of the reactor as a function of time in an H₂ plasma ($p = 100$ mTorr, $P = 125$ W) with and without a TiO₂ substrate for (a) OH (b) H₂, and (c) H_α.

appreciable during the 5-min data collection time. This suggests that H₂ decomposes in the coil region and H is not likely to recombine to form H₂ there, but it may undergo deexcitation or other recombination processes as it continues downstream, leading to the lower density observed with coaxially collected OES data, Figure 5.2c. With the TiO₂ substrate, [H] measured coaxially (i.e. downstream) is slightly lower than the substrate-free system, albeit within error. In the coil region, however, [H] is significantly lower in the presence of the catalyst, indicating that H atoms are likely interacting with the substrate (e.g. to produce the observed OH_(g)).

To gain further insight into the plasma-substrate interactions and gas-phase processes, the energetics of plasma species can be evaluated as functions of plasma parameters. $T_R(\text{OH})$ and $T_V(\text{OH})$ values were determined via spectral simulation with LIFBASE, where all fits had peak correlation (PC) values ≥ 0.89 . OES data collected 30 s after plasma ignition was used for determination of $T_R(\text{OH})$ and $T_V(\text{OH})$ because OH emission signal was prominent at this time point. Unfortunately, raw OH data could not be analyzed at low P ($P = 25\text{--}50$ W) or high p ($p = 200$ mTorr) because of limited signal intensity under these conditions. Figure 5.3 shows a representative fit of the OH $A^2\Sigma^+ \rightarrow X^2\Pi$ transition ($p = 100$ mTorr, $P = 100$ W), giving rise to $T_R(\text{OH}) = 2550$ K and $T_V(\text{OH}) = 4600$ K and with a PC value of 0.96. Although PC values are fairly high for each individual spectrum, indicating reasonable agreement between the experimental data and corresponding simulation, standard deviation weighs in as high as 16% in some cases, as listed in Table 5.2. Although challenging to illicit trends from these data, we are able to ascertain an order of magnitude for $T_R(\text{OH})$ and $T_V(\text{OH})$ and can compare these values to $T_R(\text{H}_2)$ in the same plasma system and other $T_R(\text{OH})$ and $T_V(\text{OH})$ values reported in the literature.¹⁹⁻²²

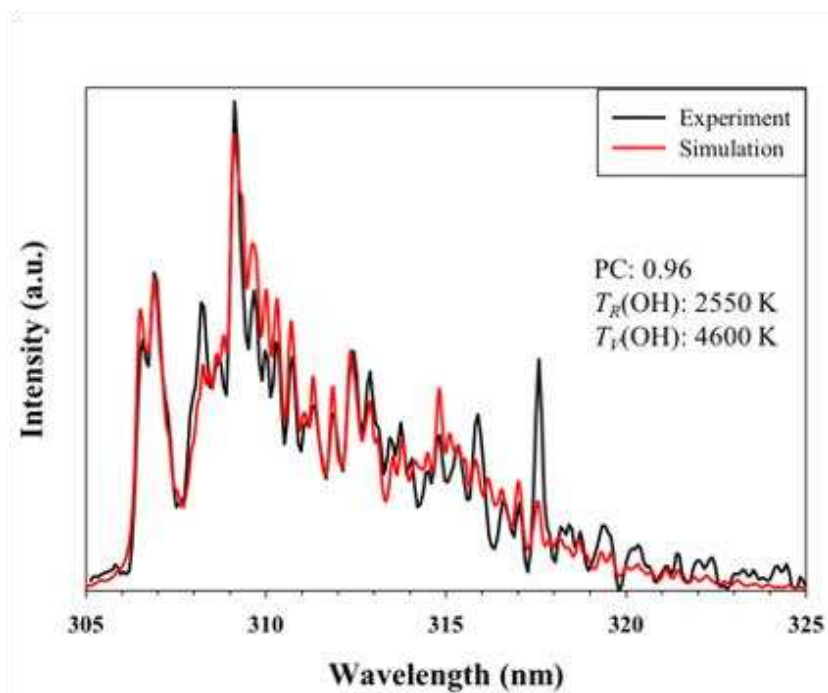


Figure 5.3. Representative emission spectrum collected coaxially for OH $A^2\Sigma^+ \rightarrow X^2\Pi$ in a H_2 plasma with a TiO_2 substrate ($p = 100$ mTorr, $P = 100$ W).

Table 5.2. $T_R(\text{OH})$ and $T_V(\text{OH})$ values obtained from a H_2 plasma with a TiO_2 substrate.^a

p (mTorr)	P (W)	T_R (K)	T_V (K)
	75	3680 (150)	4020 (40)
100	100	2940 (480)	4430 (250)
	125	3370 (290)	4360 (180)
	75	3740 (130)	4110 (40)
150	100	3520 (450)	4310 (220)
	125	3680 (230)	4150 (20)

^aValues in parentheses represent standard deviation calculated from the mean of $n \geq 3$ trials.

To better understand these gas phase trends and the impact of plasma processing on the catalyst, the substrates were analyzed before and after plasma exposure. Figure 5.4 shows representative FTIR spectra of untreated (UT) and H₂ plasma treated ($p = 100$ mTorr, $P = 100$ W, $t = 5$ min) TiO₂ substrates. The adsorption bands at 3400 cm⁻¹ and 1630 cm⁻¹ are assigned to stretching bands for O-H surface hydroxyl groups and H-O-H physically adsorbed water, respectively.²³ Symmetric and asymmetric stretching of -CH₂ is observed in the 2830 – 2990 cm⁻¹ region for the UT material.²⁴ The large absorption band below 1000 cm⁻¹ is assigned to Ti-O-Ti stretching vibration of the interconnected octahedral [TiO₆].²³ Some differences worth noting appear when comparing the two spectra. First, the disappearance of the -CH₂ peaks and the significant reduction of the O-H stretching band after plasma exposure suggests removal of impurities or cleaning of the material surface by the plasma. Moreover, narrowing of the Ti-O-Ti stretching absorption band post plasma exposure suggests the creation of a more uniform lattice environment and removal of excess impurities.

We employed XPS to further investigate the chemical composition of the surface of our catalysts before and after H₂ plasma exposure. Survey scans conducted on all of the substrates showed the presence of titanium, oxygen, and carbon prompting the collection of high-resolution data for the Ti_{2p}, O_{1s}, and C_{1s} binding environments for each spot. Elemental compositions, listed in Table 5.3, show a decrease in the amount of carbon after H₂ plasma exposure. The amount of titanium decreases slightly at high P and longer plasma exposure times ($P = 100$ W, 125 W, $t = 5$ min and $P = 125$ W, $t = 10$ min). Additionally, an increase in %O is noted after H₂ plasma exposure at all conditions except for $P = 25$ W, $t = 5$ min. Representative high resolution Ti_{2p}, O_{1s}, and C_{1s} XPS spectra prior to and post H₂ plasma exposure ($p = 100$ mTorr, $P = 150$ W, $t = 1$ min) are shown in Figure 5.5. High resolution Ti_{2p} spectra of the UT TiO₂ material, Figure

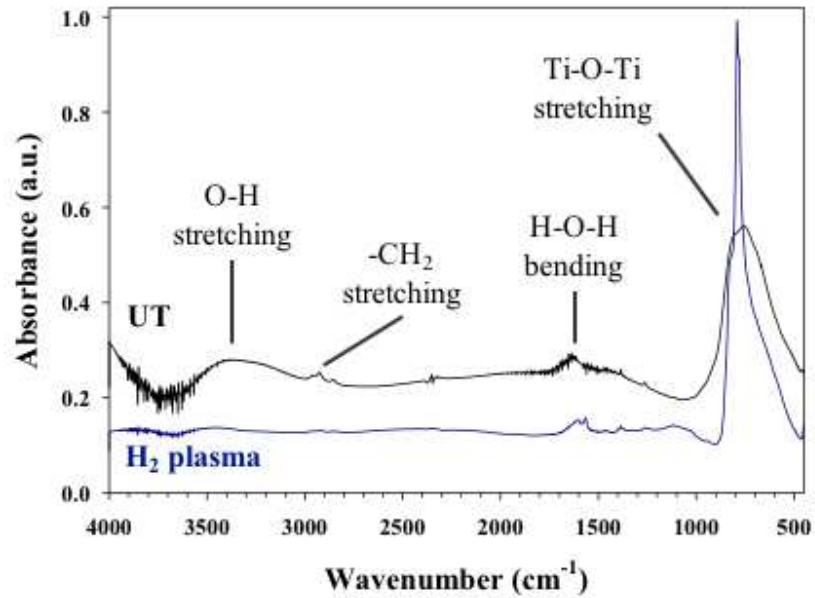


Figure 5.4. FTIR spectra of untreated and H₂ plasma treated ($p = 100$ mTorr, $P = 100$ W, $t = 5$ min) TiO₂ substrates.

Table 5.3. XPS atomic composition data for a TiO₂ substrate exposed to a 100% H₂ plasma ($p = 100$ mTorr).^a

Plasma Exposure Time	P (W)	C [%]	O [%]	Ti [%]
—	—	10.9 (2.3)	63.6 (1.4)	25.5 (1.2)
1 min	125	5.6 (0.4)	68.7 (0.9)	25.7 (0.6)
	25	9.6 (1.9)	65.0 (1.4)	25.3 (0.6)
5min	75	5.2 (0.5)	70.3 (0.9)	24.5 (0.9)
	100	4.8 (0.9)	72.0 (1.1)	23.2 (0.8)
	125	3.4 (0.6)	75.9 (3.5)	20.7 (2.9)
10 min	125	3.2 (0.5)	76.2 (1.5)	20.6 (1.5)

^aErrors are the standard deviation of the mean of 3 measurements on $n \geq 2$ samples.

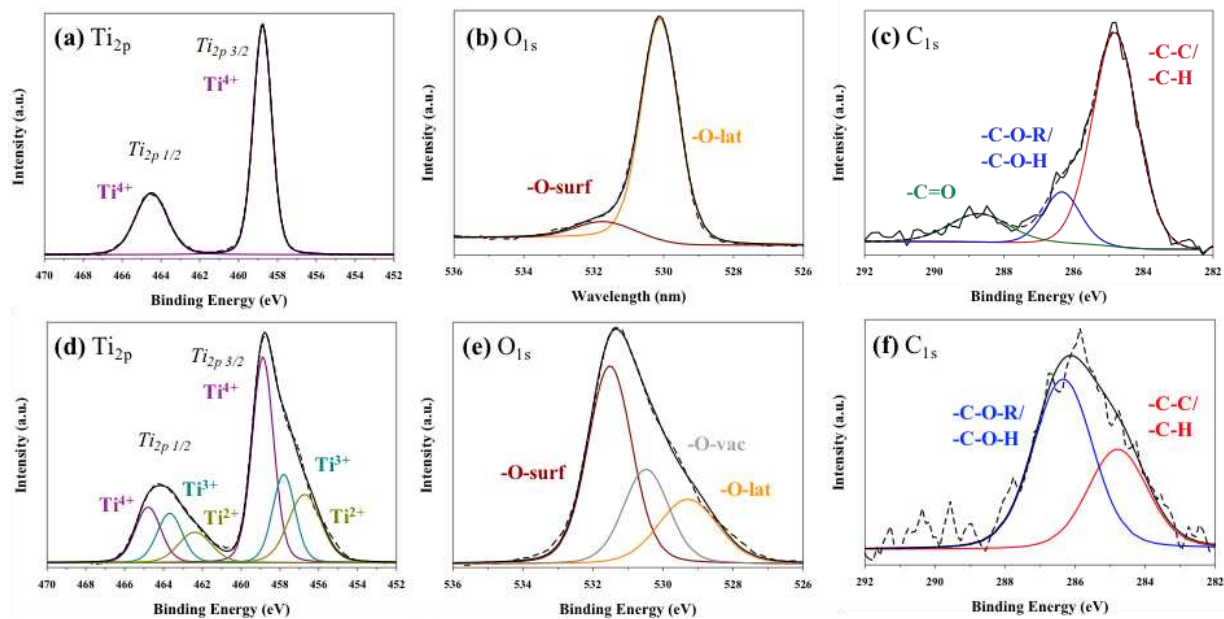


Figure 5.5. High resolution Ti_{2p} (a,d), O_{1s} (b,e), and C_{1s} (c,f) XPS spectra for untreated (top row) and H_2 plasma treated (bottom row) TiO_2 substrates ($p = 100$ mTorr, $P = 125$ W, $t = 1$ min).

5.5a, show peaks for $Ti_{2p3/2}$ and $Ti_{2p1/2}$ at binding energies of 458.8 eV and 464.7 eV, respectively, corresponding to surface titanium in the Ti^{4+} oxidation state.²⁵⁻²⁶ In some cases, Ti^{4+} was reduced (i.e., Ti^{3+} or Ti^{3+} and Ti^{2+} binding environments noted in addition to Ti^{4+}) after H_2 plasma exposure whereas in other cases, the Ti_{2p} binding environment remained nominally unchanged post H_2 plasma exposure (i.e., only Ti^{4+} binding environments present). Reduction of Ti^{4+} was not dependent on plasma parameters and was somewhat inconsistent between spots on a single sample and/or different samples produced under the same plasma conditions. Figure 5.5d shows an example Ti_{2p} high resolution spectrum of a spot where Ti^{4+} is reduced to Ti^{3+} (457.8 eV and 463.6 eV) and Ti^{2+} (456.7 eV and 462.4 eV) oxidation states. The primary contribution to the O_{1s} spectra in the UT TiO_2 arises from lattice bound oxygen (or bound to Ti^{4+}) (529.2 eV), Figure 5.5b, with a smaller peak assigned to oxygen adsorbed to the material surface, such as hydroxyl species (531.5 eV).^{25, 27} When Ti is reduced, an additional binding environment appears after hydrogen plasma exposure at 530.5 eV, corresponding to oxygen vacancies (e.g., Ti_2O_3).²⁷ Here, an increase of adsorbed surface oxygen post H_2 plasma processing, Figure 5.5e, is also observed, presumably as a result of the plasma creating oxygen vacancies within the TiO_2 lattice, which ultimately decreases the relative contribution of bound oxygen.^{25, 28} High resolution C_{1s} spectra for the UT material, Figure 5.5c, show binding environments for -C-C/-C-H (284.8 eV), -C-O-R/-C-O-H (286.3 eV), and -C=O (288.7 eV). The reduction in percent carbon after plasma exposure suggests removal of adventitious carbon, Table 5.3. Although it is difficult to elucidate specific binding environments with the low C signal, we believe binding environments attributed to -C-C/-C-H (284.8 eV) and -C-O-R/-C-O-H (286.3 eV) are still present in the H_2 plasma treated material (Figure 5.5f).

As H₂ plasmas are generally considered etching systems, we also investigated the impact of a clearly depositing system (i.e. 100% CH₄ plasmas) on the catalyst. XPS atomic composition data, Table 5.4, demonstrate a significant increase in %C post CH₄ plasma exposure. Moreover, the %C on the surface is highly dependent on plasma parameters. For example, a TiO₂ substrate exposed to a 100% CH₄ plasma at fairly mild conditions ($p = 100$ mTorr, $P = 25$ W, $t = 30$ s) results in 51.2% C whereas 91.7% C is measured under more intense depositing conditions ($p = 200$ mTorr, $P = 125$ W, $t = 2$ min). Consequently, this drastically changes the O and Ti atomic compositions at the material surface. Interestingly, a slight increase in %Ti is observed from the samples treated for 30 s compared to those exposed to the plasma for 2 min, except at $p = 200$ mTorr, $P = 125$ W where no Ti was detected. This likely indicates competing etching and depositing regimes occurring in this system, with deposition winning out as the process time lengthens and/or the applied rf power and system pressure are increased.

Further details about the types of films deposited or the possible etching processes occurring in CH₄ plasmas can be elucidated from the high resolution XPS spectra. Figure 5.6a shows high resolution Ti_{2p} spectra of an UT TiO₂ substrate and TiO₂ substrates after a 2 min exposure to a 100% CH₄ plasma under several pressure and power conditions. As stated above, binding energies for Ti_{2p_{3/2}} and Ti_{2p_{1/2}} are present at 458.6 eV and 464.2 eV, respectively, corresponding to surface titanium in the Ti⁴⁺ oxidation state.²⁵⁻²⁶ Additionally, contributions from the Ti³⁺ binding environment are noted at 457.9 eV and 462.5 eV for materials treated at $p = 200$ mTorr, $P = 25$ W.²⁵ High resolution O_{1s} spectra, Figure 5.6b, show contributions from lattice bound oxygen at 530.2 eV and adsorbed oxygen species at 532.1 eV for the UT material and after CH₄ plasma exposure.²⁹⁻³⁰ The TiO₂ substrates exposed to a CH₄ plasma have an additional peak at 533.3 eV, corresponding to oxygen singly bound to carbon in ethers.³⁰

Table 5.4. XPS atomic composition data for a TiO₂ substrate exposed to a 100% CH₄ plasma.^a

Plasma Exposure Time	<i>p</i> (mTorr)	<i>P</i> (W)	C [%]	O [%]	Ti [%]
—	—	—	10.9 (2.3)	63.6 (1.4)	25.5 (1.2)
30 sec	100	25	51.2 (4.4)	48.1 (4.3)	< 1%
		125	87.9 (2.8)	9.1 (2.0)	3.0 (0.8)
	200	25	84.8 (1.2)	14.9 (0.8)	< 1%
		125	91.3 (2.1)	7.7 (1.6)	< 1%
2 min	100	25	77.4 (6.4)	17.6 (4.4)	5.1 (2.0)
		125	61.9 (12.8)	27.8 (8.7)	10.3 (4.2)
	200	25	78.4 (2.4)	18.1 (1.3)	3.6 (1.3)
		125	91.7 (0.4)	8.4 (0.4)	—

^aErrors are the standard deviation of the mean of 3 measurements on $n \geq 2$ samples.

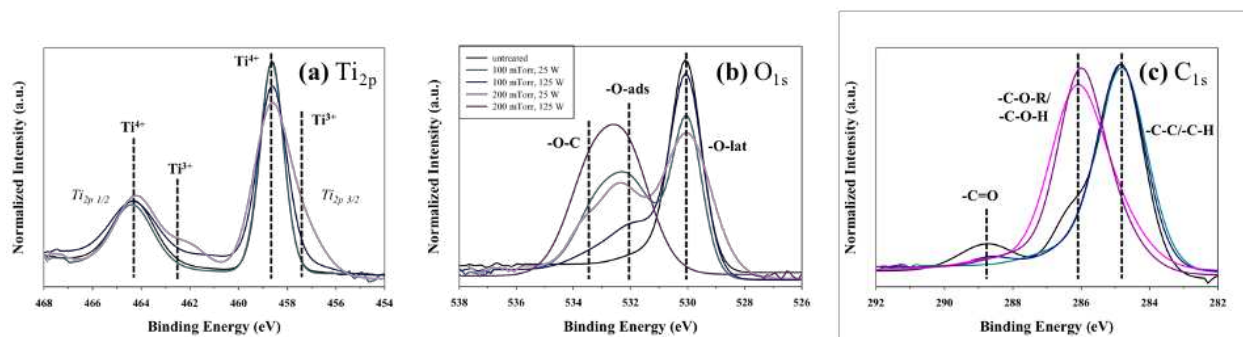


Figure 5.6. High resolution (a) C_{1s}, (b) O_{1s}, and (c) Ti_{2p} spectra of TiO₂ substrates prior and post CH₄ plasma exposure ($t = 2$ min).

Notably, the spectrum acquired under conditions with no detectable Ti in the elemental composition data ($p = 200$ mTorr, $P = 125$ W) shows no lattice bound oxygen species, only adsorbed oxygen species and oxygen bound to carbon. High resolution C_{1s} spectra, Figure 5.6c, display three specific binding environments corresponding to -C-C/-C-H (284.8 eV), -C-O-C/-C-O-H (286.6 eV), and -C=O (288.7 eV).²⁹ After CH_4 plasma exposure, the -C=O contribution decreases significantly, regardless of treatment parameters. Moreover, with $p = 200$ mTorr, the -C-O-R/-C-O-H contribution increases dramatically relative to the $p = 100$ mTorr treatment, dominating the spectra for both low and high P treatments.

Raman data, Figure 5.7, also demonstrate the presence of an amorphous hydrocarbon film on the TiO_2 after CH_4 plasma exposure. Figure 5.7a shows Raman spectra for UT TiO_2 and TiO_2 treated with a 100% CH_4 plasma ($p = 200$ mTorr) at different P . Anatase TiO_2 has six Raman active modes ($3 E_g + 2 B_{1g} + 1 A_{1g}$).³¹⁻³² The three E_g modes correspond to the high intensity band at 136 cm^{-1} and the lower intensity bands at 196 and 638 cm^{-1} . Additionally, the doublet band at 515 cm^{-1} corresponds to the A_{1g} and B_{1g} modes, and the band at $\sim 396\text{ cm}^{-1}$ belongs to the B_{1g} mode.³¹⁻³² Peaks at 429 cm^{-1} , 608 cm^{-1} , and 1100 cm^{-1} arise from the glass substrate. Figure 5.7a demonstrates carbon deposition via the appearance of the D-band and G-band for plasma parameters associated with the most intense deposition conditions in our CH_4 plasma systems (high p , high P). In conjunction with the presence of the D-band and G-band, the more intense deposition parameters also appear to coincide with overall minimized TiO_2 bands.

Figure 5.7b displays an expanded view of the E_g band at $\sim 135\text{ cm}^{-1}$. The E_g peaks correlate to the symmetric stretching vibration of O-Ti-O in TiO_2 ;³³⁻³⁴ thus, they are very sensitive to local oxygen coordination surrounding the metal ion. Here, we note a general shift

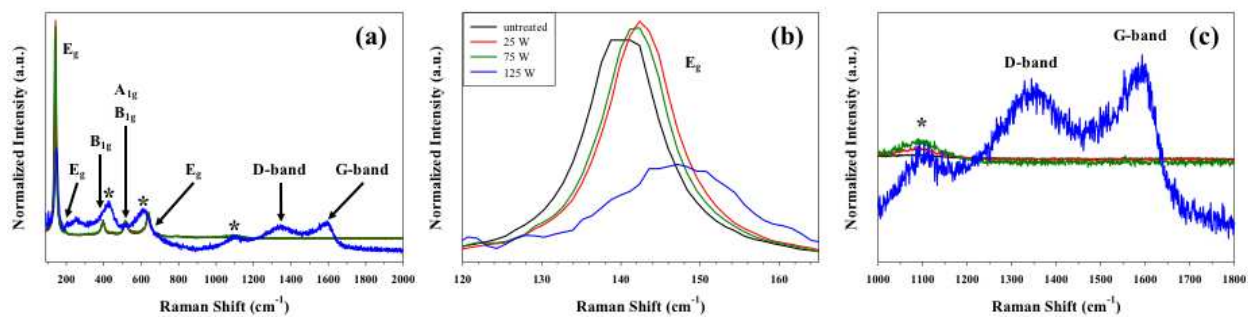


Figure 5.7. (a) Raman spectra of TiO₂ substrates [untreated and treated with a 100% CH₄ plasma at three applied rf powers ($p = 200$ mTorr, $t = 2$ min)]. Expanded views of the (b) E_g peak and the (c) D-band/G-band region. Asterisk (*) represents signal from glass slide substrate.

and broadening of the E_g peak at $\sim 135 \text{ cm}^{-1}$ to higher wavenumbers for the plasma treated substrate relative to the untreated TiO_2 . For example, the higher P plasma treatment ($P = 125 \text{ W}$) results in the largest E_g peak shift, 7 cm^{-1} , whereas the milder plasma treatments ($P = 25 \text{ W}$ and $P = 50 \text{ W}$) result in less peak shifting, $1 - 3 \text{ cm}^{-1}$, relative to the untreated TiO_2 . Nevertheless, these data demonstrate that CH_4 plasma exposure affects the underlying material beyond deposition of an amorphous hydrocarbon film over the surface of the material.

Figure 5.7a further demonstrates that carbon deposition throughout the material is observed via the appearance of the D-band and G-band for plasma parameters associated with the most intense deposition conditions (high p , high P). In conjunction with the presence of the D-band and G-band, these deposition parameters also appear to coincide with overall minimized TiO_2 bands. Figure 5.7c shows an expanded view of the D-band/G-band region for untreated TiO_2 and TiO_2 post CH_4 plasma exposure at $p = 200 \text{ mTorr}$ and several P conditions. Notably, the D-band and G-band are only present in the spectra acquired from the $P = 125 \text{ W}$ plasma treated substrate.

As substrate morphology can impact overall PAC interactions, we used SEM to evaluate material morphology of the UT and plasma treated TiO_2 materials. A representative SEM image of the UT material, Figure 5.8a, highlights the porous morphological nature of the TiO_2 nanoparticle agglomerates. Figures 5.8b and 5.8c show representative SEM images of the catalyst after exposure to 100% H_2 ($p = 100 \text{ mTorr}$, $P = 100 \text{ W}$, $t = 5 \text{ min}$) and 100% CH_4 ($p = 150 \text{ mTorr}$, $P = 125 \text{ W}$, $t = 2 \text{ min}$) plasmas, respectively. The morphology characteristic of the UT TiO_2 material does not change appreciably after exposure plasma, regardless of p or P , for the parameter space reported herein.

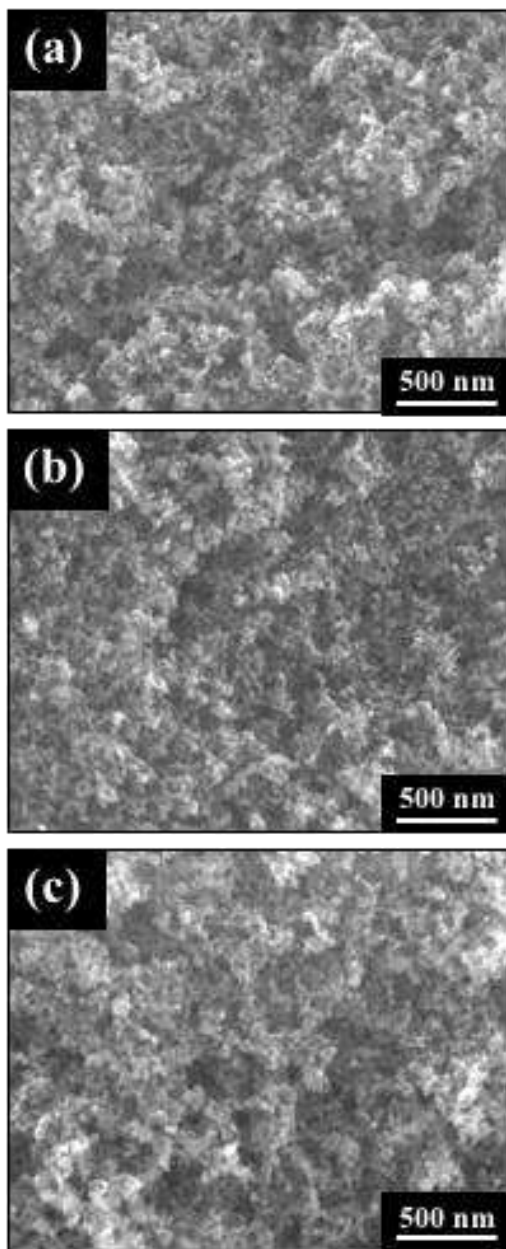


Figure 5.8. Representative SEM images (50000x) of (a) untreated (b) H₂ plasma treated ($p = 100$ mTorr, $P = 125$ W, $t = 5$ min) and (c) CH₄ plasma treated ($p = 150$ mTorr, $P = 125$ W, $t = 2$ min) TiO₂ substrates.

Clearly, H₂ and CH₄ plasmas differentially impact the resulting catalyst chemistry; thus, we compare and contrast the impact of the catalyst on gas phase chemistry in these two systems. We have previously investigated energy partitioning trends of $T_R(\text{H}_2)$ in H₂ and CH₄ plasmas (no substrate) to elucidate probable mechanisms of H₂ formation.¹⁸ Here, we utilized TR-OES to further delve into these fundamental processes by studying the first few seconds immediately following plasma ignition in H₂ and CH₄ plasmas with and without TiO₂. Figure 5.9 shows a comparison of the temporal emission profiles of H₂ in the two plasma systems with and without a catalyst. In a 100% H₂ plasma, the rise to maximum intensity and subsequent steady state emission for H₂ (Figure 5.9a) occurs within the first 0.1 s of plasma ignition. Conversely, the rise to a steady state for H₂ takes several seconds in a CH₄ plasma without a substrate. The overall characteristics of the temporal profiles do not change appreciably upon the addition of a TiO₂ substrate to the 100% H₂ plasma (Figure 5.9c). In contrast, the TiO₂ dramatically alters the temporal profile of H₂ emission in the 100% CH₄ plasma (Figure 5.9d). Here, the temporal profile mirrors the 100% H₂ plasma system, with a sharp rise within < 0.1 s. These TR-OES data provide essential insight into plasma ignition processes and potential species formation mechanisms; however, evaluation of species energetics is also a key component to understanding fundamental plasma processes during PAC.

T_R values of excited state H₂ are plotted in Figure 5.10 as a function of P for both H₂ and CH₄ plasmas with and without TiO₂. At $p = 100$ mTorr, Figure 5.10a, $T_R(\text{H}_2)$ values have a narrow range of ~500 – 550 K, display minimal power dependence, and remain constant with and without a TiO₂ catalyst in the 100% H₂ plasma system. Conversely, the $T_R(\text{H}_2)$ values in a 100% CH₄ plasma without a substrate at $p = 100$ mTorr, Figure 5.10a, decrease with increasing P , with $T_R(\text{H}_2) = \sim 580$ K and ~ 500 K at $P = 25$ W and 125 W, respectively. Addition of the

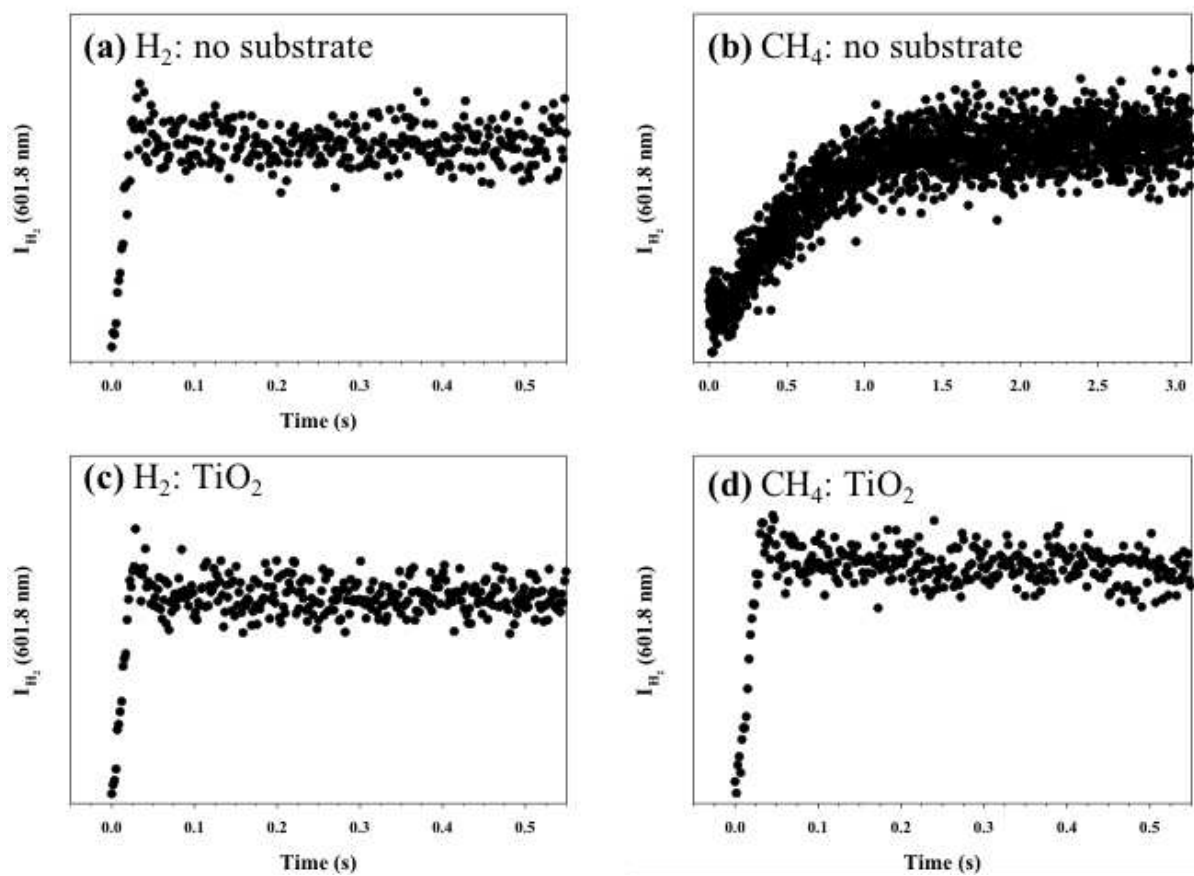


Figure 5.9. Temporal profiles of H₂ emission in a H₂ plasma (a,c) and a CH₄ plasma (b,d) without a substrate (a,b) and with a TiO₂ substrate (c,d) at $p = 100$ mTorr, $P = 125$ W.

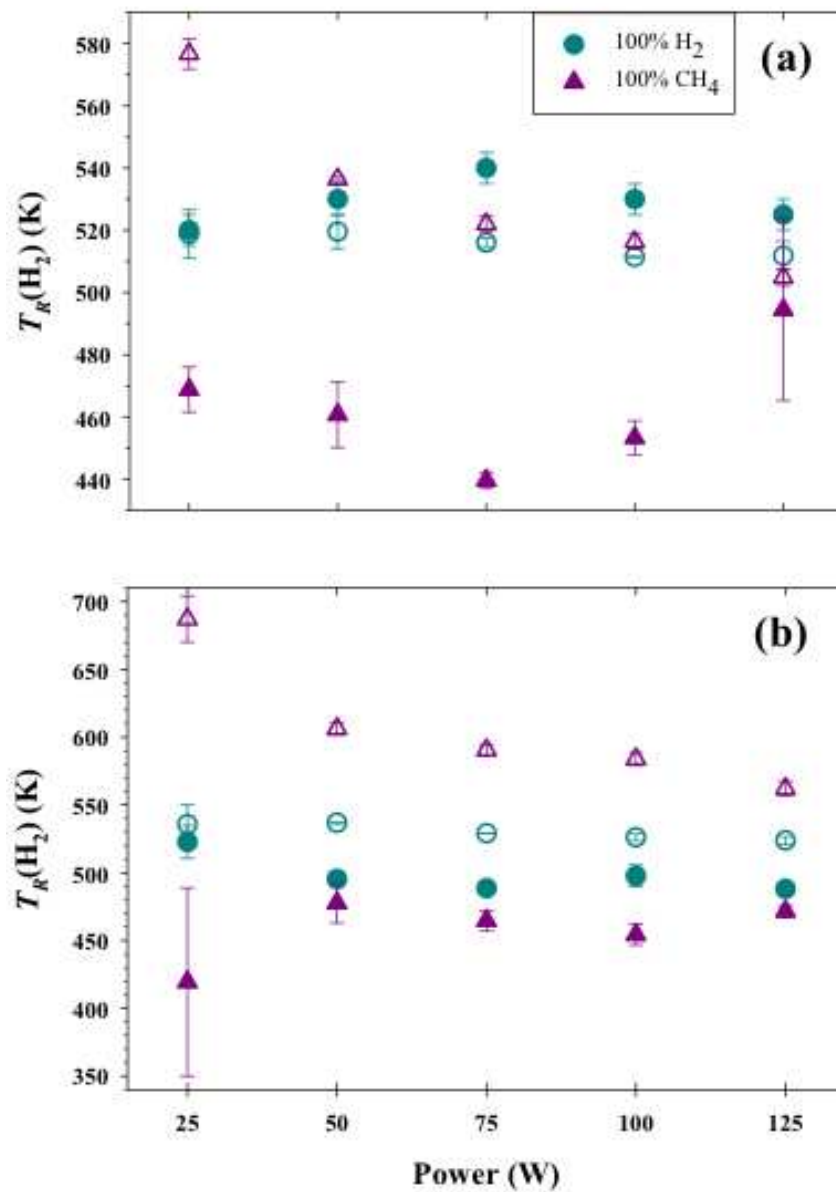


Figure 5.10. $T_R(\text{H}_2)$ data as a function of applied rf power for 100% H_2 and 100% CH_4 plasma systems without (open symbols) and with (closed symbols) a TiO_2 substrate at (a) $p = 100$ mTorr and (b) $p = 200$ mTorr. Values for $T_R(\text{H}_2)$ without substrate were previously reported.¹⁸

catalyst results in a notable decrease in $T_R(\text{H}_2)$, with values of $\sim 400 - 480$ K and minimal P dependence at $p = 100$ mTorr. Similar trends are noted in the higher-pressure system ($p = 200$ mTorr), Figure 5.10b, with $T_R(\text{H}_2)$ values elevated somewhat by $\sim 100 - 200$ K for the CH_4 plasma system (no substrate). Overall, $T_R(\text{H}_2)$ values at $p = 200$ mTorr for a 100% H_2 plasma are similar to those at $p = 100$ mTorr. Nevertheless, at $P \geq 50$ W, $T_R(\text{H}_2)$ values are reduced slightly compared to the no substrate system. Numerical values for all conditions studied with TiO_2 are listed in Table 5.5 and range from $\sim 400 - 700$ K over the entire parameter space. $T_R(\text{H}_2)$ values for the no substrate systems (both H_2 and CH_4) have been previously reported.¹⁸

To further demonstrate the impact of the catalyst on energy partitioning, $T_R(\text{CH})$ is plotted as a function of P at two different pressures in Figure 5.11a, and $T_R(\text{CH})$ values for the entire parameter space are reported in Table 5.6. At $p = 100$ mTorr, $T_R(\text{CH})$ values are decreased by $\sim 100 - 200$ K with a TiO_2 catalyst except at $P = 50$ W. Interestingly, an increase in system pressure to ≥ 150 mTorr, results in $T_R(\text{CH})$ values comparable to those in the no substrate system. Notably, $T_R(\text{CH})$ values also decrease concomitantly with an increase in system pressure, a trend we previously reported for 100% CH_4 plasmas without a substrate.¹⁷ These results demonstrate the significant impact that catalysts can have on rotational energy partitioning in PAC systems.

Additionally, we determined $T_V(\text{CH})$ for the same parameter space, Table 5.6, where values range from $\sim 2000 - 3100$ K. Figure 5.11b shows $T_V(\text{CH})$ for a CH_4 plasma system without and with a TiO_2 substrate at two different pressures. At $p = 100$ mTorr, $T_V(\text{CH})$ is significantly reduced (~ 300 K – 1200 K) upon addition of the catalyst to the discharge. This trend generally holds true at each pressure ($p = 100 - 200$ mTorr). Pressure and power trends for $T_V(\text{CH})$ are also worth noting here as $T_V(\text{CH})$ values generally decrease with increasing p for CH_4 plasmas. The P dependence demonstrates a more complex trend wherein $T_V(\text{CH})$ decreases

Table 5.5. $T_R(\text{H}_2)$ (K) values in 100% H_2 and 100% CH_4 plasma systems.^a

p (mTorr)	P (W)	H_2 plasma		CH_4 plasma	
		no substrate ^b	TiO_2	no substrate ^b	TiO_2
100	25	520 (10)	520 (5)	575 (5)	470 (10)
	50	520 (5)	530 (5)	535 (5)	460 (10)
	75	515 (5)	540 (5)	520 (5)	440 (5)
	100	510 (5)	530 (5)	515 (5)	455 (10)
	125	510 (5)	525 (5)	505 (5)	495 (30)
150	25	530 (20)	540 (20)	605 (10)	460 (20)
	50	525 (5)	545 (10)	590 (15)	450 (10)
	75	530 (5)	550 (15)	565 (5)	470 (5)
	100	525 (5)	525 (5)	560 (5)	455 (15)
	125	525 (5)	525 (5)	535 (5)	450 (10)
200	25	535 (15)	520 (15)	690 (20)	420 (70)
	50	535 (5)	500 (10)	605 (5)	480 (15)
	75	530 (5)	490 (5)	590 (5)	465 (10)
	100	525 (5)	500 (10)	585 (5)	455 (10)
	125	525 (5)	490 (5)	560 (5)	470 (5)

^aValues in parentheses represent standard deviation calculated from the mean of $n \geq 3$ trials.

^b“No substrate” values reported previously.¹⁸

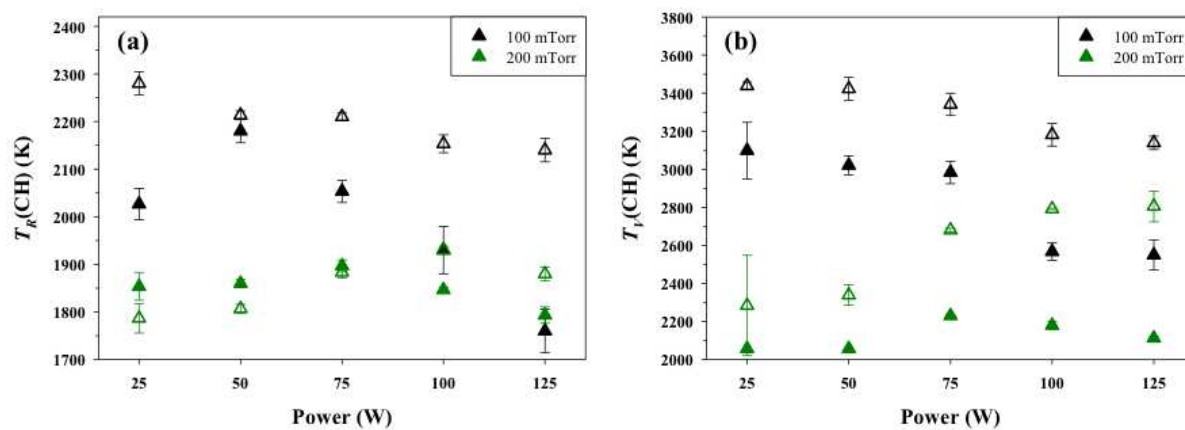


Figure 5.11. (a) $T_R(\text{CH})$ and (b) $T_V(\text{CH})$ as a function of P for a 100% CH_4 plasma without (open triangles) and with a TiO_2 substrate (closed triangles). Values for $T_R(\text{CH})$ and $T_V(\text{CH})$ without substrate were previously reported.¹⁷

Table 5.6. $T_R(\text{CH})$ and $T_V(\text{CH})$ values in a 100% CH_4 plasma with a TiO_2 substrate.^a

p (mTorr)	P (W)	T_R (K)		T_V (K)	
		no substrate ^b	TiO_2	no substrate ^b	TiO_2
100	25	2280 (20)	2030 (30)	3440 (20)	3100 (150)
	50	2210 (10)	2180 (20)	3420 (60)	3020 (50)
	75	2210 (10)	2050 (20)	3340 (60)	2980 (60)
	100	2150 (20)	1930 (50)	3180 (60)	2570 (50)
	125	2240 (20)	1760 (50)	3140 (40)	2550 (80)
150	25	1910 (20)	2030 (30)	2610 (10)	2680 (70)
	50	1960 (10)	1980 (20)	2910 (20)	2480 (50)
	75	2070 (10)	1970 (10)	3310 (60)	2620 (40)
	100	2010 (10)	1930 (40)	3090 (30)	2690 (30)
	125	1980 (40)	1880 (20)	3010 (110)	2680 (120)
200	25	1790 (30)	1850 (30)	2280 (260)	2060 (10)
	50	1810 (10)	1860 (10)	2340 (10)	2060 (10)
	75	1880 (10)	1900 (10)	2680 (10)	2230 (10)
	100	1930 (10)	1850 (10)	2790 (10)	2180 (20)
	125	1880 (10)	1790 (20)	2810(80)	2110 (10)

^aValues in parentheses represent standard deviation calculated from the mean of $n \geq 3$ trials.^b“No substrate” values reported previously.¹⁷

with increasing P at low p ($p = 100$ mTorr) but increases with P at high p ($p = 200$ mTorr). This trend has been discussed previously.¹⁷

5.3 Discussion

As noted in the Introduction, the applicability of PAC is limited by a lack of knowledge of the fundamental processes contributing to plasma-catalyst synergy. Understanding the roles of both the catalyst and plasma as well as the interactions occurring at the plasma-catalyst interface in a PAC system can help the community bypass trial-and-error approaches towards optimizing plasma-catalysis systems and establish a more informed method for optimization towards a desired application. Thus, the goal of this work is to elucidate both the impact of the catalyst on the fundamental properties of the plasma discharge and to understand the effect of plasma exposure on the catalyst's properties. Here, we utilize a nanostructured TiO₂ catalyst to report on effects on fundamental plasma processes in low pressure, inductively coupled H₂ and CH₄ plasmas. Chemical and morphological properties of the catalyst prior to and post plasma exposure were assessed in addition to the gas-phase studies as a more holistic approach towards elucidating the molecular level processes occurring in these inherently complex PAC systems.

A previous study from our lab employed OES to examine the gas phase of H₂ plasmas during processing of SnO₂ nanomaterials.¹⁹ In that study, excited state OH and Sn species were observed in the gas phase only when a substrate was placed in the discharge. Similar observations are reported here where raw OES spectra of H₂ plasmas show the presence of OH and CO species when a TiO₂ substrate is placed in the discharge, Figure 5.1b. XPS atomic composition data, Table 5.3, also show a significant reduction of carbon post H₂ plasma exposure, suggesting that adventitious carbon is removed from the material surface during

plasma processing and is likely the source for the gas phase CO species. Given that we do not see OH* without a substrate, OH* formation likely occurs through removal of oxygen from the substrate. To elucidate further details about these plasma-surface interactions, we utilized inert gas actinometry to measure relative species densities as functions of plasma parameters, Figure 5.2, revealing that [H] is not affected by the catalyst when emission is collected coaxially along the length of the reactor. Conversely, [H] in the coil region shows an overall increase compared to the coaxially collected data, presumably resulting from the continuous flow of H₂ that can dissociate to H* in the coil. Interestingly, when a TiO₂ substrate is placed in the discharge [H] is significantly reduced only in the coil region of the reactor. Shirazi *et al.* found that H atoms originating either from dissociative adsorption of H₂ or CH₄ or from H atoms produced in the bulk plasma can be readily adsorbed on a Ni catalyst.³⁵ Thus, the significant decrease of [H] directly above the substrate may be a result of adsorption of H atoms on the TiO₂ catalyst surface. Conversely, [OH] was similar in both the coil and coaxial data, indicating that once OH* forms in the coil region it persists as it continues downstream in the reactor. One additional noteworthy observation from the Figure 5.2 actinometry data is that [OH] decreases to nearly zero over the 5-min treatment time. In H₂ plasmas, the only source of oxygen is the TiO₂ substrate, thereby serving as a limiting reagent for OH species production, especially if surface oxygen were removed from the substrate through plasma processes.

FTIR and XPS results further corroborate the H₂ plasma OES data. For example, FTIR data (Figure 5.4) suggest the creation of a more uniform lattice environment and removal of carbon and oxygen species. Additionally, high resolution XPS data demonstrate increases in the -O_{vac} and -O_{surf} binding environments (Figures 6b and 6e) and reduction of Ti⁴⁺ (Figures 6a and 6d) after plasma exposure. Although Ti⁴⁺ was not always reduced, an increase in the -O_{vac} and -

O_{surf} binding environments was always observed post plasma treatment. Changes in atomic composition (Table 5.3) are noted after 1 and 5 minutes of plasma exposure ($P = 125$ W), but atomic compositions are within error for the 5 and 10 min plasma treatments, indicating significant changes to the catalyst's surface chemistry likely occur within the first few minutes of plasma exposure. Together, the OES and materials characterization data suggest etching of surface oxygen by the hydrogen plasma. It is thus useful to consider which gas phase species act as etchants in this system to further illuminate potential etching mechanisms.

Both hydrogen and argon plasma treatments have been used widely as a preparation method for catalyst reduction; consequently, several investigations of the primary etching pathways within these systems have been reported.³⁶⁻³⁹ For example, one study suggests the products of electron-mediated reactions with ethanol may be the primary reducing agents in Ar plasmas.³⁸ Moreover, a recent review of plasma catalyst preparation states that both hydrogen radicals and electrons are strong reducing agents for metal catalysts in H_2 plasmas.³⁹ A previous study from our lab provided a discussion on the potential etchants of SnO_2 nanomaterials in low pressure, inductively coupled rf H_2/Ar plasmas, concluding that H^* acted as the primary etchant.¹⁹ Given the similar parameters utilized in this study, we believe H^* acts as the primary etchant here as well. Moreover, the significant decrease in $[H]$ when the catalyst is in the plasma, Figure 5.2b, indicates that hydrogen atoms interact with the substrate to form OH or other species (e.g., H_2).

One approach to discerning key mechanistic processes occurring in our plasma systems includes determination of internal molecular plasma temperatures and trends. For example, $T_R(OH)$ and $T_V(OH)$ were calculated for the 100% H_2 plasma system with TiO_2 as OH is an etch product that also changes with plasma parameters. Importantly, a non-Boltzmann distribution

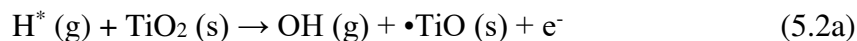
behavior is expected for OH $A^2\Sigma^+$, H₂ $d^3\Pi_u$, and CH $A^2\Delta$ in low pressure plasmas because the collisional timeframe is on the same order as the radiative lifetime.^{21, 40-41} As such, the rotational states have no time to relax before undergoing radiative decay. Thus, T_R values measured in our systems can be used to elucidate formation mechanisms because T_R becomes an image of the formation process rather than the kinetic temperature. Furthermore, some formation mechanisms can favor production of high or low rotational excited states which can drastically change T_R and ultimately provide insight into understanding mechanistic phenomena occurring in our systems.²¹

$T_R(\text{OH})$ values cover a fairly large range (~2900 K to 3700 K), and $T_V(\text{OH})$ values are routinely higher (~4000 – 4400 K). Although the representative emission spectrum of the OH $A^2\Sigma^+ \rightarrow X^2\Pi$ transition in Figure 5.3, shows a high PC value (0.96), our associated experimental error does not allow clear conclusions regarding energy partitioning trends from these data. Nevertheless, we can compare the range of these values to those reported in the literature. Stuckert *et al.* determined $T_R(\text{OH})$ and $T_V(\text{OH})$ in H₂O and H₂ plasmas with SnO₂ nanomaterials under similar pressure and power ranges.¹⁹ Reported $T_V(\text{OH})$ values were ~3450 – 4020 K, and $T_R(\text{OH})$ values ranged from ~ 1800 to 5400 K, with typically higher $T_R(\text{OH})$ values reported in the H₂ system compared to the H₂O system. Notably, these values generally align with those reported herein. A study by Sarani *et al.* suggests vibrational-rotational populations of OH can be formed via different mechanisms of generation for excited state species with different J levels.²⁰ The authors suggest lower rotational states ($J < 13$) are produced in their system (atmospheric pressure DBD plasma jet, Ar/water vapor mixtures) through a combination of direct electron impact excitation from the ground state and dissociative excitation, resulting in $T_R(\text{OH}) = 625$ K. Meanwhile the $13 < J < 25$ states, are characterized by a higher rotational temperature [$T_R(\text{OH}) = 5000$ K], suggesting dissociative excitation as the main pathway for OH

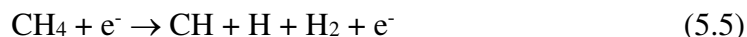
$A^2\Sigma^+$ formation. Other reported $T_R(\text{OH } A^2\Sigma^+)$ values range from ~450 K – 3700 K with $T_V(\text{OH } A^2\Sigma^+) = \sim 6000$ K.²¹⁻²² A critical review of $T_R(\text{OH})$ determination by Bruggeman and coworkers demonstrates that even at atmospheric pressure, rotational population distributions of $\text{OH } A^2\Sigma^+$ provide an image of its formation process.²¹ Thus, although many of these literature values arise from atmospheric pressure plasma systems, the wide range of $T_R(\text{OH})$ values reported likely evolve from different formation processes.

Notably, $T_R(\text{OH})$ values are also much larger than $T_R(\text{H}_2)$ or $T_R(\text{CH})$ values reported herein. In a related study by Cruden *et al.*, rotational temperatures of five molecular species (i.e., CF, CN, CO, C₂, SiF) were measured in a low pressure (30 mTorr) inductively coupled CF₄-based plasma.⁴² The authors determined that SiF, produced solely from plasma-surface interactions with the reactor wall, had a higher rotational temperature (~2300 K) than those for molecules produced primarily from gas phase reactions (e.g. CF and CN, ~1250 K). Species produced via a combination of gas-phase and plasma-surface interactions (identified as CO and C₂) exhibited intermediate T_R values of 1600 K and 1800 K, respectively. Their results suggest that species produced as etch products leave the surface with significant internal energies and further supports the elevated $T_R(\text{OH})$ values measured in our systems.

Based on our materials analyses and the measured $T_R(\text{OH})$ and $T_V(\text{OH})$ values in our plasmas, we determined probable mechanistic pathways for OH^* formation, depicted in Reactions 5.1 – 5.2, where “•” represents an active site on the material surface.



One reason we included H₂ plasmas in our PAC studies is that hydrogen species comprise a significant component of CH₄ plasma decomposition. As such, it is important to determine how these species interact with the catalyst. Precursor dissociation in CH₄ plasma discharges generally leads to an array of product species such as CH_x, H, H₂, and C₂.⁴³⁻⁴⁴ Consequently, several groups have previously reported on energy partitioning of CH or C₂ in CH₄ plasmas.⁴⁵⁻⁴⁸ Electron impact dissociation of CH₄ is the dominant pathway for generating these species in the plasma with either subsequent radical recombination reactions to form higher order hydrocarbons or further electron impact dissociation.^{9,49} Specifically, Reactions 5.3 – 5.5 are hypothesized to be the primary routes for CH₄ decomposition. Simulation of DBD methane plasma conversion showed that Reaction 5.3 accounts for ~79% of electron impact dissociation of CH₄ and Reactions 5.4 – 5.5 account for ~15% and ~5%, respectively.⁵⁰



Although formation of CH has been directly related to CH₄ decomposition,⁴⁸ interpretation of energy partitioning results should also consider the relevant amount of discharge power converted to rotational and vibrational excitation of other species in the plasma. For example, H₂ is an important component to CH₄ plasma chemistry utilized for production of amorphous hydrocarbon films deposited via PECVD.^{43-44, 51-52} Furthermore, hydrogen production via hydrocarbon reforming has received much attention as an alternative energy source;⁵³⁻⁵⁴ thus, we sought to combine $T_R(\text{H}_2)$ values with energy partitioning trends for CH in CH₄ systems.

Our proceeding study included investigations of $T_R(\text{H}_2)$ trends and discussion on probable excitation mechanisms for H₂ in 100% H₂ and 100% CH₄ plasmas sans catalyst.¹⁸ These data are

depicted by the open symbols in Figure 5.10. Notably, $T_R(\text{H}_2)$ values (no substrate) are typically higher in 100% CH_4 plasmas ($\sim 500 - 700$ K) compared to 100% H_2 plasmas ($\sim 500 - 550$ K). Although discernable differences between $T_R(\text{H}_2)$ values and trends in these two plasma systems have been discussed in detail previously,¹⁸ the TR-OES studies performed here lend additional insight into formation mechanisms. Temporal profiles of H_2 emission in a 100% H_2 plasma and a 100% CH_4 plasma without TiO_2 , Figures 10a and 10b, respectively, demonstrate clear differences in formation rates. With a TiO_2 substrate in the system, little changes for the 100% H_2 plasma, whereas a dramatic change in the H_2 temporal profile is observed for the CH_4 system (Figure 5.9d). The H_2 energetics in these two systems with the catalyst support these TR-OES results. Specifically, in the 100% H_2 plasmas, $T_R(\text{H}_2)$ values are not significantly altered by the presence of the TiO_2 (Figure 5.10), suggesting TiO_2 does not affect H_2 excitation pathways in H_2 plasmas. Contrarily, $T_R(\text{H}_2)$ values in the 100% CH_4 plasma decrease by $\sim 100 - 200$ K in the presence of the catalyst, strongly indicating the catalyst plays a significant role in H_2^* formation processes in CH_4 plasmas.

Density functional theory calculations have recently been used to investigate the interactions of hydrogen species with catalysts and hydrogenation mechanisms in PAC systems.^{35, 55-56} In one such study, Shirazi *et al.* examined the diffusion of H atoms to the surface and into the bulk of Ni(111) for different amounts of H atom surface coverage.³⁵ Their results suggest the H atom coverage on the catalyst can strongly influence reaction kinetics. For example, when a threshold H atom surface coverage is surpassed, adsorption of H atoms or dissociative adsorption of H_2 or CH_4 becomes an endothermic, and thus, unfavorable process. In this case, associative desorption of H_2 or the consumption of surface bound H atoms by another reactant will occur to release active sites for further adsorption of species. A higher rate of H

atom diffusion to a subsurface also gives rise to a higher H atom adsorption on the surface, resulting in the reduction of surface bound H atoms and increases the rate of hydrogenation. Indeed, another study by these authors showed that catalytic hydrogenation reactions proceed faster in the presence of high H-coverage.⁵⁵ Furthermore, the adsorbate surface coverage is highly dependent on PAC reaction conditions. Thus, changes in plasma parameters can result in significant changes to the surface chemistry and ultimately modify the reaction kinetics at the catalyst surface.

Similar to $T_R(\text{H}_2)$ in the 100% CH_4 plasma, $T_R(\text{CH})$ also decreases upon the addition of a TiO_2 catalyst, Figure 5.11a (100 mTorr). Here, $T_R(\text{CH})$ values are reduced by $\sim 100 - 200$ K except at $P = 50$ W where $T_R(\text{CH})$ values are within error for the no substrate and TiO_2 substrate systems. The addition of a substrate to the plasma may impact rotational cooling pathways by providing an extra surface for collisional cooling, leading to the lower $T_R(\text{H}_2)$ and $T_R(\text{CH})$ values. Rotational relaxation is a relatively fast process as fewer than ten collisions are typically required to reach equilibrium.⁵⁷ Thus, although $T_R(\text{CH})$ decreases with the addition of the catalyst to the discharge at $p = 100$ mTorr, at $p = 150 - 200$ mTorr $T_R(\text{CH})$ values for the catalyst systems are generally within experimental error of the no catalyst system, indicating that gas-phase rotational cooling processes are likely the principal processes occurring at these increased pressures.

Our data clearly demonstrate the impact of a TiO_2 catalyst on rotational energy partitioning for H_2 $d^3\Pi_u$ and CH $A^2\Delta$ in CH_4 plasmas; yet, rotational excitation pathways via electron impact have threshold energies ($\sim 0.01 - 0.1$ eV) much lower than activation energies of heterogeneous catalysis reactions.⁵⁸ Consequently, the internal energy of rotationally excited species is too low to induce thermal catalysis in plasma. Vibrationally excited species, on the other hand, have threshold energies ($\sim 0.1 - 1$ eV) close to or greater than activation energies in

catalysis reactions and are typically not de-excited before they reach the catalyst surface (unlike ions and electronically excited species).⁵⁸⁻⁶⁰ As such, vibrationally excited species can strongly influence plasma-surface interactions in PAC systems. Numerous studies have focused on elevating the vibrational energy of reactants to enhance dissociative adsorption in catalytic reactions. To date, these studies have mainly focused on CH₄⁶¹⁻⁶⁵ and N₂⁶⁶⁻⁶⁹ because of their applications in H₂ generation via methane reforming and NH₃ synthesis, respectively. Since dissociative adsorption of CH₄ and N₂ becomes the rate-limiting steps in catalytic reactions,⁵⁸ an understanding of how energy is partitioned into vibrational degrees of freedom and how to ultimately control that energy is key to enhancing conversion rates in PAC systems.

$T_V(\text{CH})$ measured in our plasmas without and with a TiO₂ substrate in the discharge indicate $T_V(\text{CH})$ is significantly decreased (~2550 – 3100 K) upon addition of the catalyst. We have previously illustrated a similar trend in 100% N₂ plasmas, where $T_V(\text{N}_2)$ was measured without and with two different catalysts, TiO₂ and zeolite NaY.⁷⁰ In these studies, $T_V(\text{N}_2)$ decreased by ~400 – 1000 K with either catalyst in the discharge. Moreover, when our reactor was lined with multiple catalytic zeolite substrates, the observed decrease in $T_V(\text{N}_2)$ was profoundly enhanced. These results suggest that vibrationally excited molecules leave the surface with some energy loss, resulting in the observed reduced $T_V(\text{N}_2)$ values.

Notably, an important piece of surface relaxation mechanisms involves the adsorption of the excited species onto the catalyst surface.^{1,71} Dombrowski *et al.* described a precursor-mediated mechanism in which vibrationally excited methane molecules first trap on the catalyst surface via physisorption before chemisorption or desorption occurs.⁷² Depending on the vibrational lifetime and nature of the adsorbate/catalyst interaction, the molecule may either desorb with increased vibrational energy from energy exchange with the catalytic surface or the

molecule may become vibrationally quenched by the surface interaction. Several studies have shown that vibrationally excited methane molecules interact more favorably with catalytic Ni surfaces than ground state molecules, and that ultimately, these plasma-catalyst interactions lower the reaction barrier for C-H dissociation of CH₄.^{15-16, 73} One of these studies measured T_R and T_V of CH A²Δ in a packed bed DBD reactor filled with SiO₂ pellets only and SiO₂ with 3 wt% loading of Ni catalyst to elucidate a better understanding of plasma-catalyst synergies in CH₄ reforming systems.¹⁵⁻¹⁶ Their OES results show that although $T_R(\text{CH})$ remains unchanged by the introduction of the catalyst, the Ni catalyst significantly increases $T_V(\text{CH})$ with catalyst bed temperatures, but was essentially independent of bed temperature without the catalyst. Specifically, a close examination of the emission spectra for the CH A²Δ → X²Π band reveals the intensity of the $\nu(0, 0)$ and $\nu(1, 1)$ vibrational bands are decreased at elevated bed temperatures, whereas the relative intensity of the $\nu(2, 2)$ vibrational band is independent of bed temperature. These results suggest that vibrationally excited CH reacts selectively on the catalyst surface, resulting in intensity changes of the $\nu(0, 0)$ and $\nu(1, 1)$ vibrational bands and consequently, the observed elevated $T_V(\text{CH})$ values.¹⁵ This synergistic effect, however, was only observed when the catalyst bed temperature exceeded 400 °C.

Another study by Tu *et al.* examined the impact of TiO₂ on $T_R(\text{N}_2)$ and $T_V(\text{N}_2)$ in a N₂ packed bed DBD.⁷⁴ Similar to the results presented in the Nozaki *et al.* study on $T_V(\text{CH})$,¹⁵ Tu *et al.* found that $T_V(\text{N}_2)$ increased from ~2300 – 2800 K to ~3200 – 4100 K with the catalyst in the discharge.⁷⁴ Upon catalyst packing, the authors also observed a change in the discharge behavior from a filamentary discharge to a combination of surface discharges on the catalyst and micro discharges generated in void spaces between TiO₂ pellets. The authors suggest changes in discharge behavior and concomitant increase in $T_V(\text{N}_2)$ from catalyst packing coincide with

changes in the electron energy distribution function, wherein there is nominally a shift in the distribution to higher energy electrons.

Our results differ from the studies by Nozaki *et al.*¹⁵ and Tu *et al.*⁷⁴ in that T_V displays the opposite behavior when the catalyst is placed in the discharge (i.e. T_V decreases upon catalyst introduction). Possible explanations for these differences may be related primarily to the differences between the two plasma systems. The DBD systems operate at atmospheric pressure whereas our system operates at much lower pressures. At atmospheric pressure the collisional time is typically shorter than the radiative lifetime of the species of interest.²¹ Thus, in our systems fewer collisions are likely to occur compared to the DBD systems. With the addition of a substrate, there is a greater likelihood of productive plasma-surface collisions, effectively quenching the CH excited states.

Furthermore, the catalyst in our system occupies only a small amount of the total volume, whereas the DBD reactors are packed with pellets, allowing more surface area for plasma-catalyst interactions. These interactions can be complex when the catalysts lie within the discharge zone as a variety of species can interact with catalyst. Interactions between the plasma and the catalyst can be viewed from two perspectives: (1) the influence of the catalyst on plasma characteristics and (2) the influence of the plasma on the catalyst. The presence of a catalyst could significantly enhance the electric field, especially around contact points between the pellets/electrodes.^{58, 75} Several simulation studies have verified that a packed bed reactor could achieve a higher electric field compare with a non-packed one.⁷⁶⁻⁷⁷ A higher electric field generally leads to a higher electron energy, which could promote decomposition. Additionally, if the catalyst does indeed enhance the average electron energy, then this enhancement could depend on the amount of catalyst in the discharge. Electron temperature (T_e) measured from

OES lines in our system (described previously⁷⁸) indicate that T_e ranged from $\sim 2.4 - 2.7$ eV in CH₄ plasmas (Table A.1), independent of pressure and power. Moreover, the presence of the TiO₂ catalyst does not appreciably affect T_e , further suggesting the change in $T_V(\text{CH})$ noted in our systems may not arise from a change to the plasma discharge, but rather may be related to vibrational quenching from plasma-surface interactions. Similarly, Nozaki *et al.* noted that the reduced field and electron density were not affected by the presence of a Ni catalyst in their simulations, indicating that plasma-catalyst reactions were the primary cause for the observed changes in $T_V(\text{CH})$.¹⁶

Herrera *et al.* further explored synergistic behavior of plasma-catalysis systems in a N₂/H₂ packed-bed DBD reactor with three types of transition metal catalysts on Al₂O₃ support (i.e., Fe/Al₂O₃, Ni/Al₂O₃, CO/Al₂O₃).⁷⁹ Their results demonstrate the metal-on-oxide support catalysts had no significant effect on the plasma's electrical or optical properties compared to the same system with just the Al₂O₃ support substrate. These results bolster the argument that the observed synergy results from plasma modification of the catalyst surface rather than catalyst modification of the bulk plasma properties. Indeed, plasmas can significantly alter the chemical and morphological properties of catalytic materials in PAC systems; thus, changes to the catalyst properties will, in turn, have an effect on the overall PAC processes.

Our XPS (Table 5.4, Figure 5.6) and Raman data (Figure 5.7) from catalysts exposed to CH₄ plasma indicate that although amorphous carbon film deposition occurs, the plasma also modifies the underlying substrate under some parameter conditions. High resolution Ti_{2p} spectra show reduction of Ti from Ti⁴⁺ to Ti³⁺ at $p = 200$ mTorr, $P = 25$ W (Figure 5.6a) and Raman spectra (Figure 5.7b) indicate the presence of oxygen vacancies within the material. Indeed, high resolution O_{1s} data (Figure 5.6b) show an increase in adsorbed oxygen species after CH₄ plasma

exposure also indicative of oxygen vacancies.^{25, 28} Overall, these results imply concomitant etching and deposition processes occur within the CH₄ plasma system. Interestingly, some studies suggest carbon deposition is significantly reduced by synergistic effects during PAC^{58, 80} and plasma treatment has been used as a preparation method for catalysts to reduce coke formation.^{39, 81-82} This plasma treatment step serves to reduce the metal catalyst and results in higher metal dispersion and catalyst reactivity.⁸⁰ Plasma treatment for catalyst preparation in PAC systems has been studied primarily with respect to selectivity and conversion efficiencies;⁸⁰ thus, fundamental questions regarding the synergistic effects remain unanswered. These ideas could be further explored via a more holistic experimental approach utilizing gas-phase diagnostics and materials analysis to gain additional insight into synergistic plasma-catalyst interactions.

5.4 Summary

As evidenced from our data, the presence of a catalytic material can drastically alter the gas phase chemistry of the plasma. Within a CH₄ plasma, differences in species energetics and kinetics are observed with the introduction of a TiO₂ catalyst. Although the catalyst did not affect $T_R(\text{H}_2)$ in H₂ plasmas, pronounced decreases in $T_R(\text{CH}, \text{H}_2)$ and $T_V(\text{CH})$ are observed in the CH₄ plasmas. Materials characterization reveals an amorphous hydrocarbon film is deposited in the CH₄ plasma, although competing etching processes may also be occurring under some conditions. Conversely, materials analysis post H₂ plasma exposure reveals that the plasma acts primarily as an etching system. As PAC systems are extremely complex and convoluted, it is difficult to determine whether the catalyst has more influence on the plasma characteristics or the plasma's impact on the catalyst promotes changes. Ultimately, much work remains to be done to

deconvolute plasma-catalyst synergies. Although this work emphasized the importance of analyzing both the gas phase and catalyst in PAC systems, additional data on gas-surface interactions is vital to the future of this emerging technology. For example, our imaging of radicals interacting with surfaces (IRIS) technique measures a molecule's propensity to scatter from substrates may provide more evidence for how plasma species interact synergistically with catalysts. Future work should include a holistic experimental approach focused on elucidating interactions at the plasma-surface interface by combining gas-phase diagnostics, IRIS, and comprehensive materials characterization.

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CHAPTER 6

INVESTIGATING THE IMPACT OF TiO₂ ON N₂ ROTATIONAL AND VIBRATIONAL TEMPERATURES IN LOW PRESSURE PLASMAS

This chapter is based on work published in *Journal of Physics D: Applied Physics* by Angela R. Hanna, Tara L. Van Surksum, and Ellen R. Fisher, and is reproduced with permission. The published study describes the impact of two catalytic materials (nano-structured TiO₂ and micro-structured zeolite) on N₂ rotational and vibrational temperatures in low pressure N₂ plasmas. Note that a portion of this work was previously presented in Dr. Angela R. Hanna's dissertation. Dr. A. R. Hanna established the Boltzmann plot method for determination of $T_V(N_2)$ within the Fisher group. She also collected and analyzed the data pertaining to N₂ plasma without substrates and performed the study on zeolite materials. As such, the results and discussion presented herein have been excerpted and adapted for this dissertation to represent my direct contributions to this work. Specifically, the results described in this chapter include the determination of $T_R(N_2)$ and $T_V(N_2)$ in a 100% N₂ plasma with a TiO₂ substrate. Morphological and chemical characterization of the catalyst before and after plasma exposure were also assessed and presented herein. The work included in this chapter was supported by the National Science Foundation (NSF CBET-1803067). I would like to thank Dr. Patrick McCurdy for assistance with SEM and XPS analyses.

6.1 Introduction

Plasma assisted catalysis (PAC) generally describes the coupling of a plasma and catalytic material for enhanced decomposition of a waste stream. In PAC systems, the plasma state can provide high energy species that help reactants reach their dissociation energies and/or

activation energies, and the catalyst can aid in targeted product synthesis by enhancing selectivity.¹⁻² This results in a synergistic environment wherein both the plasma and catalyst can be chemically or physically altered by each other. Currently, limited understanding of the underlying phenomena contributing to plasma-catalyst synergy inhibits the implementation of PAC as a viable technology. As such, fundamental investigations regarding gas-phase processes and plasma-surface interactions are considered vital to the future of PAC development.^{1, 3-5}

The combination of the plasma and the catalyst can affect processes occurring both in the gas phase and on the catalyst surface. The plasma can inherently modify catalyst properties to alter its morphology and chemical composition.⁶ Several studies have examined how the plasma affects the material in PAC systems.⁷⁻⁸ Few studies, however, have explored how the catalyst modifies the fundamental plasma properties. Catalyst properties, such as roughness and dielectric constant, can modify the electrical properties of the plasma and ultimately affect physiochemical properties of the plasma such as the electron energy distribution.¹ This, in turn, can affect energy partitioning and rates of gas phase processes.

Although it is generally understood that catalyst particle size can influence overall rate and efficiency of PAC processes,⁹⁻¹⁰ little is understood about how low temperature plasmas (LTPs) interact with micro- and nano-structured materials. For PAC to become an efficient, working technology, it is vital to understand how the material affects gas-phase properties and the interactions occurring at the plasma-surface interface. Currently, optimization of plasma-catalysis setups (e.g., reactor design, plasma process conditions, catalyst choice) are determined through trial-and-error approaches. Elucidating fundamental gas phase processes by measuring species kinetics and internal plasma temperatures [i.e., rotational temperature (T_R) and vibrational temperature (T_V)] can afford insights into the underlying mechanisms at work in PAC

systems. Furthermore, by examining both the impact of the catalyst on gas-phase properties and how the plasma affects materials properties, information on gas-surface interface processes can be inferred.

Two studies that examined energy partitioning of N₂ plasma species in model PAC systems measured T_V and T_R of N₂ utilizing TiO₂ in a packed bed atmospheric dielectric barrier discharge (DBD) system [system pressure (p) of ~101 Pa]¹¹ and Co-ZSM-5 in a radio frequency (rf) plasma, operated near atmospheric pressure ($p = 90$ Pa).¹² Tu *et al.* found that $T_V(\text{N}_2)$ increased dramatically from ~2300 – 2800 K to ~3200 – 4100 K when TiO₂ pellets were placed in the plasma and attributed this to an increase in electron temperature (T_e) as a result of the catalyst.¹¹ Interestingly, the TiO₂ catalyst had no effect on $T_R(\text{N}_2)$ at the lowest applied discharge power (P) of 40 W and removed all the positive linear dependence of $T_R(\text{N}_2)$ on P observed without TiO₂ ($P = 40 - 70$ W). Although Tu *et al.* noted some of these changes may indicate heating of the substrate, the true origin of these effects remains unclear. Niu *et al.* also observed differences in $T_V(\text{N}_2)$ and $T_R(\text{N}_2)$ when employing a Co-ZSM-5 catalyst in a N₂ discharge.¹² Here, however, $T_V(\text{N}_2)$ was ~3100 – 3400 K with the catalyst, more than 1000 K lower than that measured without the Co-ZSM-5 (~4300 – 5000 K). A slight decrease was observed as a function of rf power with the catalyst whereas the opposite trend was observed without the catalyst. Notably, all of the measurements made in the Niu *et al.* study were at $P = 5 - 25$ W,¹² discharge powers considerably lower than the lowest used by Tu *et al.*¹¹ Although no explanation was provided for the differences between these internal temperature values and those measured by Tu *et al.*, variations in P and the catalyst type could account for the observed dissimilarities.

We have further explored all these phenomena by examining the effect of adding catalysts to an inductively coupled N₂ plasma (ICP) operated at relatively low pressure (~50 – 150 mTorr or ~7 – 20 Pa). TiO₂ nanoparticles were employed as the catalyst for a direct comparison to the Tu *et al.* study.¹¹ Furthermore, the published study included results and analysis for micro-structured NaY zeolite with additional discussion on the differences noted between the nano- and micro-structured catalysts employed.¹³ $T_R(N_2)$ and $T_V(N_2)$ were measured with the catalyst in the discharge as functions of p and P using optical emission spectroscopy (OES). Time-resolved OES (TR-OES) was also employed to measure rates of N₂ formation and decay. N₂ kinetics and energetics are discussed in comparison to previously reported results for an N₂ plasma with no substrate.¹⁴ We have also examined the morphology and chemical composition of the catalysts using scanning electron microscopy (SEM) and X-ray photoelectron spectroscopy (XPS) both before and after plasma exposure to determine the impact of the plasma on the catalyst. Our holistic approach to plasma diagnostics and comprehensive materials characterization enables us to more thoroughly investigate potential synergisms arising from the coupling of low temperature plasma and catalytic materials.

6.2 Results and Discussion

Energy partitioning within N₂ plasmas has been extensively studied over the past few decades.¹⁴⁻²³ As a result, a wide range of plasma operating parameters have been explored, creating an array of reported $T_R(N_2)$ and $T_V(N_2)$ values. Prior to the PAC studies described within this chapter, the Fisher group measured rotational and vibrational temperatures for N₂ in a 100% N₂ plasma (no substrate).¹⁴ This previous work allows for direct comparison between our N₂ plasma systems (no substrate and catalyst) and serves as a reference point to many of the

results described throughout this chapter. Figure 6.1 shows a typical N₂ emission spectrum acquired with a TiO₂ substrate placed in the coil region of the reactor. $T_R(\text{N}_2)$ for the $\text{C}^3\Pi_u \rightarrow \text{B}^3\Pi_g$ transition was determined from simulated fits of experimental spectral data using SpecAir²⁴ whereas a Boltzmann plot was used to calculate $T_V(\text{N}_2)$. For $T_V(\text{N}_2)$ calculations, $\ln(I\lambda/A)$ is plotted as a function of vibrational energy (E) where I and λ are the intensity (a.u.) and wavelength (nm) of a specific emission line and A (s⁻¹) is the corresponding Einstein transition probability coefficient for the transition. The N₂ vibrational transitions, corresponding wavelengths, and A values used here are reported previously.^{21, 25} The inset in Figure 6.1 shows the Boltzmann plot created from the corresponding displayed N₂ emission spectrum. The slope of the linear regression is inversely proportional to T_V , which ultimately yields $T_V = 3140 \pm 20$ K for the particular set of conditions shown in Figure 6.1.

Rotational and vibrational temperatures were determined under several sets of plasma conditions. Figure 6.2 shows T_R and T_V data for N₂ with and without a TiO₂ substrate in a 100% N₂ plasma ($p = 100$ mTorr) as a function of P . Numerical values for $T_R(\text{N}_2)$ and $T_V(\text{N}_2)$ measured under all conditions studied here are listed in Table 6.1. The $T_R(\text{N}_2)$ data in the 100% N₂ plasma (no substrate), reported previously¹⁴, show a small, but fairly linear increase with increasing P , with values near room temperature ($\sim 310 - 340$ K), Figure 6.2a. Addition of a TiO₂ substrate does not appreciably change the overall values, but the P dependence has largely disappeared, within experimental error. In contrast, the T_V values shown in Figure 6.2b show a strong linear dependence on P , both with and without the TiO₂ catalyst in the plasma. Interestingly, with the catalyst, the measured temperatures decrease by $\sim 400 - 1000$ K and the dependence on P decreases by approximately a factor of 2. This decrease in $T_V(\text{N}_2)$ was documented at all pressures studied herein (50 – 150 mTorr), Table 6.1. Notably, $T_V(\text{N}_2)$ reaches

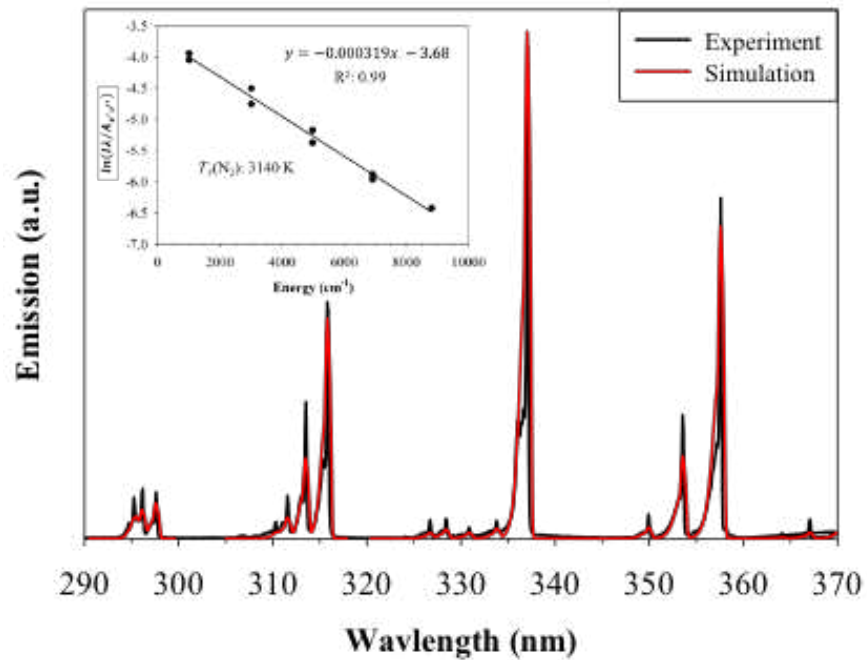


Figure 6.1. Representative emission spectrum at $p = 100$ mTorr, $P = 100$ W for N_2 ($\text{C}^3\Pi_u \rightarrow \text{B}^3\Pi_g$) in a N_2 plasma with TiO_2 . Simulation of the spectrum using SpecAir yields $T_R = 350$ K. Inset shows a Boltzmann plot of N_2 vibrational distribution in a 100% N_2 plasma under the same conditions with a TiO_2 catalyst.

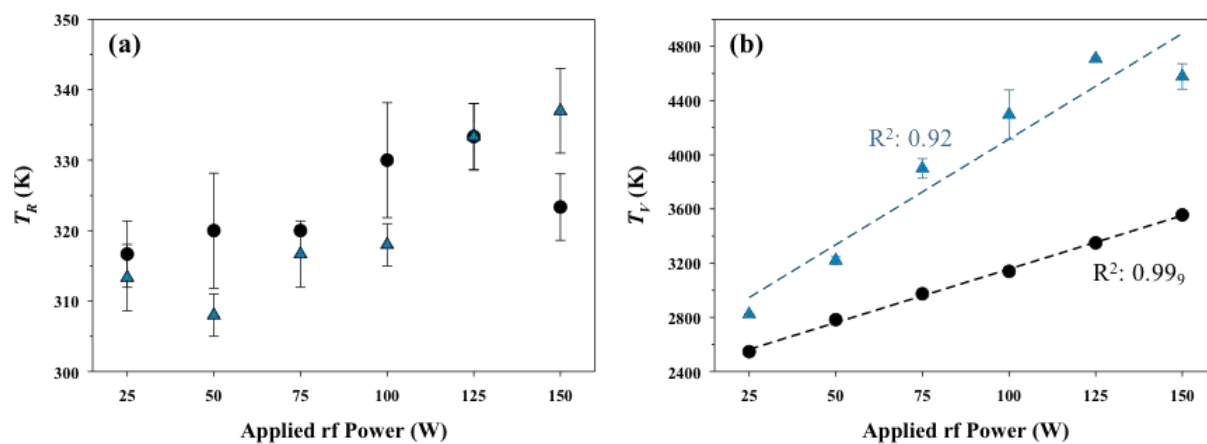


Figure 6.2. (a) $T_R(\text{N}_2)$ and (b) $T_V(\text{N}_2)$ from a N_2 plasma system at $p = 100$ mTorr with (black circles) and without (blue triangles) a TiO_2 substrate. Values for T_R without a substrate were previously reported.¹⁴

Table 6.1. $T_R(N_2)$, $T_V(N_2)$ values in a N_2 plasma system with TiO_2 .^a

p (mTorr)	P (W)	T_R (K)	T_V (K)
50	25	300 (10)	2310 (20)
	50	300 (10)	2560 (10)
	75	310 (10)	2780 (10)
	100	320 (10)	3120 (120)
	125	320 (10)	3700 (270)
	150	370 (10)	4620 (70)
100	25	320 (10)	2550 (10)
	50	320 (10)	2780 (10)
	75	320 (10)	2970 (20)
	100	330 (10)	3140 (20)
	125	330 (10)	3350 (10)
	150	320 (10)	3560 (20)
150	25	300 (10)	2520 (20)
	50	300 (10)	2770 (10)
	75	330 (10)	3010 (10)
	100	330 (10)	3150 (10)
	125	330 (10)	3310 (20)
	150	340 (10)	3480 (10)

^aValues in parentheses represent standard deviation calculated from the mean of $n \geq 3$ trials.

values nearly an order of magnitude higher than $T_R(\text{N}_2)$, suggesting that rotational relaxation is more efficient than vibrational relaxation. Within N_2 plasmas containing a TiO_2 substrate, as p increases from 50 mTorr to 150 mTorr, some interesting trends emerge. At lower P (25 – 75 W), $T_V(\text{N}_2)$ at 100 and 150 mTorr are within experimental error but are elevated compared to the 50 mTorr data. At higher P , as pressure is increased to 150 mTorr, there is significant quenching of the vibrational excited states, resulting in a decrease in $T_V(\text{N}_2)$ as a function of p .

Our results clearly demonstrate that the presence of a TiO_2 catalyst within the plasma can impact $T_V(\text{N}_2)$ and agree to a certain extent with the results reported by Tu *et al.* for a TiO_2 packed bed DBD system.¹¹ Overall, both $T_R(\text{N}_2)$ values (~300 – 600 K) and $T_V(\text{N}_2)$ values (~2500 – 4500 K) are similar to the Tu *et al.* system. In the DBD system, however, opposite trends with respect to $T_V(\text{N}_2)$ are reported. Namely, Tu *et al.* described a decrease in $T_V(\text{N}_2)$ with increasing P and an increase of $T_V(\text{N}_2)$ upon packing with TiO_2 .¹¹ They attributed this behavior to greater vibrational-translation relaxation at higher P , and the increase in $T_V(\text{N}_2)$ was attributed to an enhancement of the average electron energy in the plasma.

Possible explanations for the disparities between these reported trends and the results reported herein may be attributed to inherent differences between the two types of plasma systems used. First, the DBD reactor operates at atmospheric pressure, whereas our systems operate in a much lower pressure regime (50 – 150 mTorr), with a concomitant much longer the mean free path in our system. At atmospheric pressure, electronic quenching (the process by which a collision with species M removes energy from excited state species towards any other final product²⁶) determines the lifetime of the excited electronic state, occurring on a longer timescale compared to radiative decay. As such, fewer collisions are likely to occur in our systems than in the DBD system. Upon the addition of a substrate, there is a greater likelihood

of productive plasma-surface collisions, effectively quenching N₂ excited states. Furthermore, plasma processing time is an important consideration, as the DBD system studied by Tu *et al.* operated on the μs timescale,¹¹ whereas our temperature studies investigate steady-state emissions from N₂ molecules on the timescale of minutes. Arguably, there can be vast differences in long-lived and short-lived species within plasma discharges;²⁷ therefore, future studies probing plasma internal temperatures as a function of time may be useful to understanding species' evolution during plasma processing.

Second, the catalyst in our system occupies only a small fraction of the total plasma volume, whereas Tu *et al.*'s reactor is completely packed with TiO₂ nanoparticles.¹¹ Thus, the surface area of catalyst available for interaction with the plasma is much larger in the DBD system. Moreover, the packed reactor reduces the plasma volume and gives rise to changes in the discharge mode which could promote decomposition or non-uniform electric fields in the system.²⁸ If the hypothesis that the catalyst enhances the average electron energy in the plasma is true, then this enhancement could be dependent on the amount of catalyst present. We have previously used the OES spectra acquired in our system to measure T_e in our plasmas, reporting $T_e \sim 1.6$ eV in a 100% N₂ plasma (no substrate), regardless of P .¹⁴ Here, we measured $T_e \sim 1.8$ eV for the same system with a TiO₂ substrate, also independent of P at $p = 50$ and 100 mTorr. The lack of significant dependence on P suggests increasing the overall energy of the system preferentially results in increasing the internal energy of neutrals or positive ions, rather than heating the electrons. Nevertheless, T_e appears to be slightly elevated in the presence of the TiO₂ catalytic material, indicating this catalyst does indeed slightly enhance the average T_e in our systems.

Additional OES analysis reveals that not only does a TiO₂ catalyst affect energy partitioning within a N₂ plasma, but the presence of new gas-phase species is also observed when the catalyst is placed in the discharge. A representative raw emission spectrum of 100% N₂ plasma ($p = 100$ mTorr, $P = 75$ W) features the observed N₂ C³Π_u → B³Π_g, NO A²Σ⁺ → X²Π, and OH A²Σ⁺ → X²Π bands when TiO₂ is placed in the coil region of the reactor space, Figure 6.3a. Comparatively, when no substrate is present in the discharge, little to no emissions from NO or OH are observed,¹³ highlighting the significant impact of the catalyst on the gas phase of the plasma. The presence of oxygen-containing gas phase species arises as the plasma interacts with the TiO₂ catalyst, resulting in removal of surface oxygen species. Additionally, the decrease in $T_v(\text{N}_2)$ in the presence of the catalyst suggests that within our systems, vibrationally excited molecules interact with the substrates and rebound with some energy loss.

To further explore this impact, relative species' densities were calculated using inert gas actinometry where molecular emissions of N₂ (337.1 nm), OH (309.0 nm), and NO (235.9 nm) were monitored. Figure 6.3b shows the relative amount of N₂ present remains nearly constant with increasing P . This P dependence is similar to observations in a N₂ plasma with a zeolite substrate where the N₂ density is within error from $P = 50 - 150$ W.¹³ In an N₂ plasma with a TiO₂ substrate, OH density also remains constant as a function of P . Conversely, NO density remains fairly constant at low applied rf power until $P = \sim 75 - 100$ W, where it begins to decrease. Moreover, the P trends of the oxygen-containing gas phase species differ from the N₂ zeolite PAC system, where OH and NO densities both increase with respect to P .¹³ In another study from the Fisher research group, the impact of a zeolite catalyst on gas phase chemistry in an N₂O plasma was examined.²⁹ In that work, a sharp decrease in NO density is observed at $P = 75$ W with a simultaneous increase in N₂ and atomic oxygen, suggesting that NO may react with

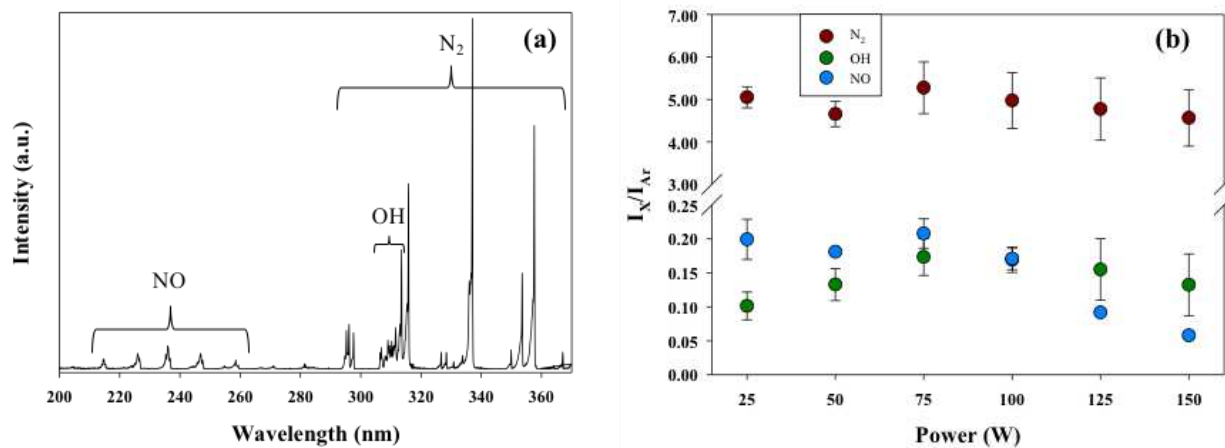


Figure 6.3. (a) Representative emission spectrum ($P = 75$ W) and (b) relative species density as a function of applied rf power in a 100 mTorr N₂ plasma system with TiO₂.

atomic nitrogen species to form N₂ and O. Because OH density remains fairly constant as a function of P in this system, it is likely that NO is also still being formed from interactions between the plasma and the substrate, but is being decomposed in the gas phase at high P . In this system, however, we do not observe atomic oxygen species or an increase in N₂ density. To gain further insight into the processes occurring in this system, future investigations could include actinometry studies of TiO₂ in other types of N_xO_y plasma systems. Additionally, gas phase investigations with multiple TiO₂ substrates in the plasma would allow for a larger surface area for gas-surface interactions and may help to illuminate clearer density trends or expound the presence of additional gas phase species, such as atomic oxygen.

The interactions between the plasma and the catalyst are obviously imperative to PAC synergy. Thus, choosing an appropriate catalyst is an essential consideration when constructing a viable PAC system. Catalyst pore size and geometry are a couple of important factors to consider in PAC systems as these structural characteristics can have a substantial impact on the fundamental plasma properties. For example, Zhang *et al.* demonstrated that pore shape and size had a significant effect on the electric field within a plasma resulting in changes to the electron density and temperature.³⁰ Our published report compared the impacts of both nano-structured TiO₂ and micro-structured zeolites on N₂ rotational and vibrational temperatures.¹³ To illustrate the impact of these two catalysts on $T_V(\text{N}_2)$, ΔT_V was calculated via equation 6.1 and the error reported was appropriately propagated.

$$\Delta T_V = [T_V(\text{catalyst}) - T_V(\text{no substrate})] \quad (6.1)$$

Notably, Figure 6.4 demonstrates that vibrational cooling of N₂ occurs with either catalyst present in the discharge. A similar observation was also made in N₂O plasma where decreased $T_V(\text{N}_2)$ values were also documented for three different catalysts (Pt foil, nano-

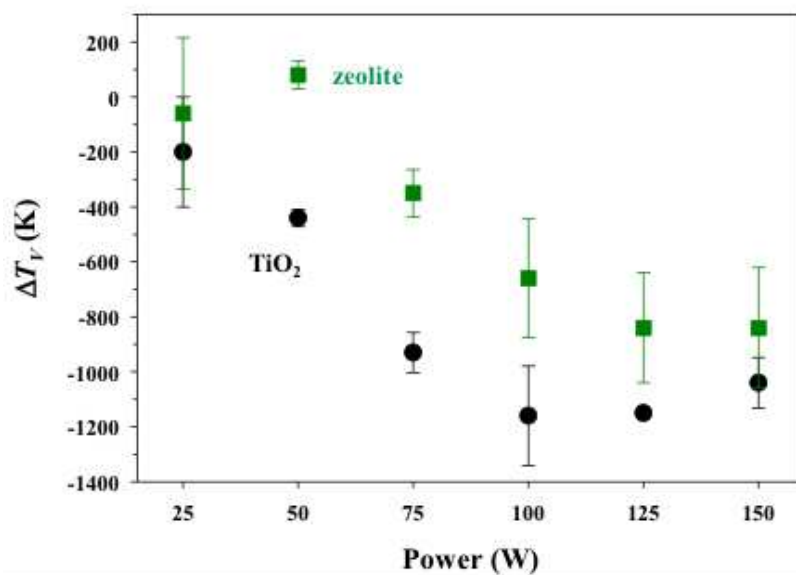


Figure 6.4. ΔT_V for N_2 as a function of applied rf power in a 100% N_2 plasma ($p = 100$ mTorr) with a TiO_2 substrate (black circles) and a zeolite substrate (green squares). Zeolite data were collected and analyzed by A. R. Hanna.

structured Pt powder, and micro-structured zeolite).²⁹ Here, although decreased $T_V(\text{N}_2)$ values were also documented in the presence of a micro-structured zeolite pellet, the difference compared to a substrate-less system was not as drastic as with a nano-structured TiO_2 substrate. Similarly, in the N_2O plasma system, the nano-structured Pt powder catalyst resulted in markedly decreased $T_V(\text{N}_2)$ values compared to the flat Pt and micro-structured zeolite substrates.²⁹ In our systems, the TiO_2 substrates have significantly smaller pores than the zeolite, suggesting that plasma generation near the pores of the TiO_2 substrate may be heightened, ultimately leading to more vibrational quenching interactions with the catalyst surface. TiO_2 is also a known photocatalyst, and the UV light generated from the plasma may further activate these materials and also contribute to vibrational quenching. Evaluating steady state emission spectroscopy provides valuable information regarding species densities and energetics; however, TR-OES data can help to elucidate additional details about the entangled dynamics in PAC-relevant systems.

Emission intensity of N_2 (337.0 nm) was monitored as a function of time and rate constants of formation (k_f) and destruction (k_d) were determined by fitting the resulting intensity curve with first order exponentials (e^{-kt}). As evidenced in Figure 6.5a, the system with no substrate reaches a steady state with no subsequent decay, hence k_d is not reported. The addition of a TiO_2 catalyst to the discharge, however, significantly changes the gas-phase chemistry and a subsequent decay to a steady state is evident at high powers ($P \geq 100$ W), Figure 6.5b. To further assess kinetic trends, TR-OES data were collected as a function of P at $p = 100$ mTorr, Table 6.2. Without a catalyst present, k_f values decrease as a function of P . Upon addition of a TiO_2 substrate, k_f values are lower, except at $P = 125$ W where k_f values of the two systems are within error of each other. At $P = 150$ W, a clear formation curve followed by a subsequent decay curve were present in some cases, whereas in other cases only a decay curve was present

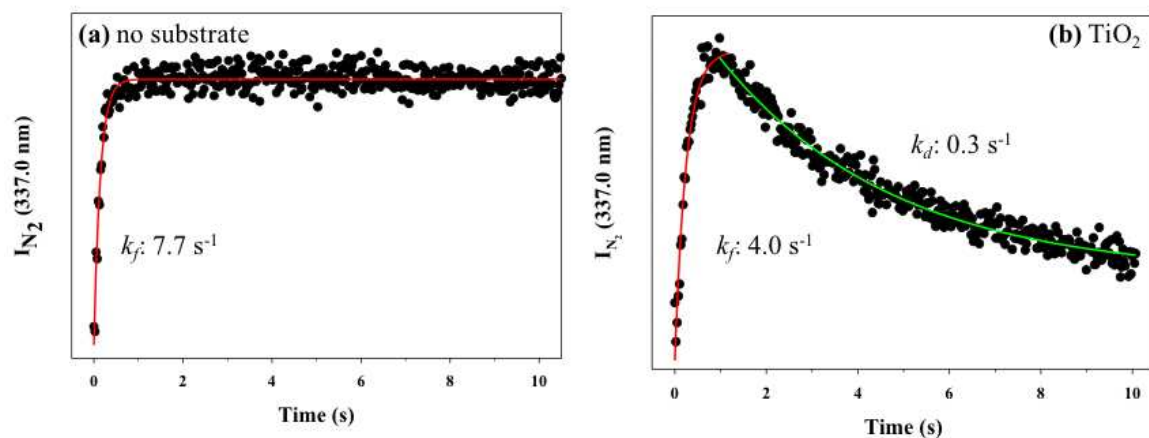


Figure 6.5. Intensity of N₂ emission plotted as a function of time at (a) $p = 100$ mTorr, $P = 50$ W with no substrate; (b) $p = 100$ mTorr, $P = 150$ W with a TiO₂ substrate. Rate constants of formation and destruction were determined by fitting a first order exponential to each curve (red and green lines, respectively). The no substrate data were collected and analyzed by A. R. Hanna.

Table 6.2. k_f (s^{-1}) and k_d (s^{-1}) values in a 100% N_2 plasma without and with a TiO_2 substrate.^a

P (W)	no substrate ^b k_f (s^{-1})	TiO_2 k_f (s^{-1})	TiO_2 k_d (s^{-1})
25	10.0 (5.8)	3.1 (0.4)	—
50	8.1 (1.6)	5.7 (0.6)	—
75	5.3 (2.9)	0.71 (0.17)	—
100	4.8 (0.4)	3.5 (0.4)	0.28 (0.014)
125	2.4 (0.3)	3.7 (2.4)	0.27 (0.028)
150	1.3 (0.06)	—	0.29 (0.094)

^a Values in parentheses represent standard deviation calculated from the mean of $n \geq 3$ trials.

^b No substrate data collected and analyzed by A. R. Hanna.

at the integration time utilized (25 ms). Thus, a k_f value is not reported for the $P = 150$ W with TiO_2 substrate system. Comparatively, when a zeolite catalyst (single substrate and multiple substrates) was added to plasma, k_f values differed from the no substrate system except at high power.¹³ The plasma discharge mode switches between operating in E-mode [capacitively-coupled electrostatic pre-discharge mode (low P)] and H-mode [inductively-coupled electromagnetic main discharge mode (high P)] between 125 W and 150 W, such that at 150 W the plasma is operating in H-mode. These results suggest that catalysts may have a greater impact on the reaction kinetics when the discharge is operating in E-mode.

Differences in kinetic trends between the two catalyst systems are also worth noting here. The documented k_d values for a TiO_2 , Table 6.2, remain constant at $\sim 0.28 \text{ s}^{-1}$ regardless of P . Conversely, in the zeolite system, k_d values increase with P and are lower than the TiO_2 system.¹³ Mehta *et al.* argue the gas-phase is heavily influenced by active nitrogen species (i.e., N , N_2^+ , and vibrationally excited N_2) and increased reaction rates in the presence of catalysts arise from N_2 molecules in low vibrational states on the surface.³¹ Notably, $T_V(\text{N}_2)$ values are lower (i.e. less vibrationally active) for the TiO_2 catalyst system relative to the zeolite system. Regardless of the catalyst material or morphology, it is clear that the catalyst alters the gas-phase of the plasma. Consequently, we have also investigated how the catalysts were changed through gas-surface interactions.

N_2 plasmas have been used to create metal nitrides and other materials as nitrogen is known to readily replace oxygen in metal oxide lattices.³²⁻³³ Thus, we have examined the morphology and surface composition of our catalyst prior to and after N_2 plasma exposure using SEM and XPS. Figure 6.6 highlights the approximate sizes of the TiO_2 nanoparticles and pores. The commercially purchased TiO_2 material agglomerates into nanoparticle clusters with a porous

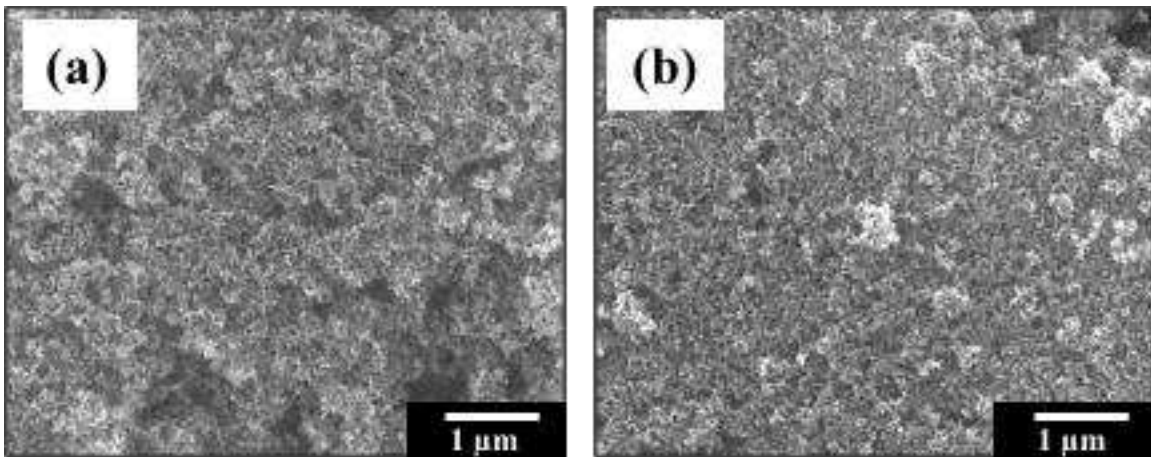


Figure 6.6. Representative SEM images (x20000) of TiO₂ (a) as prepared on Si wafer substrate and (b) post N₂ plasma exposure ($P = 150$ W; $p = 100$ mTorr; $t = 10$ min).

structure when pasted onto the glass substrate, Figure 6.6a. Notably, the morphological features do not change appreciably upon exposure to the N₂ plasma, Figure 6.6b, regardless of P or p over the parameter space explored herein.

Figure 6.7 contains high-resolution O_{1s} and Ti_{2p} spectra for TiO₂ prior to and post N₂ plasma exposure ($p = 100$ mTorr, $P = 150$ W, $t = 10$ min). The primary contribution to the O_{1s} spectra in untreated TiO₂ arises, as expected, from oxygen bound to Ti⁴⁺ (530.2 eV),⁸ Figure 6.7a, with a smaller peak assigned to oxygen adsorbed to the material surface, such as hydroxyl species (532.1 eV).^{8,34} An increase of adsorbed surface oxygen post N₂ plasma processing, Figure 6.7d, is likely the result of the plasma creating oxygen vacancies within the TiO₂ lattice, which ultimately decreases the relative contribution of the bound oxygen.^{8,35} High resolution Ti_{2p} spectra of the untreated TiO₂ material, Figure 6.7b, show binding energies for Ti_{2p3/2} and Ti_{2p1/2} at 458.6 eV and 464.2 eV, respectively, corresponding to surface titanium in the Ti⁴⁺ oxidation state.⁸ Additional binding environments at 457.9 eV and 462.5 eV corresponding to Ti³⁺ exist in the spectrum of the TiO₂ substrates post N₂ plasma exposure, Figure 6.7e, suggesting nitrogen doping.^{8,33} Specifically, the formation of an O-Ti-N binding environment by substitution of an O atom in the TiO₂ lattice with a N atom is attributed to a shift toward lower binding energy.³⁶ High-resolution C_{1s} spectra, Figure 6.7c and 6.7f, show binding environments for -C-C/-C-H (284.8 eV), -C-O-R/-C-O-H (286.3 eV), and -C=O (288.7 eV) for the TiO₂ substrate before and after plasma treatment. From these spectra and the corresponding elemental composition, Table 6.3, exposure to the N₂ plasma does not appear to significantly change the nature or amount of carbon on the TiO₂ nanoparticle surface. We do, however, observe a small, but non-negligible amount of nitrogen incorporated into the TiO₂ catalyst surface. Similarly, Lu *et al.* utilized Fourier transform infrared spectroscopy and XPS to

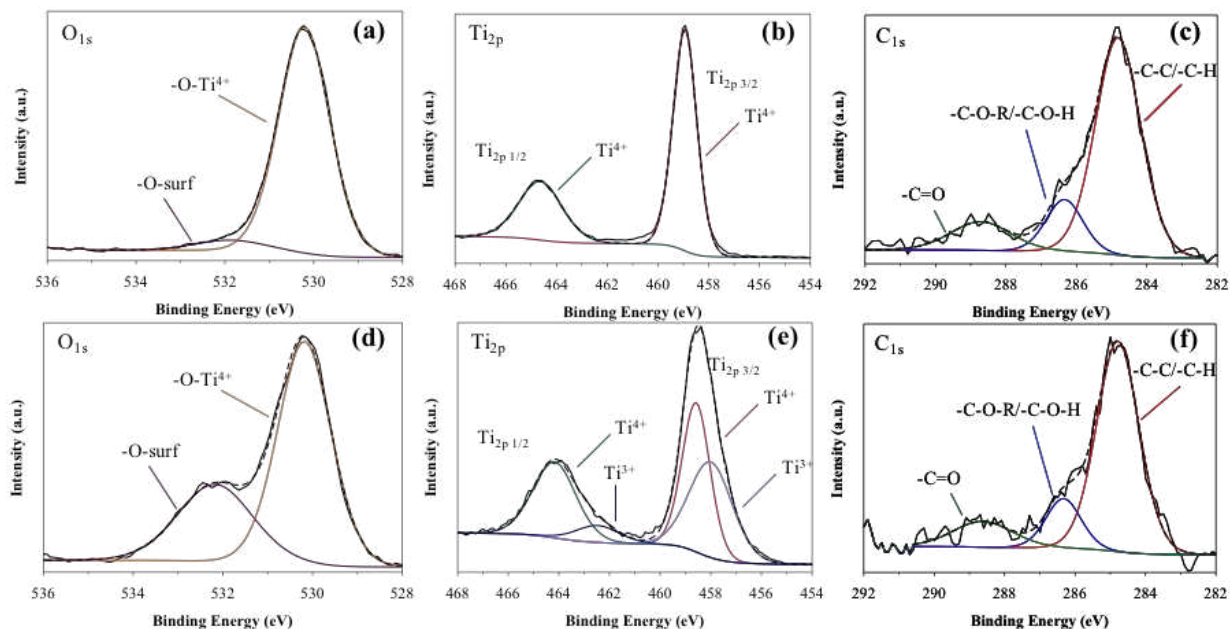


Figure 6.7. XPS high resolution O_{1s} , Ti_{2p} , and C_{1s} data for TiO_2 prior to plasma exposure (a, b, c) and after N_2 plasma ($p = 100$ mTorr, $P = 150$ W, $t = 10$ min) exposure (d, e, f).

Table 6.3. XPS atomic composition data for TiO₂.^{a,b}

	Untreated	N ₂ plasma
Ti [%]	25.5 (1.2)	19.1 (2.1)
O [%]	63.6 (1.4)	58.8 (1.8)
C [%]	10.9 (2.3)	9.5 (2.3)
N [%]	--	6.6 (1.8)
Si [%]	--	6.0 (2.2)

^aValues in parentheses represent one standard deviation for the measurement.

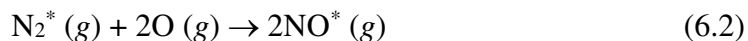
^bTreatment conditions: $p = 100$ mTorr, $P = 150$ W, $t = 10$ min

document nitrogen doping into the structure of TiO₂ coated dielectric of their parallel-plate DBD reactor.³⁶ Pulsipher *et al.* also observed nitrogen incorporation into TiO₂ substrates upon exposure to a range of nitrogen-containing plasmas, including N₂-based systems.³⁷

As discussed throughout this chapter, we sought to not only examine the impact of the catalyst on fundamental gas-phase processes in the plasma but are also to understand the plasma's impact on catalyst properties. Elucidating the entangled impact of both the plasma and the material on each other helps to unravel the synergistic effects and complex chemical processes and work needed to ultimately improve the performance of these processes for practical applications. Hueso *et al.* also noted the importance of examining both the gas-phase of the plasma and the catalyst to deconvolute plasma-catalyst synergies for improving process performance.³⁸ They studied conversion of NO and CH₄ in mixed gas plasma systems with two catalytic materials, a perovskite-type catalyst and SiO₂. In addition to gas conversion calculations, they utilized OES to identify the prominent gas-phase species in their plasma systems and XPS to evaluate surface chemistry of their catalysts before and after plasma exposure. Interestingly, in their systems, decreased NO removal efficiency was observed in the presence of either catalyst. XPS results from Hueso *et al.* show the presence of adsorbed nitrogen species [$-\text{NO}_x$ ($x \leq 2$) and $-\text{NO}_2$] on the perovskite-type catalyst after plasma exposure.³⁸ The adsorbed species pass through a maximum concentration as a function of time and then decrease when steady-state conditions are reached. The authors attribute this to a high concentration of NO* shown in their OES results. NO* can be reactive towards oxide surfaces and give rise to the $-\text{NO}_x$ and $-\text{NO}_2$ adsorbed species corroborated by their XPS results.³⁸⁻⁴⁰ Removal and decomposition of these species from the surface can ultimately yield NO, possibly explaining the reduced NO removal efficiency. These results are important in that they consider

both the gas-phase and material in PAC systems in an effort to elucidate plasma-catalyst synergies; yet, the authors did not monitor the gas-phase via OES with a catalyst present in the plasma. Results presented throughout this chapter demonstrate that plasma chemistry can change significantly upon addition of a catalyst to the discharge. Thus, a thorough analysis of the plasma with and without a catalyst is an essential consideration when investigating inherently complex PAC systems.

Our experimental approach allows us to gain further insight into the mechanistic phenomena and plasma-catalyst synergies in PAC systems. Figure 6.8 depicts the gas-surface interactions that we believe are the most prevalent in our system. XPS data reveal nitrogen doping into the TiO₂ lattice under some parameters. The etching of lattice oxygen can occur when excited state nitrogen impinges and reacts to form additional gas-phase species (i.e., NO, OH) as depicted in Figure 6.8 and reaction 6.2.



Ultimately, there is still much work to be done to understand the underlying mechanisms involved in PAC. Nevertheless, the work presented herein clearly demonstrates that catalytic materials can alter energy partitioning with the gas-phase of the plasma.

6.3 Summary

Evaluation of energy partitioning and materials characterization data reveal a synergistic nature between the plasma and TiO₂ catalyst wherein the material impacts the gas-phase of the plasma and the plasma alters chemical characteristics of the catalyst. The presence of the catalyst in the N₂ discharge resulted in a pronounced decrease of N₂ vibrational temperatures while no clear or significant impact on the rotational temperature was reported. For PAC to

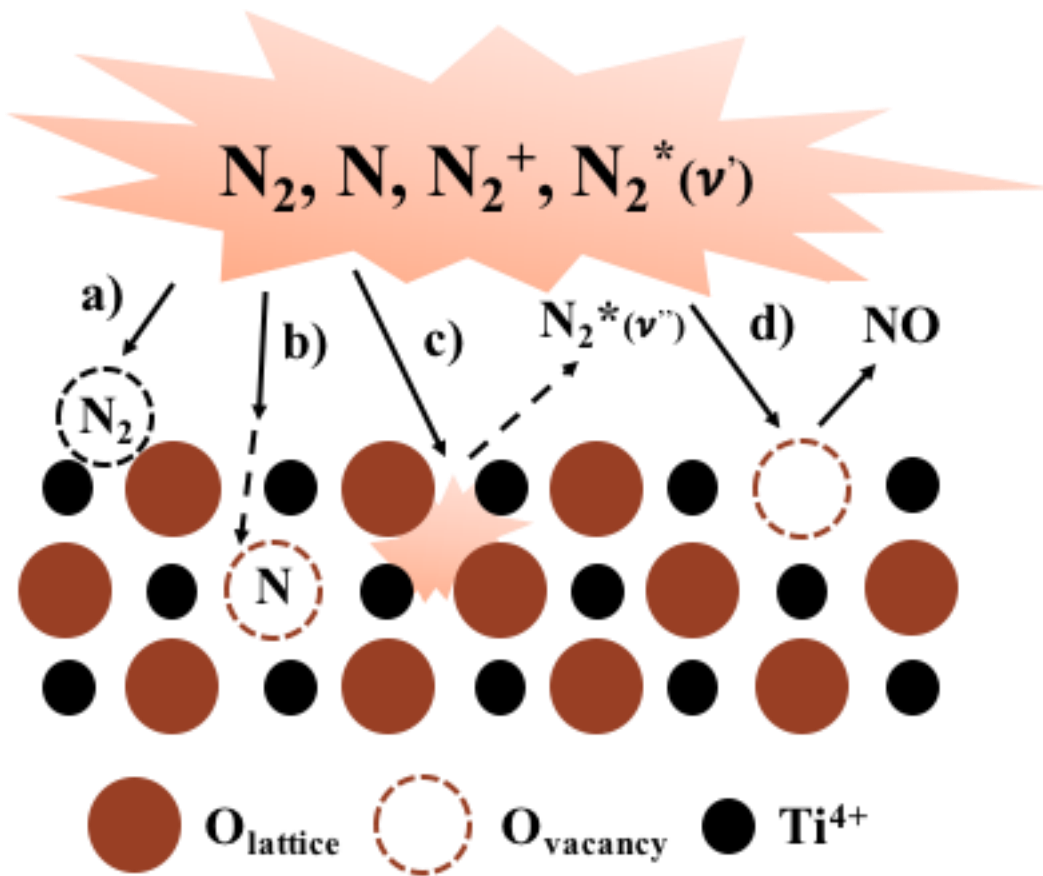


Figure 6.8. Schematic representation of various surface modification process occurring during N_2 plasma processing: (a) surface adsorption; (b) N-doping of the substrate; (c) energetic bombardment resulting in vibrational quenching; (d) etching and formation of new gaseous species. This figure has been modified from the published version (original version created by A. R. Hanna) to reflect the new information presented within this chapter.¹³

become a viable tool for pollution control, fundamental plasma characteristics must first be examined to elucidate mechanistic phenomena that control PAC synergies. Specifically, investigations into plasma-surface interactions are vital to the future of this technology. Employing our unique imaging radicals interacting with surfaces (IRIS) technique to determine a molecule's propensity to scatter from catalytic surfaces could provide insight into gas-surface interactions and will be used in future work. A holistic experimental approach employing gas-phase, gas-surface interface, and materials analyses will be essential to increasing the potential for utilizing PAC as a pollution remediation tool.

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CHAPTER 7

ELUCIDATING ENERGETIC AND KINETIC TRENDS IN ENVIRONMENTALLY RELEVANT MIXED GAS PLASMA SYSTEMS

The studies presented within this chapter employ optical spectroscopy techniques to elucidate energetic and kinetic trends of several molecular species (i.e., CH, CN, CO, H₂, OH, N₂) in CH₄/N₂ and CH₄/H₂O plasma systems. Time-resolved optical emission spectroscopy results suggest formation of CN may be related to the excited nitrogen species available in a CH₄/N₂ plasma. Moreover, there are vast differences in rotational and vibrational temperatures between different plasma species. This indicates that the rotational and vibrational temperatures of the excited state species in our system are not equilibrated with each other and that different species have achieved different degrees of equilibration between rotational and vibrational modes. Mechanistic phenomena regarding molecule formation in these plasma systems will be discussed. This work was supported by funding through the National Science Foundation (NSF CBET – 1803067) and the American Chemical Petroleum Research Fund (ACS PRF 59776 – ND6).

7.1 Introduction

Nonthermal, low temperature plasmas (LTPs) comprise a variety of electrons, ions, atoms and molecular species that are not in equilibrium with each other and can have significantly different kinetic energies.¹ Specifically, the translational energy of the electrons in LTPs are much larger than the heavy species in the plasma (i.e., ions, neutrals, radicals).¹ Consequently, the electron temperature (T_e) is much higher than the gas temperature (T_g), and the highly

energetic electrons initiate numerous reactions through electron impact collisions.¹ Because reactive species generated in the plasma lead to complex physical and chemical reactions, an LTP is a highly promising approach to surface modification, etching, deposition, or synthesis of new molecules. An example of the last instance can be found in plasma assisted catalysis (PAC) applications, which generally describes the coupling of a plasma and catalyst for enhanced processing of the input gas stream to either convert the feed gas mixture to another gas mixture or to grow a material from the precursor gas. For example, carbon deposition from CH₄ or C₂H₂ produces a significant amount of H₂.² Additionally, the conversion of volatile organic compounds and NO_x emissions into harmless constituents via PAC is of particular interest to the plasma community.³ Regardless of the end application, a thorough understanding of the molecular formation processes is critical to the advancement of plasma technology.

Optical spectroscopy diagnostics have been widely employed to examine molecule formation processes in LTPs because of their relatively simple configuration and the nonintrusive nature of the technique.⁴ For example, Wang *et al.* used optical emission spectroscopy (OES) to better understand the formation and role of active gas-phase species in the plasma-enhanced synthesis of ammonia.⁵ The authors examined emission intensities of several excited state species (i.e., N₂⁺, N, H_α, NH) in a N₂/H₂ dielectric barrier discharge (DBD) without and with catalyst packing. Identification of atomic N and the H_α Balmer line via OES suggests dissociation of the precursor gases. Furthermore, with catalyst packing, the increase in NH₃ yield in conjunction with the increased intensity for each of the studied gas phase species suggests that the generation of these species may help promote NH₃ formation. Another recent OES study examined the effects of pulsed plasma parameters during the reforming process in a 50% CH₄/50% CO₂ dielectric barrier discharge (DBD).⁶ The authors noted that the emission

spectrum comprised CH, C₂, H_α, CO, and CO₂⁺ species and determined the rotational (T_R) and vibrational (T_V) temperatures of CH A²Δ → X²Π in their system. The large difference between $T_V(\text{CH})$ (6500 ± 1000 K) and $T_R(\text{CH})$ (547 ± 10 K) indicates a significant internal non-equilibrium in the plasma which the authors hypothesize ultimately facilitated temperature control and enhanced the conversion process.⁶

Although these studies provide useful information on the excited state species in the plasma, OES is a powerful diagnostic tool that can also be used to probe kinetics and energy distributions.⁴ Indeed, the future of plasma technology relies on a deeper understanding of gas phase kinetic and energetic pathways.³ Such information is crucial to accurate plasma modelling and the development of efficient PAC systems. In this work, species formation (k_f) and destruction (k_d) rates are determined by employing time-resolved OES (TR-OES). Additional insight into molecule formation mechanisms and decomposition pathways is gained via the rotational and vibrational temperatures of molecular species within our plasma systems. One important consideration with internal plasma temperature determination is that different molecular species within the same plasma system may exhibit vastly different rotational and vibrational temperatures. Thus, examining several molecular species within a plasma system provides enhanced insight into the overall plasma chemistry. Additionally, a single plasma species may be produced via different mechanisms (e.g., direct impact excitation, decomposition, recombination) and may exhibit different T_R or T_V values as a function of plasma parameters. Indeed, plasma temperatures tend to be highly dependent on plasma parameters.⁷⁻⁹ For example, Raud *et al.* calculated $T_R(\text{N}_2)$ and $T_R(\text{OH})$ in a 2 Torr Ar/0.5% O₂ rf discharge as a function of power density, demonstrating that $T_R(\text{OH})$ increased with growing power density whereas $T_R(\text{N}_2)$ displayed the opposite trend.⁸ In addition, $T_R(\text{N}_2)$ was consistently higher than $T_R(\text{OH})$ over the

parameter range studied, suggesting that $T_R(\text{N}_2)$ was not directly related to the gas temperature in their system. Thus, a more complete understanding of the relationship between plasma parameters and kinetic and energetic outcomes can provide prolific insights into the roles of the reactive species in physical or chemical catalytic reactions and can ultimately provide reference for the optimization of plasma devices and the efficiency of PAC systems.

In this work, we investigated the kinetics and energy partitioning trends of several molecular species (i.e., CH, CN, CO, H₂, N₂, OH) in two CH₄-containing plasma mixtures as functions of feed gas composition and applied rf power (P) using steady state OES and TR-OES. Note that all experiments described within this chapter were performed at a total system pressure of 150 mTorr. CH₄/N₂ and CH₄/H₂O gas mixtures were chosen these studies because of their environmental relevance for PAC applications. For all steady state experiments (e.g., actinometry, internal temperature determination), a small amount of Ar (10%) was added to the precursor mixture. The remaining 90% of the feed gas comprised of CH₄/N₂ or CH₄/H₂O mixtures at different ratios. TR-OES experiments used the same ratio mixtures, but no Ar was added to these experiments. Some of the results in this report are compared to our previous energy partitioning studies of 100% N₂ and 100% CH₄.¹⁰⁻¹² By coupling kinetic and energy partitioning data for multiple species within our plasmas systems, we can begin to unravel the complex chemical processes responsible for plasma behavior.

7.2 Results

a. *CH₄/N₂ plasma system.* Representative raw OES spectra for two different gas ratios of a CH₄/N₂ plasma system (with 10% Ar added) are shown in Figure 7.1. Emission peaks arising from Ar transitions appear in both spectra, although many of these lines are obscured by

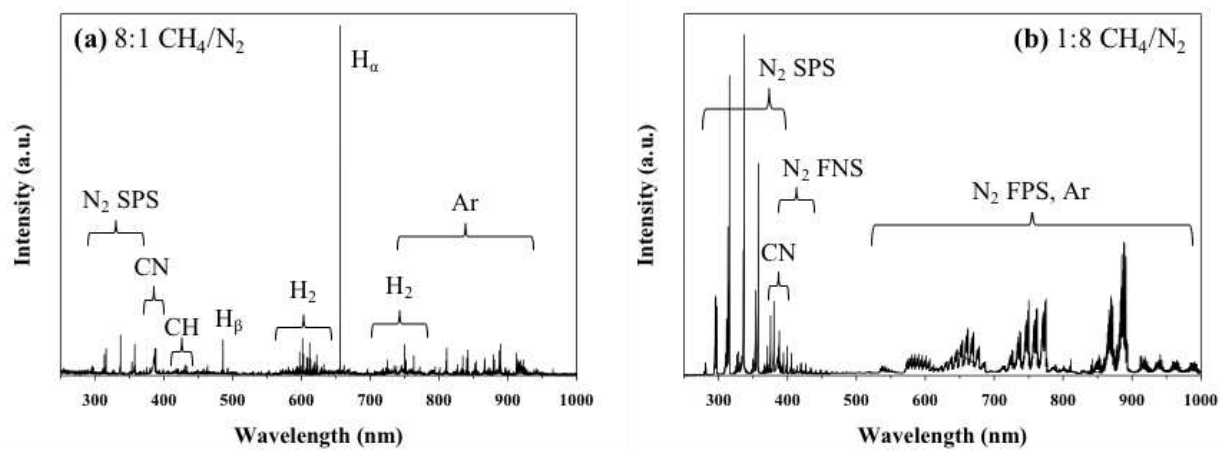


Figure 7.1. Raw OES spectra ($P = 125$ W) of a (a) 8:1 CH₄/N₂ plasma and a (b) 1:8 CH₄/N₂ plasma. Emission lines and bands attributed to the major emitting species are labeled.

the N₂ first positive system (FPS) ($B^3\Pi_g \rightarrow A^3\Sigma_u^+$) in the 1:8 CH₄/N₂ plasma (Figure 7.1b). Emission corresponding to H_α (656.2 nm), H_β (486.1 nm), and H₂ molecular bands centered at ~610 nm and ~740 nm is observed in the spectrum of the 8:1 CH₄/N₂ plasma system (Figure 7.1a). Emission bands for the CH $A^2\Delta \rightarrow X^2\Pi$ (431.1 nm) and the CN $B^2\Sigma^+ \rightarrow X^2\Sigma^+$ (388.3 nm) transitions are also observed. Although only the N₂ second positive system (SPS) ($C^3\Pi_u \rightarrow B^3\Pi_g$) is clearly seen in the spectrum of the 8:1 CH₄/N₂ ratio mixture, the N₂ FPS ($B^3\Pi_g \rightarrow A^3\Sigma_u^+$) and N₂⁺ first negative system (FNS) ($B^2\Sigma_u^+ \rightarrow X^2\Sigma_g^+$) are also observed in the spectrum for the 1:8 CH₄/N₂ system, Figure 7.1b. In addition to the N₂ molecular bands, CN emission is also noted in the 1:8 CH₄/N₂ system.

The emission spectra for a CH₄/N₂ plasma (Figure 7.1) can comprise different plasma species and display noticeable variations in species intensities depending on the feed gas ratio. Inert gas actinometry was used to determine how relative species densities (denoted here with brackets, e.g., “[CN]”) changed as a function of the precursor ratio. Depicted in Figure 7.2, relative densities were derived for CH (431.1 nm), CN (388.3 nm), H_α (656.2 nm), H₂ (601.1 nm), and N₂ (337.0 nm) at several feed gas ratios for a CH₄/N₂ plasma. As expected, the densities of species resulting primarily from CH₄ decomposition (CH, H_α, and H₂) decrease while [N₂] increases with a concomitant increase of N₂ fraction in the feed gas. [CN] initially increases with N₂ feed gas fraction before reaching a maximum density at a 1:1 CH₄/N₂ ratio. As the N₂ fraction becomes greater than the CH₄ fraction, a subsequent decrease in [CN] is observed. Notably, these data were collected at a 50 ms integration time with 150 averages per scan over the course of several minutes. Thus, these data provide us with an effectively steady-state snapshot of the plasma. These steady state concentrations provide us with valuable information regarding the gas-phase species in the plasma; however, TR-OES can be used to

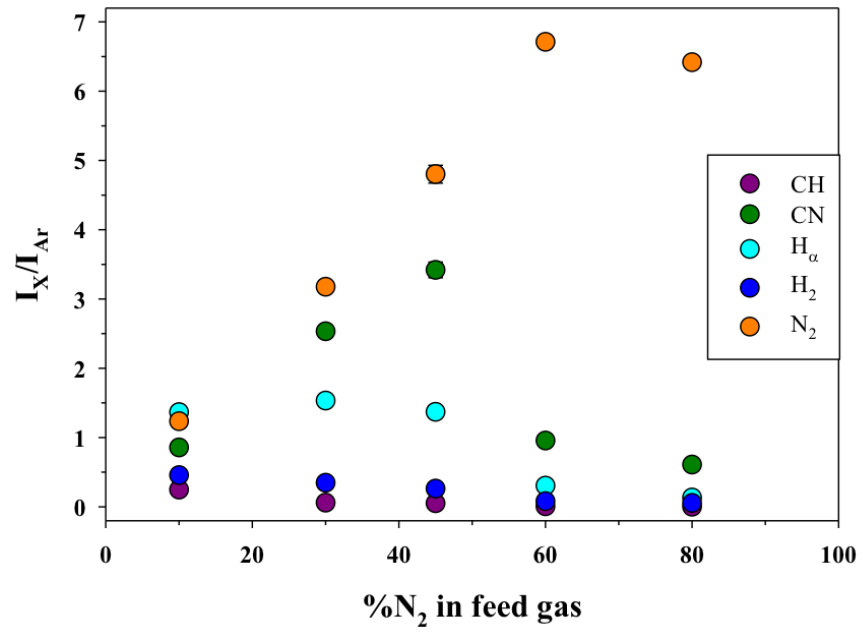


Figure 7.2. Relative densities of excited state species in CH₄/N₂ plasma as a function of %N₂ in the feed gas mixture ($P = 75$ W).

examine the temporal evolution of plasma species, yielding kinetic insight into possible mechanisms of species formation and destruction.

Figure 7.3 shows the intensity of CN emission as a function of time for each gas ratio explored. Notably, there are significant differences in the temporal profiles between each of the feed gas ratios. When the feed gas composition comprises mostly CH₄ (8:1 and 2:1 CH₄/N₂ ratios), only a rise in emission intensity to a steady state is observed. As more N₂ is added to the feed gas, however, the rise to maximum emission intensity is followed by a subsequent decay in intensity until a steady state is reached. Although a temporal decay for CN is observed at all powers in the 1:8 CH₄/N₂ system, the 1:1 and 1:2 CH₄/N₂ systems display a decomposition curve only at $P \geq 75$ W. By fitting the intensity curves with a first order exponential (e^{-kt}), we obtain information about the rates of formation (k_f) and destruction (k_d) for CN. Figure 7.4a shows CN k_f values as a function of %N₂ in the feed gas at $P = 25$ W, 75 W, 125 W. At low N₂ fraction (<50%), CN k_f ranges from $\sim 1.5 - 2.9$ s⁻¹ and does not appear to be dependent on P . As the percent N₂ in the feed gas increases ($\geq 50\%$), however, the observed CN kinetic trends change significantly. Specifically, CN k_f increases concomitantly with the percent N₂ and with P . At $\geq 50\%$ N₂ in the feed gas, CN k_f values range from $\sim 1.5 - 21.0$ s⁻¹, changing dramatically with plasma parameters. Notably, no CN k_f value is reported for $P = 25$ W in the 8:1 CH₄/N₂ plasma system because of low CN emission intensity. Likewise, at $P = 125$ W in the 1:8 CH₄/N₂ plasma, a fit for CN k_d could not be obtained because no formation curve was observable even at the fastest integration times used for these experiments (1.5 ms). CN k_d was also measured where decay curves were present, Figure 7.4b. Overall, CN k_d trends are similar to those for CN k_f as k_d also increases concomitantly with percent N₂ and with P , ranging from $\sim 2.9 - 15.4$ s⁻¹. All k_f and k_d values are listed in Table 7.1 for reference.

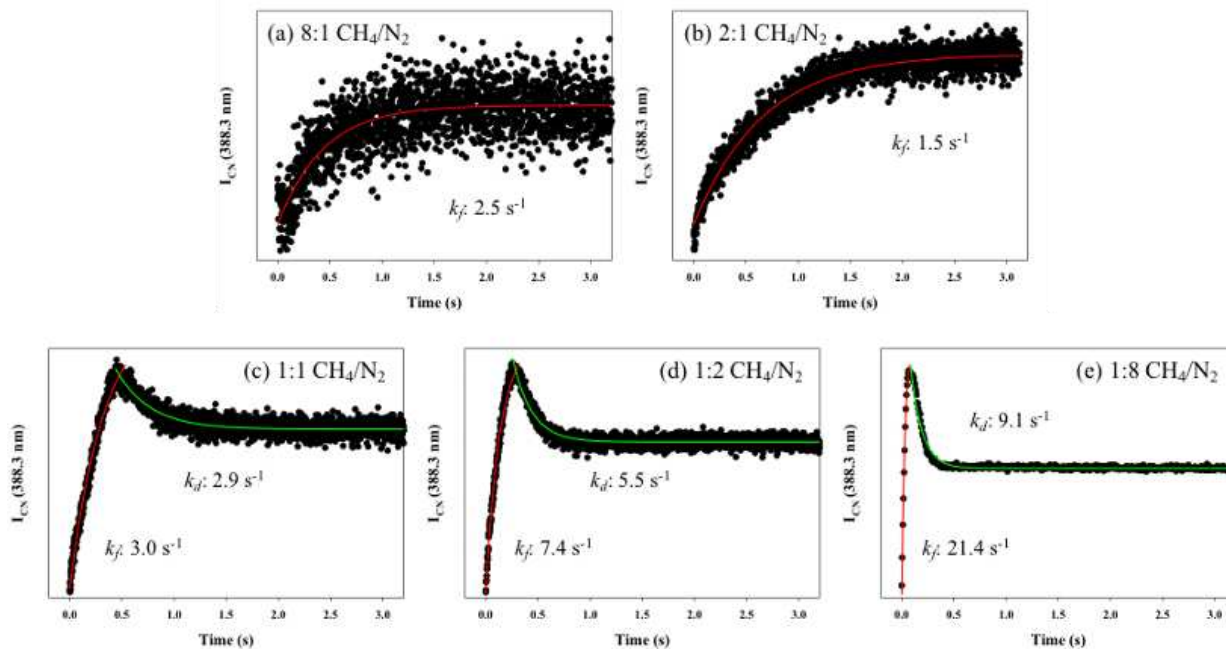


Figure 7.3. Intensity of CN emission plotted as a function of time ($P = 75 \text{ W}$) in (a) 8:1 CH_4/N_2 , (b) 2:1 CH_4/N_2 , (c) 1:1 CH_4/N_2 , (d) 1:2 CH_4/N_2 , and (e) 1:8 CH_4/N_2 plasmas. Rate constants of formation and destruction were determined by fitting a first order exponential to each portion of the curve (solid lines). Y-axes are intensities of the selected CN emission line in arbitrary units.

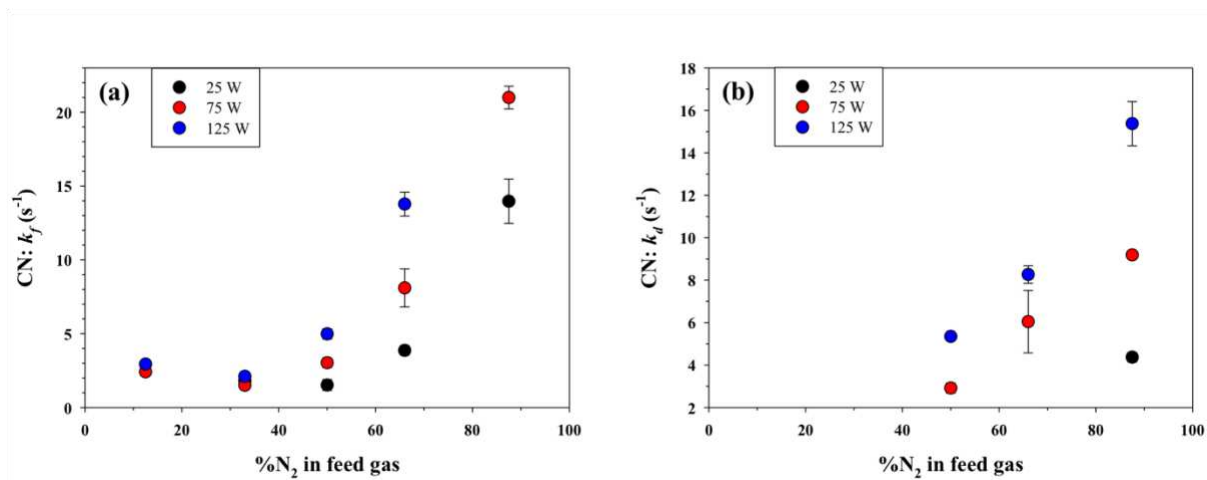


Figure 7.4. (a) CN k_f (s⁻¹) and (b) CN k_d (s⁻¹) values as a function of %N₂ in CH₄/N₂ plasmas at three applied rf powers (25 W, 75 W, and 125 W).

Table 7.1. Calculated k_f and k_d values for N₂ and CN.^{a,b}

8:1 CH ₄ /N ₂			
P (W)	N ₂ : k_f	CN: k_f	CN: k_d
25	—	—	—
75	—	2.4 (0.2)	—
125	—	2.9 (0.1)	—
2:1 CH ₄ /N ₂			
P (W)	N ₂ : k_f	CN: k_f	CN: k_d
25	—	1.8 (0.2)	—
75	—	1.5 (0.1)	—
125	—	2.1 (0.1)	—
1:1 CH ₄ /N ₂			
P (W)	N ₂ : k_f	CN: k_f	CN: k_d
25	1.7 (1.2)	1.5 (0.4)	—
75	2.0 (0.1)	3.0 (0.3)	2.9 (0.2)
125	3.0 (0.1)	5.0 (0.3)	5.4 (0.1)
1:2 CH ₄ /N ₂			
P (W)	N ₂ : k_f	CN: k_f	CN: k_d
25	1.1 (0.1)	3.9 (0.3)	—
75	3.0 (0.2)	8.1 (1.3)	6.0 (1.5)
125	4.1 (0.2)	13.8 (0.8)	8.3 (0.4)
1:8 CH ₄ /N ₂			
P (W)	N ₂ : k_f	CN: k_f	CN: k_d
25	2.1 (0.1)	14.0 (1.5)	4.4 (0.2)
75	10.0 (0.4)	21.0 (0.8)	9.2 (0.1)
125	14.9 (6.0)	—	15.4 (1.0)

^a Values in parentheses represent the standard deviation calculated from the mean of $n \geq 3$ trials.

Table 7.1 also lists k_f values for N_2 for feed gas conditions comprising $\geq 50\%$ N_2 . At low N_2 content ($< 50\%$), only a decay to steady state is observed (i.e. no formation curve was present) and destruction rates could not be reliably obtained from these data. Representative temporal profiles highlighting N_2 decay for low N_2 content plasmas are shown in Figures 7.5a and 7.5b. For the 1:1 and 1:2 CH_4/N_2 systems (Figures 7.5c and 7.5d, respectively), N_2 temporal emission profiles also show a clear destruction curve immediately following plasma ignition. Following the initial destruction curve, however, a formation curve to a steady state also occurs with these two feed gas ratios. Although an N_2 destruction curve is not observed in the 1:8 CH_4/N_2 plasma system, the first 1–2 data points immediately following plasma ignition were consistently elevated relative to the formation curve. We have previously observed and discussed this phenomenon in pulsed 100% Ar and 100% N_2 discharges, attributing it to “hot electrons” which tend to overshoot steady state values at the beginning of the active glow.⁴ Overall, N_2 k_f trends are similar to the those for CN k_f and k_d . N_2 k_f increases concomitantly with both P and % N_2 in the feed gas, and values range from $\sim 1.1 - 14.9$ s^{-1} across the parameter space. Evaluation of plasma kinetics can provide insight into plasma ignition and initial plasma processes; yet, steady-state energetics is also a critical component to a comprehensive evaluation of fundamental plasma processes.

As noted in Section 7.1, we also determined rotational and vibrational temperatures for several species in our plasma systems. All T_R and T_V values measured for diatomic gas-phase species in the CH_4/N_2 system are listed in Table 7.2 for reference. Figure 7.6a shows a representative N_2 emission spectrum for a 1:2 CH_4/N_2 plasma ($P = 75$ W) along with the corresponding Boltzmann plot used to determine $T_V(N_2)$ for that particular spectrum. As

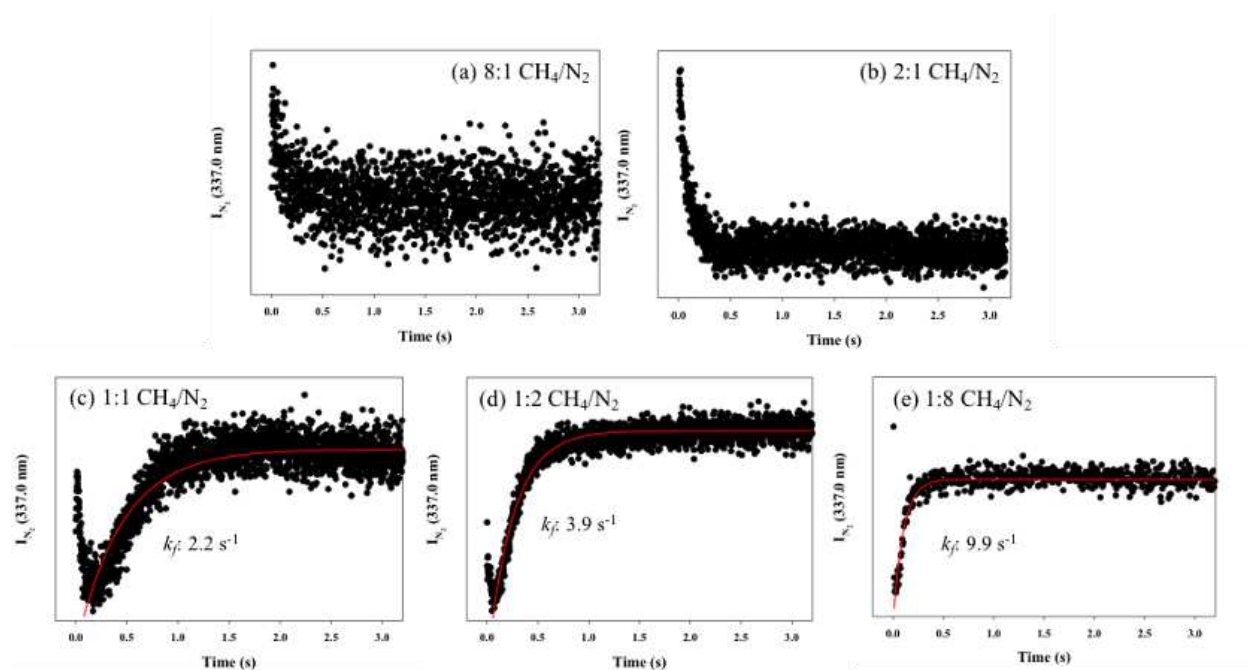


Figure 7.5. Intensity of N₂ emission plotted as a function of time ($P = 75$ W) in (a) 8:1 CH₄/N₂, (b) 2:1 CH₄/N₂, (c) 1:1 CH₄/N₂, (d) 1:2 CH₄/N₂, and (e) 1:8 CH₄/N₂ plasmas. Rate constants of formation and destruction were determined by fitting a first order exponential to each portion of the curve (solid lines). Y-axes are intensities of the selected N₂ emission line in arbitrary units.

Table 7.2. T_R (K) and T_V (K) values for CH₄/N₂ plasma systems.^{a,b}

8:1 CH ₄ /N ₂							
P (W)	T_R (CH)	T_V (CH)	T_R (CN)	T_V (CN)	T_R (H ₂)	T_R (N ₂)	T_V (N ₂)
25	1700 (10)	2830 (190)	1140 (10)	3200 (220)	700 (30)	320 (20)	2910 (250)
50	1640 (20)	2190 (10)	1180 (20)	3970 (80)	640 (30)	380 (20)	4700 (290)
75	1720 (30)	2170 (30)	1180 (20)	4160 (30)	600 (20)	280 (20)	5840 (380)
100	1600 (20)	2120 (30)	1180 (10)	4230 (20)	590 (10)	330 (20)	6600 (540)
125	1640 (30)	2230 (30)	1180 (10)	4230 (80)	540 (20)	320 (20)	6920 (530)
2:1 CH ₄ /N ₂							
P (W)	T_R (CH)	T_V (CH)	T_R (CN)	T_V (CN)	T_R (H ₂)	T_R (N ₂)	T_V (N ₂)
25	—	—	1080 (30)	4020 (30)	—	260 (20)	4420 (10)
50	—	—	1070 (10)	4570 (10)	—	270 (10)	5780 (20)
75	—	—	1030 (10)	4760 (20)	—	290 (10)	6910 (20)
100	—	—	990 (10)	4870 (10)	—	290 (10)	7680 (40)
125	—	—	990 (10)	4930 (10)	—	290 (10)	8240 (40)
1:1 CH ₄ /N ₂							
P (W)	T_R (CH)	T_V (CH)	T_R (CN)	T_V (CN)	T_R (H ₂)	T_R (N ₂)	T_V (N ₂)
25	—	—	950 (10)	4010 (50)	—	280 (10)	4400 (20)
50	—	—	930 (10)	4510 (20)	—	280 (10)	5670 (20)
75	—	—	860 (10)	4740 (20)	—	300 (10)	6440 (140)
100	—	—	870 (10)	4640 (20)	—	310 (10)	7120 (30)
125	—	—	920 (10)	4360 (180)	—	300 (10)	7560 (110)

1:2 CH ₄ /N ₂							
<i>P</i> (W)	<i>T_R</i> (CH)	<i>T_V</i> (CH)	<i>T_R</i> (CN)	<i>T_V</i> (CN)	<i>T_R</i> (H ₂)	<i>T_R</i> (N ₂)	<i>T_V</i> (N ₂)
25	—	—	870 (20)	3370 (100)	—	280 (10)	3660 (20)
50	—	—	820 (10)	3470 (20)	—	310 (30)	4470 (10)
75	—	—	810 (10)	3520 (40)	—	300 (10)	5040 (40)
100	—	—	800 (10)	3600 (20)	—	300 (10)	5340 (70)
125	—	—	790 (10)	3670 (30)	—	290 (10)	5470 (90)
1:8 CH ₄ /N ₂							
<i>P</i> (W)	<i>T_R</i> (CH)	<i>T_V</i> (CH)	<i>T_R</i> (CN)	<i>T_V</i> (CN)	<i>T_R</i> (H ₂)	<i>T_R</i> (N ₂)	<i>T_V</i> (N ₂)
25	—	—	880 (10)	3910 (20)	—	270 (10)	3030 (40)
50	—	—	1000 (30)	3770 (10)	—	290 (10)	3550 (10)
75	—	—	990 (10)	3800 (10)	—	300 (10)	4040 (20)
100	—	—	960 (10)	3900 (10)	—	290 (10)	4610 (40)
125	—	—	950 (10)	3910 (20)	—	300 (10)	5220 (50)

^a Values in parentheses represent the standard deviation calculated from the mean of $n \geq 3$ trials.

^b “—” represents conditions where species is not present above experimental noise.

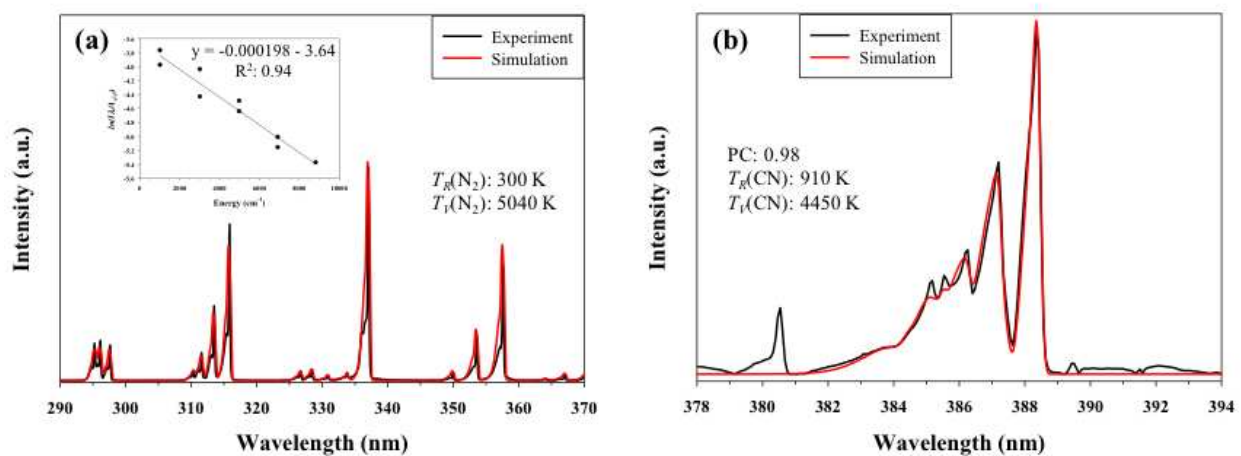


Figure 7.6. Representative emission spectra and simulated fits of the (a) $\text{N}_2 \text{C}^3\Pi_u \rightarrow \text{B}^3\Pi_g$ (1:2 CH_4/N_2 plasma, $P = 75 \text{ W}$) and (b) $\text{CN B}^2\Sigma^+ \rightarrow \text{X}^2\Sigma^+$ (1:1 CH_4/N_2 plasma, $P = 125 \text{ W}$) transitions. Inset in (a) is the corresponding Boltzmann plot of the N_2 vibrational distribution.

discussed in Chapter 2, $T_R(\text{N}_2)$ was determined from simulated fits of the experimental spectrum with SpecAir.¹³ Select $T_R(\text{N}_2)$ and $T_V(\text{N}_2)$ values as a function of %N₂ in the feed gas for a CH₄/N₂ plasma are displayed in Figures 7.7a and 7.7b, respectively. $T_R(\text{N}_2)$ values range from ~280 – 350 K with no clear dependence on P or feed gas composition. Previous studies from our lab have also reported similar $T_R(\text{N}_2)$ values in several feed gas systems (e.g., N₂, NO, N₂O, N₂/O₂).¹⁰⁻¹¹ In those studies, $T_R(\text{N}_2)$ remained independent of several plasma parameters (e.g., pressure, power, feed gas, catalyst presence), indicating that $T_R(\text{N}_2)$ efficiently thermalizes to approximately room temperature regardless of parameter conditions. In contrast, $T_V(\text{N}_2)$ clearly demonstrates dependence on both P and feed gas composition. Specifically, $T_V(\text{N}_2)$ generally increases as the CH₄ content in the CH₄/N₂ plasma also increases. $T_V(\text{N}_2)$ also increases as P increases at all the feed gas compositions explored, ranging from ~2910 K at $P = 25$ W to ~6920 K at $P = 125$ W in the 8:1 CH₄/N₂ system. A slight increase in $T_V(\text{N}_2)$ at each P is noted as the feed gas ratio is changed to 2:1 CH₄/N₂, and further increases in N₂ content results in a decrease in $T_V(\text{N}_2)$ at each P . Notably, $T_V(\text{N}_2)$ values are also nearly an order of magnitude greater than $T_R(\text{N}_2)$ values, suggesting rotational relaxation is more efficient than vibrational relaxation for N₂. Overall, $T_V(\text{N}_2)$ displays a wide value range (~2910 – 8940 K) for our studied parameter space, and can be compared to previously reported $T_V(\text{N}_2)$ values for a 100% N₂ plasma¹⁰⁻¹¹ in Figure 7.7b. Comparatively, $T_V(\text{N}_2)$ values in 100% N₂ plasmas ranged from ~2250 – 3550 K ($p = 150$ mTorr) and displayed both pressure and P dependences.

We also evaluated T_R and T_V for CN as functions of P and feed gas composition. Figure 7.6b shows a representative experimental emission spectrum and simulated fit (via LIFBASE¹⁴) for the CN B²Σ⁺ → X²Σ⁺ transition in a 1:1 CH₄/N₂ plasma ($P = 125$ W), along with the calculated $T_R(\text{CN})$, $T_V(\text{CN})$, and peak correlation (PC) values for that particular spectrum.

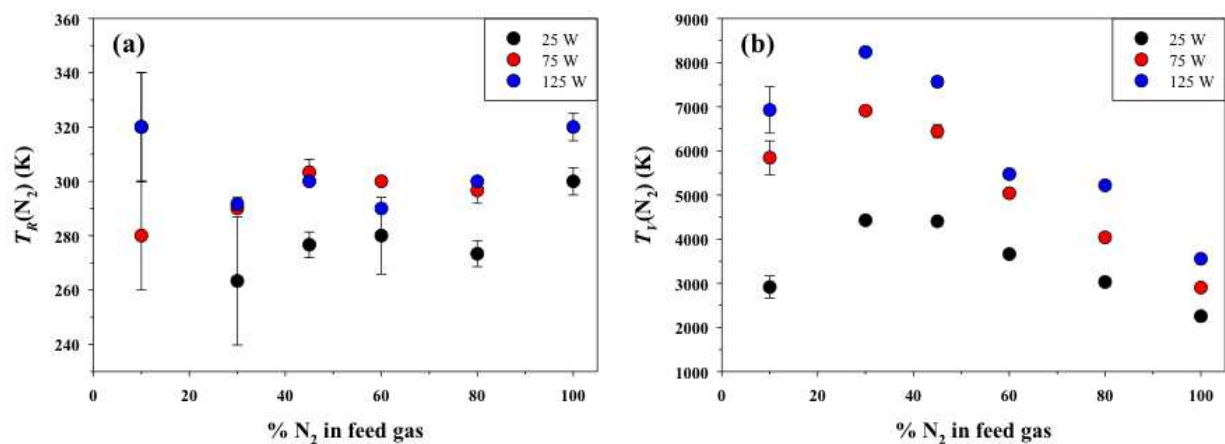


Figure 7.7. (a) $T_R(N_2)$ and (b) $T_V(N_2)$ values as a function of % N_2 in CH_4/N_2 plasmas at three applied rf powers (25 W, 75 W, and 125 W). The $T_R(N_2)$ and $T_V(N_2)$ values shown for a 100% N_2 plasma system were reported previously.¹⁰⁻¹¹

Notably, peak correlation values were ≥ 0.94 for each simulated spectrum at $P \geq 50$ W ($PC \geq 0.77$ for $P = 25$ W), indicating good agreement between the experimental data and simulation. Figure 7.8a shows that $T_R(\text{CN})$ values for our CH_4/N_2 plasmas range from $\sim 790 - 1180$ K over our parameter space. Although $T_R(\text{CN})$ values do not appear to have a strong P dependence, $T_R(\text{CN})$ generally decreases as N_2 content in the feed gas increases up to a 1:2 CH_4/N_2 ratio. This is followed by a slight increase in $T_R(\text{CN})$ in the 1:8 CH_4/N_2 plasma system. As shown in Figure 7.8b, $T_V(\text{CN})$ ranges from ~ 3200 to 4930 K and does not appear to have either a strong P or feed gas composition dependence over the studied parameter space.

$T_R(\text{CH}, \text{H}_2)$ and $T_V(\text{CH})$ values calculated for the 8:1 CH_4/N_2 ratio system are listed in Table 7.2, which also contains $T_R(\text{CN}, \text{N}_2)$ and $T_V(\text{CN}, \text{N}_2)$ values. At N_2 contents $> 8:1$ CH_4/N_2 , CH was either present in very small amounts or not observed at all and several H_2 rotational transition lines were obscured by emission from the N_2 FPS. Thus, $T_R(\text{CH}, \text{H}_2)$ and $T_V(\text{CH})$ values were not calculated for other gas precursor ratios. $T_R(\text{H}_2)$ values in the 8:1 CH_4/N_2 plasma system ranged from ~ 540 to 700 K and decreases as P increases. These values and trends are nearly identical to those reported for $T_R(\text{H}_2)$ in a 100% CH_4 plasma.¹⁵ Conversely, $T_R(\text{CH})$ values are ~ 300 K lower than those reported for a 100% CH_4 plasma.¹² Here, $T_R(\text{CH})$ values range from ~ 1600 to 1720 K for an 8:1 CH_4/N_2 plasma system, with $T_V(\text{CH})$ values significantly higher, ranging from ~ 2120 to 2830 K. Comparatively, $T_V(\text{CH})$ values measured in a 100% CH_4 plasma ($p = 150$ mTorr) lie a bit higher, ranging between ~ 2610 and 3310 K.¹² Both $T_R(\text{CH})$ and $T_V(\text{CH})$ values reported herein display no clear trends with respect to P .

Figure 7.9 shows rotational and vibrational temperatures as a function of P for each plasma species examined in the 8:1 CH_4/N_2 system. Notably, these data exhibit a wide range of values for T_R within our system, Figure 7.9a, ranging from ~ 300 K for $\text{N}_2 \text{C}^3\Pi_u \rightarrow \text{B}^3\Pi_g$ to

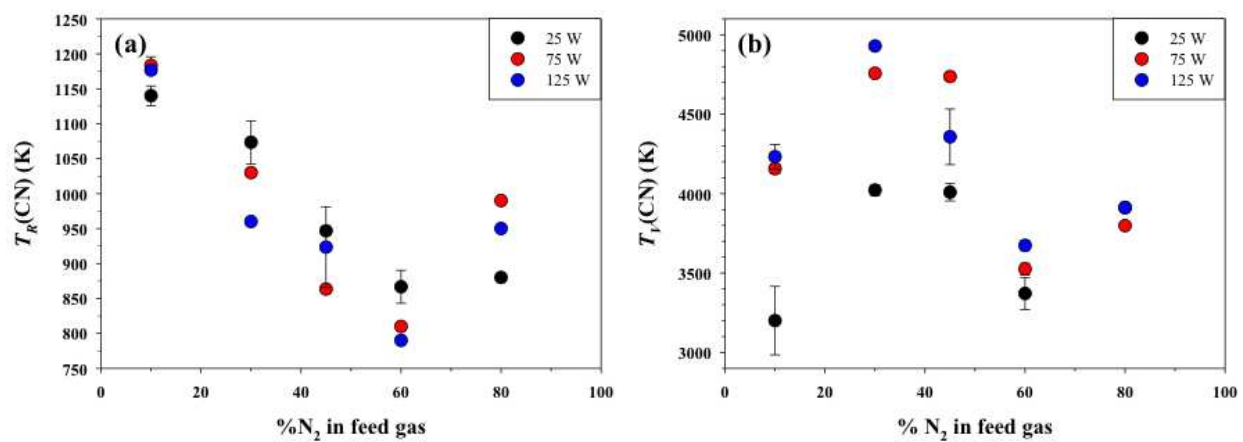


Figure 7.8. (a) $T_R(CN)$ and (b) $T_V(CN)$ values as a function of % N_2 in the feed gas at three applied rf powers (25 W, 75 W, and 125 W).

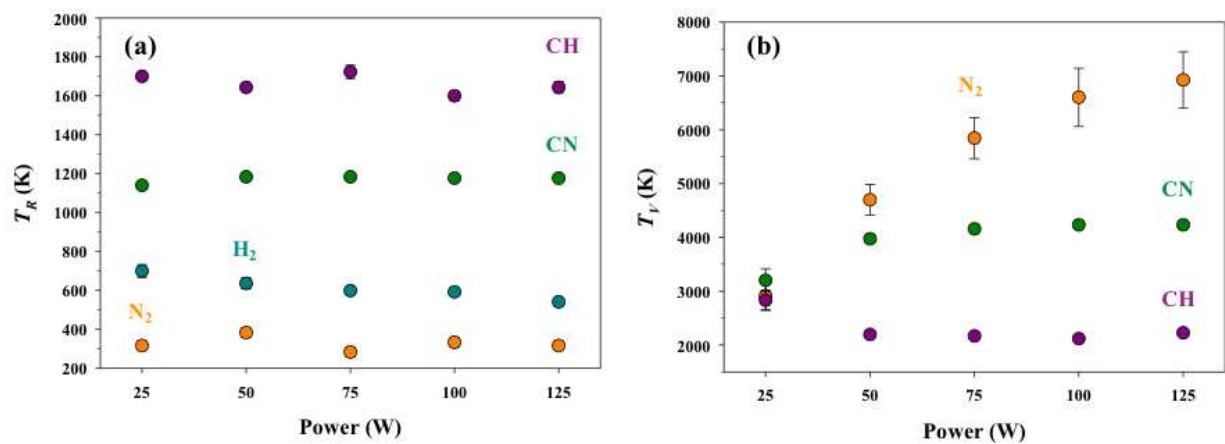


Figure 7.9. (a) T_R and (b) T_V for multiple species plotted as a function of applied rf power in an 8:1 CH₄/N₂ plasma system.

nearly 1750 K for $\text{CH } A^2\Delta \rightarrow X^2\Pi$. Values for $T_R(\text{H}_2)$ and $T_R(\text{CN})$ lie between these extremes at ~ 620 K and ~ 1180 K, respectively. T_V values exhibit much higher values, ranging from ~ 2100 K for $\text{CH } A^2\Delta \rightarrow X^2\Pi$ to ~ 6920 K for $\text{N}_2 \text{ C}^3\Pi_u \rightarrow \text{B}^3\Pi_g$, Figure 7.9b. The vast differences in T_R and T_V values of different species indicate a thermal non-equilibrium and may be inherently related to a combination of species formation mechanisms, excited state lifetimes, or other heating mechanisms (e.g., Franck-Condon heating, charge exchange).¹⁶ These ideas will be explored further below in Section 7.3.

b. *CH₄/H₂O plasma system.* Raw OES spectra in Figure 7.10 show the emitting excited state species in $\text{CH}_4/\text{H}_2\text{O}$ plasmas at two different feed gas ratios. Notably, peaks arising from Ar transitions appear in both spectra. In the 8:1 $\text{CH}_4/\text{H}_2\text{O}$ plasma, species resulting from CH_4 decomposition (i.e., CH, atomic hydrogen, H_2) dominate the spectrum, Figure 7.10a. Additionally, emission from $\text{CO } A^1\Pi \rightarrow X^1\Sigma$ and $\text{OH } A^2\Sigma^+ \rightarrow X^2\Pi$ also appear in the spectrum for this feed gas ratio. As the feed gas composition shifts to a majority H_2O (1:8 $\text{CH}_4/\text{H}_2\text{O}$, Figure 7.10b), emission peaks from $\text{OH } A^2\Sigma^+ \rightarrow X^2\Pi$, atomic O, and the hydrogen Balmer series clearly emerge.

Inert gas actinometry allows further evaluation of how species densities change as a function of feed gas composition, Figure 7.11. As expected, $[\text{OH}]$ and $[\text{O}]$ increase concomitantly with H_2O feed gas fraction, whereas both $[\text{CH}]$ and $[\text{H}_2]$ decrease. The $[\text{H}_\alpha]$ (shown in the inset of Figure 11) increases from ~ 2.3 in an 8:1 $\text{CH}_4/\text{H}_2\text{O}$ plasma to a value of ~ 25.0 in the 1:8 $\text{CH}_4/\text{H}_2\text{O}$ system. For $[\text{CO}]$ we observe a trend similar to $[\text{CN}]$ in the CH_4/N_2 system in that $[\text{CO}]$ increases to a maximum density at 1:1 $\text{CH}_4/\text{H}_2\text{O}$ and then decreases as the H_2O fraction continues to increase. Similar to formation of CN in the CH_4/N_2 system, CO must be formed from a bimolecular collision between the two precursor gases (CH_4 and H_2O) or their

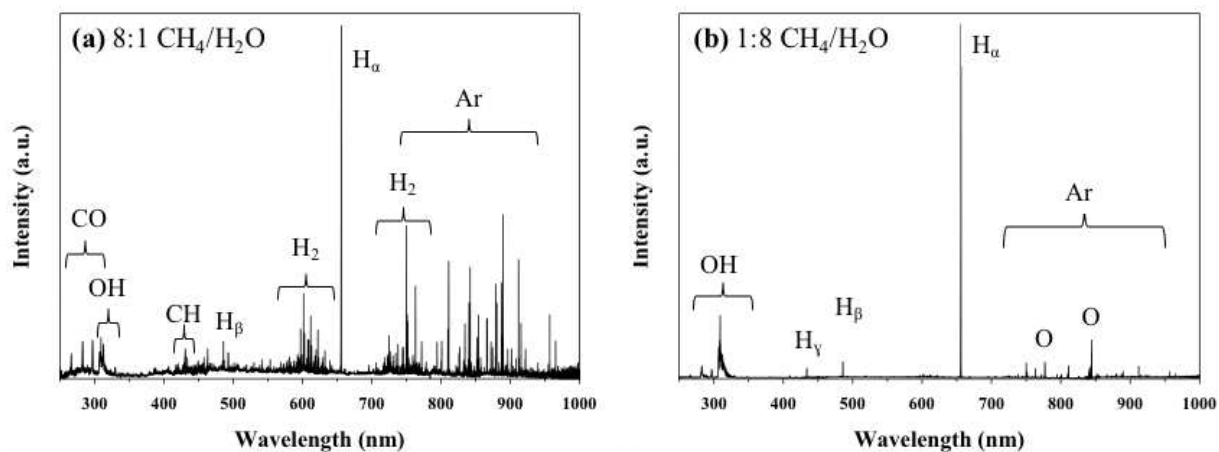


Figure 7.10. Raw OES spectra ($P = 125$ W) of a (a) 8:1 CH₄/H₂O plasma and a (b) 1:8 CH₄/H₂O plasma. Emission lines and bands attributed to the major emitting species are labeled.

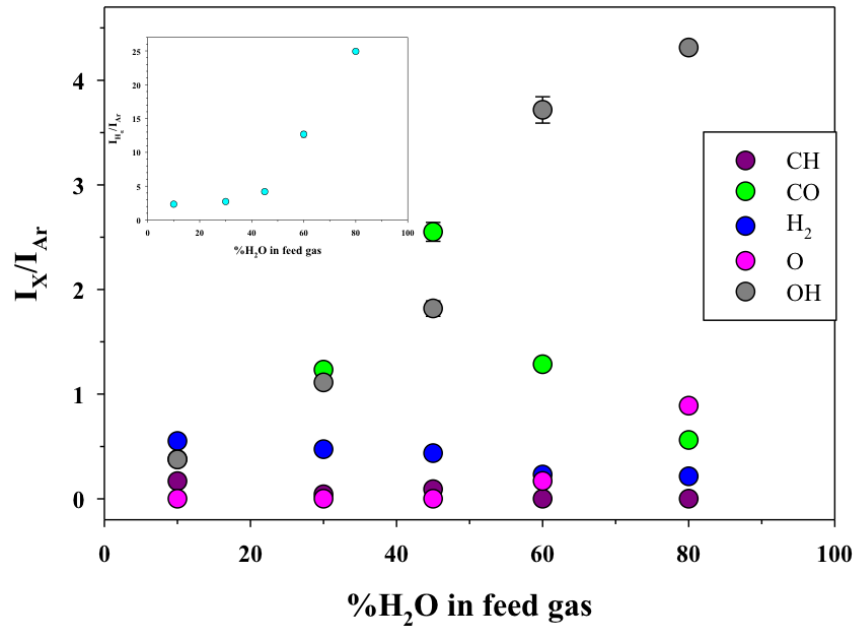


Figure 7.11. Relative densities of excited state species in CH₄/H₂O plasmas as a function of %H₂O in the feed gas ($P = 125$ W).

decomposition products; thus, decreases in the relative amounts of a precursor gas may significantly hinder formation of species such as CO or CN.

TR-OES provides insight into formation and destruction rates of CO and OH, in CH₄/H₂O plasmas. Figure 7.12a shows a temporal emission profile for CO (296.9 nm) with a clear rise to a steady state emission intensity. Unlike the CN or N₂ emission profiles in Figures 7.3 and 7.5, only a formation profile was present for CO throughout the entire parameter range studied (i.e. no decay curve was observed). The data plotted in Figure 7.12b show that CO k_f values do not change significantly across the parameter space and do not depend on the feed gas composition. For feed gas ratios comprising $\leq 50\%$ H₂O, CO k_f increases slightly with an increase in P . Overall, CO k_f values range from $\sim 1.6 - 2.5 \text{ s}^{-1}$, Table 7.3.

Table 7.3 also lists OH k_d values, with values ranging from $\sim 1.6 - 14.6 \text{ s}^{-1}$. Notably, only a decay curve is present for OH emission at each parameter (i.e. no formation curves observed), as depicted by the representative OH decay curve in Figure 7.13a. All measured OH k_d values are plotted in Figure 7.13b. In general, OH k_d values decrease with increasing H₂O feed gas fraction. At low H₂O fractions, OH k_d strongly increases with increasing P , whereas at $> 50\%$ H₂O in the feed gas, no feed gas or P dependence is observed and OH k_d values are $\sim 2.0 \text{ s}^{-1}$.

Rotational and vibrational temperatures were also measured for several of the excited state species present in the CH₄/H₂O system. Figure 7.14a shows a representative emission spectrum for the OH A²Σ⁺ → X²Π transition and corresponding simulated fit and calculated $T_R(\text{OH})$, $T_V(\text{OH})$, and PC values (1:2 CH₄/H₂O; $P = 25 \text{ W}$). PC values were ≥ 0.80 for each simulated spectrum of OH, indicating fair agreement between experimental data and simulation. Table 7.4 lists all $T_R(\text{OH})$ and $T_V(\text{OH})$ values and Figure 7.14b shows select $T_R(\text{OH})$ and $T_V(\text{OH})$ data as a function of %H₂O in CH₄/H₂O plasmas. $T_V(\text{OH})$ values are elevated compared to

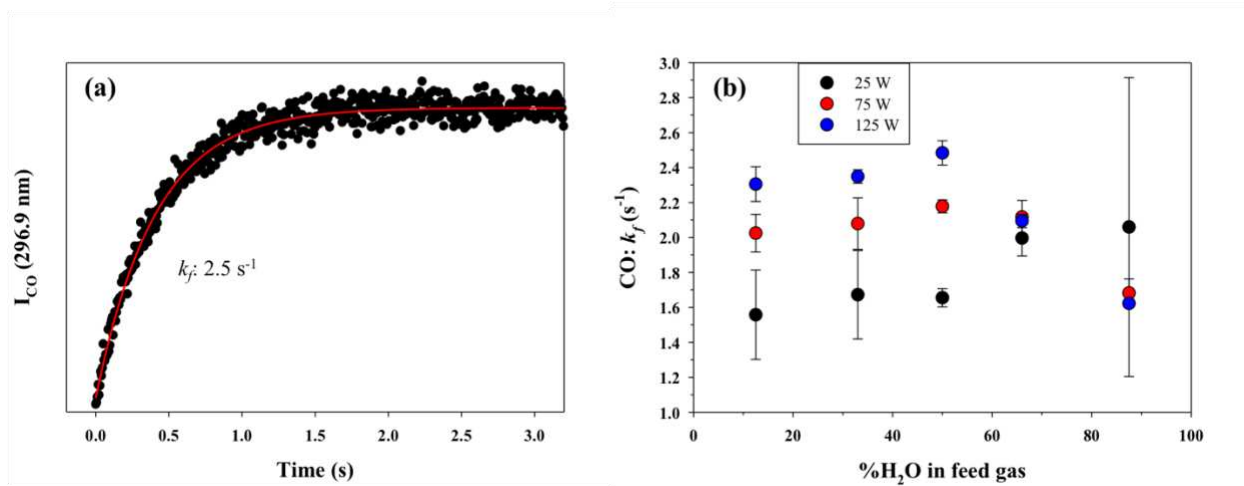


Figure 7.12. (a) Intensity of CO emission as a function of time (1:1 $\text{CH}_4/\text{H}_2\text{O}$, $P = 125$ W); and (b) CO k_f (s^{-1}) as a function of % H_2O in $\text{CH}_4/\text{H}_2\text{O}$ plasmas at three applied rf powers (25 W, 75 W, and 125 W).

Table 7.3. Calculated CO k_f and OH k_d values.^{a,b}

8:1 CH ₄ /H ₂ O		
<i>P</i> (W)	CO: k_f	OH: k_d
25	1.6 (0.3)	6.0 (1.3)
75	2.0 (0.1)	14.6 (0.7)
125	2.3 (0.1)	—
2:1 CH ₄ /H ₂ O		
<i>P</i> (W)	CO: k_f	OH: k_d
25	1.7 (0.3)	3.0 (0.3)
75	2.1 (0.1)	6.4 (0.1)
125	2.3 (0.1)	9.5 (0.7)
1:1 CH ₄ /H ₂ O		
<i>P</i> (W)	CO: k_f	OH: k_d
25	1.7 (0.1)	1.9 (0.1)
75	2.2 (0.1)	2.8 (0.1)
125	2.5 (0.1)	3.2 (0.1)
1:2 CH ₄ /H ₂ O		
<i>P</i> (W)	CO: k_f	OH: k_d
25	2.0 (0.1)	1.9 (0.4)
75	2.1 (0.1)	2.2 (0.1)
125	2.1 (0.1)	2.5 (0.1)
1:8 CH ₄ /H ₂ O		
<i>P</i> (W)	CO: k_f	OH: k_d
25	2.5 (0.9)	1.6 (0.2)
75	1.7 (0.1)	1.9 (0.1)
125	1.6 (0.1)	2.3 (0.1)

^a Values in parentheses represent the standard deviation calculated from the mean of $n \geq 3$ trials.

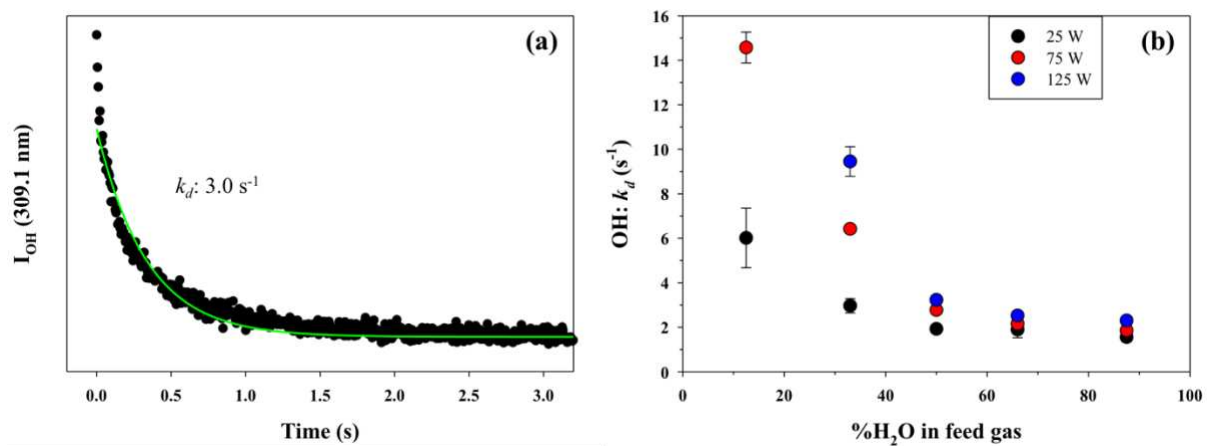


Figure 7.13. (a) Intensity of OH emission as a function of time (1:1 $\text{CH}_4/\text{H}_2\text{O}$, $P = 125 \text{ W}$) and (b) OH $k_d \text{ (s}^{-1}\text{)}$ as a function of $\% \text{H}_2\text{O}$ in $\text{CH}_4/\text{H}_2\text{O}$ plasmas at three applied rf powers (25 W, 75 W, and 125 W).

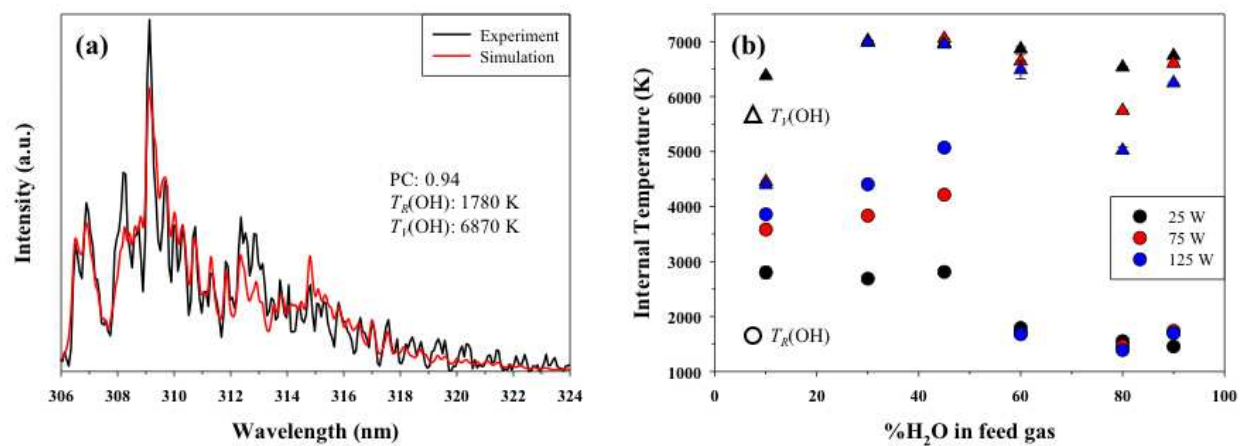


Figure 7.14. (a) Representative emission spectrum and simulated fit of OH A²Σ⁺ → X²Π (1:2 CH₄/H₂O plasma, P = 25 W) and (b) T_R(OH) (circles) and T_V(OH) (triangles) as a function of %H₂O in CH₄/H₂O plasmas at three applied rf powers (25 W, 75 W, and 125 W).

Table 7.4. T_R (K) and T_V (K) values for CH₄/H₂O plasma systems.^{a,b}

8:1 CH ₄ /H ₂ O					
P (W)	T_R (CH)	T_V (CH)	T_R (H ₂)	T_R (OH)	T_V (OH)
25	1480 (30)	2250 (340)	680 (10)	2800 (100)	6380 (10)
50	1610 (60)	2440 (120)	640 (10)	3250 (170)	4520 (20)
75	1500 (20)	2400 (290)	630 (10)	3580 (10)	4450 (20)
100	1580 (10)	2510 (130)	620 (10)	3780 (130)	4440 (20)
125	1540 (60)	2430 (210)	620 (10)	3860 (70)	4400 (10)
2:1 CH ₄ /H ₂ O					
P (W)	T_R (CH)	T_V (CH)	T_R (H ₂)	T_R (OH)	T_V (OH)
25	—	—	—	2690 (40)	7020 (10)
50	—	—	—	3300 (10)	6980 (10)
75	—	—	—	3830 (10)	6980 (20)
100	—	—	—	4190 (10)	7020 (10)
125	—	—	—	4400 (30)	6990 (20)
1:1 CH ₄ /H ₂ O					
P (W)	T_R (CH)	T_V (CH)	T_R (H ₂)	T_R (OH)	T_V (OH)
25	—	—	—	2810 (70)	6970 (20)
50	—	—	—	3550 (40)	7000 (30)
75	—	—	—	4210 (10)	7050 (10)
100	—	—	—	4770 (50)	6910 (20)
125	—	—	—	5070 (10)	6950 (10)

1:2 CH ₄ /H ₂ O					
<i>P</i> (W)	<i>T_R</i> (CH)	<i>T_V</i> (CH)	<i>T_R</i> (H ₂)	<i>T_R</i> (OH)	<i>T_V</i> (OH)
25	—	—	—	1790 (10)	6870 (40)
50	—	—	—	1700 (10)	6790 (10)
75	—	—	—	1690 (10)	6640 (130)
100	—	—	—	1660 (10)	6620 (30)
125	—	—	—	1680 (40)	6480 (160)
1:8 CH ₄ /H ₂ O					
<i>P</i> (W)	<i>T_R</i> (CH)	<i>T_V</i> (CH)	<i>T_R</i> (H ₂)	<i>T_R</i> (OH)	<i>T_V</i> (OH)
25	—	—	—	1550 (10)	6530 (10)
50	—	—	—	1460 (10)	6160 (60)
75	—	—	—	1460 (10)	5740 (10)
100	—	—	—	1430 (10)	5870 (200)
125	—	—	—	1390 (10)	5020 (60)
H ₂ O					
<i>P</i> (W)	<i>T_R</i> (CH)	<i>T_V</i> (CH)	<i>T_R</i> (H ₂)	<i>T_R</i> (OH)	<i>T_V</i> (OH)
25	—	—	—	1450 (10)	6740 (10)
50	—	—	—	1610 (10)	6530 (90)
75	—	—	—	1740 (30)	6600 (20)
100	—	—	—	1650 (40)	6190 (10)
125	—	—	—	1690 (20)	6240 (10)

^a Values in parentheses represent the standard deviation calculated from the mean of $n \geq 3$ trials.

^b “—” represents conditions where species is not present above experimental noise.

$T_R(\text{OH})$, exhibiting different levels of thermalization between $T_R(\text{OH})$ and $T_V(\text{OH})$, depending on feed gas composition. For example, $T_V(\text{OH})$ values for the 8:1 $\text{CH}_4/\text{H}_2\text{O}$ system are generally lower than the other feed gas compositions, except at $P = 25$ W. Overall, $T_V(\text{OH})$ values range from $\sim 4440 - 7050$ K and display little dependence on P or feed gas composition. Nevertheless, $T_V(\text{OH})$ values for the 1:8 $\text{CH}_4/\text{H}_2\text{O}$ plasma appear to display some P dependence, as $T_V(\text{OH})$ decreases with increasing P . Moreover, $T_R(\text{OH})$ values also display interesting trends with respect to feed gas composition. At high H_2O fraction ($> \sim 60\%$), $T_R(\text{OH}) = \sim 1390 - 1790$ K and remains relatively constant with P and feed gas. Conversely, $T_R(\text{OH})$ rises to $\sim 2690 - 5070$ K and exhibits a P dependence in feed gas compositions comprising $\leq 50\%$ H_2O . The striking differences in $T_R(\text{OH})$ values and trends suggest the possibility of different formation mechanisms based on the feed gas composition, discussed further in Section 7.3.

$T_R(\text{CH}, \text{H}_2)$ and $T_V(\text{CH})$ values were calculated for the 8:1 $\text{CH}_4/\text{H}_2\text{O}$ ratio system, Table 7.4. At H_2O content greater than the 8:1 $\text{CH}_4/\text{H}_2\text{O}$ ratio, both CH and H_2 were either present in very small amounts or not observed at all. As such, $T_R(\text{CH}, \text{H}_2)$ and $T_V(\text{CH})$ values were not calculated for these gas ratios. $T_R(\text{H}_2)$ values in the 8:1 $\text{CH}_4/\text{H}_2\text{O}$ plasma system ranged from $\sim 620 - 680$ K and decrease as P increases. Overall, these values and trends are similar to those reported for $T_R(\text{H}_2)$ in a 100% CH_4 plasma¹² and the 8:1 CH_4/N_2 system described above. Conversely, $T_R(\text{CH})$ values range from $\sim 1480 - 1610$ K and are slightly lower than those reported in the 8:1 CH_4/N_2 plasma (Table 7.2). $T_V(\text{CH})$ values, however, generally align with those reported in the CH_4/N_2 system, ranging from $\sim 2250 - 2510$ K. Both $T_R(\text{CH})$ and $T_V(\text{CH})$ values reported herein display no clear trends with respect to P . Similar to the Figure 7.9 data, rotational and vibrational temperatures in the $\text{CH}_4/\text{H}_2\text{O}$ system also exhibit a wide range of values. Differences in T_R and T_V values are discussed in detail in Section 7.3.

7.3 Discussion

PAC can be a viable pollution remediation tool; however, the applicability of this technology is inherently hindered by a vast data gap in fundamental, gas-phase chemistry and physics. Examination of kinetic and energetic processes occurring in the gas-phase can provide significant insight into molecule formation mechanisms, decomposition pathways, and the overall plasma chemistry. Importantly, it is essential to simultaneously examine multiple plasma species as different molecules within the same plasma system may exhibit vastly different internal temperatures. One additional consideration is a single plasma species can be produced via different mechanisms (e.g., direct impact excitation, decomposition, recombination, among others), which may result in very different energy partitioning for that species as functions of different plasma parameters. Here, we evaluated kinetic and energetic trends of several plasma species within two environmentally relevant mixed gas plasma systems, CH_4/N_2 and $\text{CH}_4/\text{H}_2\text{O}$.

a. CH₄/N₂ plasma system. Raw OES spectra (Figure 7.1) and actinometry data (Figure 7.2) for the CH_4/N_2 system demonstrate several excited state species are produced with relative densities highly dependent on the feed gas ratio. Over the past several decades, CH_4/N_2 plasmas have been widely employed for production of *a*-C:H:N films.¹⁷⁻²⁰ As such, several previous studies investigated production mechanisms for gas phase species and film precursors in these systems using OES.^{18, 21-23} In particular, CH radicals were identified as an important film growth precursor because they present three “dangling bonds” when incorporated into a growing film and consequently, display a high sticking coefficient.¹⁸ Thus, several studies focused particularly on CH contributions to materials deposited by CH_4/N_2 plasmas.^{18, 20} In CH_4 -

based plasmas, CH ($A^2\Delta$) is hypothesized to form mainly via a dissociative excitation process, Reaction 7.1,²⁴



Additionally, excited nitrogen species promote CH₄ dissociation, resulting in the production of CH radicals over CH₃ radicals.²⁵ OES measurements made over a range of pressure conditions demonstrated that addition of nitrogen to a constant CH₄ flow resulted in enhanced emission of CH and CN.^{18, 21} In our systems, an increase in the N₂ fraction is simultaneously associated with a decrease in CH₄. Thus, we observe a decrease in [CH], even if N₂ enhances CH formation. Similarly, the observed decreases in [H_α] and [H₂] with an increase in N₂ content are also expected as these species arise primarily from CH₄ decomposition.

The actinometry trends for CN, however, are quite different from the other species in the system. Although some studies have reported a similar [CN] maximum in a 1:1 CH₄/N₂ mixture followed by a decrease in [CN] as the N₂ fraction further increases,¹⁸ others have shown [CN] increases to a maximum at ~50% N₂ and remains stable with increasing N₂ until the feed gas comprises ~90% N₂.^{21, 26} Because CN must be formed via some bimolecular recombination process from the two precursors in our system, we suspect that the rise of [CN] with nitrogen content up to 50% and subsequent decrease at nitrogen contents >50% may be driven by the amount of nitrogen- and carbon-containing precursors available. Thus, a decrease in either of the precursors will result in an overall decrease in [CN].

In a low pressure (100 mTorr) rf CH₄/N₂ plasma, Clay *et al.* also observed both a decrease in the CH emission intensity and an increase in the CN emission intensity as the N₂/CH₄ ratio approached ~0.5.²¹ Yet as the N₂/CH₄ ratio was increased to 2, the CN intensity remained stable at the maximum. The authors suggest the increase in reactive nitrogen species in their

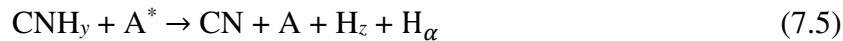
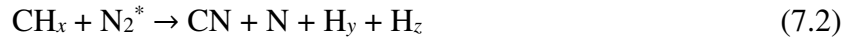
system results in a reduction of the molecular $C_xH_y^*$ species necessary for film formation. Consequently, a decrease in CH is observed while the CN emission peaks develop.²¹ Importantly, Clay *et al.* also analyzed *a*-C:H:N film growth rates, noting a decrease in film growth rate with an increase in the N_2/CH_4 ratio, providing key insight into how the gas phase species may participate in film growth.²¹ We did not perform any film analysis here; thus, future investigations should include film analyses or analysis of catalyst characteristics and plasma-surface interactions for PAC studies to provide further insight into probable mechanistic processes.

OES is a powerful diagnostic tool that provides not only species identification and species density trends, but also temporal emission data (TR-OES), which provides insight into formation and destruction processes. Chatei *et al.* examined temporal concentration trends of CN species using OES to elucidate contributions of gas phase and plasma-surface reactions for production of CN.²⁷ Their results demonstrate that a cut off of N_2 flow in $CH_4/CO_2/N_2$ plasmas results in an immediate sharp decrease of [CN] to zero within 2 minutes, indicating N_2 flow is essential to CN production. Notably, film growth continues from the still flowing CH_4 precursor and consequently, CN can no longer be removed from the surface as the available nitrogen is buried below the *a*-C:H film continuing to be formed. Conversely, when CH_4 flow is cut off, [CN] decreases sharply at first but then stabilizes. Thus, CN formation cannot be explained exclusively by gas-phase reactions. To further explore this observation, the authors removed their substrate holder from the discharge, observing that [CN] decreased sharply during the two minutes immediately following cut off of CH_4 flow. A slower decrease of [CN] follows until approximately 10 minutes post CH_4 flow cut off when all solid carbon in the reactor is eliminated and [CN] vanishes to zero. This study indicates that reactions involving nitrogen

species are essential to formation of CN as are plasma-surface interactions. Similarly, in our systems, when the glass reactor walls are coated with *a*-C:N:H films, we observe CN emission with a 100% N₂ plasma.²⁶ The Fisher group has also previously noted, however, that plasma-film interactions are not the only contributor to the CN production as stronger CN emissions are observed with the addition of a hydrocarbon precursor (e.g., CH₄, C₂H₂) to a N₂ plasma.²⁶

Our TR-OES studies of CN and N₂ display interesting trends, most notably, their respective temporal profiles (Figures 7.3 and 7.5, respectively) contain nearly opposite behaviors. For example, in the 8:1 and 2:1 CH₄/N₂ systems, a decay in N₂ intensity and a simultaneous rise in CN intensity are observed. In the 1:1 and 2:1 CH₄/N₂ systems, a quick initial decay in N₂ intensity is followed by a rise to a steady state intensity. Conversely, CN intensity first rises to a maximum before decaying to steady state. Finally, in the 1:8 CH₄/N₂ system, we observe no clear destruction curve for N₂ (i.e. only a formation curve is present). Although we note both a formation and destruction curve for CN with this gas ratio, CN k_f values are much higher than those found with other gas ratios. Additionally, we could not obtain a CN k_f value at $P = 125$ W because no formation curve was observed at the integration time used for these experiments. Indeed, several studies have indicated that CN formation is primarily controlled by the concentration of excited gas-phase nitrogen species because of their high activation energy (>14 eV).²¹ In particular, CN is formed from the reaction of these nitrogen species with carbon-containing species, with reaction control arising primarily from the concentration of excited N₂. Thus, production of CN in our systems may be directly related to activated nitrogen species which allow CN to form more rapidly, resulting in the increase in CN k_f with both increased P and nitrogen content in the feed (Figure 7.4, Table 7.1).

Energy partitioning data can further elucidate the chemical reactions that may occur in our plasmas. $T_R(\text{CN})$ data shown in Figure 7.8 generally decrease as the nitrogen content increases to ~60%. This is followed by a slight increase in $T_R(\text{CN})$ in the 1:8 CH_4/N_2 system except at $P = 25$ W where $T_R(\text{CN})$ values are within error of each other. The >300 K difference in $T_R(\text{CN})$ between the 8:1 CH_4/N_2 and 1:2 CH_4/N_2 plasma systems suggests that different excitation mechanisms may be occurring in the different feed gas ratios. Hu *et al.* hypothesize that CN radical formation in CH_4/N_2 discharges are typically the result of the mechanistic processes described in gas-phase Reactions 7.2 – 7.5.²³



Here, $x + y = z$ (Reaction 7.2 and 7.4), $y = z + \alpha$ (Reaction 7.5) and A^* represents excited state N, N_2 , or CH_x . In Reactions 7.2 and 7.3, CN radicals are directly formed from reaction with other species (e.g., CH_x , N_2 , N). Reactions 7.4 and 7.5 describe a two-step process including the formation of an intermediate compound containing C-N bonding which then yields CN on further reaction with activated plasma species. From Reactions 7.2 – 7.5, CN ($\text{B}^2\Sigma^+$) may be formed either via dissociative excitation or electron impact excitation from the ground state. As noted above, plasma-film interactions can also play a significant role in CN formation.²⁶⁻²⁷ Both ground state ($\text{X}^2\Sigma^+$) and excited state ($\text{B}^2\Sigma^+$) CN production has been correlated with plasma-film interactions.²⁷⁻²⁸

Hu *et al.* also observe a link between excited N_2 species and production of CN molecules.²³ These authors observed that trends of CN emission aligned with N_2 SPS emission

trends as a function of CH₄/N₂ feed gas ratio, suggesting that CN production may be tied to excited N₂ (C³Π_u). The authors suggest resonant excitation between excited N₂ molecules and CN radicals may occur as the energy of the N₂ C³Π_u → B³Π_g transition (3.26 eV) is similar to that of the CN B²Σ⁺ → X²Σ⁺ transition (3.19 eV).²³ Additionally, Clay *et al.* suggest the high energy of excited N₂ molecules may favor production of atomic N,²¹ which in turn, favors production of CN radicals as reactions between N atoms and carbon species are exothermic.²⁹ In our OES spectra (Figure 7.1) we do not observe emission from atomic N species, in keeping with many studies that show such emission is not often observed in rf plasmas.²¹ Because T_e is much greater in microwave discharges (~8 eV) compared to rf discharges (~1–3 eV), nitrogen is expected to be more highly activated.^{21, 30} This highly activated nitrogen leads to atomic nitrogen with a longer radiative lifetime.²¹ In contrast, the nitrogen atoms typically produced in rf discharges are short lived and tend to recombine rapidly to produce molecular nitrogen or possibly CN radicals (Reaction 7.3).²³ Hu *et al.* also suggest the lifetime of excited N atoms is shortened by bonding with carbon-containing species, which could reduce the probability of observation in OES data.²³ Additionally, atomic nitrogen peaks can be obscured by the N₂ FPS (B³Π_g → A³Σ_u⁺) emission band.

Hu *et al.* also observed that the intensities of both the N₂ SPS and the N₂⁺ FNS increased by a factor of 2 to 10 when CH₄ was added.²³ This enhancement was also reported by Clay *et al.*²¹ Indeed, mass spectroscopic studies indicate there are numerous excited C_xH_y species (radicals and ions) present in CH₄/N₂ plasmas.³¹⁻³² These species tend to undergo collisional reactions rather than deexcitation processes.²¹ The addition of CH₄ and other hydrocarbon species (radicals and ions) thus potentially act as Penning collisional agents for nitrogen species activation, Reactions 7.6 – 7.7.²¹



The enhanced nitrogen activation by these processes may be responsible for the elevated $T_V(\text{N}_2)$ values observed at high CH_4 content in our CH_4/N_2 plasmas (Figure 7.7b).

Penning collisional processes typically result in a vibrational distribution which deviates from Boltzmann behavior.³³⁻³⁴ When calculating $T_V(\text{N}_2)$, we observed increasing deviation from Boltzmann behavior as the CH_4 fraction in the feed gas simultaneously increased. Bruggeman *et al.* notes that although N_2 vibrational population distributions can deviate significantly from a Boltzmann distribution, the rotational levels tend to equilibrate very quickly with the gas kinetic temperature.³⁵ Our results indicate that although $T_V(\text{N}_2)$ values are dependent on the feed gas composition, $T_R(\text{N}_2)$ values are not (Figure 7.7a). Additionally, $T_V(\text{N}_2)$ values are approximately an order or magnitude larger than $T_R(\text{N}_2)$. Moreover, $T_R(\text{N}_2)$ values exhibited the lowest T_R values in our systems (Figure 7.9a). Goyette *et al.* explains that changes in rotational quantum number from inelastic collisions between electrons and molecules are produced by long-range dipole and quadrupole interactions.³⁶ Because N_2 is a homonuclear molecule with no permanent dipole, the electron exerts a torque through the permanent quadrupole moment of the molecule. Since we hypothesize that N_2 is excited primarily through direct electron impact from a lower-lying level, the rotational distribution of the excited level will reflect the lower-lying level. Thus, the equilibration of the lower-lying level is being indirectly probed in this case.

In general, a non-Boltzmann distribution behavior is expected for excited state species in low pressure plasmas because the collisional timeframe is on the same order as the radiative lifetime.³⁵ As such, rotational states have little time to relax before undergoing radiative decay. Thus, T_R values measured in our systems can be used to elucidate formation mechanisms because

T_R becomes an image of the formation process rather than the kinetic temperature. Furthermore, some formation mechanisms can favor production of high or low rotational excited states which can drastically change T_R and ultimately provide insight into understanding mechanistic phenomena.³⁵ Notably, the Figure 7.9 data indicate the rotational and vibrational temperatures of excited state species in our systems are not equilibrated with each other. Insight into formation mechanisms for each of these species may help to explain these observed differences.

Previous studies from our lab examined rotational temperatures of H₂ and CH in CH₄ plasmas and reported similar T_R values and trends for these two molecules as those observed in a CH₄/N₂ system.^{12, 15} The significant differences between the $T_R(\text{H}_2)$ and $T_R(\text{CH})$ values observed in a 100% CH₄ plasma were ascribed to a combination of differences in the species densities, radiative lifetimes, and consequently their excitation pathways. In our systems, we believe that dissociative electron excitation of a CH_x parent molecule is the primary production mechanism for CH*. Similarly, dissociative excitation of methane molecules may also contribute to production of H₂*; yet, several studies have reported that direct electron impact excitation is the primary pathway for H₂* formation in CH₄ discharges because of the relatively high concentration of molecular hydrogen formed via methane dissociation.²⁴ Notably, N₂*, which is also produced primarily via direct electron impact excitation of the N₂ precursor, has $T_R(\text{N}_2)$ values near room temperature. $T_R(\text{N}_2)$ values within this range (~300 – 400 K) have been reported for a variety of nitrogen plasma systems including N₂/CO₂ DBD³⁷ and low pressure ICP N₂ plasmas.¹¹ Moreover, our lab has previously reported similar $T_R(\text{N}_2)$ values for both excited and ground state molecules in a 100% N₂ plasma, finding little difference.¹⁰ This bolsters the idea that rotational relaxation and thermalization readily occurs within N₂ rf discharges.

Considering the reported $T_R(\text{CN})$ values in our 8:1 CH_4/N_2 plasma system, $T_R(\text{CN})$ values range from ~ 790 to 1180 K and are independent of P . Several possible CN^* formation mechanisms were discussed above. Although our reported kinetic and energetic data provide some insight into possible mechanisms for CN formation, information regarding the exact processes cannot be easily disentangled. In a related study, Cruden *et al.* determined rotational temperatures of five molecular species (i.e., CF, CN, C_2 , CO, and SiF) from emission spectra of a low pressure (30 mTorr) inductively coupled CF_4 plasma.¹⁶ Four different rotational temperatures were obtained between the five molecules studied. Species produced primarily in the plasma bulk (CF and CN) yielded the lowest rotational temperatures (~ 1250 K) whereas SiF, an etch product from the reactor walls, had the highest rotational temperature at ~ 2300 K. C_2 and CO, which are produced both in the plasma bulk and as a product of plasma/surface interactions from the reactor walls had intermediate rotational temperatures (1600 K and 1800 K, respectively). Importantly, differences in internal plasma temperatures have been attributed to differences in spatial variations and concentrations.³⁸⁻³⁹ Simulations demonstrate that neither temperature nor concentration is guaranteed to be spatially uniform within the plasma.⁴⁰ Future investigations using spatially-resolved emission spectra could provide further insight into CN formation mechanisms and $T_R(\text{CN})$ values and trends.

Vibrational temperatures were also obtained for CF, CN, C_2 , and SiF in the study by Cruden *et al.* with values ranging from 1750 K to 5950 K.¹⁶ Similar to the results reported herein (CH_4/N_2 plasma system), species with lower T_R had the highest T_V , a trend not observed here in the $\text{CH}_4/\text{H}_2\text{O}$ plasma system. Our results suggest that different species have achieved different degrees of equilibration between rotational and vibrational modes, and thus, may not be equilibrated with translational temperatures.

b. *CH₄/H₂O plasma system.* Similar to the results displayed in Figure 7.9, the excited state species in the CH₄/H₂O system also exhibit vast differences in rotational and vibrational temperatures, Table 7.4. $T_R(\text{H}_2)$ values align with those reported in a 100% CH₄ plasma (Table 4.1)¹⁵ and in the CH₄/N₂ plasma system (Table 7.2). Interestingly, we observe very little emission from H₂ as the H₂O fraction in the CH₄/H₂O plasma system increases, Figure 7.10b. We were unable to determine $T_R(\text{H}_2)$ with the Boltzmann plot method for H₂O fractions greater than 8:1 CH₄/H₂O because of the low intensity of some of the higher rotational transitions in the H₂ $d^3\Pi_u \rightarrow a^3\Sigma_g^+$ (0, 0) Fulcher (α) band. These observations indicate that H₂ formation likely results primarily from CH₄ decomposition rather than H₂O decomposition or from a recombination reaction involving atomic hydrogen species. Chapter 4 includes a more detailed discussion on probable H₂ formation pathways in a CH₄ plasma.¹⁵

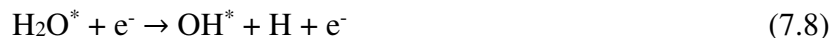
Notably, $T_R(\text{CH})$ and $T_V(\text{CH})$ values for both of the plasma systems discussed in this chapter (CH₄/N₂ and CH₄/H₂O) are slightly lower than those in a 100% CH₄ plasma system (Table 3.1).¹² Although some $T_R(\text{CH})$ values are ~220 K lower in the CH₄/H₂O system than in the CH₄/N₂ system, other $T_R(\text{CH})$ values are within error between the two systems. Additionally, the $T_R(\text{CH})$ and $T_V(\text{CH})$ values in Tables 7.2 and 7.4 generally align with those reported for the CH₄/H₂ system (Table 4.2).¹⁵ Notably, the values reported in Table 4.2 were obtained from different feed gas ratios of a CH₄/H₂ plasma at $p = 200$ mTorr, and the values reported in this chapter were collected at a total pressure of 150 mTorr. Thus, we cannot make a direct comparison between these systems. Nevertheless, $T_R(\text{CH})$ and $T_V(\text{CH})$ values reported in the Chapter 4 CH₄/H₂ system are also slightly lower than (albeit generally within error of) those reported in a 100% CH₄ plasma at $p = 200$ mTorr. The combination of these results may suggest

that addition of another feed gas (e.g., H₂, N₂, H₂O) to CH₄ may affect CH formation pathways to varying extents.

The feed gas composition also appears to have a strong effect on $T_R(\text{OH})$ and $T_V(\text{OH})$ values in mixtures of CH₄ and H₂O, Figure 7.14b. In a related study, Sarani *et al.* measured $T_R(\text{OH})$ in an atmospheric pressure plasma jet generated in Ar/water vapor mixtures with varying concentrations of H₂O.⁴¹ $T_R(\text{OH})$ increased with the addition of water to the feed gas from 620 K in a 100% Ar plasma to 1130 K for a mixture comprising 0.76% H₂O. Similarly, Bruggeman and coworkers noted a concurrent increase in $T_R(\text{OH})$ with H₂O concentration in a He/H₂O rf atmospheric pressure glow discharge.⁴² They observed formation of a two-temperature Boltzmann distribution for OH ($A^2\Sigma^+$) at ~940 ppm H₂O, indicating a lower rotational temperature for lower rotational states and an elevated rotational temperature for the higher rotational states. In a second publication by Bruggeman and coworkers, the authors determined that excited OH radicals tend to show significant overpopulation of high rotational states in atomic gases and water vapor.⁴³ The overpopulation of the high OH ($A^2\Sigma^+$) rotational states [and thus, higher reported $T_R(\text{OH})$ values] are explained by a combination of the formation process and quenching rates. H₂O is the most efficient electronic quenching partner of OH ($A^2\Sigma^+$)⁴³; however, for high concentrations of water, the quenching time constants become on the same order of magnitude as rotational energy transfer (RET).⁴²⁻⁴³ This inhibits the thermalization of OH ($A^2\Sigma^+$) before radiative decay occurs, and consequently, higher $T_R(\text{OH})$ values are observed at high [H₂O] for the systems described by Sarani *et al.*⁴¹ and Bruggeman *et al.*⁴². Additionally, Bruggeman and coworkers observed no change in the rotational population distribution with increasing power, suggesting that the non-Boltzmann behavior in their systems is related to water concentration rather than other plasma parameters.⁴²

Our $T_R(\text{OH})$ results clearly display different trends from the studies mentioned above. Namely, $T_R(\text{OH})$ is much lower at high levels of $\text{H}_2\text{O}_{(\text{v})}$ in the feed gas, and a power dependence is observed for feed gas compositions of $\leq 50\%$ H_2O (Figure 7.14b). Notably, our system operates at pressures (150 mTorr) much lower than atmospheric pressure; thus, fewer collisions occur in our system than at higher pressures within the same time frame. As collisional time is on the same order as the radiative lifetime, the $T_R(\text{OH})$ values observed in our system are an image of the formation process of OH ($\text{A}^2\Sigma^+$). This suggests that, regardless of the feed gas composition, $T_R(\text{OH})$ is more dependent on OH ($\text{A}^2\Sigma^+$) formation processes rather than collisional quenching processes (e.g., electronic quenching with H_2O).

The formation of OH ($\text{A}^2\Sigma^+$) primarily occurs via direct dissociative electron excitation of water vapor, Reaction 7.8, or direct electron impact excitation of ground state OH, Reaction 7.9.⁴¹



Sarani *et al.* characterized $T_R(\text{OH})$ by a two-temperature Boltzmann distribution in their system and suggested that vibrational-rotational populations of OH can be formed via different mechanisms depending on their J level.⁴¹ The authors hypothesize that lower rotational states ($J < 13$) were produced via a combination of Reactions 7.8 and 7.9 resulting in $T_R(\text{OH}) = 625$ K. Conversely, the $13 < J < 25$ rotational levels were characterized by a much higher rotational temperature [$T_R(\text{OH}) = 5000$ K]. Because OH ($\text{A}^2\Sigma^+$) radicals produced via Reaction 7.8 result in high rotationally excited levels, the authors suggest that the hydroxyl radicals characterized by the $13 < J < 25$ rotational levels are almost exclusively generated by Reaction 7.8.⁴¹ This

interpretation suggests that the elevated $T_R(\text{OH})$ values observed at low H_2O feed gas concentration may be related to formation of $\text{OH} (\text{A}^2\Sigma^+)$ primarily via Reaction 7.8. In contrast, the lower $T_R(\text{OH})$ values observed at high H_2O feed gas concentration indicate that Reaction 7.9 may also significantly contribute to $\text{OH} (\text{A}^2\Sigma^+)$ formation. Indeed, if the ground state $[\text{OH}]$ is sufficiently large as would be expected with a larger concentration of H_2O , then Reaction 7.9 will be important to the formation processes of $\text{OH} (\text{A}^2\Sigma^+)$.⁴² One additional consideration for the formation of OH^* is the recombination between H and O atoms which produces rotationally “hot” $\text{OH} (\text{A}^2\Sigma^+)$.⁴⁴ This is described in Reaction 7.10, where either the atomic hydrogen or oxygen atom or both atoms may already be in an excited state.



In our systems, an increase in power leads to greater destruction of OH molecules and consequently, higher atomic H and O densities. Thus, the observed power dependence for $T_R(\text{OH})$ may be related to Reaction 7.10.

Evaluating steady state emission data provides valuable information regarding energy partitioning and further insight into molecular formation mechanisms can be gained when combined with the kinetics data afforded by TR-OES. Figure 7.13a shows OH intensity is high upon plasma ignition, immediately followed by a decrease to steady state at longer times. k_d is highly dependent on the feed gas composition and power (at low H_2O concentrations). The absence of a formation curve for OH suggests that OH^* indicates that the formation process is faster than the time resolution of our experiment. Additionally, the presence of the decay curve suggests that OH^* produced from H_2O decomposition either continues to decompose into atomic hydrogen and oxygen species or participates in further reactions (e.g., formation of CHO, recombination to form H_2O , etc.). Zaima and Sasaki also utilized TR-OES to examine OH

($A^2\Sigma^+$) production processes in a pulsed $\text{CH}_4/\text{O}_2/\text{Ar}$ DBD burner flame.⁴⁴ Increases in OH density and decreases in $T_R(\text{OH})$ aligned simultaneously with the plasma current pulses. These authors suggest two reaction processes may be contributing to the pulsed responses of $[\text{OH}]$ and $T_R(\text{OH})$, one that produces rotationally “hot” OH and another that produces “cold” OH. They hypothesize that “cold” OH is produced simultaneously with the pulsed high energy electrons. Indeed, further studies probing $T_R(\text{OH})$ as a function of time both in pulsed and continuous wave plasmas could provide useful insight into formation mechanisms of OH ($A^2\Sigma^+$).

Because CO k_f remains relatively constant over the parameter space, the formation of CO does not appear to be directly related to OH formation or destruction processes. Although CO k_f values are generally not dependent on feed gas ratio, there appears to be a slight P dependence at low H_2O concentration. This dependence could be related to the total amount of oxygen species present in the plasma, a clearly essential component for formation of CO. For example, an increase in P corresponds to a decrease in $[\text{OH}]$ and an increase $[\text{O}]$ and $[\text{H}]$ species. Currently, most literature discussing CO formation in plasmas utilizes CO_2 as a feed gas component (e.g., CH_4/CO_2 mixtures). Thus, CO primarily results from CO_2 decomposition, rather than formation through a recombination reaction as is the case in our systems. Moreover, the carbon and oxygen species needed to form CO arise from the two different precursors. As it is difficult to determine exact gas phase formation mechanisms from the CO k_f data presented here, further gas phase investigations including the determination of $T_R(\text{CO})$ and $T_V(\text{CO})$ may be useful.

7.4 Summary

Optical spectroscopy techniques were employed to evaluate kinetic and energetic processes in two environmentally relevant mixed gas plasma systems (CH_4/N_2 and $\text{CH}_4/\text{H}_2\text{O}$).

Determination of rotational and vibrational temperatures for several molecular species in each plasma system demonstrate that the excited state species in our systems are not equilibrated with each other and that different species have achieved different degrees of equilibration between rotational and vibrational modes. When combined with evaluation of TR-OES data, T_R and T_V values provide insight into molecule formation pathways. Furthermore, our results suggest that formation of some molecular species are dependent on the feed gas composition. For example, our results indicate CN^* formation is dependent on activated nitrogen species in the plasma. Possible formation mechanisms for the excited state species examined in this chapter serve to provide a deeper understanding of the relationship between plasma parameters and kinetic and energy partitioning outcomes as well as the roles of reactive species. Collectively, these data help provide the foundation for increasing the utility of PAC.

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CHAPTER 8

RESEARCH SUMMARY AND PERSPECTIVES

This chapter summarizes the major aspects and themes of the research presented within this dissertation. Potential avenues for future directions of research to address current limitations of plasma-assisted catalysis (PAC) applicability are also proposed.

8.1 Research Summary

Low energy requirements and the enormous potential for feed gas decomposition and conversion make plasma-assisted catalysis (PAC) an attractive approach for pollution remediation of waste gas streams;¹⁻³ however, a lack of knowledge on the fundamental processes contributing to observed plasma-catalyst synergies in PAC systems severely limits its utility.⁴⁻⁵ To fully utilize the advantages of these plasma systems, an understanding of the roles of the catalyst and the plasma, as well as the interactions occurring at the plasma-surface interface must be understood. Evaluating the contributions of the plasma and catalyst to the observed synergies requires a multi-pronged approach, wherein the fundamental chemistry of each region of the plasma-substrate system is characterized (Figure 1.1). This approach to deciphering key molecular-level processes in plasmas is an emergent theme throughout this dissertation and involves an array of complementary analysis techniques to both probe the gas-phase of the plasma and comprehensively characterize the material of interest.

Plasma diagnostic tools are employed to evaluate kinetic and energetic processes for multiple molecular species in low-temperature, inductively-coupled plasma (ICP) systems with precursors of increasing complexity, including mixed gas systems. A primary goal of this work

has been the determination of internal molecular temperatures within PAC systems. This emphasis comes from the estimation that these values collectively represent a key component to understanding the reactions that drive the chemistry and the mechanisms involved in plasma-surface interactions. Moreover, these data help to establish the relationship between system parameters and energetic outcomes. Specifically, rotational and vibrational temperatures (T_R and T_V , respectively) have been calculated for several excited state diatomic species (e.g., CH, CN, H₂, N₂, OH). Our data indicate that our ICPs generate vibrationally hot species with $T_V > T_R$ for each molecule studied. Importantly, this work has clearly demonstrated differences between T_R values of several molecular species within the same plasma system. For example, in a CH₄/N₂ plasma (8:1 precursor ratio; $p = 150$ mTorr, $P = 75$ W), T_R values for CH and CN (~1720 K and ~1180 K, respectively) are significantly elevated compared to $T_R(\text{H}_2)$ (~600 K) and $T_R(\text{N}_2)$ (~280 K). As N₂ ($\text{C}^3\Pi_u$) and H₂ ($\text{d}^3\Pi_u$) are typically excited via direct electron impact in N₂ and CH₄ discharges,⁶⁻⁸ this thermal nonequilibrium between molecular species implies that formation mechanisms play a significant role in resulting rotational temperatures for diatomic molecules. Additionally, studies as functions of various system parameters demonstrate the significant impact of pressure (p), applied rf power (P), and feed gas ratio on fundamental plasma processes. For example, $T_R(\text{H}_2)$ increases simultaneously with system pressure and decreases with increasing power in a 100% CH₄ plasma, whereas no clear pressure or power trends appear for $T_R(\text{H}_2)$ in a 100% H₂ plasma (Chapter 4). Moreover, $T_R(\text{CN})$ is dependent on the feed gas ratio in a mixed gas CH₄/N₂ plasma system (Chapter 7), indicating that different formation mechanisms may be occurring under different parameter conditions. Time-resolved spectroscopic studies allow us to further probe these complex molecular level processes by measuring species formation and destruction rates as functions of plasma parameters. Time-

resolved optical emission spectroscopy (TR-OES) results presented in Chapter 7 demonstrate that the kinetics of both N_2 and CN formation and destruction are highly dependent on the feed gas ratio while TR-OES studies in Chapters 5 and 6 demonstrate that the presence of a catalyst also impacts kinetic processes.

A second chief component to the work presented throughout this dissertation centers on understanding the effect of the plasma on the substrate properties. A combination of materials analysis techniques were employed to evaluate chemical and morphological properties before and after plasma exposure. X-ray photoelectron data (XPS) data of a TiO_2 catalyst presented in Chapter 5 demonstrates that H_2 plasma significantly reduces titanium from Ti^{4+} to Ti^{3+} and Ti^{2+} oxidation states. Reduction of titanium is also observed to a lesser extent after exposure to CH_4 (Chapter 5) and N_2 (Chapter 6) plasmas. Moreover, an increase of adsorbed oxygen species relative to lattice oxygen post plasma exposure indicates the formation of oxygen vacancies via plasma-surface interactions.

By utilizing a combination of optical spectroscopy and materials characterization techniques to investigate both the gas phase and catalyst characteristics, insight into key molecular-level processes in PAC systems can be constructed. Specifically, the studies presented herein have sought to understand mechanistic phenomena occurring in the gas-phase and at the plasma-surface interface in PAC-relevant systems. Overall, this work offers unique insight into these fundamental processes which are crucial to advancing PAC technology. For research to continue to address PAC implementation limitations, however, future studies should include investigations into systems of increasing complexity and continue to yield important and valuable information about the plasma-surface interface.

8.2 Future Directions

The results presented and discussed herein demonstrate original research that can be used as a foundational basis for PAC applications. The implications of this work are far reaching, and yet, significant additional research must be done to establish full applicability of PAC. To encapsulate the complex chemistry occurring in a PAC environment, further research efforts should include a holistic approach to characterizing the plasma-catalyst environment. Elucidating fundamental chemical processes occurring at the molecular level in (1) the gas phase of the plasma, (2) the catalytic material, and (3) at the plasma-surface interface will provide valuable insight towards understanding the multifaceted environment of PAC systems.

As demonstrated throughout this dissertation, monitoring species emission via OES can provide valuable information beyond species identification. Species densities, plasma temperatures, and kinetics information obtained via OES can afford tremendous insight into the underlying mechanisms at work within our plasma systems. Although OES provides useful data, it is also important to evaluate ground state species, which comprise the majority of species in low temperature ICPs.⁹ As a complementary technique to OES, broadband absorption spectroscopy (BAS) is a gas-phase diagnostic tool that can be readily implemented in the Fisher group laboratories to obtain information on ground state species. With the addition of a halogen-deuterium light source interfaced to a second quartz window on the upstream end of the reactor (Figure 2.1b), we can collect absorption data of relevant species within our plasma systems.¹⁰ Preliminary BAS data, Figure 8.1, shows absorption of the CH $A^2\Delta \leftarrow X^2\Pi$ transition in a 100% CH₄ plasma. Fitting this spectrum within LIFBASE gives rise to $T_R = 1690$ K. Notably, $T_R(\text{CH } X^2\Pi)$ is significantly lower than $T_R(\text{CH } A^2\Delta)$ (~2010 K) under the same plasma parameter conditions, indicating that a higher degree of thermalization may be achieved for the ground state

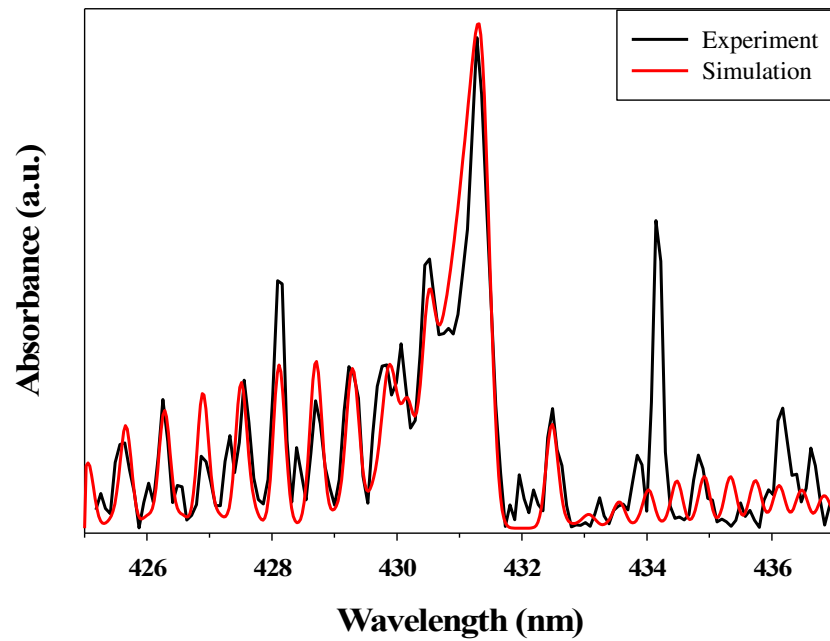


Figure 8.1. Broadband absorption spectrum ($p = 150$ mTorr, $P = 100$ W) for CH X²Π → A²Δ in a CH₄ plasma. Simulation of this spectrum using LIFBASE yields $T_R = 1690$ K, PC = 0.94.

species compared to the excited state species. Interestingly, the Fisher group has noted the opposite trends for N_2 and NO species in N_xO_y plasma systems. Specifically, $T_R(N_2, NO)$ for ground state species are elevated compared to those for excited state species.^{8, 10} Our OES temperature studies of CH_4 and N_xO_y plasmas have demonstrated significant differences in T_R and T_V values and trends between the two types of plasma systems, indicating there are fundamental differences in how these species and plasma systems behave.^{8, 10-11} The preliminary BAS spectrum in Figure 8.1 provides a glimpse into the ground state energetics of $T_R(CH\ X^2\Pi)$ in our plasma systems. Clearly, further BAS investigations would provide valuable information that would aid in understanding the key molecular processes that occur in PAC systems.

Future investigations should also include studying plasma systems of increasing complexity. Although we have studied mixed gas plasma systems comprising CH_4 mixtures with either N_2 or $H_2O_{(v)}$ (Chapter 7), real world waste gas streams comprise a vast array of gas-phase species. Several VOCs, NO_x species, and even sulfur contaminants contribute significantly to the overall chemistry of exhaust systems of interest for remediation through PAC. As precursor gases become more complex, the interactions between gas-phase species and catalysts will undoubtedly become more complex and convoluted. As such, a thorough understanding of the molecular-level processes occurring in increasingly complex systems will provide valuable information towards increasing the overall applicability of PAC by tailoring the chemistry occurring in the system. It is crucial to investigate the role that each of these component species plays in the overall chemistry, energy, and reactivity of environmentally-relevant plasma systems. Thus, increasing the complexity of the plasma precursors should also include increasing the complexity of the hydrocarbon feed gases (e.g., C_2H_6 , C_2H_4 , C_6H_6) or utilizing multiple precursors to further probe mixed gas systems. Additionally, studies

performed in Chapter 7 did not include the use of a catalyst. As demonstrated in the work presented throughout this dissertation, a catalyst can significantly change the plasma chemistry. Preliminary investigations of an 8:1 CH₄/N₂ plasma show that $T_V(N_2)$ is reduced for $P > 25$ W ($p = 200$ mTorr) when a TiO₂ substrate is introduced to the discharge, Figure 8.2. With the catalyst, $T_V(N_2)$ values decrease by up to ~1800 K. Moreover, $T_V(N_2)$ data show a linear dependence on P both with and without the TiO₂ catalyst in the plasma. These results mimic $T_V(N_2)$ trends for a 100% N₂ plasma with and without a TiO₂ substrate (Figure 6.2).¹² Although this suggests similar $T_V(N_2)$ trends may exist for the other CH₄/N₂ feed gas ratios studied in Chapter 7, further investigations of other molecular species in this system could provide key insight into PAC processes.

Studies focused on the catalyst in PAC systems are also important to increasing applicability. A host of catalysts have been used in PAC systems including platinum, palladium, zeolites, and several metal oxide materials (e.g., TiO₂, Al₂O₃, SnO₂, ZnO, MgO).¹³⁻¹⁵ Numerous studies have focused on optimizing conversion rates of toxic pollutants to clean gas species by comparing various catalyst types and morphologies.¹⁶⁻¹⁷ Although the results presented in this dissertation up to this point have only included TiO₂ nanoparticles as the catalyst material, studies with SnO₂ nanoparticles, ZnO nanoparticles, and ZnO microrods as catalysts were also executed. These preliminary results are presented in Appendix A. As noted elsewhere, the Fisher research group has studied the effect of Pt and zeolite materials on N₂O plasma chemistry.¹⁸ The presence of Pt nanopowder or micro-structured zeolites in the plasma significantly decreased the concentration of NO at high powers, whereas the flat Pt foil substrate did not. Moreover, whereas all catalyst materials decreased $T_V(N_2)$, the Pt materials had a limited effect on $T_V(NO)$. These results along with those presented in this dissertation clearly

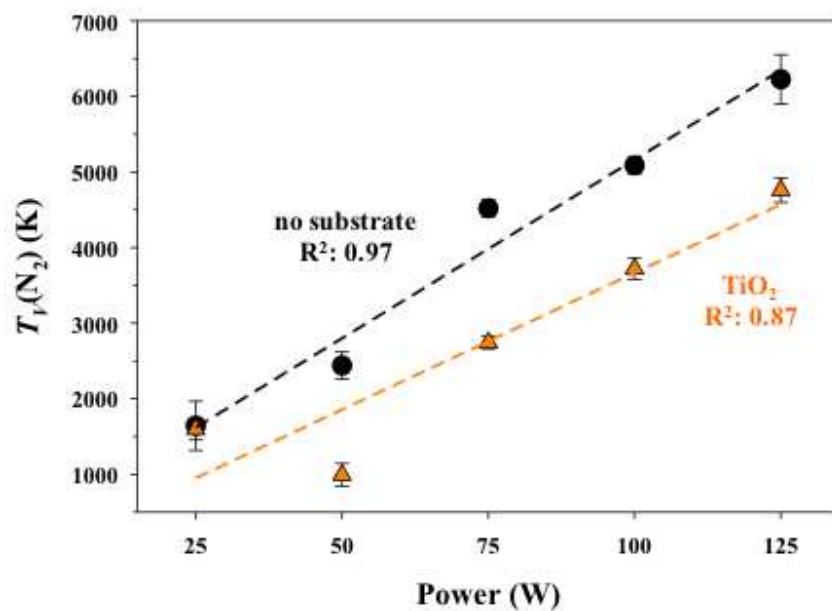


Figure 8.2. $T_v(N_2)$ in an 8:1 CH_4/N_2 plasma (10% Ar, $p = 200$ mTorr) without a substrate (black circles) and with a TiO_2 substrate (orange triangles). Dashed lines represent linear regression analysis for the two data sets, with the R^2 values shown.

indicate that careful selection of catalysts is important when designing a PAC system for commercial or industrial implementation. Further fundamental studies must be performed to fully understand the impact of different catalysts and morphologies on plasma chemistry.

Notably, in addition to selection of the catalyst material, modification of catalyst surfaces can increase catalytic performance.¹⁹⁻²³ Several studies have shown that pre-treating a catalyst with a reducing plasma environment can create oxygen vacancies in metal oxide catalyst materials.^{19, 22-23} This is demonstrated in Chapter 5 where high resolution XPS spectra show the reduction of Ti^{4+} to Ti^{3+} and Ti^{2+} oxidation states with a simultaneous increase in adsorbed oxygen species after exposure to a 100% H_2 plasma. The presence of oxygen vacancies within the metal oxide material can enhance conversion of NO_x and VOC species.¹⁹⁻²¹ Notably, the Fisher research group stands uniquely poised to enter this area of research, with significant contributions to plasma-enhanced surface modification techniques. Surface modification via plasma processing could be an invaluable tool towards creating better catalytic materials to be used in PAC systems.

A primary challenge to understanding low-temperature plasma chemistry within the context of PAC systems lies in deciphering plasma-surface interactions.^{3, 24-25} Thus, it is critical to distinguish effects arising from (a) different types of species bombarding the surface; (b) synergistic or coupled reactions at the surface (e.g., ion bombardment assisting chemical etching²⁶⁻²⁷) and (c) energy partitioning within molecules. All can impact how molecules interact with a surface, especially because the rates of many surface reactions are likely controlled by molecular vibrational and electronic states.²⁸ Our unique imaging of radicals interacting with substrates (IRIS) technique utilizes a laser and plasma molecular beam and laser-induced fluorescence images are collected with and without a substrate in the path of the

beam to determine scatter coefficients and the concomitant surface reactivity.²⁹⁻³⁰ IRIS allows us to measure plasma-surface interactions during plasma processing of a substrate. Previous Fisher group work showed that the surface reactivity probability of CH in a CH₄ plasma is near unity and appears independent of several plasma parameters (e.g., pressure, power) and substrate conditions (e.g., substrate temperature and substrate bias).³¹ The high surface reactivity of CH implies that almost all incident CH radicals have been lost to the surface of the material. Some studies suggest carbon deposition is mitigated by synergistic effects during PAC,³²⁻³³ and plasma desorption of VOCs from adsorbent catalysts can occur via energetic species bombardment to form CO₂ and other hydrocarbon decomposition products.³⁴⁻³⁵ Certainly, it would be of significant interest to use IRIS to study the interaction of CH on catalytic substrates to further elucidate plasma-catalyst synergies. Indeed, studying other radical species (e.g., C₂, CN, N₂, NO, OH) that are prevalent in PAC systems using the IRIS technique is also essential to provide a more complete picture of the processes occurring in a PAC environment by providing foundational information on plasma-surface interactions.

Significant foundational work still remains to be done to understand and increase the future success of PAC systems as a pollution remediation tool. These future directions serve to explore each aspect of the PAC environment (gas phase, catalyst, plasma-catalyst interface) in an effort to elucidate the roles that each component [gas-phase species, catalyst material, or plasma parameter (pressure, power, precursor)] has on the overall chemistry of the PAC system. Understanding the effects that each of these components has on the PAC environment on a molecular level will allow us to control and essentially tune the chemistry of the system as needed for specific applications. Thus, fundamental investigations such as those performed or

suggested throughout this dissertation will ultimately provide the significant foundational advancement necessary for PAC utility.

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APPENDIX A

THE IMPACT OF SnO₂ AND ZnO CATALYSTS ON MOLECULAR PLASMA TEMPERATURES WITHIN CH₄ DISCHARGES: PRELIMINARY RESULTS

The discussions in Chapter 5 focus on rotational and vibrational energy partitioning for H₂ $d^3\Pi_u \rightarrow a^3\Sigma_g^+$ and CH $A^2\Delta \rightarrow X^2\Pi$ in H₂ and CH₄ plasmas with a catalytic TiO₂ substrate. In addition to TiO₂, the impact of other metal oxide catalysts on CH₄ plasma chemistry were also explored. This appendix contains preliminary results for the determination of characteristic plasma temperatures within a 100% CH₄ plasma containing several nano-structured and micro-structured catalytic materials.

A.1 Background

A primary goal of the work presented throughout this dissertation has been the determination of rotational and vibrational temperatures within plasma-assisted catalysis (PAC) systems. An understanding of how energy is partitioned into rotational and vibrational modes can provide insight into molecule formation and decomposition pathways. We have examined the impact of a nano-structured TiO₂ catalyst on fundamental gas-phase properties in CH₄ and N₂ plasmas (discussed in Chapters 5 and 6, respectively). Furthermore, we sought to understand the impact of the plasma discharge on the material as PAC processes rely on the synergistic effect between both the catalyst and the plasma. The work presented in this appendix expands on these fundamental studies by examining the impact of several other catalytic materials (i.e., SnO₂ nanoparticles, ZnO nanoparticles, ZnO microrods) on CH₄ plasma chemistry. These materials were chosen because of their photocatalytic nature, which is thought to be advantageous in PAC

systems. Although, plasma-triggered photocatalytic effects are not well understood,¹ UV light generated from plasmas is thought to induce the formation of electron-hole pairs.²⁻³ Plasma photocatalysis has been studied as a method of VOC degradation and removal⁴⁻⁶ and several photocatalysts have been used in PAC studies (e.g., Fe₂O₃, TiO₂, ZnO).⁴⁻⁶ Nevertheless, TiO₂ is the currently most promising photocatalytic material for PAC applications because of its stability, strong oxidizing power, chemical inertness, non-toxicity, and low cost.¹ Thus, we have also included the TiO₂ data presented in Chapter 5 here to directly compare results between photocatalytic materials.

For these studies, commercially purchased SnO₂ nanopowder (< 100 nm, Aldrich) and ZnO nanopowder (< 50 nm, Aldrich, > 97%) substrates were made by creating a slurry of as received nanoparticles and methanol. The nanoparticles (NP) were suspended in methanol until saturation; then the NP solution was doctor bladed onto glass slides or p-type <100> silicon wafers (Wacker-Chemitronic GMBH, Germany) of ~3 × 3 cm. ZnO microrods (MR) were grown hydrothermally on glass slides and silicon wafers in 0.1 M solutions of zinc nitrate (Alfa Aesar, 99%), Zn(NO₃)₂•4H₂O, and hexamethylene tetramine (Alfa Aesar, 99+ %), C₆H₁₂N₄, in a stopped flask on a hot plate at 95 °C for six hours.⁷ Subsequently, the ZnO MR materials were thoroughly washed with water to remove residual salt or amino complex and allowed to dry at room temperature overnight. All substrates used were placed in the coil region of the plasma reactor ~30 cm upstream from the quartz window, as depicted in Figure 2.1.

Of burgeoning interest to the PAC community is the correlation between catalyst properties (e.g., chemical identity, material morphology, pore size) and their influence on plasma characteristics (e.g., species densities, energy partitioning, formation of microplasmas within catalyst pores). This was explored to some extent in Chapter 6 and our related published study

where we examined the effects of nano-structured TiO₂ and micro-structured zeolite on N₂ discharge characteristics.⁸ Here, we have chosen to examine the impact of several nano-structured photocatalysts on CH₄ plasma characteristics. Additionally, both nano-structured and micro-structured ZnO catalysts were included in this study to elucidate the influence of material morphology. SEM images, Figure A.1, highlight the size disparity between the nano-structured and the micro-structured materials. The commercially purchased SnO₂ NP and ZnO NP agglomerate into nanoparticle clusters with a porous network when pasted on the silicon wafer substrate (Figure A.1a and Figure A.1b, respectively). The morphological features of the as-prepared ZnO MR are shown in Figure A.1c, where rods of varying lengths extend in all directions across the substrate surface. The inset in Figure A.1c shows a higher magnification image of the rod-like features.

A.2 Characteristic Plasma Temperatures

Within our plasma systems, energy can be transferred from the rf power source to the electrons and internal energy modes (i.e., rotational, vibrational) of the atoms, molecules, and ions of the system. Electrons, in particular, play a crucial role in governing plasma chemistry. Energy from the external electromagnetic field is transferred to the electrons of the system which excite and sustain the plasma.⁹ Thus, in addition to elucidating rotational and vibrational energy partitioning trends, we have determined T_e (described in Section 2.5.1), for these systems. Table A.1 lists T_e for a CH₄ (~10% Ar) plasma without and with each of the catalysts in the coil region of the reactor. Notably, T_e values range from ~2 – 3 eV over our studied parameter space, regardless of the presence or nature of the catalyst. Moreover, the lack of pressure and power dependence indicates increasing energy within the system preferentially results in increasing the

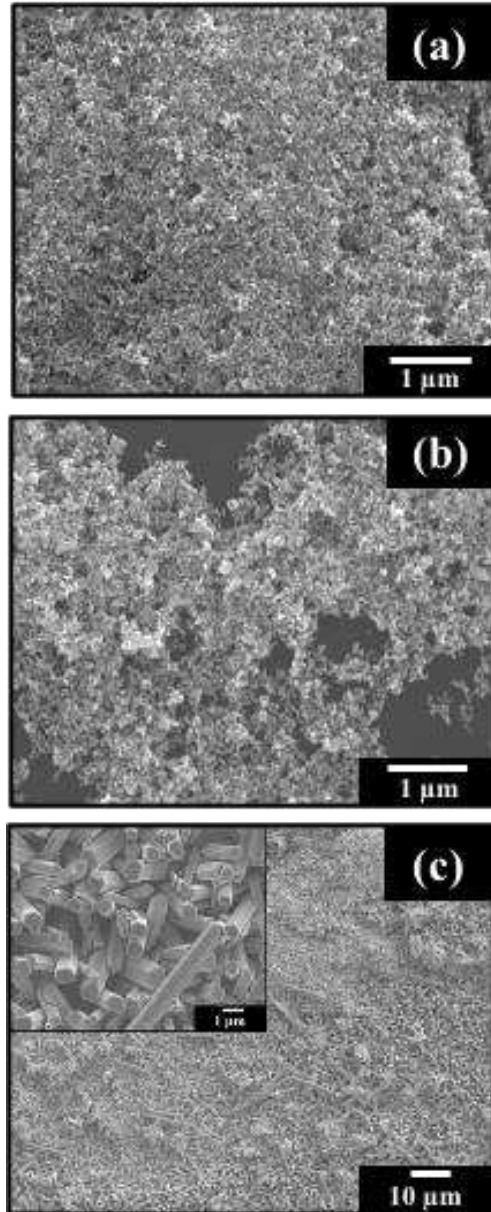


Figure A.1. SEM images of (a) SnO₂ nanoparticles (x20000), (b) ZnO nanoparticles (x20000), and (c) ZnO microrods (x1000). Magnification of inset in (c) is x10000.

Table A.1. T_e (eV) values in a CH₄ plasma without and with substrates.^a

p (mTorr)	P (W)	no substrate	SnO ₂ NP	TiO ₂ NP	ZnO NP	ZnO MR
100	25	2.4 (0.3)	3.0 (0.5)	2.8 (0.8)	2.7 (0.4)	2.4 (0.3)
	50	2.6 (0.4)	2.5 (0.5)	2.1 (0.2)	2.7 (0.4)	2.4(0.3)
	75	2.7 (0.4)	2.4 (0.3)	2.2 (0.3)	2.7 (0.4)	2.2 (0.2)
	100	2.7 (0.4)	2.7 (0.4)	2.5 (0.4)	2.8 (0.4)	2.5 (0.4)
	125	2.7 (0.4)	2.4 (0.3)	2.6 (0.4)	2.6 (0.4)	2.9 (0.5)
150	25	2.7 (0.3)	2.6 (0.3)	2.6 (0.4)	2.8 (0.6)	1.0 (0.10)
	50	2.7 (0.4)	2.6 (0.3)	2.7 (0.3)	1.9 (0.2)	2.1 (0.1)
	75	2.8 (0.3)	2.9 (0.4)	2.7 (0.3)	2.2 (0.2)	1.9 (0.1)
	100	2.8 (0.4)	2.4 (0.3)	2.7 (0.3)	2.9 (0.5)	2.5 (0.2)
	125	2.9 (0.4)	2.9 (0.4)	2.5 (0.3)	2.7 (0.3)	2.5 (0.3)
200	25	1.7 (0.1)	2.9 (0.2)	2.5 (0.5)	2.6 (0.3)	1.1 (0.1)
	50	2.4 (0.2)	3.0 (0.4)	2.6 (0.3)	2.9 (0.5)	2.5 (0.2)
	75	2.4 (0.2)	2.8 (0.4)	2.7 (0.3)	2.9 (0.2)	2.8 (0.1)
	100	2.6 (0.3)	2.8 (0.3)	2.7 (0.3)	1.4 (0.1)	2.5 (0.2)
	125	2.6 (0.3)	2.7 (0.3)	2.8 (0.4)	2.7 (0.3)	2.5 (0.2)

^aValues in parentheses represent standard error calculated from the weighted mean of $n \geq 3$ trials.

overall energy of the neutral species and ions rather than the electrons. These hypotheses were previously studied in N_xO_y plasmas,¹⁰⁻¹¹ and are further explored here.

Overall, electrons can play a substantial role in governing molecular-level processes in plasmas. Electron impact reactions lead to the production of excited state atoms and molecules, which are largely governed by T_e .⁹ Understanding production mechanisms for a particular species is critical to comprehending molecular plasma temperatures. Moreover, it is important to examine energy partitioning of multiple species within a plasma system to understand the overall character of the plasma. In CH_4 plasmas, electron impact excitation of H_2 from the ground state is the primary route to H_2^* production;¹² however, decomposition and/or recombination reactions and dissociative excitation of methane via collisions with molecules may also contribute to the production of H_2^* . We have previously investigated energy partitioning trends for $T_R(H_2)$ in H_2 and CH_4 plasmas both without a substrate (Chapter 4) and with a catalytic TiO_2 substrate (Chapter 5) to gain further insight into H_2^* formation mechanisms in our systems. Here, we have determined $T_R(H_2)$ values in a 100% CH_4 plasma with three other types of catalytic materials (i.e., SnO_2 NP, ZnO NP, ZnO MR).

Figure A.2 shows $T_R(H_2)$ plotted as a function of P and catalyst material in a CH_4 plasma. Numerical values for all conditions studied are listed in Table A.2 and range from ~400 – 700 K over the parameter space explored. $T_R(H_2)$ data for a CH_4 plasma without a substrate at $p = 100$ mTorr, Figure A.2a, demonstrate a small decreasing trend with increasing P where $T_R(H_2)$ values at $P = 25$ W are ~ 580 K and decrease to ~ 500 K at $P = 125$ W. Addition of the SnO_2 NP, TiO_2 NP, or ZnO NP catalysts to the plasma discharge all result in a decrease in $T_R(H_2)$, with values ranging from ~400 – 480 K and minimal power dependence at $p = 100$ mTorr. Conversely, the presence of micro-structured ZnO (MR) appears to have a slightly different effect on rotational

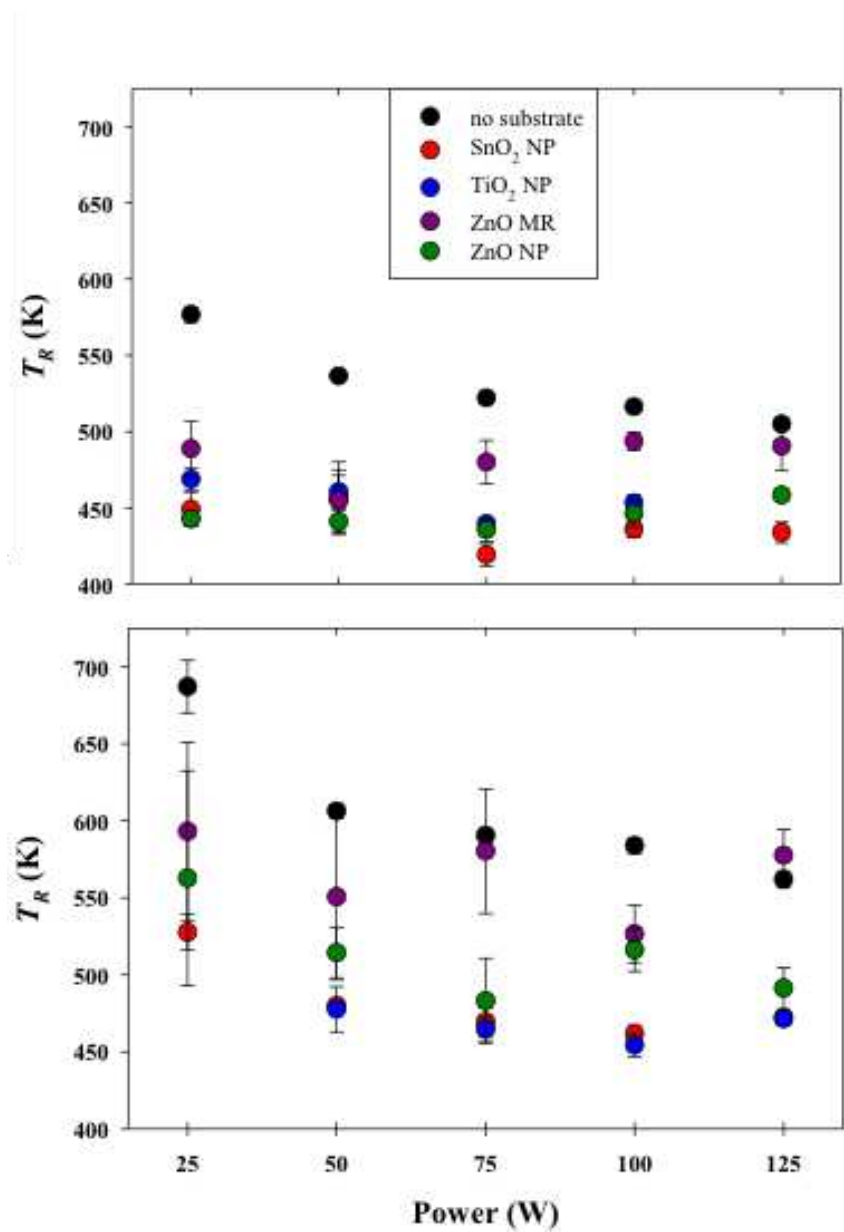


Figure A.2. $T_R(\text{H}_2)$ data as a function of applied rf power for a CH₄ plasma without and with substrates at (a) $p = 100$ mTorr and (b) $p = 200$ mTorr.

Table A.2. $T_R(\text{H}_2)$ (K) values in a CH_4 plasma without and with substrates.^a

p (mTorr)	P (W)	no substrate	SnO_2 NP	TiO_2 NP	ZnO NP	ZnO MR
100	25	580 (10)	450 (10)	470 (10)	440 (10)	490 (20)
	50	540 (10)	460 (20)	460 (10)	440 (10)	450 (20)
	75	520 (10)	420 (10)	440 (10)	440 (10)	480 (10)
	100	520 (10)	440 (10)	450 (10)	450 (10)	490 (10)
	125	500 (10)	430 (10)	--	460 (10)	490 (20)
150	25	600 (10)	470 (10)	460 (20)	520 (40)	540 (50)
	50	480 (10)	460 (10)	450 (10)	460 (20)	640 (20)
	75	570 (10)	440 (10)	470 (10)	510 (20)	570 (20)
	100	560 (10)	440 (10)	450 (10)	420 (10)	530 (50)
	125	540 (10)	430 (10)	450 (10)	480 (10)	490 (30)
200	25	690 (20)	530 (10)	420 (70)	560 (70)	590 (60)
	50	610 (10)	480 (10)	480 (10)	510 (20)	550 (50)
	75	590 (10)	470 (10)	460 (10)	480 (30)	580 (40)
	100	580 (10)	460 (10)	450 (10)	520 (10)	530 (20)
	125	560 (10)	470 (10)	470 (10)	490 (10)	570 (20)

^aValues in parentheses represent standard deviation calculated from the mean of $n \geq 3$ trials.

energy partitioning of H₂ compared to the nano-structured materials. Here, there is a notable decrease in $T_R(\text{H}_2)$ at $P \leq 50$ W from the no substrate system, and the values align well those reported for the nano-structured materials. However, at $P \geq 75$ W, $T_R(\text{H}_2)$ values increase slightly and are closer to the $T_R(\text{H}_2)$ values measured for the no substrate plasma system. Similar trends are noted at a higher pressure ($p = 200$ mTorr), Figure A.2b, but $T_R(\text{H}_2)$ values are elevated by $\sim 100 - 200$ K, regardless of substrate presence or composition. The observed decrease in $T_R(\text{H}_2)$ suggests that the catalysts may impact H₂^{*} formation processes. More discussion on this idea is provided in Section 5.3. Moreover, the elevated $T_R(\text{H}_2)$ values for the ZnO MR catalyst compared to the nano-structured catalysts (including ZnO NP) suggest that material morphology may play a more important role in energetics for some plasma species than the material chemistry.

To further demonstrate the impact of the catalyst on energy partitioning, $T_R(\text{CH})$ as a function of P at two different pressures is shown in Figure A.3, and Table A.3 provides $T_R(\text{CH})$ values for the entire parameter space. At $p = 100$ mTorr, Figure A.3a, $T_R(\text{CH})$ values range from $\sim 1780 - 2770$ K with minimal power dependence. Moreover, the presence of nano-structured substrates (SnO₂ NP, TiO₂ NP, ZnO NP) in the discharge results in a notable decrease in $T_R(\text{CH})$ ($\sim 100 - 200$ K) compared to the no substrate system. In contrast, ZnO MR substrates show a slightly different and more complex trend for $T_R(\text{CH})$ at $p = 100$ mTorr. Interestingly, an increase in pressure to 150 mTorr and 200 mTorr (Figure A.3b), results in $T_R(\text{CH})$ values similar to the no substrate system, regardless of the type of catalyst used. Exceptions to this trend are at $P = 25$ W (ZnO MR substrate) and $P = 50$ W (ZnO NP substrate). $T_R(\text{CH})$ values for catalyst-containing systems also decrease concomitantly with an increase in system pressure, regardless of substrate. We have previously discussed this pressure trend for $T_R(\text{CH})$ in 100% CH₄ plasmas

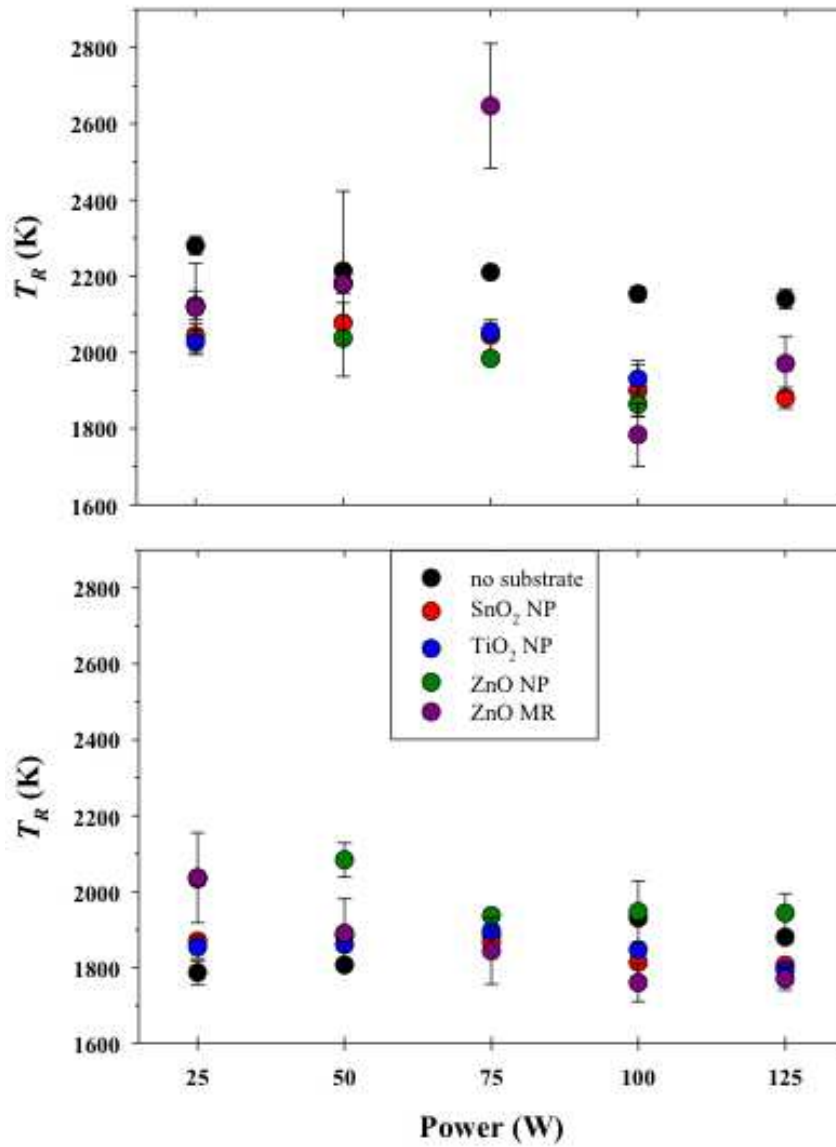


Figure A.3. $T_R(\text{CH})$ data as a function of applied rf power for a CH_4 plasma without and with substrates at (a) $p = 100$ mTorr and (b) $p = 200$ mTorr.

Table A.3. $T_R(\text{CH})$ (K) values in a CH_4 plasma without and with substrates.^a

p (mTorr)	P (W)	no substrate	SnO_2 NP	TiO_2 NP	ZnO NP	ZnO MR
100	25	2280 (20)	2050 (30)	2030 (30)	2120 (40)	2120 (120)
	50	2210 (10)	2080 (50)	2180 (20)	2040 (10)	2370 (110)
	75	2210 (10)	2040 (40)	2050 (20)	1980 (10)	2770 (60)
	100	2150 (20)	1900 (70)	1930 (50)	1860 (30)	1780 (80)
	125	2240 (20)	1880 (30)	--	--	1970 (70)
150	25	1910 (20)	1940 (10)	2030 (30)	1980 (20)	1990 (100)
	50	1960 (10)	1950 (10)	1980 (20)	1980 (60)	1700 (90)
	75	2070 (10)	1960 (10)	1970 (10)	1880 (20)	1730 (50)
	100	2010 (10)	1950 (20)	1930 (40)	1980 (40)	2130 (70)
	125	1980 (40)	1890 (20)	1880 (30)	1900 (50)	2030 (40)
200	25	1790 (30)	1870 (10)	1850 (30)	2030 (20)	2040 (120)
	50	1810 (10)	1880 (20)	1860 (10)	2080 (40)	1890 (90)
	75	1880 (10)	1870 (30)	1900 (10)	1940 (10)	1840 (50)
	100	1930 (10)	1810 (10)	1850 (10)	1950 (80)	1760 (50)
	125	1880 (10)	1810 (10)	1790 (20)	1940 (50)	1770 (30)

^aValues in parentheses represent standard deviation calculated from the mean of $n \geq 3$ trials.

without a substrate in Chapter 3.¹³ The addition of a substrate to the plasma may impact rotational cooling pathways by providing an extra surface for collisional cooling leading to the lower $T_R(\text{H}_2)$ and $T_R(\text{CH})$ values. Rotational relaxation is a relatively fast process as fewer than ten collisions are typically required to reach equilibrium.¹⁴ Thus, although $T_R(\text{CH})$ is reduced with the addition of the catalyst to the discharge at $p = 100$ mTorr, at $p = 150 - 200$ mTorr $T_R(\text{CH})$ values for the catalyst systems are generally within experimental error of the no catalyst system, indicating that gas-phase rotational cooling processes are likely the principal processes occurring at these increased pressures.

T_V for excited state CH are listed in Table A.4, and values range from $\sim 2000 - 4000$ K over the parameter space. At $p = 100$ mTorr, Figure A.4a, $T_V(\text{CH})$ is significantly reduced (~ 300 K – 1200 K) upon addition of a catalyst to the discharge. This trend generally holds true for both SnO₂ NP and TiO₂ NP substrates at each pressure; however, somewhat different trends are noted for both the ZnO NP and ZnO MR catalysts. For the ZnO substrates, as pressure is increased to 200 mTorr, Figure A.4b, $T_V(\text{CH})$ values are generally higher than the no substrate system at $P \leq 50$ W, but at $P \geq 75$ W, $T_V(\text{CH})$ values for the ZnO catalyst systems are the same as a system without a substrate. This observed decrease of $T_V(\text{CH})$ with increasing P documented for the ZnO catalysts in Figure A.4b may be related to the plasma mode which shifts from E-mode (low plasma density) to H-mode (higher plasma density) at $\sim 75 - 100$ W. A previous study from the Fisher research group noted that the discharge mode and the resulting rotational and vibrational distributions appear to be interrelated for one of the three catalysts included in that study.¹⁵ Although $T_V(\text{CH})$ decreases upon the addition of SnO₂ NP and TiO₂ NP catalysts at all pressures, this vibrational cooling effect is only significant at low pressure ($p = 100$ mTorr) for the ZnO catalysts. A pressure dependence for $T_V(\text{CH})$ is also worth mentioning for the data presented in

Table A.4. $T_V(\text{CH})$ (K) values in a CH_4 plasma without and with substrates.^a

p (mTorr)	P (W)	no substrate	SnO_2 NP	TiO_2 NP	ZnO NP	ZnO MR
100	25	3440 (20)	2750 (100)	3100 (150)	3070 (60)	2880 (190)
	50	3420 (60)	2970 (140)	3020 (50)	2920 (60)	3000 (180)
	75	3340 (60)	2780 (50)	2980 (60)	2670 (20)	2110 (80)
	100	3180 (60)	2540 (50)	2570 (50)	2390 (20)	2380 (80)
	125	3140 (40)	2680 (30)	--	--	2130 (70)
150	25	2610 (10)	2150 (30)	2680 (70)	3440 (430)	3200 (170)
	50	2910 (20)	2230 (20)	2480 (50)	2930 (130)	3490 (370)
	75	3310 (60)	2330 (30)	2620 (40)	2710 (130)	3690 (290)
	100	3090 (30)	2740 (70)	2690 (30)	2870 (150)	2140 (120)
	125	3010 (110)	2650 (100)	2680 (120)	2440 (30)	2780 (200)
200	25	2280 (10)	2060 (40)	2060 (10)	3560 (210)	3600 (40)
	50	2340 (20)	2140 (40)	2060 (10)	3110 (30)	2940 (330)
	75	2680 (20)	2070 (40)	2230 (10)	2870 (460)	2380 (120)
	100	2790 (20)	2180 (30)	2180 (20)	2550 (90)	2880 (360)
	125	2810 (10)	2060 (20)	2110 (10)	2720 (30)	2500 (40)

^aValues in parentheses represent standard deviation calculated from the mean of $n \geq 3$ trials.

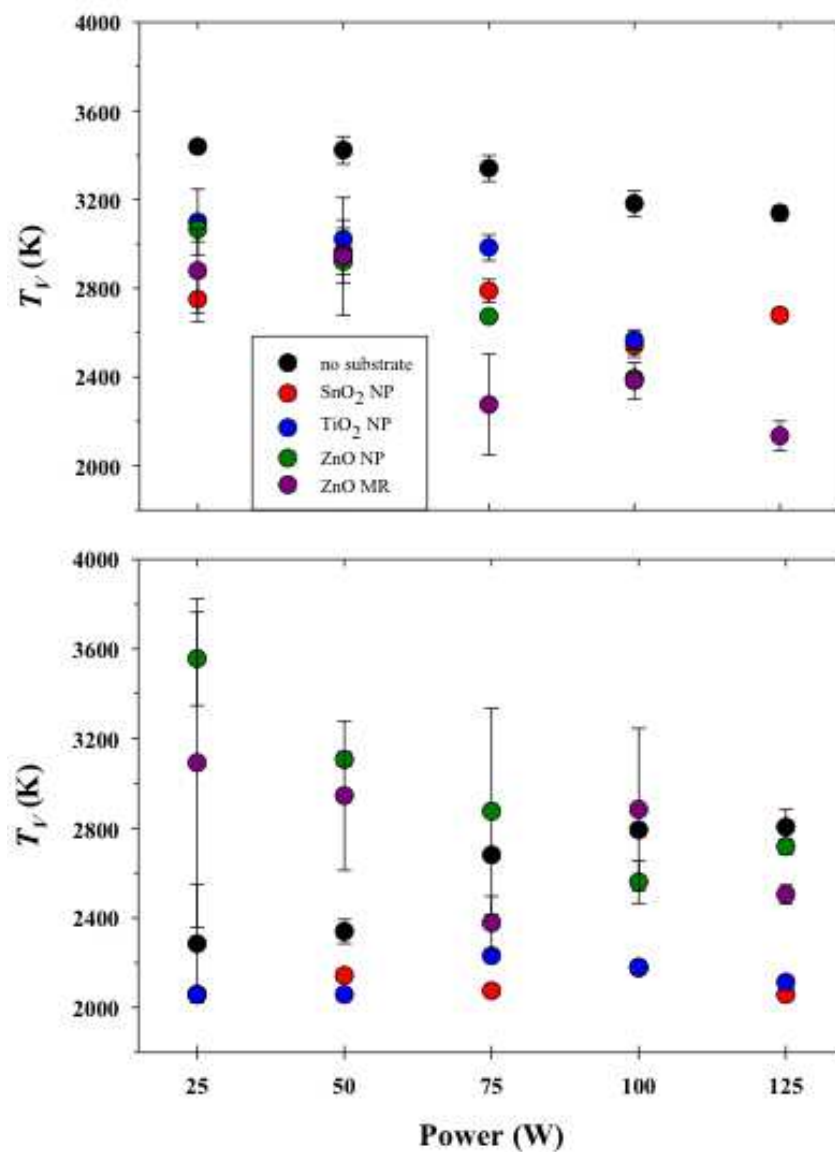


Figure A.4. $T_V(\text{CH})$ data as a function of applied rf power for a CH_4 plasma without and with substrates at (a) $p = 100$ mTorr and (b) $p = 200$ mTorr.

Figure A.4a. $T_V(\text{CH})$ values generally decrease with increasing pressure for CH_4 plasma systems without a substrate and with SnO_2 NP or TiO_2 NP whereas ZnO NP and ZnO MR substrates display minimal pressure dependence for $T_V(\text{CH})$. Overall, our data demonstrate that both material morphology (Figure A.2) and chemical identity (Figure A.4) may have a significant impact on gas-phase processes. To gain additional insight into these phenomena, it would be beneficial to characterize the chemical characteristics of the catalysts both before and after plasma exposure and to study the plasma-surface interface.

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APPENDIX B

INDEPENDENT RESEARCH PROPOSAL

This appendix contains the entirety of an independent research proposal, entitled *Utilizing Cold Plasma and Polymer Blending to Develop Defect-Free Mixed Matrix Membranes for CO₂ Gas Separations*, prepared by Tara L. Van Surksun in partial fulfillment of the doctoral requirements of the Department of Chemistry at Colorado State University. It details the combined approach of utilizing plasma-based fabrication methods and performance testing to better understand material structure-function relationships with the goal of developing defect-free mixed matrix membranes.

B.1 Abstract

Mixed matrix membranes (MMMs) have the potential to be an efficient and effective method for capturing and removing CO₂ from industrial sources; yet, there are significant limitations currently inhibiting MMM implementation. Particle agglomeration of the inorganic fillers, poor distribution throughout the polymeric matrix, and poor interfacial compatibility between the polymer and filler hinder advances toward increasing both the permeability and selectivity of these membranes. The overarching goal of this proposal is to design and develop MMMs that will address these materials-based limitations with novel fabrication approaches. Our tactics will feature the use of both cold plasma and polymer blending to ultimately develop MMMs with enhanced permeability and selectivity towards CO₂. The use of these techniques during the fabrication process allows for creating a material with highly tunable chemical properties. Importantly, we also seek to understand how to tailor the chemical and physical

properties of the material for enhanced separations performance. Gas permeation experiments will allow us to determine the efficacy of these strategies. Additionally, comprehensive materials characterization will be coupled with performance testing results and fabrication methodologies to better understand material structure-function relationships. Such information will provide insight into understanding how to develop MMMs with the desired chemical and physical properties necessary for industrial scale implementation.

B.2 Background and Motivation

In 2017, global emission of CO₂ through combustion of fossil fuels exceeded 36 billion tons, 15% of which came from the United States.¹ Escalating atmospheric CO₂ concentrations disturb the global carbon cycle causing additional adverse effects such as global warming and ocean acidification.² Although renewable energy consumption continues to rise,³ fossil fuel-based energy sources are expected to remain a vital component to the world's energy resources for the next several decades;⁴ thus, mitigation of industrial sources of CO₂ must be addressed. To overcome these increasing environmental concerns, researchers are adopting various technologies to remove and capture CO₂ from flue gases. As most costs associated with carbon capture and storage are associated with the capture component,⁵ cost reductions can be achieved through development of innovative separation technologies.

Membrane-based technology is a promising approach towards CO₂ capture and separations development.⁶⁻⁸ Compared to other conventional separations approaches, membranes are low cost, energy efficient, and environmentally sustainable.^{7,9-10} Gas separation membranes must have high permeability and high selectivity for efficient and economic CO₂ separation. Polymeric membranes have been extensively studied for gas separation,^{6,10-11}

however, there is a tradeoff limit between selectivity and permeability with polymer membranes,¹² constraining their potential for industrial gas separation. Recently, mixed matrix membranes (MMMs), membranes containing a bulk polymer phase and an inorganic filler phase, have gained significant interest for CO₂-based separations. MMMs combine the desirable properties of both polymer membranes (i.e., cost effective, large-scale production) and inorganic membranes (i.e., enhanced selectivity and permeability, chemical and thermal stability) for enhanced material performance. The incorporation of inorganic fillers into the polymer matrix can increase affinity for CO₂ and improve gas diffusivity by increasing the free volume between polymer chains.^{5,7} Moreover, fillers can enhance the physical properties of the membranes including thermal stability, mechanical strength, and stability against physical aging.⁵

Currently, MMM performance requires further improvements for industrial scale implementation. Both permeability and selectivity must be enhanced to improve the overall performance. Challenges inhibiting material development are highlighted in Figure B.1 and include particle agglomeration or sedimentation of the fillers and poor interfacial compatibility between polymer and filler.^{5, 8, 13-14} These undesirable filler/polymer interface morphologies can include voids, matrix rigidification, or blocked pores.⁷⁻⁸ Voids form when there is poor interfacial adhesion between the polymer and the filler. This leads to increased permeability and reduced selectivity by providing a lower resistance pathway for gas molecules. Matrix rigidification occurs when a rigid polymer layer forms around the filler, causing immobilization of the polymer chain, ultimately leading to decreased permeability and increased selectivity. The blocked pore morphology occurs when the inorganic filler is partially or fully blocked by the rigidified polymer. Partial pore blockage has the same effect on MMMs as matrix rigidification, whereas complete pore blockage significantly reduces both permeability and selectivity.

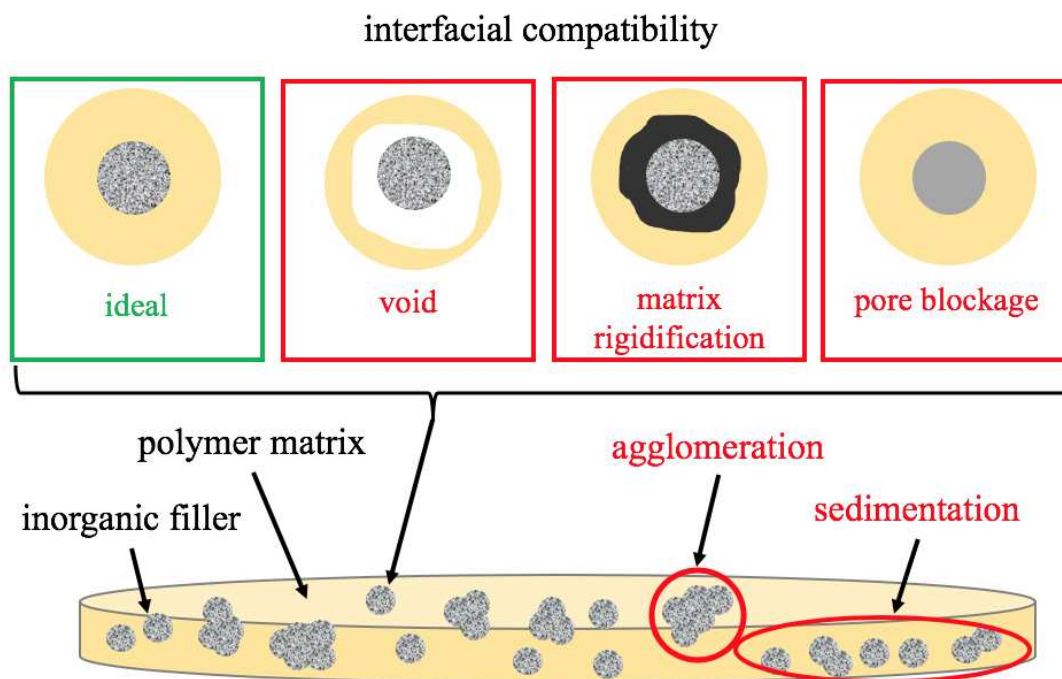


Figure B.1. Diagram illustrating challenges in MMM fabrication.

Typically, fillers are chosen based on their gas sorption behavior and pore sizes;¹⁴ common filler choices include zeolites, silica, carbon molecular sieves (CMS), carbon nanotubes, metal-organic frameworks, and metal oxides.^{8, 13-14} Yet, filler selection remains a major challenge in MMM fabrication and design because of the compatibility issues discussed above. Consequently, current efforts towards MMM development have focused on choosing compatible polymers and fillers and utilizing different polymer/filler combinations for creation of novel materials.

Researchers have also utilized chemical modification to alter surface and interfacial properties as a strategy to overcome compatibility challenges. For example, the use of coupling agents has been widely explored to improve interfacial interactions in MMMs.¹⁴⁻¹⁵ Introducing additional agents into the membranes, however, often leads to undesired pore blocking, ultimately reducing gas permeability.¹⁴⁻¹⁵ Hence, alternative approaches, such as plasma surface modification are necessary. Although plasma modification has also been used sparingly in the development of MMMs, it has promising potential as a more efficient and environmentally friendly approach for surface modification compared to wet chemical methods that produce hazardous waste.¹⁶

Sustainable performance of MMMs remains an important additional consideration for industrial scale implementation purposes. Under high pressure conditions, the dissolution of different penetrants in the material disrupts the polymer structure, rendering the polymeric phase of the membrane susceptible to CO₂-induced plasticization and swelling.^{6, 8} Although incorporation of the inorganic component partially aids in overcoming stability issues presented in traditional membranes, MMMs still encounter problems with plasticization and swelling.⁶ As plasticization causes a significant loss in gas selectivity, the development of new polymer matrices via grafting, blending, and crosslinking is warranted for overcoming any material

shortcomings. Thus, employing novel fabrication and modification methods for the polymer phase is regarded as a necessary approach for the development of defect-free MMMs.⁹

To address current MMM limitations, new fabrication and modification approaches must be explored. For example, polymer blending has not been widely studied in combination with inorganic filler materials, but has shown promising potential for gas separation applications.⁸ Additionally, plasma treatment has shown potential particularly for modification of inorganic fillers. For example, de Clippel *et al.* utilized cold N₂ plasma to impart nitrogen functionalities onto carbon-silica microsphere fillers.¹⁷ They found that plasma functionalization of the filler increased CO₂ gas selectivity in CO₂/H₂ mixtures compared to literature values, with only a slight concomitant drop in membrane permeance. Plasmas offer a wide, tunable parameter space to tailor material surface properties for desired functionalities. Plasma-based methods are an environmentally friendly alternative to other methods and can be scaled up for commercial use. Finally, thoughtful selection of polymers and fillers remains a crucial component to advancing MMM technology as material-environment interactions are highly dependent on the inorganic constituent and polymer matrix properties. Exploration of promising polymer/filler combinations remains vital to MMM research.^{8, 14} Our approach will utilize both polymer blending and plasma modification tools, as these are promising, largely unexplored solutions to MMM development.

B.3 Specific Aims

The goal of the proposed research is to fabricate MMMs with high permeability and selectivity for CO₂ gas separations, while maintaining the desirable physical characteristics necessary for industrial scale implementation. Moreover, we seek to understand how the

physical and chemical properties of the membrane can be tuned to optimize material performance. This requires a molecular-level understanding of the material structure-function relationship. To this end, we will address the following three specific aims:

1. Develop fully integrated polymer/inorganic composite membranes. Fabrication of MMMs will focus on creating materials with a uniform distribution of inorganic fillers and high interfacial contact area between fillers and the polymer matrix. Multiple fabrication and surface modification strategies will be employed in conjunction with different polymer/filler combinations to fabricate fully integrated MMMs.
2. Evaluate and optimize chemical and mechanical properties of MMMs. Materials analyses coupled with performance testing will be used to tune and optimize fabrication methodologies for desired physical and chemical properties.
3. Achieve an understanding of material structure-function relationships. Expand fundamental understanding of the relationship between material characteristics and MMM performance.

B.4 Proposed Work

Development of Fabrication Methodologies. The first phase of this project will focus on developing fabrication strategies for producing defect-free MMMs. A combination of fabrication methodologies and surface modification strategies will be employed to tune material properties for improved membrane properties and performance. Importantly, the approach necessitates mindful selection of the polymers and fillers utilized to fabricate MMMs with the desired chemical and physical properties. Thus, we outline below several polymers and fillers

with unique chemical and mechanical properties that may be useful when designing our materials. Additionally, strategic fabrication and modification methods critical to overcoming challenges currently inhibiting MMM implementation will be discussed below.

Selection of Polymers and Inorganic Fillers. Our studies will employ a variety of polymers and polymer blends with well-known gas separation properties. Polysulfones and polyimides are commonly used polymers for gas separation applications. Their high thermal stability, chemical resistance, and excellent gas separation properties allow them to withstand the aggressive feed conditions often found in industrial settings.^{6, 8} As such, initial studies will utilize both polysulfones [including polysulfone (PSF) and polyethersulfone (PES)] and polyimides [including polyimide (PI) and polyetherimide (PEI)] in our fabrication investigations. We will also use polyethylene glycol (PEG) polymers in our MMM fabrication process because of its strong affinity towards CO₂ molecules.⁸ Each of these polymers has been used in conjunction with various fillers to create MMMs with enhanced performance (i.e., selectivity, permeability) compared to their corresponding traditional membrane.¹⁸⁻²⁰ Additionally, PEG is commonly studied as an additive to improve gas separation performance in polymeric membranes. Improvements in both selectivity and mechanical strength are reported with these PEG blended membranes.²¹ Thus, our studies will include investigations into polymer blending within MMMs as a method to tune material properties. This is discussed in further detail below.

Optimizing filler loading percentage is another key to creating MMMs that are both permeable and selective, yet structurally sound enough to endure the sometimes-harsh conditions required for MMM implementation at the industrial scale. Thus, our fabrication processes will include investigations of different filler loading percentages. Our investigations will include a few common types of fillers that have been used in MMM development for their desirable

chemical properties. Zeolites, in particular, are commonly used in MMMs because their defined pore structure and size-selective nature make them attractive for separations applications.

Although various types of zeolites have been used as MMM fillers, zeolite 4A, zeolite NaY, and ZSM-5 appear to be the most promising zeolite choices for CO₂ separations.^{7-8, 13} A pore size of 3.8 Å for zeolite 4A, for example, is close to the kinetic diameter of CO₂ (3.3 Å),⁷ allowing for ideal separations properties for CO₂ separation and capture. Conversely, the pore size of zeolite NaY is much larger (~9 Å),⁷ which can facilitate gas diffusion and increase permeability. Moreover, Y-type zeolites are often chosen over X-type zeolites because their larger Si/Al ratio and lower number of coordinated cations can lead to higher CO₂ adsorption capacity, consequently favoring CO₂ separations.²² Such information is essential to consider while designing and optimizing our materials.

Silica and CMS, other common filler options, will also be utilized in our MMM fabrication investigations. Both nonporous and mesoporous silica particles have been utilized as the inorganic component in MMMs.²³ Nonporous silica particles do not participate in gas transport. Rather, they change the molecular packing of the polymer chains around the filler particles and consequently, increase free volume in the membrane.²³ If the free volume is too large, however, selectivity substantially decreases. Additionally, the large pore sizes create a major drawback of mesoporous silica, as they are commonly too large to achieve size selectivity.¹⁴ Mesoporous silica, however, exhibits better filler-polymer interaction than most other molecular sieves because of its higher surface area and attached silanol groups which are able to create hydrogen bonds with the polymer chain.⁷ Although increased interfacial compatibility is exhibited with mesoporous silica particles, voids still exist within the material, leaving room for improvement in material design.

CMS are highly porous materials with pore sizes similar to gas molecules. These properties ensure high gas permeability and allow discrimination of certain gas species. Vu *et al.* studied the gas separation performance of MMMs comprising CMS and Matrimid® 5218 and reported a 45% increase in CO₂/CH₄ selectivity for the MMM over the Matrimid® matrix alone.²⁴ The authors also claimed that CMS exhibited better interfacial compatibility with the polymer than the zeolites.

Fabrication and Modification Methods. Although selection of appropriate polymer matrices and inorganic fillers in MMMs can help overcome some challenges associated with material development, often materials properties are still far from ideal for their desired applications. Thus, additional fabrication methods or modifications may be necessary to create defect-free MMMs. As discussed above, substantial work on various approaches to modify both the polymer and inorganic phases of MMMs has been performed to overcome challenges hindering advancement of MMMs. We will employ several strategies to fabricate and modify MMMs, outlined here.

Polymer Blending. One noteworthy approach to combat the permeability/selectivity tradeoff limit of polymer membranes has been to modify membrane properties via blending techniques.^{8, 21} Polymer blending yields the benefits of two different polymers to enhance separation properties. Although this approach has also been used extensively to overcome plasticization issues in CO₂ separation membranes,^{8, 21} research into using polymer blending in MMMs is limited.⁸ A recent review article by Wong *et al.* illustrates that while blending modifications can significantly enhance membrane properties, many polymer blends still fall below the Robeson upper bound limit.⁸ Thus, additional research into the separation properties of different polymer blends is needed. Furthermore, other types of modification may be

necessary to surpass the upper bound limit. Incorporating inorganic fillers into polymer blended matrices may help overcome the limitations currently hindering separations properties of both polymer-blended membranes and MMMs. Thus, our fabrication approaches will include creating polymer blended MMMs by using various polymer blends and inorganic fillers. Via blending, we can tune our membrane properties (e.g., CO₂ affinity, polymer rigidity, plasticity resistiveness) by combining different ratios of polymers to create MMMs with more desirable properties than a construct formed from a single polymer. As briefly mentioned above, PEG has been frequently used in blended polymeric membranes to enhance CO₂ affinity. Additionally, PI blends are common for CO₂ separations because PI has excellent thermal and mechanical stability and high selectivity despite its low permeability and plasticization resistance.²¹ Thus, we will start with blends that incorporate these polymers and include inorganic fillers, such as zeolites, into the matrix. Although polymer blending may improve MMM permeability or selectivity, we suspect compatibility issues between the polymer and filler may remain, and additional modification methods may be necessary to overcome interfacial compatibility challenges.

Plasma Surface Modification and Plasma-Induced Grafting. Although inorganic fillers can enhance diffusivity and selectivity in membranes, they often suffer from poor compatibility and interfacial adhesion within the polymer matrix. Plasma modification provides an alternative route to modify fillers or polymer matrices and avoid undesirable polymer-interface morphologies. Plasmas can modify surface properties of materials via etching, deposition, or functionalization while still retaining the material's bulk characteristics. Plasma has been notoriously used as a tool for polymer membrane modification,²⁵⁻²⁷ yet, its use in MMM modification has been minimal. Advantages of plasma-surface modification include a highly

tunable parameter space (e.g., precursor, pressure, power, substrate placement), low processing temperatures, and the ability to modify virtually any type of material. Proposed experiments will utilize plasma to modify both the polymer and inorganic components of MMMs.

Inorganic filler modification will be performed via a rotating drum radio frequency (rf) plasma reactor. The rotating drum allows for the ability to modify unsupported and unusually shaped materials. A detailed schematic of the design of this reactor has been previously published.²⁸ Experiments performed by Shearer and Fisher validate an effective reactor design for multiple plasma processes.²⁸ For example, they utilized the reactor to examine the efficacy of both depositing (plasma polymerized allyl alcohol) and non-depositing NH_3 plasmas to effectively modify the surface of commercially purchased Fe_2O_3 nanoparticles. The viability of the rotating drum reactor to produce customizable surface chemistries for MMMs will be evaluated by exploring a range of plasma parameters. Both continuous wave (CW) and pulsed plasma conditions will be assessed in addition to reactor rotation speed. Furthermore, we will investigate additional plasma parameters (e.g., pressure, power, treatment time) to optimize the filler surface chemistry for incorporation into the polymer matrix.

Our studies will utilize both plasma-induced grafting and plasma surface functionalization techniques to modify the polymer and/or fillers. De Clippel *et al.* plasma treated carbon-silica fillers with cold N_2 plasma to introduce amine functionalities.¹⁷ These modifications resulted in increased mixed gas selectivity. As the introduction of amine functionalities improves affinity towards the acidic CO_2 ,²⁹ our initial studies will include use of N_2 - and NH_3 -based plasmas to functionalize filler surfaces.

Grafting techniques are among the approaches used to overcome both particle agglomeration and interfacial voids within the polymer matrix.⁷ Grafting of MMMs can be

performed by 1) grafting the polymer matrix or 2) grafting the inorganic fillers. For example, Liang *et al.* created highly hydrophilic polyvinylidene fluoride ultrafiltration composite membranes by plasma-induced graft copolymerization of poly(methacrylic acid).³⁰ This approach provided sufficient carboxyl groups as anchor sites for amine-functionalized silica nanoparticles to bind to and ultimately improved membrane performance. Similarly, Mauter *et al.* grafted silver nanoparticles with PEI and combined them with plasma functionalized PSF to create ultrafiltration membranes with improved separation properties over PSF alone.³¹ These studies demonstrate the effectiveness of surface grafting techniques for successfully incorporating inorganic particles into polymer matrices and ultimately improving membrane performance. With plasma-induced grafting, rare gas plasma irradiation creates active sites on the material surface and subsequent exposure to a polymerizing monomer results in the formation of the grafted layer. The extent of grafting on a surface can be controlled by plasma irradiation time or grafting time. Thus, this technique allows for controlled modification processes with the additional advantages of low processing temperatures (to avoid damage) and low-cost.

Additional Fabrication Considerations. Challenges associated with interface morphology and particle agglomeration can also be reduced by considering additional fabrication or post treatment methods. Polymer membranes are typically fabricated via casting, wherein the polymer is dissolved in a solvent and then molded to a desired thickness and allowed to dry. With MMMs, how the inorganic fillers are combined with the polymer can affect interfacial properties. For example, to avoid agglomeration, the “prime protocol”^{14, 32-33} is utilized, wherein a small amount of polymer solution is first added to the particle suspension to coat the inorganic particles with a thin layer of polymer. Then the remainder of the polymer solution is added to

the primed solution. Mahajan *et al.* demonstrated that “primed” zeolite 4A sieves resulted in higher successful filler loading compared to “unprimed” native zeolite. Thus, priming fillers could be a useful approach for optimizing filler loading.³² Another approach to achieve good particle dispersion involves adding the inorganic fillers to the solvent rather than the polymer solution before mixing the two separate solutions together.¹⁴ The resulting suspension has a low viscosity which allows for a high shear rate with vigorous stirring and consequently reduces agglomeration of the inorganic fillers.³⁴⁻³⁵ Moreover, post treatment methods such as thermal annealing can overcome low adhesion challenges between the fillers and polymer matrix as well as increase plasticity resistance.^{6, 14} As such, our approach will include these considerations when designing and optimizing our materials.

Materials Characterization. Materials will be characterized throughout the fabrication and modification processes to determine chemical bulk and surface properties. Filler properties will be assessed before and after surface modification to ensure the desired modification has been achieved. Additionally, MMMs will be characterized after filler incorporation within the polymer matrix to determine the presence of voids or particle agglomeration. Several types of analyses will be performed to comprehensively assess material morphology, chemical properties, and mechanical properties. Scanning electron microscopy will be utilized in conjunction with energy dispersive X-ray spectroscopy to examine material architecture and determine the degree of incorporation of inorganic fillers into the polymer matrix. X-ray diffraction, Fourier transform infrared spectroscopy, and X-ray photoelectron spectroscopy will be employed to determine bulk and surface chemistry before and after modification and fabrication processes. Additionally, mechanical properties essential for MMM commercial implementation will be assessed (e.g., thermogravimetric analysis, tensile strength, Young’s modulus). These materials

analyses will be utilized in conjunction with performance testing results to tune and optimize the chemical and mechanical properties of MMMs via our fabrication strategies.

Performance Testing. To address the second specific aim of the project, the performance of the materials will be assessed. Specifically, gas transport properties will be measured via variable pressure/constant volume permeation method, which measures the steady-state gas flux through a membrane of known thickness under a given pressure differential. A permeation chamber will be constructed to house the membrane and perform gas permeation measurements. We will measure the permeability of several gases (e.g., H₂, O₂, N₂, CO₂, CH₄) and gas mixtures chosen based on their relevancy to flue gas composition. Additionally, gas selectivity will be calculated from permeation measurements by using the ratio of the permeability coefficient of gas A over that of gas B.⁵ After permeation experiments, membranes will be analyzed using the characterization techniques described above to determine the effects of the permeation experiments on membrane properties. Consequently, permeation and selectivity data will be evaluated in conjunction with materials properties and fabrication techniques. When coupled with materials characterization data, gas permeability and selectivity results will provide insight into material structure-performance. The ability to correlate specific material properties and behavior will allow us to modify and tailor our fabrication approaches to design a material with the desired properties for improved performance.

Initial Experimental Plan. The approach outlined above provides details on several types of polymers, fillers, and fabrication/modification methods that could be explored and combined in many different ways with the goal of developing defect-free MMMs. A list of the materials and fabrication/modification methods described in this proposal are summarized and outlined in Table B.1.

Table B.1. Selection of polymers, fillers, and fabrication and modification approaches for MMMs.

Polymer Selection	Projected Outcome	Initial Studies
PSF, PES	high thermal stability, chemical resistance, and resistance to plasticization	X
PI, PEI	high thermal stability and chemical resistance, excellent gas separations properties	X
PEG	improved selectivity	
Filler Selection	Projected Outcome	
zeolite 4A	improved selectivity	X
zeolite NaY	improved permeability	X
mesoporous silica	enhanced interfacial compatibility	
CMS	high permeability and selectivity, good interfacial compatibility	
Fabrication & Modification Approaches	Projected Outcome	
polymer blending	tune CO ₂ affinity, polymer rigidity, and plasticity resistiveness	X
filler plasma modification (N ₂ - & NH ₃ -based plasmas)	incorporate amine functionalities for increased CO ₂ affinity and improved interfacial compatibility	X
plasma-induced grafting	enhance interfacial compatibility, reduce particle agglomeration	

Our approach will focus on fabrication methods that utilize plasma modification and polymer blending techniques because these are both promising, yet minimally explored approaches for MMM development. Initial studies will examine polymer blends of PSF and PI as several researchers have reported these blends exhibit good compatibility and increased gas separations performance over the native polymers.³⁶⁻³⁸ Additionally, filler selection is a critical consideration to MMM development. Zeolites have been widely studied as the inorganic component in MMMs because of their desirable gas separation properties. As such, zeolites will be the first filler we choose to explore in our studies. Even with careful material selection and polymer blending, however, we anticipate compatibility issues may persist between polymer and filler. Plasma modification of the filler will be the first route towards enhancing polymer/filler compatibility. We will utilize either N₂ or NH₃ plasmas to impart amine functionalities onto filler surfaces, as these systems previously resulted in improved interfacial compatibility and CO₂ separations.^{14, 17, 39} Overall, we anticipate these initial studies will result in new MMM fabrication approaches that demonstrate success via enhanced separations performance.

Potential Challenges and Resolutions. We designed our approach with multiple routes to both fabrication and surface tailoring, which should provide alternate routes around obstacles we may encounter. Thus, depending on the outcome of our initial studies, we may choose to examine different polymer blends or fillers based on the desirable properties they hold. Some strategies to overcome the possible challenges we may encounter are highlighted in Figure B.2. This roadmap highlights several fabrication approaches discussed throughout the body of this proposal to overcome challenges relating to both poor interfacial compatibility and particle dispersion. The roadmap will be referenced to adjust fabrication and modification procedures if we encounter MMM fabrication challenges.

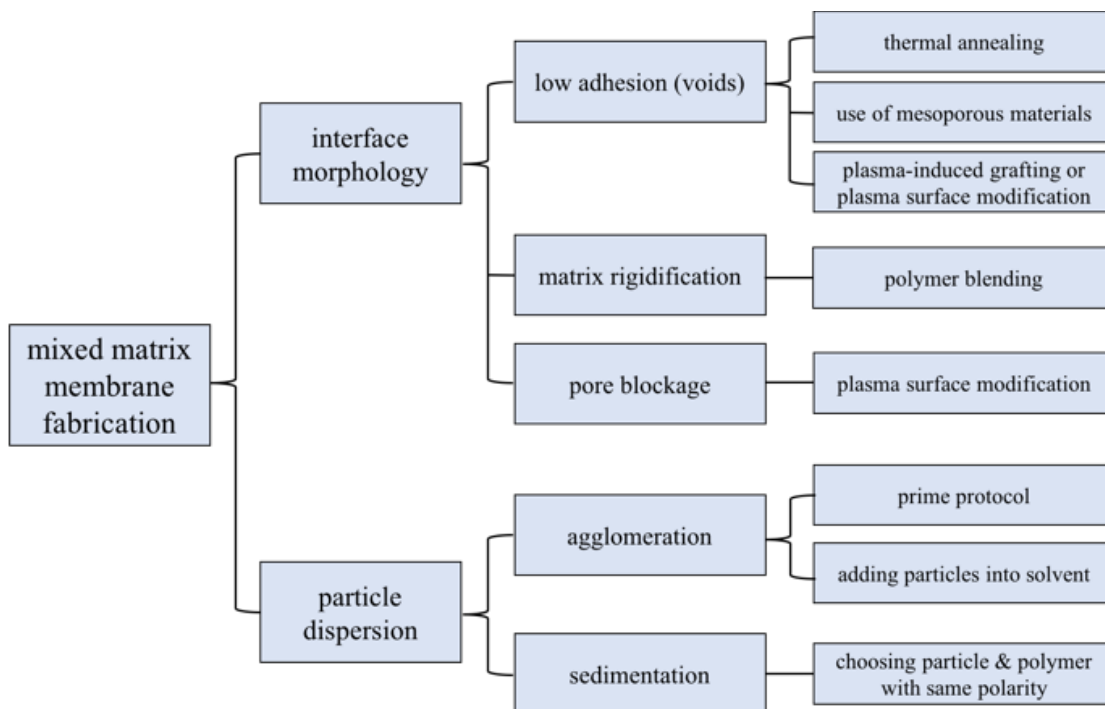


Figure B.2. Strategies to overcome MMM fabrication challenges.

B.5 Summary

The studies presented here offer a unique approach to designing and fabricating MMMs for use in gas separations applications. We anticipate the proposed approach will address current limitations inhibiting MMM development and provide an efficient and environmentally friendly alternative to traditional wet chemical methods typically used in MMM fabrication. Moreover, the tunable parameter space inherent to plasma-based methods will allow us to tailor and optimize materials properties for enhanced performance. Overall, via comprehensive characterization of the material throughout the fabrication, modification, and performance testing processes, our investigations will provide insight into the material-structure function relationships critical to advancing MMM technology.

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LIST OF ABBREVIATIONS

Ar	argon
BAS	broadband absorption spectroscopy
C _{1s}	carbon 1s (XPS spectrum)
CCD	charge coupled device
CH ₄	methane
CVD	chemical vapor deposition
DBD	dielectric barrier discharge
DLC	diamond-like carbon
e ⁻	electron
EDS	energy dispersive spectroscopy
EEDF	electron energy distribution function
E mode	inductance or electrostatic mode
FTIR	Fourier transform infrared spectroscopy
FWHM	full width at half maximum
H ₂	diatomic hydrogen
HC	hydrocarbon
H ₂ O	water
H mode	conductance or electromagnetic mode
ICP	inductively coupled plasma
IRIS	imaging of radicals interacting with surfaces
<i>K_B</i>	Boltzmann's constant
<i>k_d</i>	rate of destruction
<i>k_f</i>	rate of formation
LIF	laser-induced fluorescence
LTP	low temperature plasma
min	minute
MR	microrods
N _{1s}	nitrogen 1s (XPS spectrum)
N ₂	diatomic nitrogen
NO _x	nitrogen oxides
NP	nanoparticles
NTP	non-thermal plasma
O _{1s}	oxygen 1s (XPS spectrum)
OES	optical emission spectroscopy
<i>P</i>	applied radio frequency power
<i>p</i>	total system pressure
PAC	plasma-assisted catalysis
PC	peak correlation
PECVD	plasma enhanced chemical vapor deposition
rf	radio frequency
s	second
SEM	scanning electron microscopy
SnO ₂	tin (IV) oxide

t	time, plasma treatment time
T_e	electron temperature
T_g	gas temperature
T_i	ion temperature
Ti _{2p}	titanium 2p (XPS spectrum)
TiO ₂	titanium dioxide
T_R	rotational temperature
T_T	translational temperature
TR-OES	time-resolved optical emission spectroscopy
T_V	vibrational temperature
UT	untreated or no plasma treatment
VOCs	volatile organic compounds
WCA	water contact angle
XPS	x-ray photoelectron spectroscopy
ZnO	zinc oxide